Radiation Report

TPS7H1301-SP Total Ionizing Dose (TID) Report

ABSTRACT

This report discusses the total ionizing dose (TID) parametric results for the Texas Instruments TPS71301-SP, 3V to 6.3V input, 400mA, -6V to -0.6V radiation hardened switched capacitor voltage inverter with integrated low dropout regulator. The study was done to determine the TID effects under high dose rate (HDR) up to 100krad(Si). The results show that all samples passed within the specified limits up to 100krad(Si).

Table of Contents

List of Figures

List of Tables

Trademarks

Gammacell® is a registered trademark of MDS Nordion Inc..
All trademarks are the property of their respective owners.

1 Device Information

1.1 Product Description

The TPS7H1301-SP is a low noise regulated switched-capacitor voltage inverter with an integrated adjustable low dropout regulator designed for use in area sensitive, space environment applications.

Operating with an input voltage range of 3V to 6.3V, the TPS7H1301 delivers up to 400mA output current with an adjustable voltage range of -0.6V to -6V. The device features external compensation capability through direct error amplifier access via the STAB pin and operates at an internal switching frequency of 500kHz.

The TPS7H1301-SP is packaged in a 14-pin HBL ceramic flat package. A standard microcircuit drawing (SMD) is 5962R2421501VXC.

1.2 Device Details

Table 1-1 lists the device information used in this TID HDR characterization.

Table 1-1. Device and Exposure Details

TID Exposure Details	
TI Device	TPS7H1301-SP
TI Part Name	5962R2421501VXC
Package	14-pin HBL (CFP)
Technology	LBC7
Quantity Tested	20
Lot Accept/Reject	Passed up to 100krad(Si)
HDR Radiation Facility	Texas Instruments, Dallas, TX
HDR Dose Level	50 krad(Si), 100 krad(Si)
HDR Dose Rate	153.2rads(Si)/s
HDR Radiation Source	Gammacell® (Hopewell, GR420) Co-60
Irradiation Temperature	Ambient room temperature

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H1301-SP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, condition A was used. The product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production automated test equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H1301-SP HDR exposure was performed on biased and unbiased devices in a Co-60 gamma cell at the TI facility in Dallas, Texas. The unattenuated dose rate of this cell is 153.2rads(Si)/s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and full post-radiation electrical evaluation using Texas Instruments ATE was conducted. ATE test limits are set per datasheet electrical limits based on qualification and characterization data. Post-radiation measurements were taken within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR exposure were tested in two conditions (biased and unbiased) as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2-1 shows the diagram for HDR exposure with biased condition.

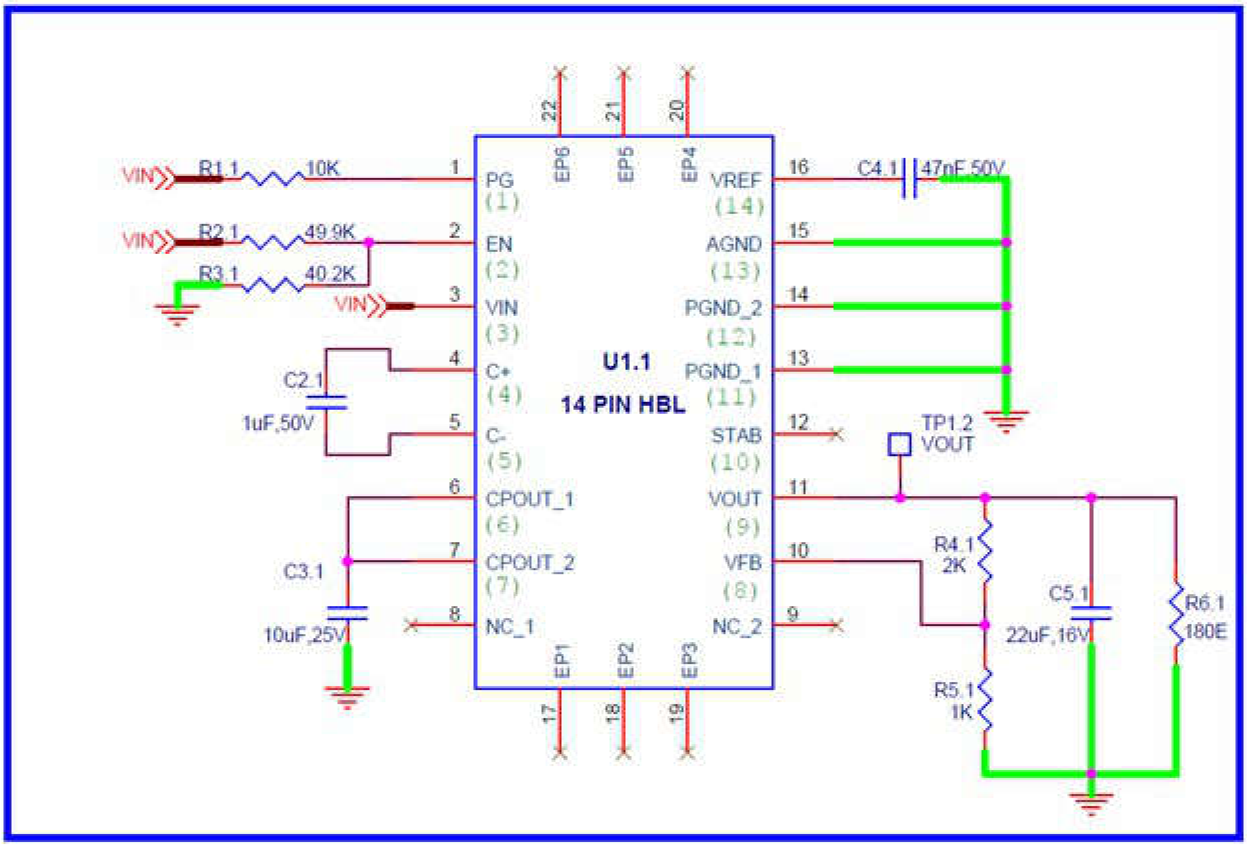


Figure 2-1. Bias Diagram Used in TID Exposure

2.4 Test Configuration and Condition

HDR devices were stressed at 50krad(Si) and 100krad(Si) for biased and unbiased conditions.

Table 2-1. HDR: 50krad (Si) and 100krad (Si)/s Biased Device Information

Total Samples: 10	
Exposure Levels	
50krad(Si)	100krad(Si)
45, 46, 47, 48, 49	55, 56, 57, 58, 59

Table 2-2. HDR: 50krad (Si) and 100krad (Si)/s Unbiased Device Information

Total Samples: 10	
Exposure Levels	
50krad(Si)	50krad(Si)
40, 41, 42, 43, 44	50, 51, 52, 53, 54

3 TID Characterization Test Results

3.1 TID Characterization Summary Results

The parametric data for the TPS7H1301-SP passes up to 100krad(Si) HDR TID irradiation. The drifts of the electrical parameters through HDR were within the datasheet limits.

Overall, the TPS7H1301-SP showed a strong degree of hardness to HDR TID irradiation up to 100krad(Si) for both biased and unbiased exposure conditions. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. The parameters that showed a greater degree of change between pre- and post-irradiation were still within the electrical performance characteristics specified in the datasheet electrical parameters. See *TPS7H130X-SP 3V to 6.3V Input, 400mA, -6V to -0.6V Radiation Hardened Switched Capacitor Voltage Inverter with Integrated Low Dropout Regulator* for the datasheet electrical parameters and associated tests.

See Appendix A for the HDR report up to 100krad(Si).

3.2 Specification Compliance Matrix

Over 3V ≤ V_{IN} ≤ 6.3V, $V_{OUT\ (set)}$ = -1.8, I_{OUT} = 10mA, C_{REF} = 47nF, over operating free-air temperature range (T_A = -55℃ to 125℃), typical values are at T_A = 25℃, unless otherwise noted.

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	Test No
POWER SUPPLIES and CURRENTS								
V_{UVLOR}	Input supply UVLO rising				2.7		V	60.2
V_{UVLOF}	Input supply UVLO falling				2.53		V	60.3
$V_{UVLO(HYS)}$	Input supply UVLO Hysteresis				150		mV	60.4
I_Q	Quiescent Current	I = 0A, V_{EN} = 7V			15	45	mA	31.3, 31.5, 205.2, 205.4
I_{SHDN}	Shutdown Current	V_{EN} = 0V, I_{OUT} = 0A			0.8	1.5	mA	31.2, 31.4, 205.1, 205.3
I_{FB}	Feedback leakage current	V_{FB} = -0.7V			100	500	nA	31.1
ENABLE								
$V_{EN(rising)}$	Enable rising threshold (turn-on)			0.57	0.6	0.625	V	65.2, 65.6
$V_{EN(falling)}$	Enable falling threshold (turn-off)			0.47	0.5	0.53	V	65.3, 65.7
$t_{EN(delay)}$	EN propagation delay,	EN high to PG high at VIN = 5V VIN = -1.8V			500	2300	µs	65.4, 65.8
$I_{EN(LKG)}$	Enable leakage current	V_{EN} = 7V			100	500	nA	65.1, 65.5
POWER GOOD								
$V_{PG(rise)}$	Power good rising threshold as a percent of V_{OUT}	SR VOUT = 10V/s		92%	95%	98%		71.3, 71.6
$V_{PG(fall)}$	Power good falling threshold as a percent of V_{OUT}	SR VOUT = 10V/s		87%	90%	93%		71.4, 71.7
$V_{PG(OL)}$	Power good output low	$I_{PG(SINK)}$ = 2mA			90	190	mV	70.3, 70.4
$V_{IN(MIN\_PG)}$	Minimum V_{IN} for valid PG (V_{PG} < 0.5V)	$I_{PG(sink)}$ = 0.5mA			0.8	1	V	71.1, 71.2,
$I_{PG(LKG)}$	Power good leakage	V_{PG} = 7V, V_{FB} = -0.7V			0.05	2	µA	70.1, 70.2
SWITCH CAP ARRAY								
$R_{DISCHARGE}$	CPOUT discharge resistance	C_{CPOUT} = 10µF	V_{CPOUT} = -0.3V		75		Ω	75.2, 75.4
$t_{DISCHARGE}$	CPOUT discharge time (CPOUT > -0.3V) to GND				6.5		ms	75.1, 75.3
f_{SW}	Switching frequency			400	500	600	kHz	35.1 to 35.6
$R_{DS(ON1)}$	Switch array MOSFET1 drain source resistance	I_{RDSON} = 100mA			300	480	mΩ	40.2
$R_{DS(ON2)}$	Switch array MOSFET2 drain source resistance	I_{RDSON} = 100mA			175	280	mΩ	40.5

3.2 Specification Compliance Matrix (continued)

Over 3V ≤ V_{IN} ≤ 6.3V, $V_{OUT\ (set)}$ = -1.8, I_{OUT} = 10mA, C_{REF} = 47nF, over operating free-air temperature range (T_A = -55℃ to 125℃), typical values are at T_A = 25℃, unless otherwise noted.

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	Test No
$R_{DS(ON3)}$	Switch array MOSFET3 drain source resistance	I_{RDSON} = 100mA			235	300	mΩ	40.3
$R_{DS(ON4)}$	Switch array MOSFET4 drain source resistance	I_{RDSON} = 100mA			220	350	mΩ	40.6
$R_{CP(OUT)}$	Output resistance to $C_{P(OUT)}$	I_L = 150mA	V_{IN} = 3V		4.5		Ω	80.1
		I_L = 250mA	V_{IN} = 5V		3.5			80.2
			V_{IN} = 6.3V		3.1			80.3
DROPOUT								
I_{DO}	Dropout current	$V_{OUT(set)}$ = -1.8V $I_{OUT(meas.)}$ = 98% × $V_{OUT(NOM)}$	V_{IN} = 3	75	125		mA	44.1
			V_{IN} = 3.3	100	150			44.2
			V_{IN} = 4	200	300			44.3
			V_{IN} = 5	400				44.4
			V_{IN} = 6	400				44.5
		$V_{OUT(set)}$ = -5V $I_{OUT(meas.)}$ = 98% × $V_{OUT(NOM)}$	V_{IN} = 5.5	40	50			44.6
			V_{IN} = 6	250	300			44.7
ACCURACY								
V_{ACC}	Output voltage accuracy	V_{IN} = 3V, V_{OUT} = -0.6V,	I_{OUT} = 1mA	-1.5%		1.5%		50.1
			I_{OUT} = 150mA	-1.5%		1.5%		50.2
		V_{IN} = 3V, V_{OUT} = -1.2V,	I_{OUT} = 150mA	-1.5%		1.5%		50.5
		V_{IN} = 3V, V_{OUT} = -1.8V,	I_{OUT} = 1mA	-1.5%		1.5%		50.6
			I_{OUT} = 150mA	-1.5%		1.5%		50.7
			I_{OUT} = 400mA	-1.5%		1.5%		50.10
		V_{IN} = 6.3V, V_{OUT} = -0.6V,	I_{OUT} = 1mA	-1.5%		1.5%		50.3
			I_{OUT} = 400mA	-1.5%		1.5%		50.4
		V_{IN} = 6.3V, V_{OUT} = -5V,	I_{OUT} = 1mA	-1.5%		1.5%		50.11
			I_{OUT} = 250mA	-1.5%		1.5%		50.12
		V_{IN} = 6.3V, V_{OUT} = -6V	10mA	-3%		3%		50.13
$\Delta V_{OUT}/\Delta V_{IN}$	Line regulation	3.3V ≤ V_{IN} ≤ 6.3V	ΔV = 3V I_{OUT} = 150mA		100	1300	µV/V	55.1, 55.2
$\Delta V_{OUT}/\Delta I_{OUT}$	Load regulation	10mA ≤ I_{OUT} ≤400mA V_{IN} = 5V, V_{OUT} = -1.8V			8	35	mV/A	55.3
V_{REF}				-0.606	-0.6	-0.594	V	30.1, 30.2, 30.3

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H130X-SP 3V to 6.3V Input, 400mA, -6V to -0.6V Radiation Hardend Switched Capacitor Voltage Inverter with Integrated Low Dropout Regulator* datasheet

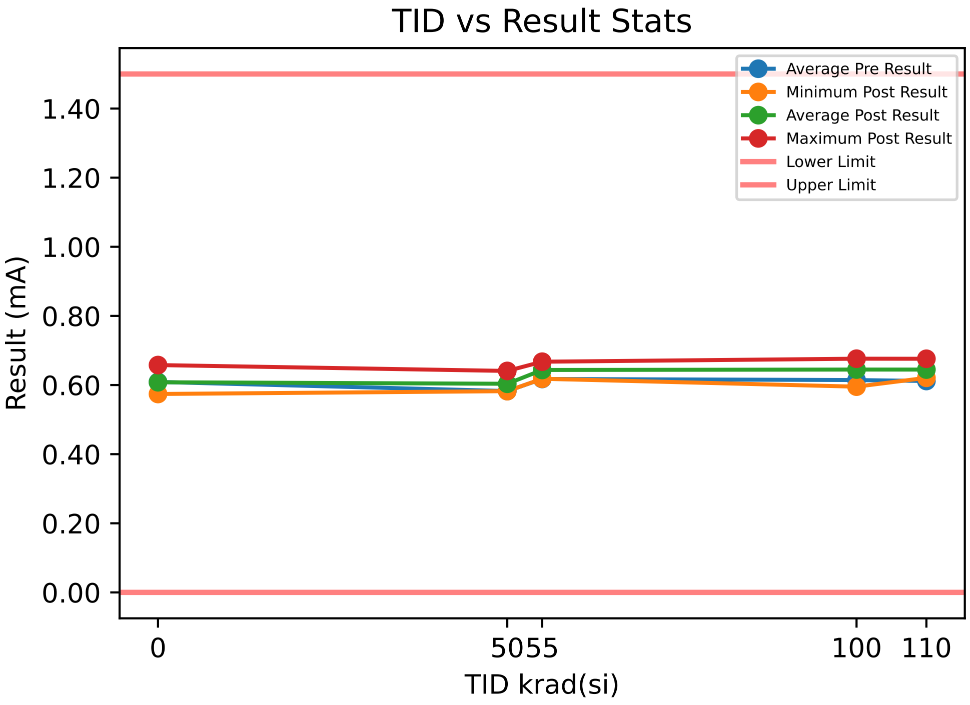
4.2 Reference Documents

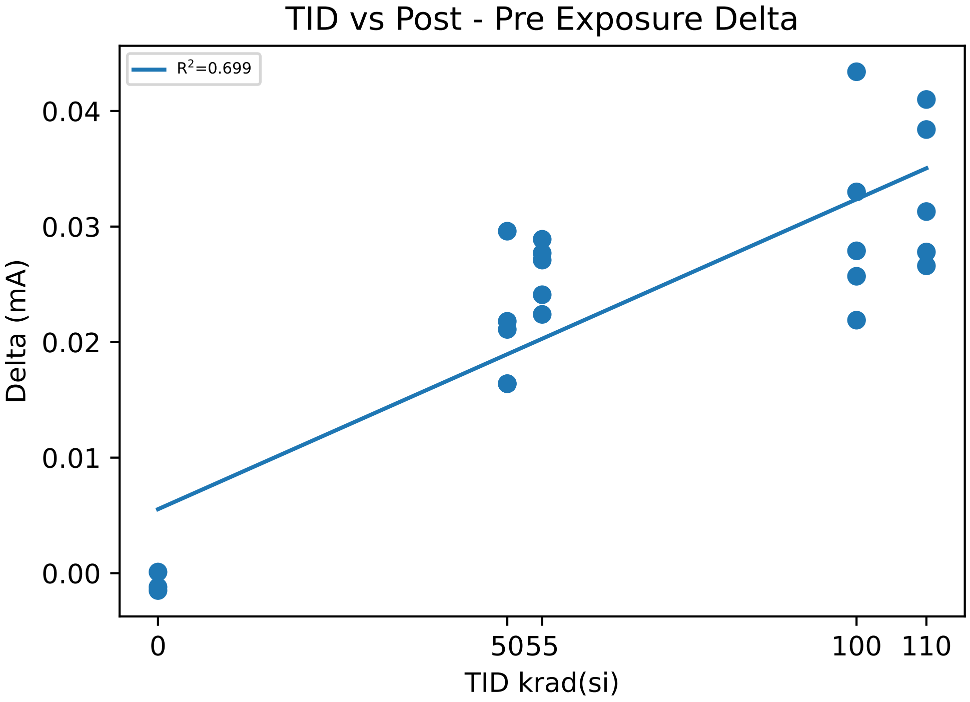
Texas Instruments' total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

A Appendix: HDR TID Report Data

This appendix contains the HDR TID report data.

Device Test: 205.1 SUPPLY_CURRENT|POST/VIN/SHUTDOWN///3/@I_SHDN





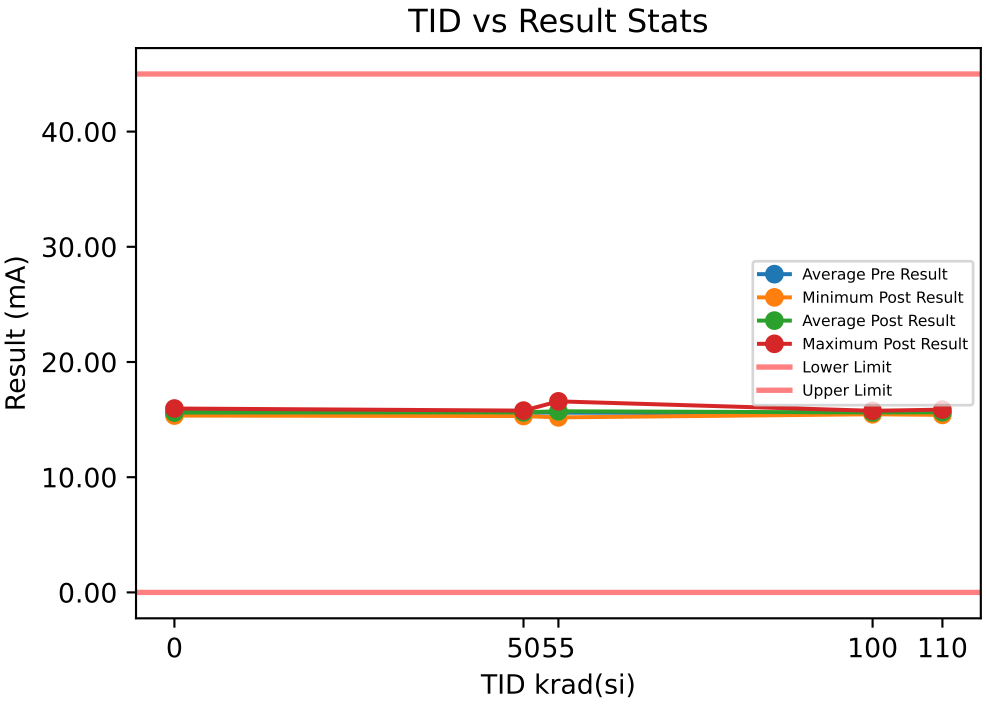
Test Results (Lower Limit = 0.0, Upper Limit = 1.5 (mA))

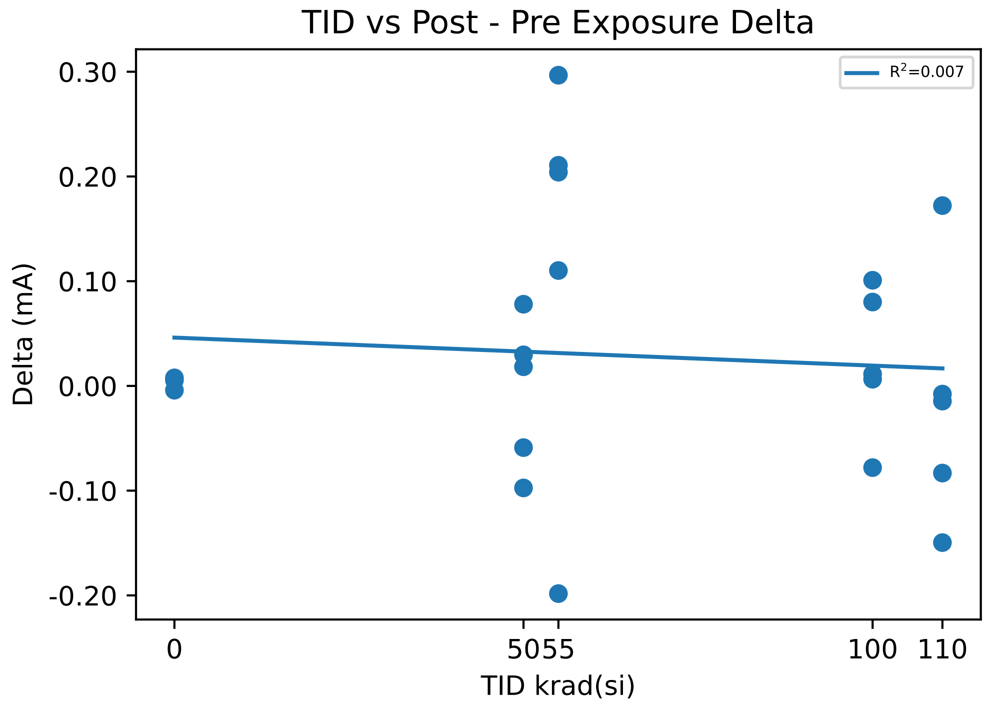
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.659	0.6578	-0.0012
2	0	CU	0.5923	0.5924	0.0001
3	0	CU	0.5756	0.5741	-0.0015
40	50	50krad Unbiased	0.5798	0.6009	0.0211
41	50	50krad Unbiased	0.5659	0.5823	0.0164
42	50	50krad Unbiased	0.5677	0.5895	0.0218
43	50	50krad Unbiased	0.6112	0.6408	0.0296
44	50	50krad Unbiased	0.5884	0.6048	0.0164
45	55	50krad Biased	0.6434	0.6675	0.0241
46	55	50krad Biased	0.5911	0.6182	0.0271
47	55	50krad Biased	0.607	0.6347	0.0277
48	55	50krad Biased	0.6076	0.6365	0.0289
49	55	50krad Biased	0.6386	0.661	0.0224
50	100	100krad Unbiased	0.6432	0.6762	0.033
51	100	100krad Unbiased	0.626	0.6694	0.0434
52	100	100krad Unbiased	0.5734	0.5953	0.0219
53	100	100krad Unbiased	0.6153	0.6432	0.0279
54	100	100krad Unbiased	0.6142	0.6399	0.0257
55	110	100krad Biased	0.6191	0.6469	0.0278
56	110	100krad Biased	0.5896	0.6209	0.0313
57	110	100krad Biased	0.6494	0.676	0.0266
58	110	100krad Biased	0.5998	0.6408	0.041
59	110	100krad Biased	0.6006	0.639	0.0384

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5756	0.60897	0.659	0.044127	0.5741	0.6081	0.6578	0.044003	-0.0015	-0.00086667	0.0001	0.00085049
50	0.5659	0.5826	0.6112	0.018441	0.5823	0.60366	0.6408	0.022611	0.0164	0.02106	0.0296	0.0054063
55	0.5911	0.61754	0.6434	0.022479	0.6182	0.64358	0.6675	0.020302	0.0224	0.02604	0.0289	0.0026959
100	0.5734	0.61442	0.6432	0.025719	0.5953	0.6448	0.6762	0.03189	0.0219	0.03038	0.0434	0.0083119
110	0.5896	0.6117	0.6494	0.023608	0.6209	0.64472	0.676	0.019992	0.0266	0.03302	0.041	0.0064041

Device Test: 205.2 SUPPLY_CURRENT|POST/VIN/QUIESCENT///3/@IQ_VIN


TID vs Result Stats


TID vs Post - Pre Exposure Delta

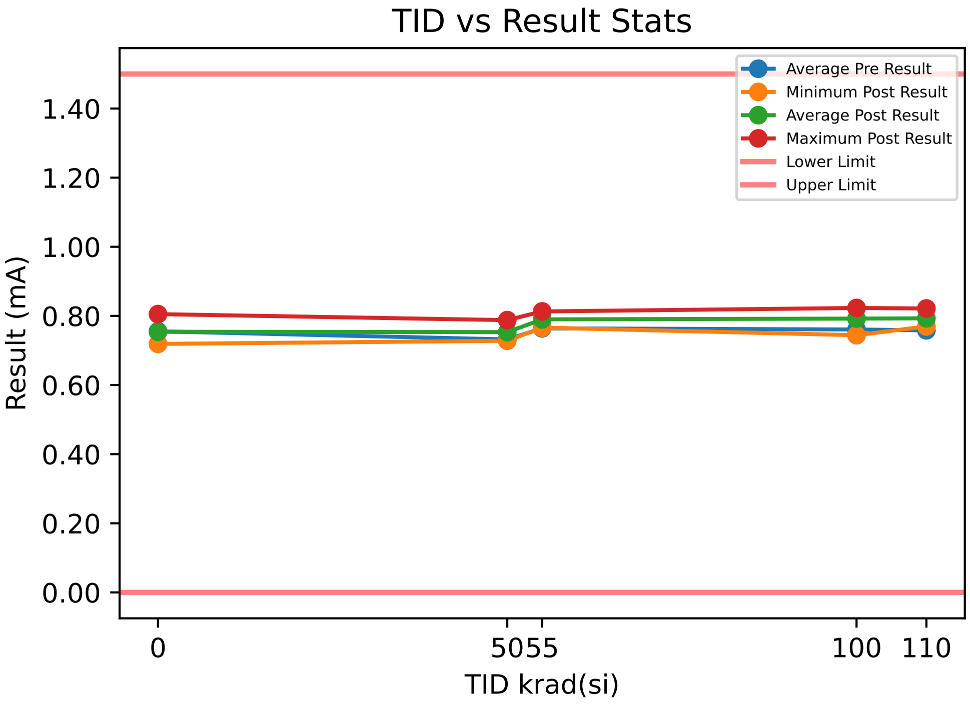
Test Results (Lower Limit = 0.0, Upper Limit = 45.0 (mA))

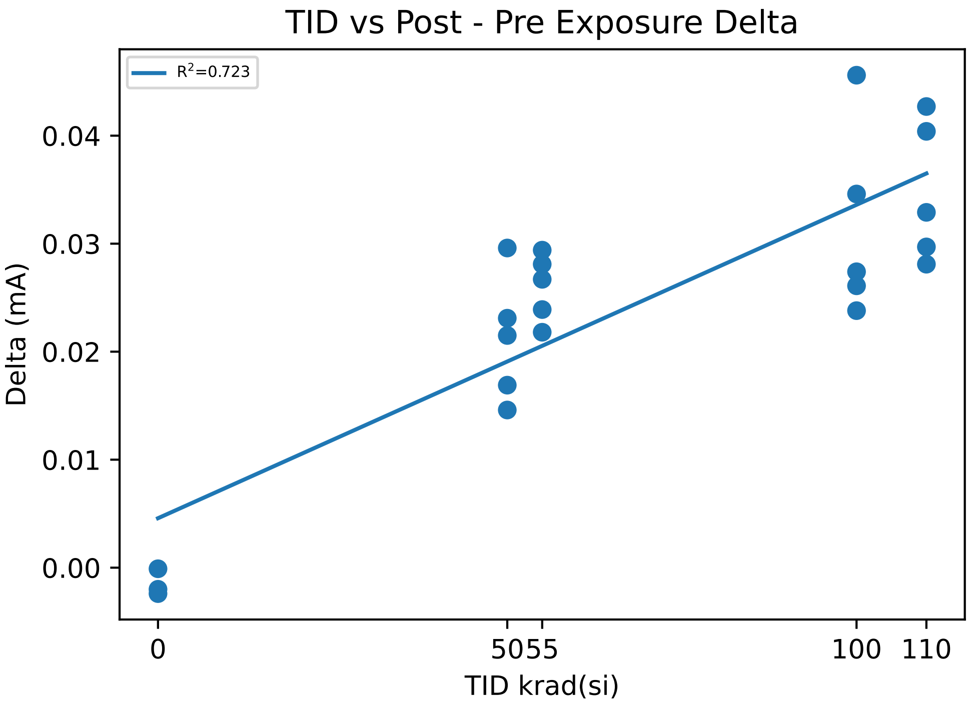
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	15.353	15.349	-0.0041
2	0	CU	15.954	15.962	0.0077
3	0	CU	15.516	15.521	0.0054
40	50	50krad Unbiased	15.698	15.776	0.078
41	50	50krad Unbiased	15.816	15.757	-0.0589
42	50	50krad Unbiased	15.407	15.309	-0.0974
43	50	50krad Unbiased	15.761	15.78	0.0183
44	50	50krad Unbiased	15.502	15.531	0.0297
45	55	50krad Biased	15.308	15.518	0.2107
46	55	50krad Biased	16.287	16.584	0.2967
47	55	50krad Biased	15.491	15.292	-0.1983
48	55	50krad Biased	14.989	15.193	0.2041
49	55	50krad Biased	15.917	16.027	0.1102
50	100	100krad Unbiased	15.463	15.564	0.1009
51	100	100krad Unbiased	15.642	15.722	0.0801
52	100	100krad Unbiased	15.843	15.765	-0.078
53	100	100krad Unbiased	15.449	15.461	0.0113
54	100	100krad Unbiased	15.583	15.589	0.0064
55	110	100krad Biased	15.578	15.495	-0.0832
56	110	100krad Biased	15.997	15.848	-0.1496
57	110	100krad Biased	15.577	15.569	-0.0078
58	110	100krad Biased	15.692	15.864	0.1722
59	110	100krad Biased	15.423	15.409	-0.0145

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.353	15.608	15.954	0.31101	15.349	15.611	15.962	0.3162	-0.0041	0.003	0.0077	0.0062554
50	15.407	15.637	15.816	0.1751	15.309	15.631	15.78	0.20768	-0.0974	-0.00606	0.078	0.07084
55	14.989	15.598	16.287	0.51071	15.193	15.723	16.584	0.57915	-0.1983	0.12468	0.2967	0.19224
100	15.449	15.596	15.843	0.15996	15.461	15.62	15.765	0.12339	-0.078	0.02414	0.1009	0.070597
110	15.423	15.654	15.997	0.21452	15.409	15.637	15.864	0.20788	-0.1496	-0.01658	0.1722	0.12026

Device Test: 205.3 SUPPLY_CURRENT|POST/VIN/SHUTDOWN///6.3/@I_SHDN


TID vs Result Stats


TID vs Post - Pre Exposure Delta

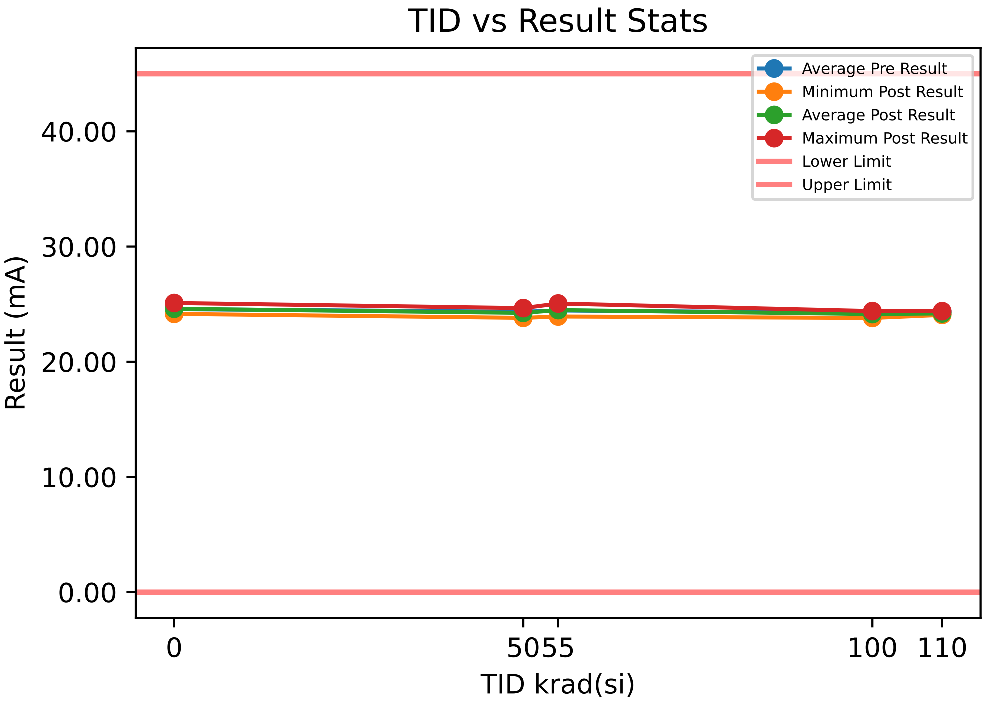
Test Results (Lower Limit = 0.0, Upper Limit = 1.5 (mA))

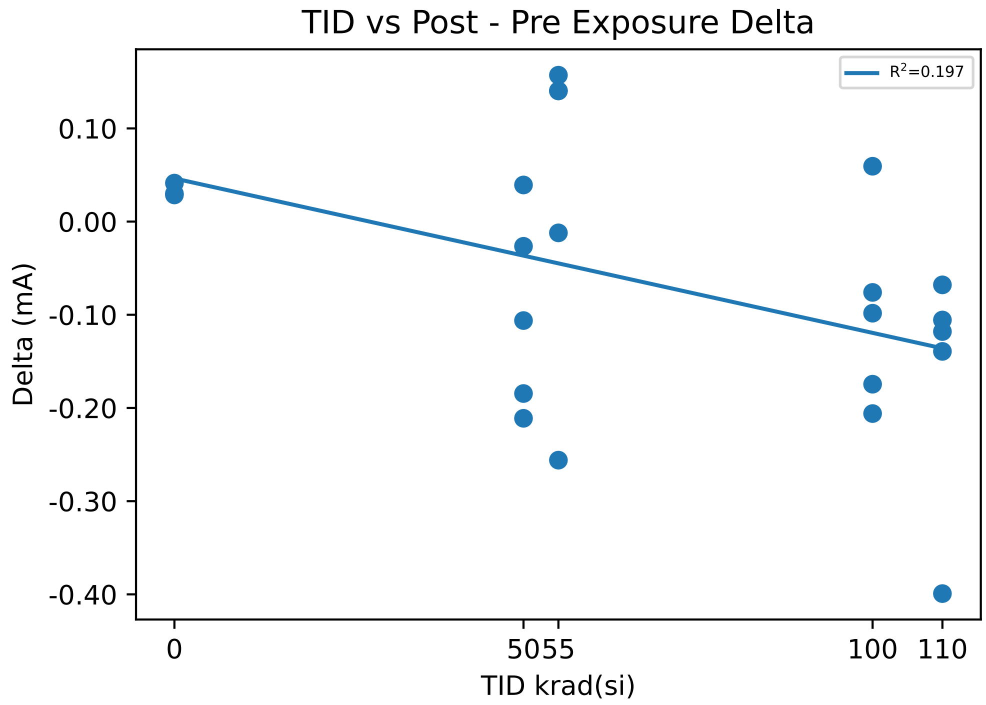
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.8072	0.8052	-0.002
2	0	CU	0.738	0.7379	-0.0001
3	0	CU	0.7214	0.719	-0.0024
40	50	50krad Unbiased	0.7253	0.7468	0.0215
41	50	50krad Unbiased	0.7112	0.7281	0.0169
42	50	50krad Unbiased	0.7154	0.7385	0.0231
43	50	50krad Unbiased	0.7582	0.7878	0.0296
44	50	50krad Unbiased	0.7498	0.7644	0.0146
45	55	50krad Biased	0.7891	0.813	0.0239
46	55	50krad Biased	0.7394	0.7661	0.0267
47	55	50krad Biased	0.7539	0.782	0.0281
48	55	50krad Biased	0.7515	0.7809	0.0294
49	55	50krad Biased	0.7864	0.8082	0.0218
50	100	100krad Unbiased	0.7884	0.823	0.0346
51	100	100krad Unbiased	0.7737	0.8193	0.0456
52	100	100krad Unbiased	0.7204	0.7442	0.0238
53	100	100krad Unbiased	0.7614	0.7888	0.0274
54	100	100krad Unbiased	0.7598	0.7859	0.0261
55	110	100krad Biased	0.7661	0.7958	0.0297
56	110	100krad Biased	0.7368	0.7697	0.0329
57	110	100krad Biased	0.7935	0.8216	0.0281
58	110	100krad Biased	0.7477	0.7904	0.0427
59	110	100krad Biased	0.7475	0.7879	0.0404

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.7214	0.75553	0.8072	0.045508	0.719	0.75403	0.8052	0.045308	-0.0024	-0.0015	-0.0001	0.0012288
50	0.7112	0.73198	0.7582	0.020955	0.7281	0.75312	0.7878	0.023503	0.0146	0.02114	0.0296	0.0058372
55	0.7394	0.76406	0.7891	0.022334	0.7661	0.79004	0.813	0.019864	0.0218	0.02598	0.0294	0.0031027
100	0.7204	0.76074	0.7884	0.025306	0.7442	0.79224	0.823	0.031774	0.0238	0.0315	0.0456	0.0088555
110	0.7368	0.75832	0.7935	0.022311	0.7697	0.79308	0.8216	0.018718	0.0281	0.03476	0.0427	0.006486

Device Test: 205.4 SUPPLY_CURRENT|POST/VIN/QUIESCENT///6.3/@IQ_VIN





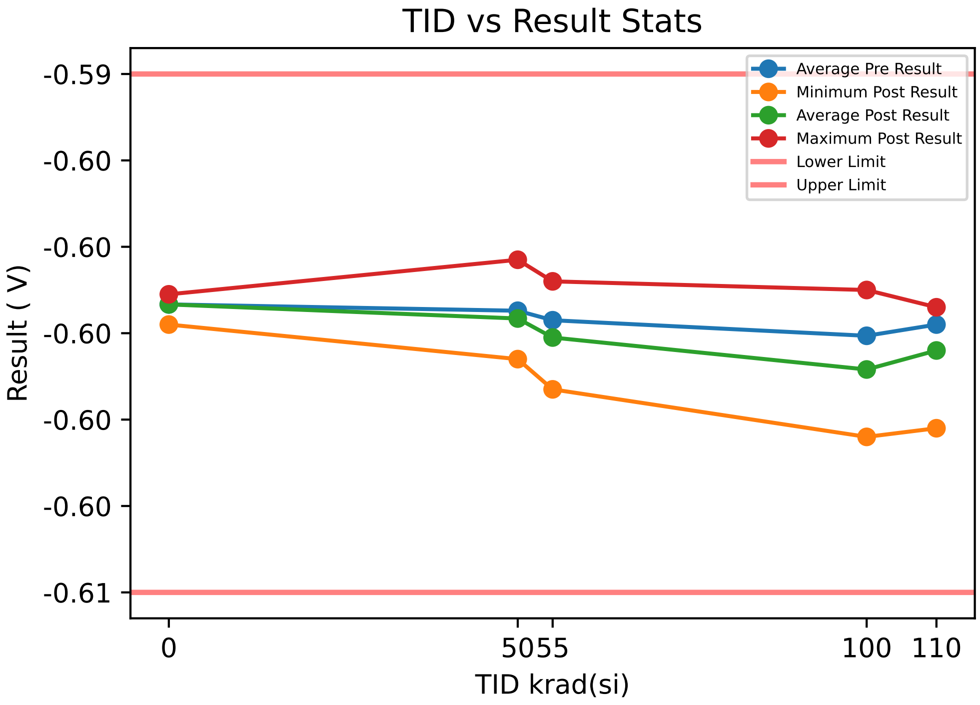
Test Results (Lower Limit = 0.0, Upper Limit = 45.0 (mA))

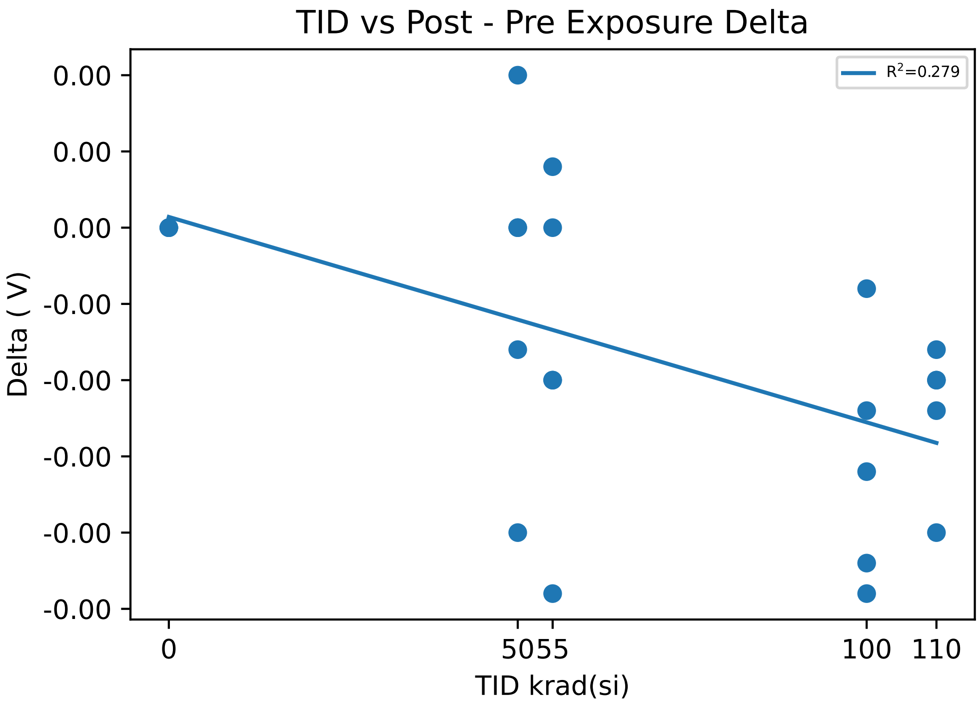
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	24.115	24.157	0.0413
2	0	CU	25.07	25.1	0.03
3	0	CU	24.513	24.542	0.0286
40	50	50krad Unbiased	24.49	24.529	0.0393
41	50	50krad Unbiased	24.869	24.658	-0.2111
42	50	50krad Unbiased	23.995	23.81	-0.1845
43	50	50krad Unbiased	24.411	24.305	-0.1062
44	50	50krad Unbiased	23.935	23.909	-0.0265
45	55	50krad Biased	24.488	24.645	0.1571
46	55	50krad Biased	24.914	25.054	0.1403
47	55	50krad Biased	24.184	23.928	-0.256
48	55	50krad Biased	24.152	24.292	0.1403
49	55	50krad Biased	24.522	24.51	-0.0121
50	100	100krad Unbiased	24.112	24.172	0.0594
51	100	100krad Unbiased	24.476	24.4	-0.076
52	100	100krad Unbiased	24.415	24.209	-0.206
53	100	100krad Unbiased	23.977	23.802	-0.1745
54	100	100krad Unbiased	24.223	24.125	-0.0983
55	110	100krad Biased	24.185	24.067	-0.118
56	110	100krad Biased	24.648	24.249	-0.3992
57	110	100krad Biased	24.498	24.392	-0.1056
58	110	100krad Biased	24.152	24.084	-0.0679
59	110	100krad Biased	24.317	24.177	-0.1393

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.115	24.566	25.07	0.47949	24.157	24.6	25.1	0.47428	0.0286	0.0333	0.0413	0.0069635
50	23.935	24.34	24.869	0.38422	23.81	24.242	24.658	0.37316	-0.2111	-0.0978	0.0393	0.10524
55	24.152	24.452	24.914	0.30889	23.928	24.486	25.054	0.41776	-0.256	0.03392	0.1571	0.17605
100	23.977	24.241	24.476	0.20735	23.802	24.141	24.4	0.21656	-0.206	-0.09908	0.0594	0.1034
110	24.152	24.36	24.648	0.2106	24.067	24.194	24.392	0.13285	-0.3992	-0.166	-0.0679	0.13292

Device Test: 30.1 VREF|/VREF//0N6V//3/@VREF





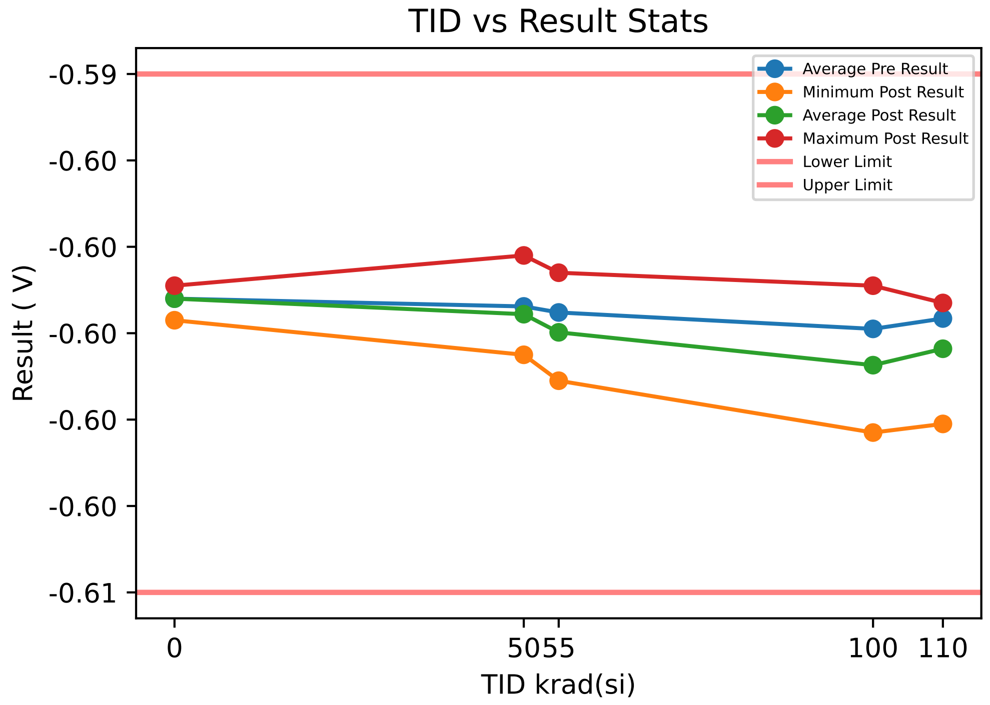
Test Results (Lower Limit = -0.606, Upper Limit = -0.594 (V))

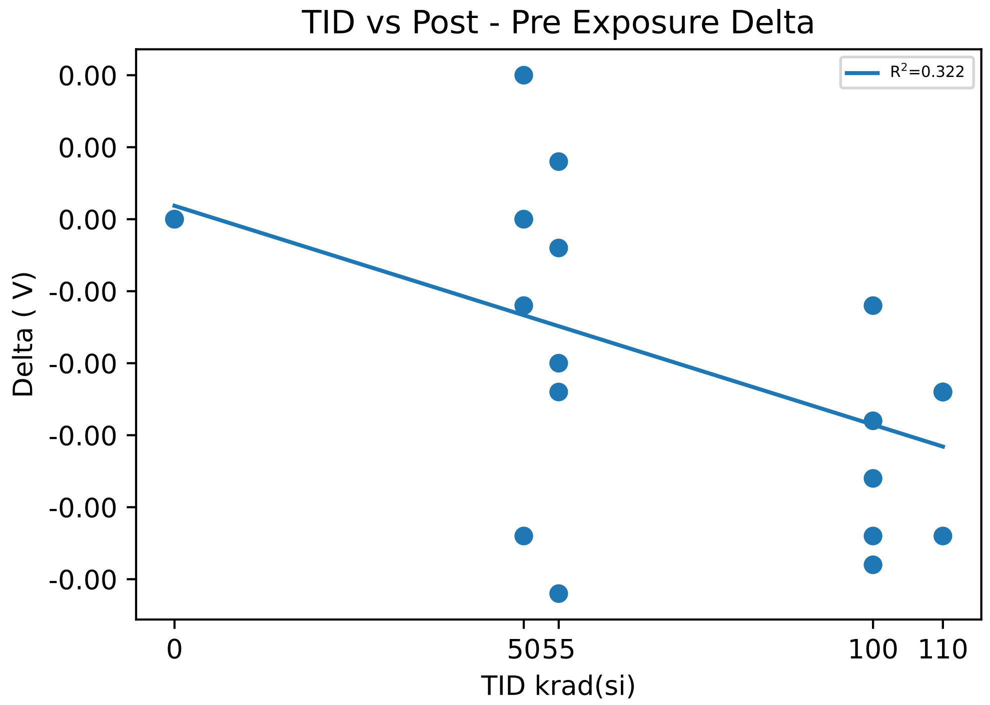
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	-0.5991	-0.5991	0
2	0	CU	-0.5991	-0.5991	0
3	0	CU	-0.5998	-0.5998	0
40	50	50krad Unbiased	-0.5993	-0.5993	0
41	50	50krad Unbiased	-0.5988	-0.5983	0.0005
42	50	50krad Unbiased	-0.5992	-0.5996	-0.0004
43	50	50krad Unbiased	-0.6005	-0.6005	0
44	50	50krad Unbiased	-0.5996	-0.6006	-0.001
45	55	50krad Biased	-0.5996	-0.5996	0
46	55	50krad Biased	-0.5999	-0.6011	-0.0012
47	55	50krad Biased	-0.5992	-0.5997	-0.0005
48	55	50krad Biased	-0.6008	-0.6013	-0.0005
49	55	50krad Biased	-0.599	-0.5988	0.0002
50	100	100krad Unbiased	-0.6018	-0.6024	-0.0006
51	100	100krad Unbiased	-0.5995	-0.6003	-0.0008
52	100	100krad Unbiased	-0.5978	-0.599	-0.0012
53	100	100krad Unbiased	-0.6012	-0.6023	-0.0011
54	100	100krad Unbiased	-0.6	-0.6002	-0.0002
55	110	100krad Biased	-0.5998	-0.6002	-0.0004
56	110	100krad Biased	-0.6001	-0.6006	-0.0005
57	110	100krad Biased	-0.6017	-0.6022	-0.0005
58	110	100krad Biased	-0.5986	-0.5996	-0.001
59	110	100krad Biased	-0.5988	-0.5994	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5998	-0.59933	-0.5991	0.00040415	-0.5998	-0.59933	-0.5991	0.00040415	0	0	0	0
50	-0.6005	-0.59948	-0.5988	0.00063797	-0.6006	-0.59966	-0.5983	0.00094499	-0.001	-0.00018	0.0005	0.00055857
55	-0.6008	-0.5997	-0.599	0.00070711	-0.6013	-0.6001	-0.5988	0.0010654	-0.0012	-0.0004	0.0002	0.00054314
100	-0.6018	-0.60006	-0.5978	0.0015614	-0.6024	-0.60084	-0.599	0.0014707	-0.0012	-0.00078	-0.0002	0.00040249
110	-0.6017	-0.5998	-0.5986	0.001239	-0.6022	-0.6004	-0.5994	0.0011136	-0.001	-0.0006	-0.0004	0.00023452

Device Test: 30.2 VREF|/VREF//1N8V//5/@VREF





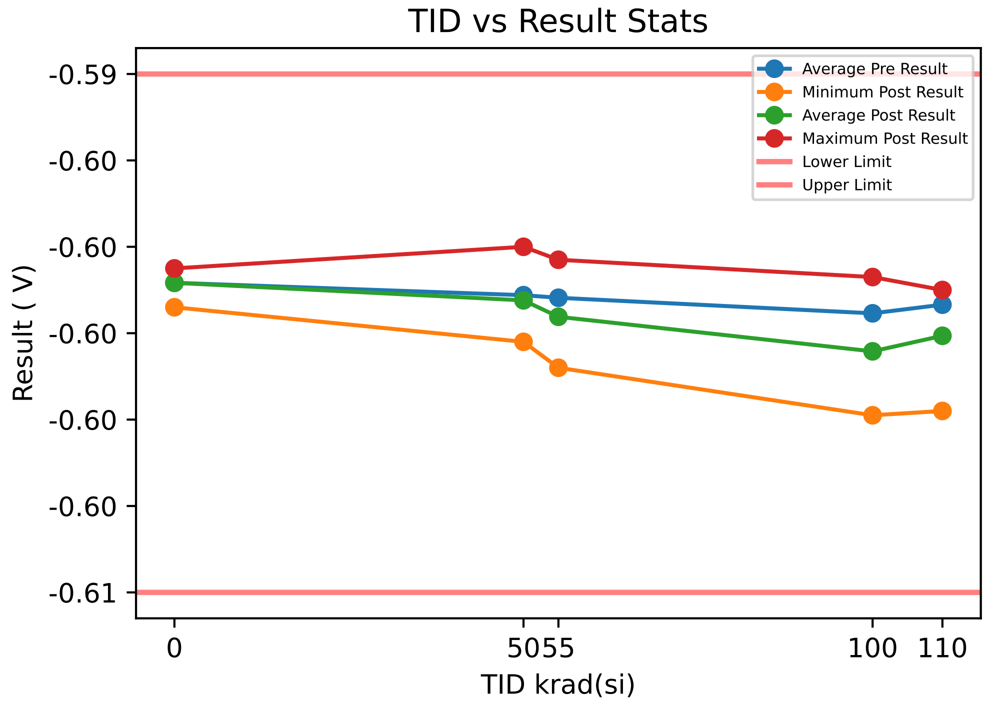
Test Results (Lower Limit = -0.606, Upper Limit = -0.594 (V))

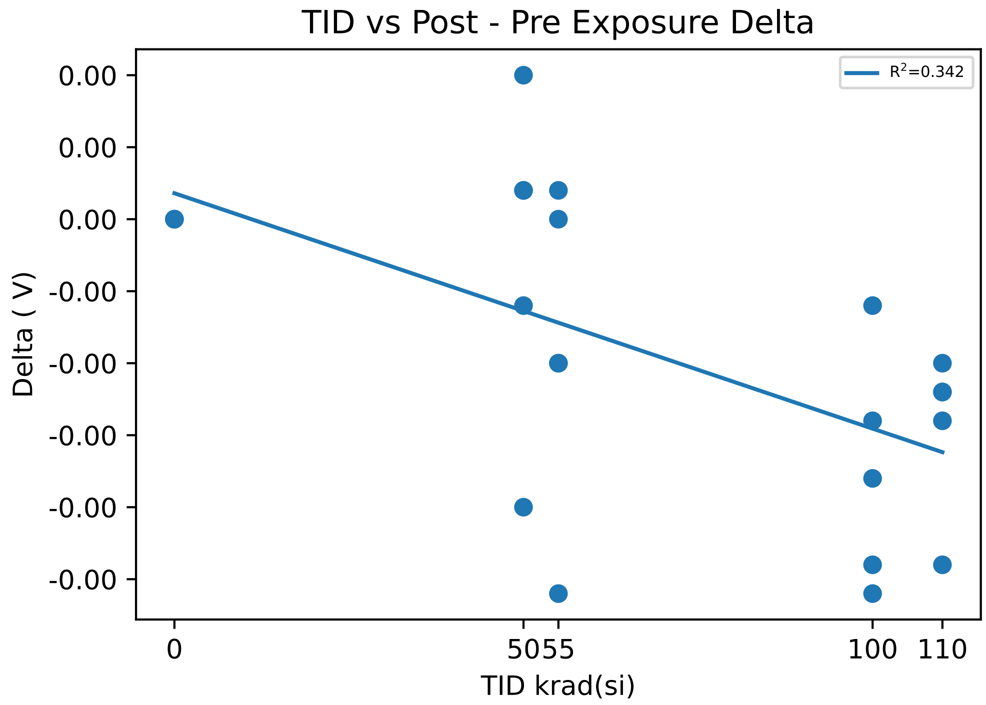
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	-0.5989	-0.5989	0
2	0	CU	-0.599	-0.599	0
3	0	CU	-0.5997	-0.5997	0
40	50	50krad Unbiased	-0.5992	-0.5992	0
41	50	50krad Unbiased	-0.5987	-0.5982	0.0005
42	50	50krad Unbiased	-0.5992	-0.5995	-0.0003
43	50	50krad Unbiased	-0.6004	-0.6004	0
44	50	50krad Unbiased	-0.5994	-0.6005	-0.0011
45	55	50krad Biased	-0.5994	-0.5995	-0.0001
46	55	50krad Biased	-0.5998	-0.6011	-0.0013
47	55	50krad Biased	-0.599	-0.5996	-0.0006
48	55	50krad Biased	-0.6006	-0.6011	-0.0005
49	55	50krad Biased	-0.5988	-0.5986	0.0002
50	100	100krad Unbiased	-0.6016	-0.6023	-0.0007
51	100	100krad Unbiased	-0.5993	-0.6002	-0.0009
52	100	100krad Unbiased	-0.5977	-0.5989	-0.0012
53	100	100krad Unbiased	-0.6011	-0.6022	-0.0011
54	100	100krad Unbiased	-0.5998	-0.6001	-0.0003
55	110	100krad Biased	-0.5996	-0.6002	-0.0006
56	110	100krad Biased	-0.6	-0.6006	-0.0006
57	110	100krad Biased	-0.6015	-0.6021	-0.0006
58	110	100krad Biased	-0.5985	-0.5996	-0.0011
59	110	100krad Biased	-0.5987	-0.5993	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5997	-0.5992	-0.5989	0.00043589	-0.5997	-0.5992	-0.5989	0.00043589	0	0	0	0
50	-0.6004	-0.59938	-0.5987	0.0006261	-0.6005	-0.59956	-0.5982	0.00094499	-0.0011	-0.00018	0.0005	0.00058907
55	-0.6006	-0.59952	-0.5988	0.00071554	-0.6011	-0.59998	-0.5986	0.0010941	-0.0013	-0.00046	0.0002	0.00056833
100	-0.6016	-0.5999	-0.5977	0.0015443	-0.6023	-0.60074	-0.5989	0.0014707	-0.0012	-0.00084	-0.0003	0.00035777
110	-0.6015	-0.59966	-0.5985	0.0012012	-0.6021	-0.60036	-0.5993	0.0010968	-0.0011	-0.0007	-0.0006	0.00022361

Device Test: 30.3 VREF|/VREF//6N0V//6.3/@VREF


TID vs Result Stats


TID vs Post - Pre Exposure Delta

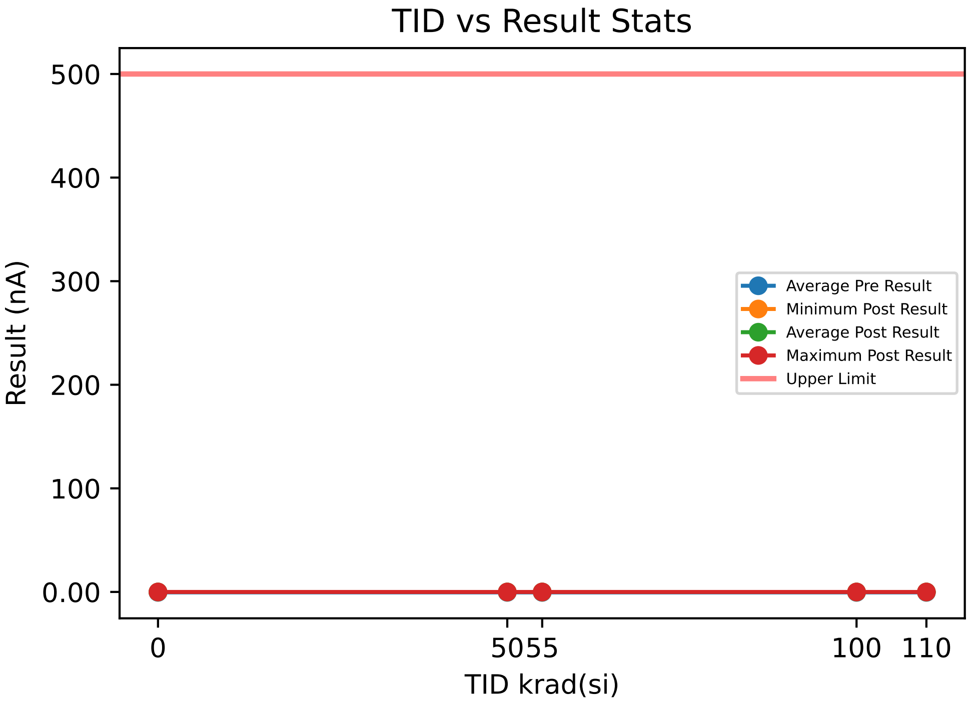
Test Results (Lower Limit = -0.606,
Upper Limit = -0.594 (V))

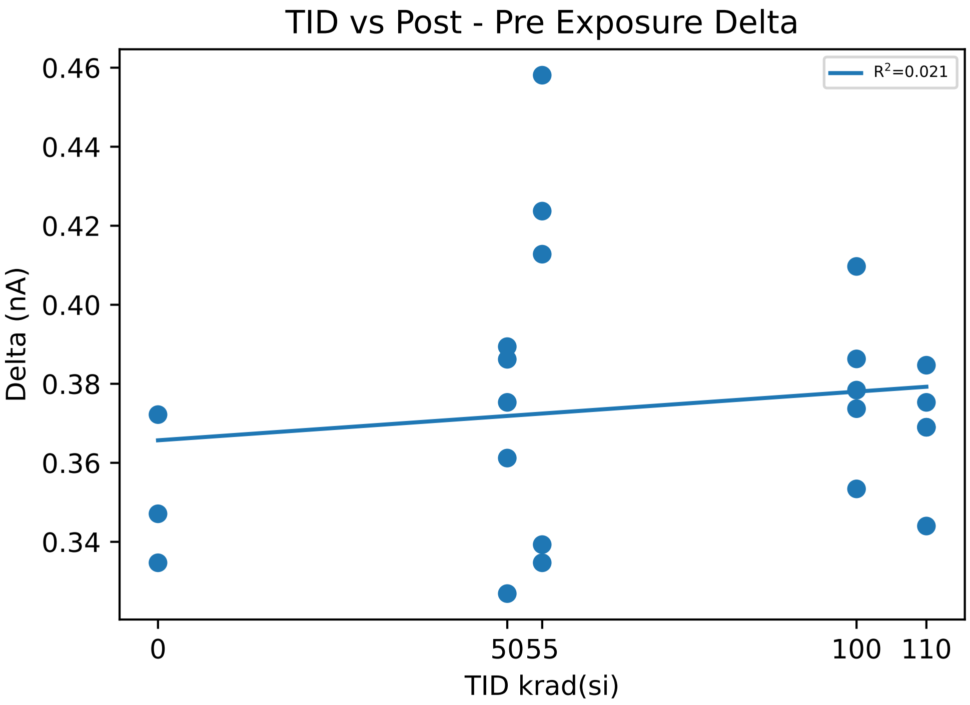
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	-0.5985	-0.5985	0
2	0	CU	-0.5986	-0.5986	0
3	0	CU	-0.5994	-0.5994	0
40	50	50krad Unbiased	-0.599	-0.5989	0.0001
41	50	50krad Unbiased	-0.5985	-0.598	0.0005
42	50	50krad Unbiased	-0.5989	-0.5992	-0.0003
43	50	50krad Unbiased	-0.6	-0.5999	0.0001
44	50	50krad Unbiased	-0.5992	-0.6002	-0.001
45	55	50krad Biased	-0.599	-0.599	0
46	55	50krad Biased	-0.5995	-0.6008	-0.0013
47	55	50krad Biased	-0.5987	-0.5992	-0.0005
48	55	50krad Biased	-0.6003	-0.6008	-0.0005
49	55	50krad Biased	-0.5984	-0.5983	0.0001
50	100	100krad Unbiased	-0.6012	-0.6019	-0.0007
51	100	100krad Unbiased	-0.5989	-0.5998	-0.0009
52	100	100krad Unbiased	-0.5974	-0.5987	-0.0013
53	100	100krad Unbiased	-0.6007	-0.6019	-0.0012
54	100	100krad Unbiased	-0.5995	-0.5998	-0.0003
55	110	100krad Biased	-0.5993	-0.5998	-0.0005
56	110	100krad Biased	-0.5997	-0.6003	-0.0006
57	110	100krad Biased	-0.6011	-0.6018	-0.0007
58	110	100krad Biased	-0.5982	-0.5994	-0.0012
59	110	100krad Biased	-0.5984	-0.599	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5994	-0.59883	-0.5985	0.00049329	-0.5994	-0.59883	-0.5985	0.00049329	0	0	0	0
50	-0.6	-0.59912	-0.5985	0.00055408	-0.6002	-0.59924	-0.598	0.00086776	-0.001	-0.00012	0.0005	0.00056745
55	-0.6003	-0.59918	-0.5984	0.00074632	-0.6008	-0.59962	-0.5983	0.0011278	-0.0013	-0.00044	0.0001	0.00055498
100	-0.6012	-0.59954	-0.5974	0.0015076	-0.6019	-0.60042	-0.5987	0.0014237	-0.0013	-0.00088	-0.0003	0.00040249
110	-0.6011	-0.59934	-0.5982	0.0011632	-0.6018	-0.60006	-0.599	0.0010854	-0.0012	-0.00072	-0.0005	0.00027749

Device Test: 31.1 LEAK|/FB/CURRENT////@I_FB


TID vs Result Stats


TID vs Post - Pre Exposure Delta

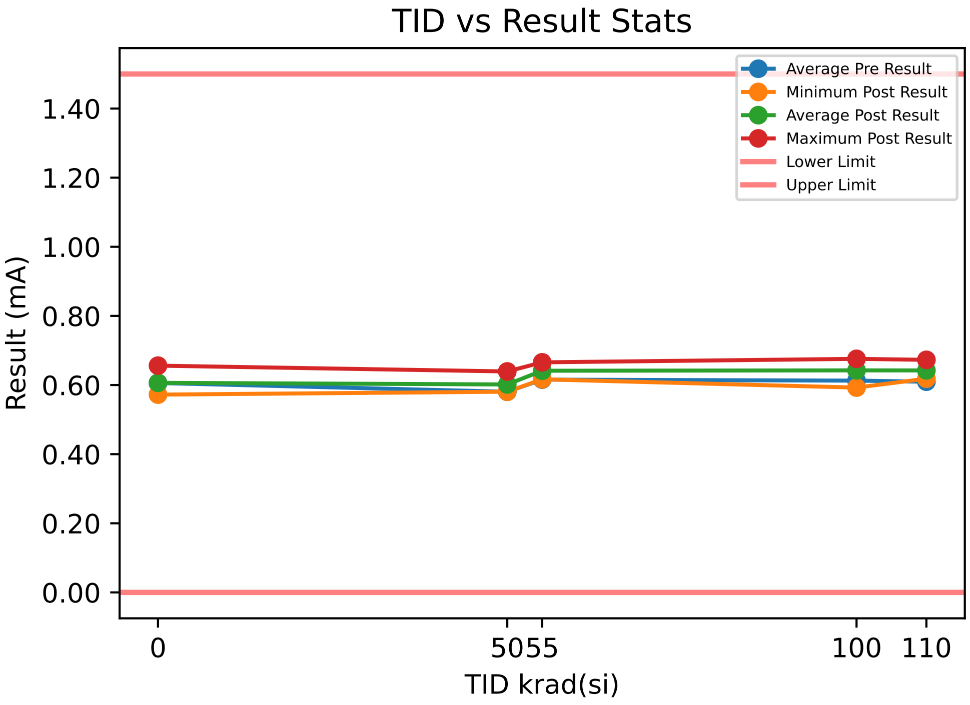
Test Results (Upper Limit = 500.0 (nA))

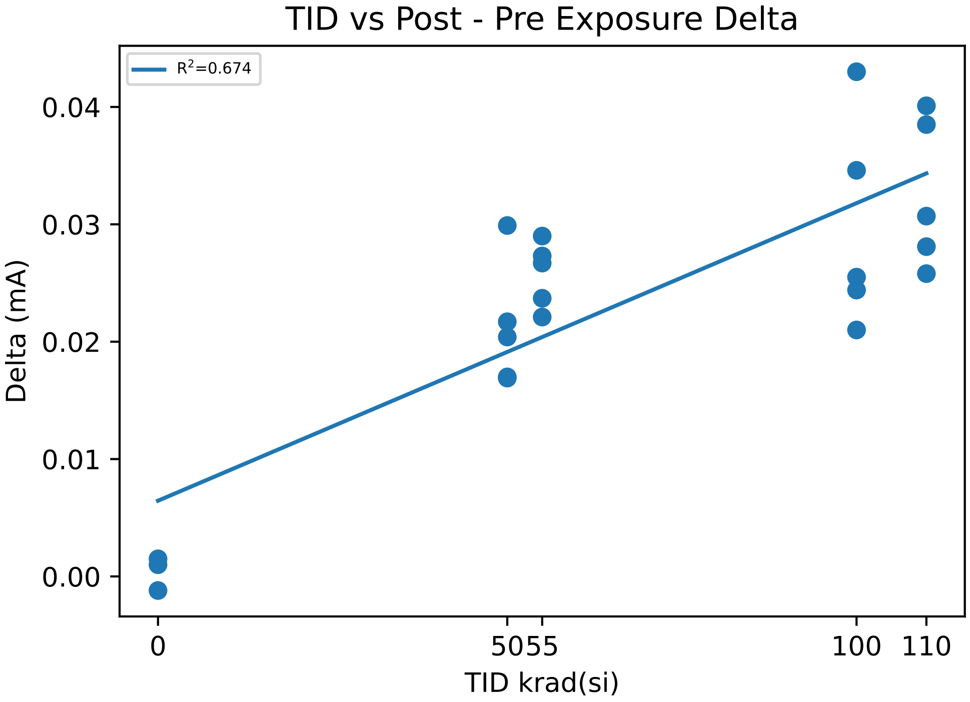
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	-0.3981	-0.0259	0.3722
2	0	CU	-0.4152	-0.0681	0.3471
3	0	CU	-0.3996	-0.0649	0.3347
40	50	50krad Unbiased	-0.3809	-0.054	0.3269
41	50	50krad Unbiased	-0.4168	-0.0415	0.3753
42	50	50krad Unbiased	-0.4543	-0.0649	0.3894
43	50	50krad Unbiased	-0.4277	-0.0415	0.3862
44	50	50krad Unbiased	-0.409	-0.0478	0.3612
45	55	50krad Biased	-0.4152	-0.0805	0.3347
46	55	50krad Biased	-0.4027	-0.0634	0.3393
47	55	50krad Biased	-0.4543	-0.0306	0.4237
48	55	50krad Biased	-0.4965	-0.0384	0.4581
49	55	50krad Biased	-0.4481	-0.0353	0.4128
50	100	100krad Unbiased	-0.4059	-0.0322	0.3737
51	100	100krad Unbiased	-0.434	-0.0556	0.3784
52	100	100krad Unbiased	-0.3996	-0.0462	0.3534
53	100	100krad Unbiased	-0.4637	-0.054	0.4097
54	100	100krad Unbiased	-0.4668	-0.0805	0.3863
55	110	100krad Biased	-0.4465	-0.0618	0.3847
56	110	100krad Biased	-0.4121	-0.0431	0.369
57	110	100krad Biased	-0.3793	-0.0353	0.344
58	110	100krad Biased	-0.4293	-0.054	0.3753
59	110	100krad Biased	-0.4121	-0.0431	0.369

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4152	-0.4043	-0.3981	0.0094694	-0.0681	-0.052967	-0.0259	0.023495	0.3347	0.35133	0.3722	0.019105
50	-0.4543	-0.41774	-0.3809	0.026788	-0.0649	-0.04994	-0.0415	0.0098404	0.3269	0.3678	0.3894	0.025386
55	-0.4965	-0.44336	-0.4027	0.036784	-0.0805	-0.04964	-0.0306	0.021425	0.3347	0.39372	0.4581	0.054435
100	-0.4668	-0.434	-0.3996	0.031348	-0.0805	-0.0537	-0.0322	0.01761	0.3534	0.3803	0.4097	0.02044
110	-0.4465	-0.41586	-0.3793	0.024922	-0.0618	-0.04746	-0.0353	0.01042	0.344	0.3684	0.3847	0.015078

Device Test: 31.2 SUPPLY_CURRENT|PRE/VIN/SHUTDOWN///3/@I_SHDN





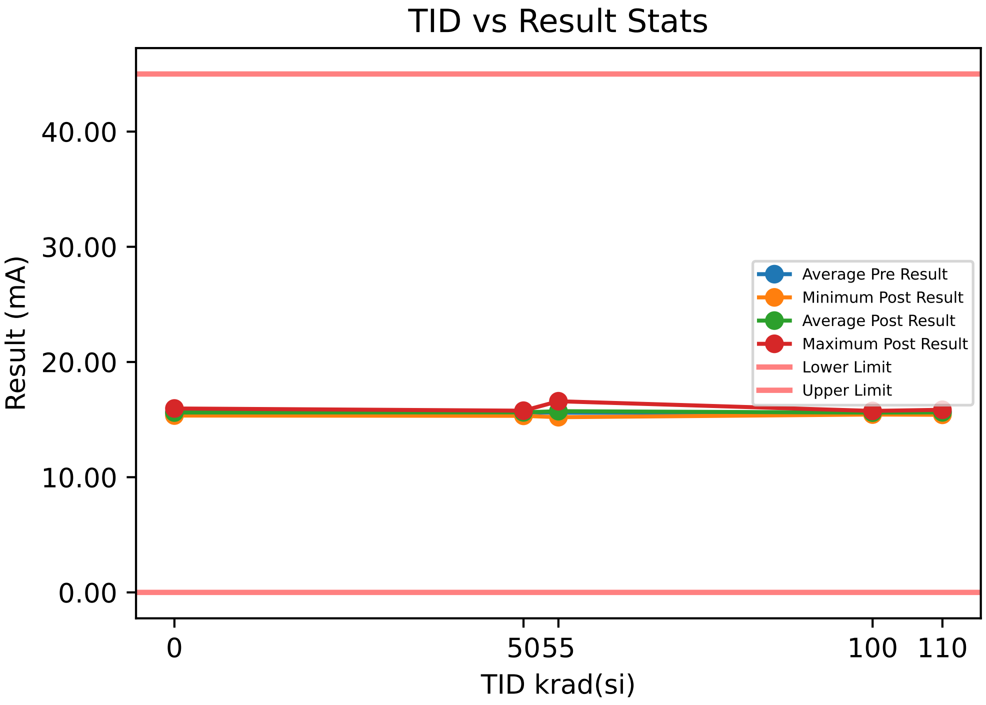
Test Results (Lower Limit = 0.0, Upper Limit = 1.5 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.6546	0.6561	0.0015
2	0	CU	0.5897	0.5907	0.001
3	0	CU	0.5735	0.5723	-0.0012
40	50	50krad Unbiased	0.5773	0.5977	0.0204
41	50	50krad Unbiased	0.5637	0.5807	0.017
42	50	50krad Unbiased	0.5655	0.5872	0.0217
43	50	50krad Unbiased	0.6094	0.6393	0.0299
44	50	50krad Unbiased	0.5868	0.6037	0.0169
45	55	50krad Biased	0.642	0.6657	0.0237
46	55	50krad Biased	0.5899	0.6166	0.0267
47	55	50krad Biased	0.6054	0.6327	0.0273
48	55	50krad Biased	0.6049	0.6339	0.029
49	55	50krad Biased	0.6358	0.6579	0.0221
50	100	100krad Unbiased	0.6412	0.6758	0.0346
51	100	100krad Unbiased	0.6243	0.6673	0.043
52	100	100krad Unbiased	0.5716	0.5926	0.021
53	100	100krad Unbiased	0.6139	0.6394	0.0255
54	100	100krad Unbiased	0.6128	0.6372	0.0244
55	110	100krad Biased	0.6165	0.6446	0.0281
56	110	100krad Biased	0.5877	0.6184	0.0307
57	110	100krad Biased	0.6471	0.6729	0.0258
58	110	100krad Biased	0.5979	0.638	0.0401
59	110	100krad Biased	0.599	0.6375	0.0385

Test Statistics (mA)

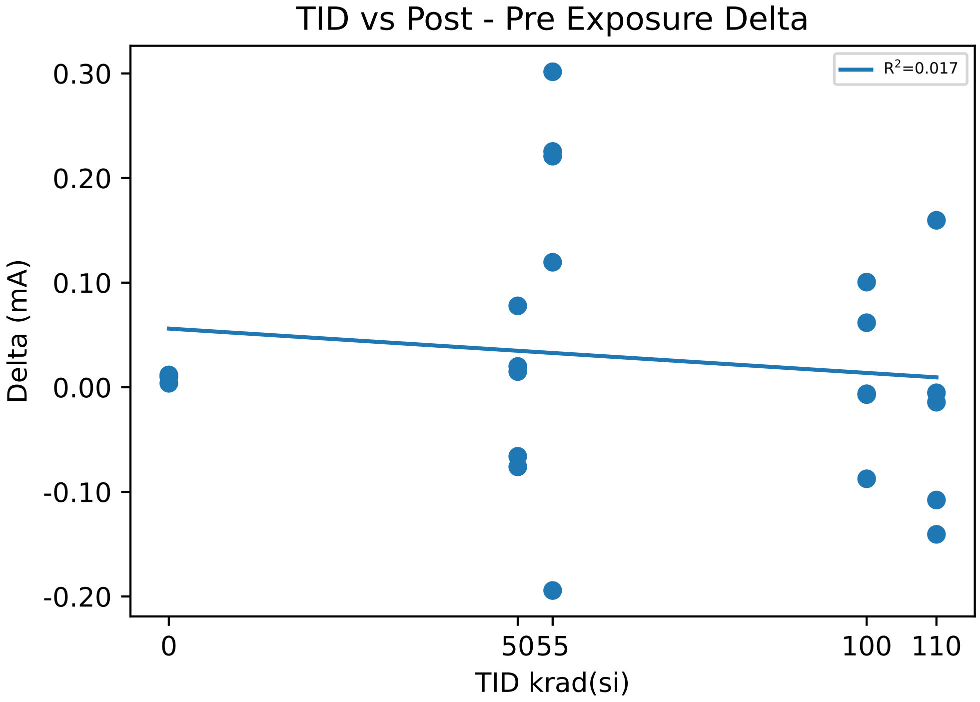
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5735	0.60593	0.6546	0.042918	0.5723	0.60637	0.6561	0.044042	-0.0012	0.00043333	0.0015	0.0014364
50	0.5637	0.58054	0.6094	0.018657	0.5807	0.60172	0.6393	0.022831	0.0169	0.02118	0.0299	0.0053082
55	0.5899	0.6156	0.642	0.022271	0.6166	0.64136	0.6657	0.020061	0.0221	0.02576	0.029	0.0028014
100	0.5716	0.61276	0.6412	0.025678	0.5926	0.64246	0.6758	0.032602	0.021	0.0297	0.043	0.0089766
110	0.5877	0.60964	0.6471	0.02336	0.6184	0.64228	0.6729	0.019713	0.0258	0.03264	0.0401	0.0063473

Device Test: 31.3 SUPPLY_CURRENT|PRE/VIN/QUIESCENT///3/@IQ_VIN



Test Results (Lower Limit = 0.0, Upper Limit = 45.0 (mA))

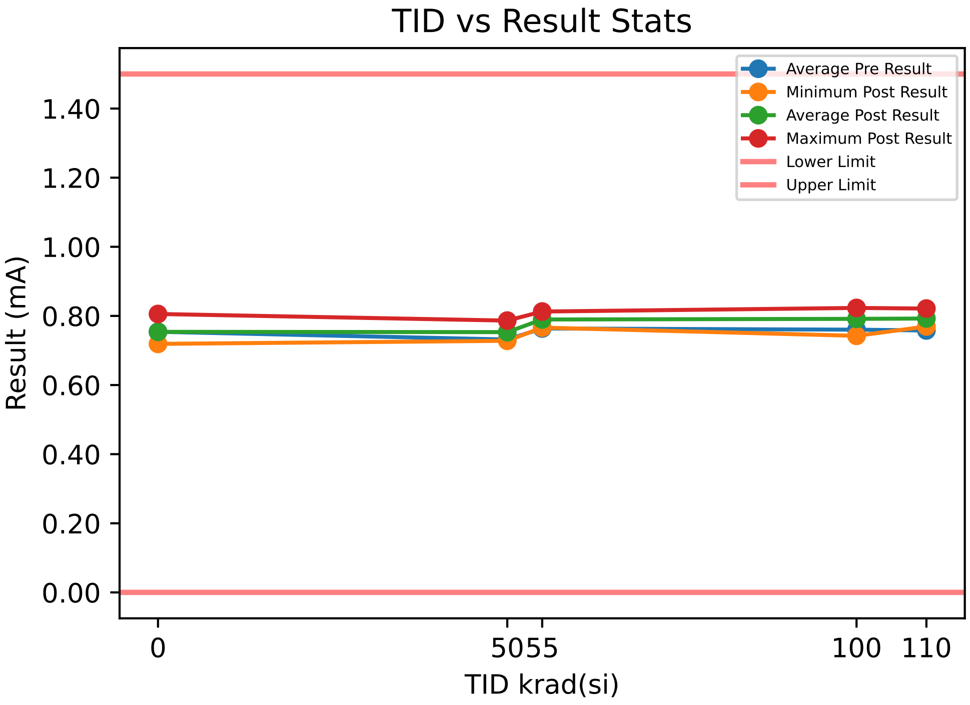
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	15.339	15.351	0.0118
2	0	CU	15.956	15.966	0.0098
3	0	CU	15.519	15.523	0.0038
40	50	50krad Unbiased	15.692	15.77	0.0778
41	50	50krad Unbiased	15.82	15.754	-0.066
42	50	50krad Unbiased	15.403	15.326	-0.0761
43	50	50krad Unbiased	15.758	15.773	0.015
44	50	50krad Unbiased	15.502	15.521	0.0199
45	55	50krad Biased	15.301	15.522	0.2209
46	55	50krad Biased	16.292	16.594	0.3016
47	55	50krad Biased	15.486	15.292	-0.1943
48	55	50krad Biased	14.982	15.207	0.2254
49	55	50krad Biased	15.918	16.038	0.1195
50	100	100krad Unbiased	15.459	15.559	0.1005
51	100	100krad Unbiased	15.639	15.7	0.0617
52	100	100krad Unbiased	15.842	15.754	-0.0875
53	100	100krad Unbiased	15.444	15.438	-0.0062
54	100	100krad Unbiased	15.578	15.571	-0.007
55	110	100krad Biased	15.576	15.468	-0.1078
56	110	100krad Biased	15.994	15.853	-0.1406
57	110	100krad Biased	15.575	15.56	-0.0143
58	110	100krad Biased	15.689	15.849	0.1596
59	110	100krad Biased	15.42	15.414	-0.0053

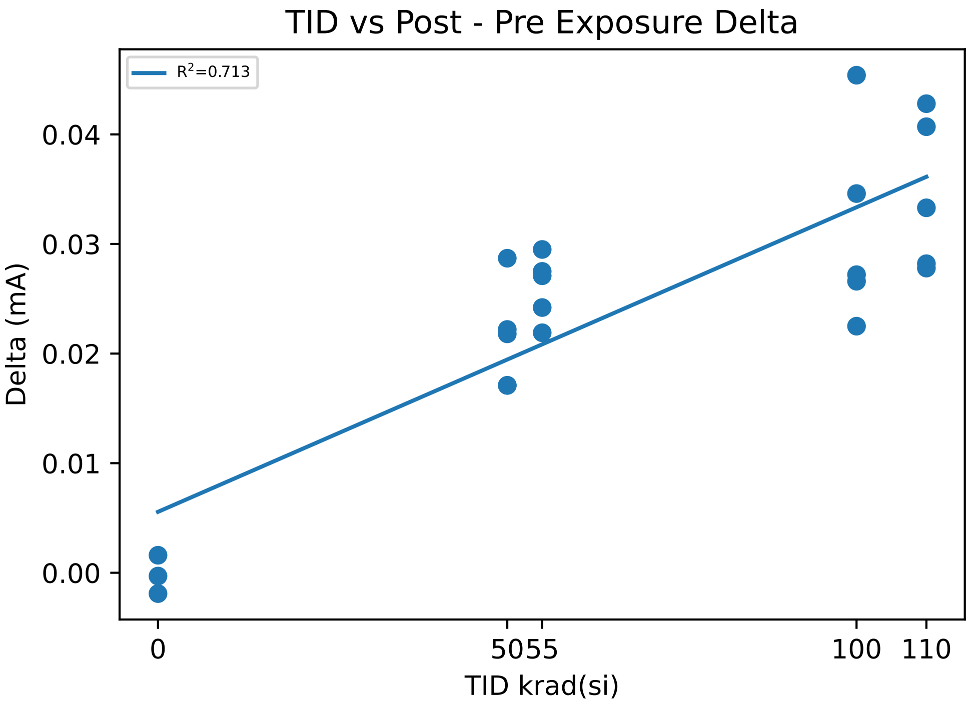


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.339	15.604	15.956	0.31725	15.351	15.613	15.966	0.31725	0.0038	0.0084667	0.0118	0.0041633
50	15.403	15.635	15.82	0.17649	15.326	15.629	15.773	0.19964	-0.0761	-0.00588	0.0778	0.064514
55	14.982	15.596	16.292	0.51584	15.207	15.73	16.594	0.58072	-0.1943	0.13462	0.3016	0.19493
100	15.444	15.592	15.842	0.16141	15.438	15.604	15.754	0.12489	-0.0875	0.0123	0.1005	0.072274
110	15.42	15.651	15.994	0.21432	15.414	15.629	15.853	0.2092	-0.1406	-0.02168	0.1596	0.11699

Device Test: 31.4 SUPPLY_CURRENT|PRE/VIN/SHUTDOWN///6.3/@I_SHDN





Test Results (Lower Limit = 0.0, Upper Limit = 1.5 (mA))

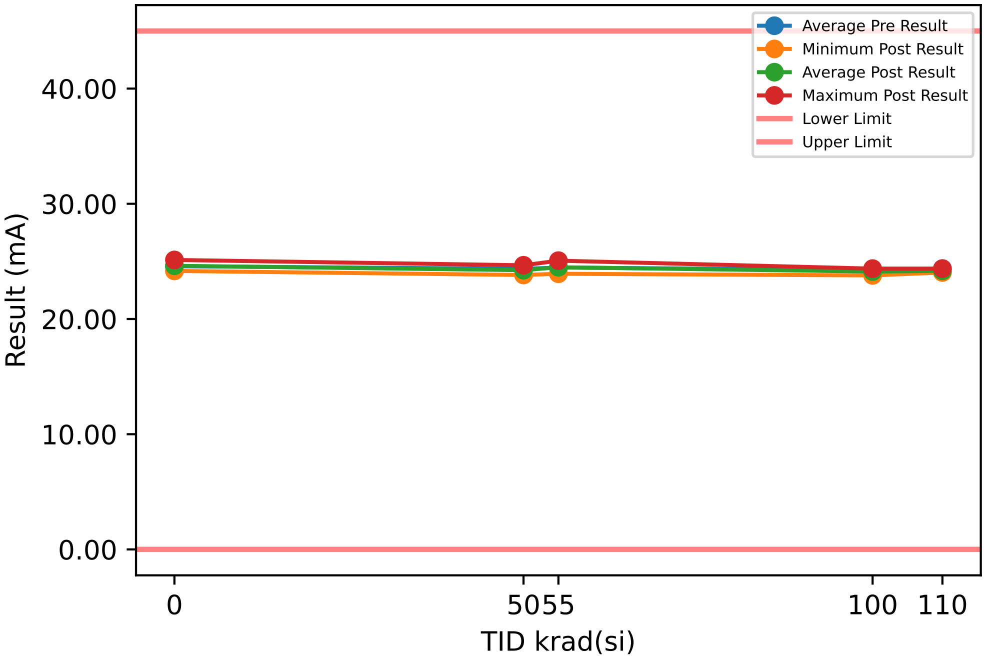
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.804	0.8056	0.0016
2	0	CU	0.7374	0.7371	-0.0003
3	0	CU	0.721	0.7191	-0.0019
40	50	50krad Unbiased	0.7254	0.7472	0.0218
41	50	50krad Unbiased	0.7109	0.728	0.0171
42	50	50krad Unbiased	0.7158	0.738	0.0222
43	50	50krad Unbiased	0.7578	0.7865	0.0287
44	50	50krad Unbiased	0.7487	0.7658	0.0171
45	55	50krad Biased	0.7885	0.8127	0.0242
46	55	50krad Biased	0.7391	0.7662	0.0271
47	55	50krad Biased	0.7538	0.7813	0.0275
48	55	50krad Biased	0.7508	0.7803	0.0295
49	55	50krad Biased	0.786	0.8079	0.0219
50	100	100krad Unbiased	0.7885	0.8231	0.0346
51	100	100krad Unbiased	0.7731	0.8185	0.0454
52	100	100krad Unbiased	0.7199	0.7424	0.0225
53	100	100krad Unbiased	0.7603	0.7875	0.0272
54	100	100krad Unbiased	0.7593	0.7859	0.0266
55	110	100krad Biased	0.7665	0.7943	0.0278
56	110	100krad Biased	0.7361	0.7694	0.0333
57	110	100krad Biased	0.7931	0.8213	0.0282
58	110	100krad Biased	0.7469	0.7897	0.0428
59	110	100krad Biased	0.747	0.7877	0.0407

Test Statistics (mA)

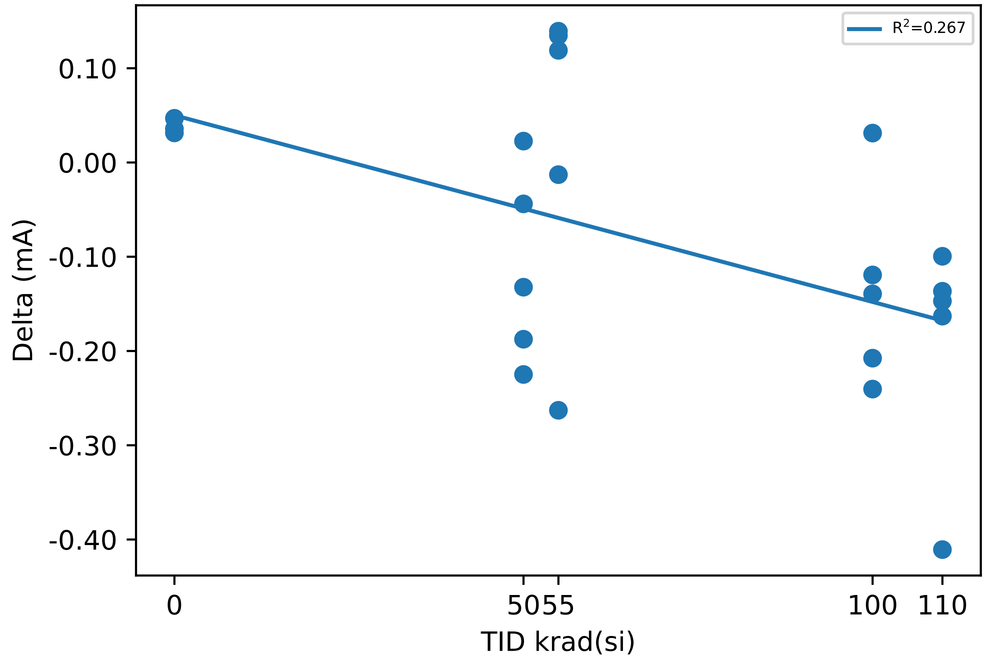
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.721	0.75413	0.804	0.043957	0.7191	0.75393	0.8056	0.045641	-0.0019	-0.0002	0.0016	0.0017521
50	0.7109	0.73172	0.7578	0.020587	0.728	0.7531	0.7865	0.02329	0.0171	0.02138	0.0287	0.0047715
55	0.7391	0.76364	0.7885	0.022259	0.7662	0.78968	0.8127	0.01982	0.0219	0.02604	0.0295	0.0029896
100	0.7199	0.76022	0.7885	0.025457	0.7424	0.79148	0.8231	0.032349	0.0225	0.03126	0.0454	0.0090282
110	0.7361	0.75792	0.7931	0.022517	0.7694	0.79248	0.8213	0.018689	0.0278	0.03456	0.0428	0.0069522

Device Test: 31.5 SUPPLY_CURRENT|PRE/VIN/QUIESCENT///6.3/@IQ_VIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



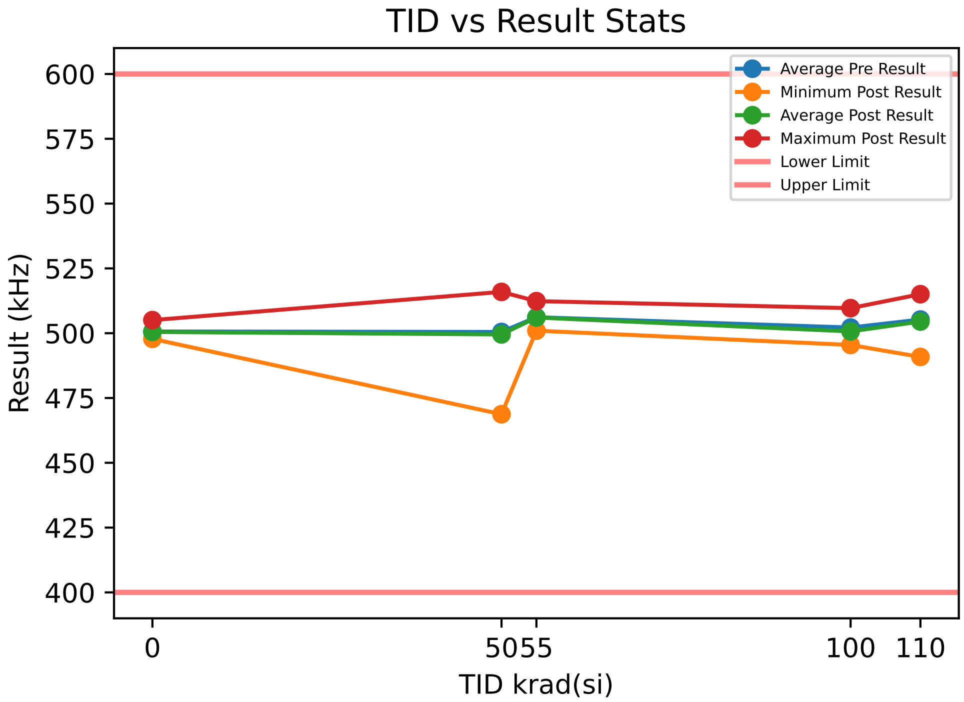
Test Results (Lower Limit = 0.0, Upper Limit = 45.0 (mA))

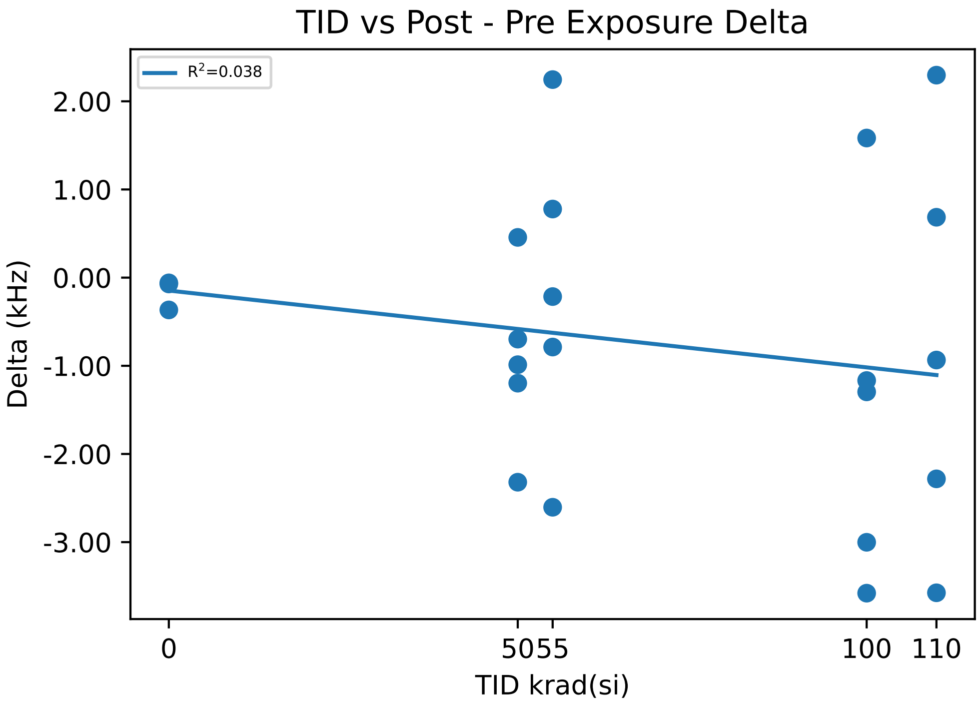
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	24.126	24.173	0.0469
2	0	CU	25.09	25.125	0.0357
3	0	CU	24.53	24.561	0.0314
40	50	50krad Unbiased	24.494	24.516	0.0227
41	50	50krad Unbiased	24.888	24.663	-0.2249
42	50	50krad Unbiased	24.007	23.82	-0.1875
43	50	50krad Unbiased	24.429	24.297	-0.1323
44	50	50krad Unbiased	23.941	23.897	-0.0439
45	55	50krad Biased	24.507	24.646	0.1393
46	55	50krad Biased	24.944	25.063	0.119
47	55	50krad Biased	24.189	23.926	-0.2629
48	55	50krad Biased	24.166	24.301	0.1348
49	55	50krad Biased	24.531	24.518	-0.0129
50	100	100krad Unbiased	24.119	24.15	0.0312
51	100	100krad Unbiased	24.492	24.373	-0.1193
52	100	100krad Unbiased	24.435	24.195	-0.2404
53	100	100krad Unbiased	23.992	23.785	-0.2076
54	100	100krad Unbiased	24.237	24.098	-0.1394
55	110	100krad Biased	24.184	24.037	-0.147
56	110	100krad Biased	24.662	24.251	-0.4107
57	110	100krad Biased	24.511	24.374	-0.1366
58	110	100krad Biased	24.168	24.069	-0.0995
59	110	100krad Biased	24.334	24.171	-0.163

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.126	24.582	25.09	0.48371	24.173	24.62	25.125	0.4787	0.0314	0.038	0.0469	0.0080019
50	23.941	24.352	24.888	0.38764	23.82	24.239	24.663	0.37176	-0.2249	-0.11318	0.0227	0.10202
55	24.166	24.467	24.944	0.31674	23.926	24.491	25.063	0.42054	-0.2629	0.02346	0.1393	0.17195
100	23.992	24.255	24.492	0.21028	23.785	24.12	24.373	0.21422	-0.2404	-0.1351	0.0312	0.1052
110	24.168	24.372	24.662	0.21305	24.037	24.18	24.374	0.1375	-0.4107	-0.19136	-0.0995	0.12482

Device Test: 35.1 SWITCHING_FREQ|/CFLYP///0mA/3/@F_SW





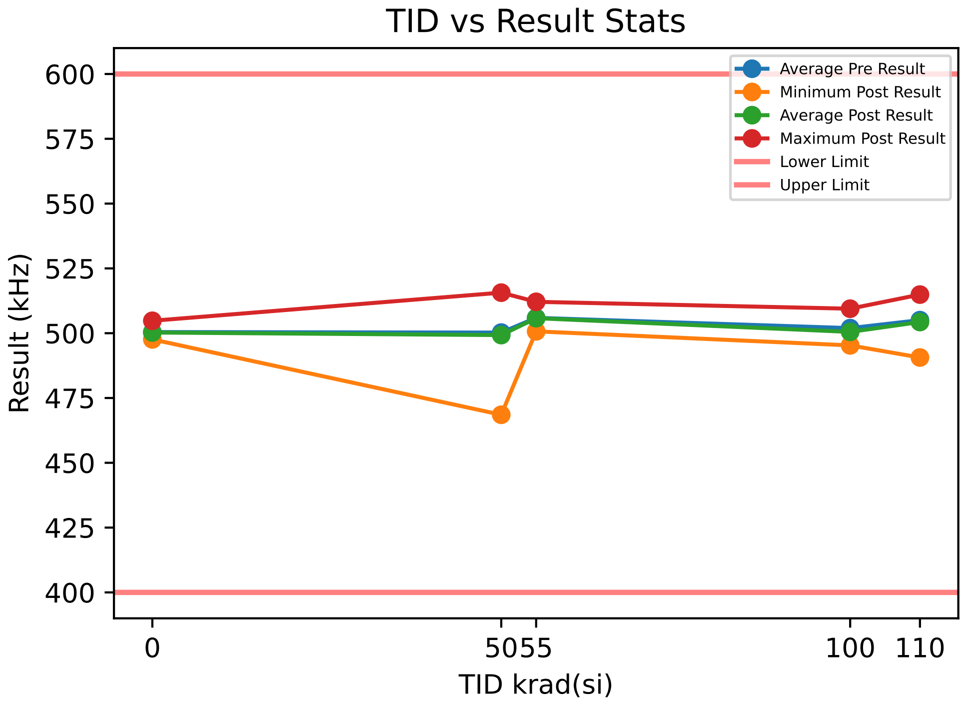
Test Results (Lower Limit = 400.0, Upper Limit = 600.0 (kHz))

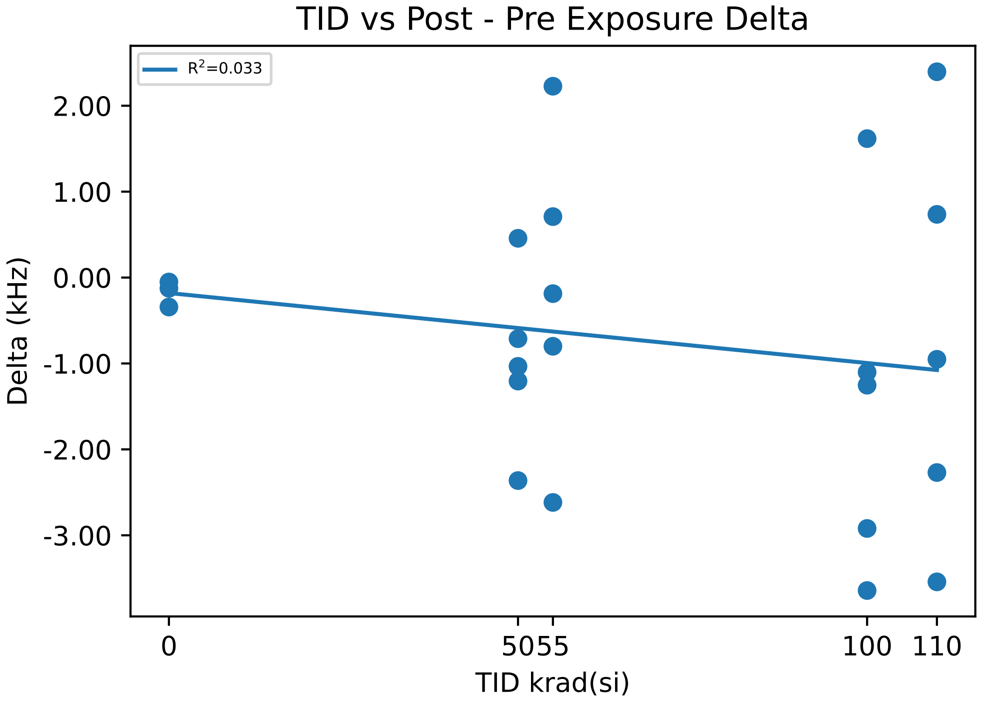
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	498.66	498.6	-0.0595
2	0	CU	505.12	505.04	-0.0717
3	0	CU	498.18	497.82	-0.3663
40	50	50krad Unbiased	507.2	506.5	-0.6973
41	50	50krad Unbiased	516.92	515.93	-0.9873
42	50	50krad Unbiased	498.4	497.2	-1.197
43	50	50krad Unbiased	511.6	509.28	-2.3204
44	50	50krad Unbiased	468.28	468.73	0.4564
45	55	50krad Biased	510.12	512.37	2.2461
46	55	50krad Biased	503.86	503.07	-0.7872
47	55	50krad Biased	508.41	508.2	-0.2148
48	55	50krad Biased	504.87	505.65	0.778
49	55	50krad Biased	503.58	500.98	-2.6044
50	100	100krad Unbiased	496.76	495.47	-1.2957
51	100	100krad Unbiased	504.35	500.77	-3.5789
52	100	100krad Unbiased	508.08	509.67	1.5835
53	100	100krad Unbiased	499.21	496.21	-3.0017
54	100	100krad Unbiased	502.51	501.34	-1.1669
55	110	100krad Biased	509.58	510.27	0.6848
56	110	100krad Biased	507.72	504.15	-3.5745
57	110	100krad Biased	504.46	502.18	-2.2823
58	110	100krad Biased	491.78	490.84	-0.9345
59	110	100krad Biased	512.75	515.05	2.2966

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	498.18	500.65	505.12	3.8734	497.82	500.49	505.04	3.9669	-0.3663	-0.16583	-0.0595	0.17372
50	468.28	500.48	516.92	19.237	468.73	499.53	515.93	18.483	-2.3204	-0.94912	0.4564	0.99777
55	503.58	506.17	510.12	2.9315	500.98	506.05	512.37	4.4519	-2.6044	-0.11646	2.2461	1.8049
100	496.76	502.18	508.08	4.4129	495.47	500.69	509.67	5.6666	-3.5789	-1.4919	1.5835	2.0148
110	491.78	505.26	512.75	8.1131	490.84	504.5	515.05	9.1726	-3.5745	-0.76198	2.2966	2.3291

Device Test: 35.2 SWITCHING_FREQ|/CFLYP///10mA/3/@F_SW





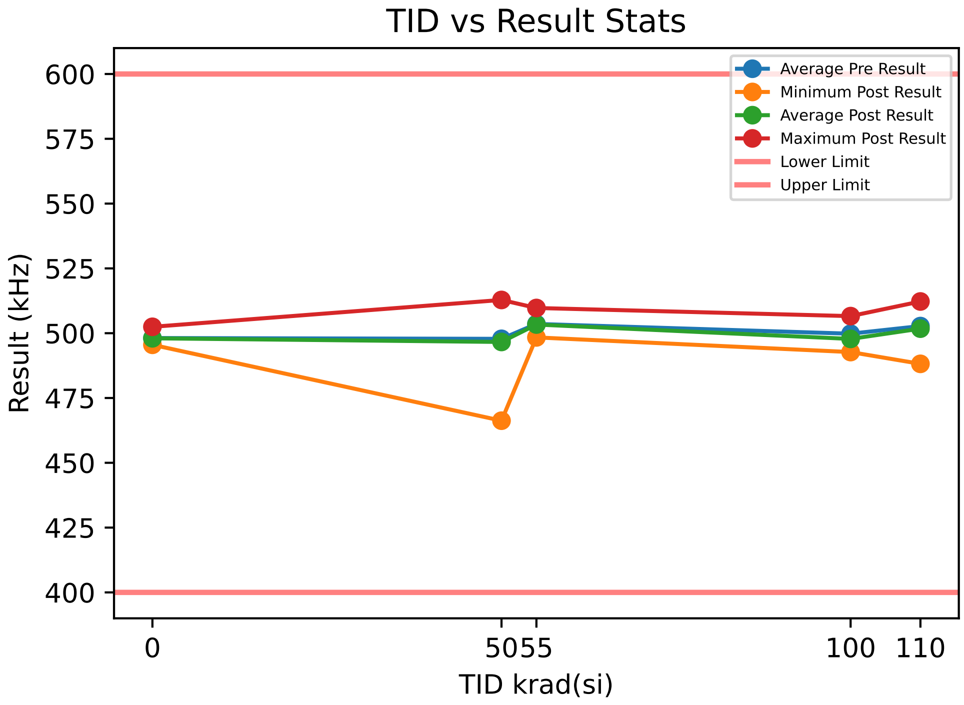
Test Results (Lower Limit = 400.0, Upper Limit = 600.0 (kHz))

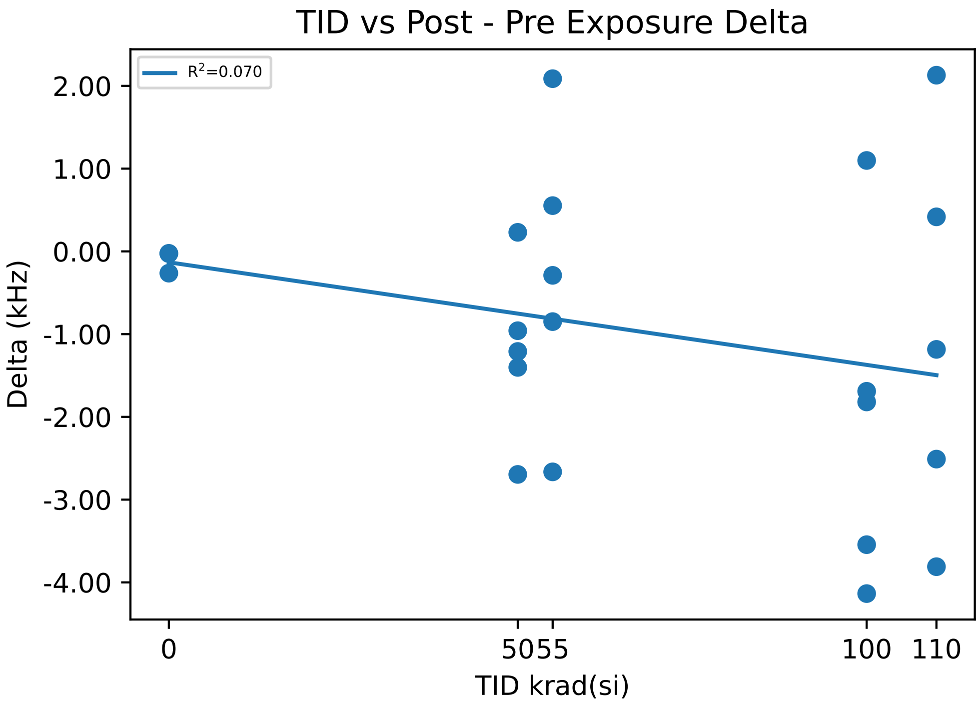
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	498.43	498.38	-0.0517
2	0	CU	504.92	504.79	-0.1249
3	0	CU	497.96	497.62	-0.3429
40	50	50krad Unbiased	506.96	506.24	-0.7113
41	50	50krad Unbiased	516.68	515.64	-1.0336
42	50	50krad Unbiased	498.15	496.95	-1.205
43	50	50krad Unbiased	511.35	508.99	-2.363
44	50	50krad Unbiased	468.08	468.53	0.457
45	55	50krad Biased	509.88	512.11	2.2271
46	55	50krad Biased	503.61	502.81	-0.8
47	55	50krad Biased	508.16	507.97	-0.1871
48	55	50krad Biased	504.65	505.36	0.7095
49	55	50krad Biased	503.33	500.71	-2.6176
50	100	100krad Unbiased	496.55	495.3	-1.253
51	100	100krad Unbiased	504.15	500.51	-3.6428
52	100	100krad Unbiased	507.84	509.45	1.6173
53	100	100krad Unbiased	498.98	496.06	-2.9204
54	100	100krad Unbiased	502.29	501.19	-1.1016
55	110	100krad Biased	509.35	510.09	0.7355
56	110	100krad Biased	507.51	503.97	-3.542
57	110	100krad Biased	504.24	501.97	-2.2695
58	110	100krad Biased	491.58	490.62	-0.9514
59	110	100krad Biased	512.5	514.9	2.3955

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	497.96	500.44	504.92	3.8896	497.62	500.26	504.79	3.9427	-0.3429	-0.17317	-0.0517	0.15148
50	468.08	500.24	516.68	19.221	468.53	499.27	515.64	18.449	-2.363	-0.97118	0.457	1.0128
55	503.33	505.93	509.88	2.9298	500.71	505.79	512.11	4.4578	-2.6176	-0.13362	2.2271	1.7959
100	496.55	501.96	507.84	4.4027	495.3	500.5	509.45	5.6426	-3.6428	-1.4601	1.6173	2.0334
110	491.58	505.04	512.5	8.0985	490.62	504.31	514.9	9.1979	-3.542	-0.72638	2.3955	2.3581

Device Test: 35.3 SWITCHING_FREQ|/CFLYP///150mA/3/@F_SW





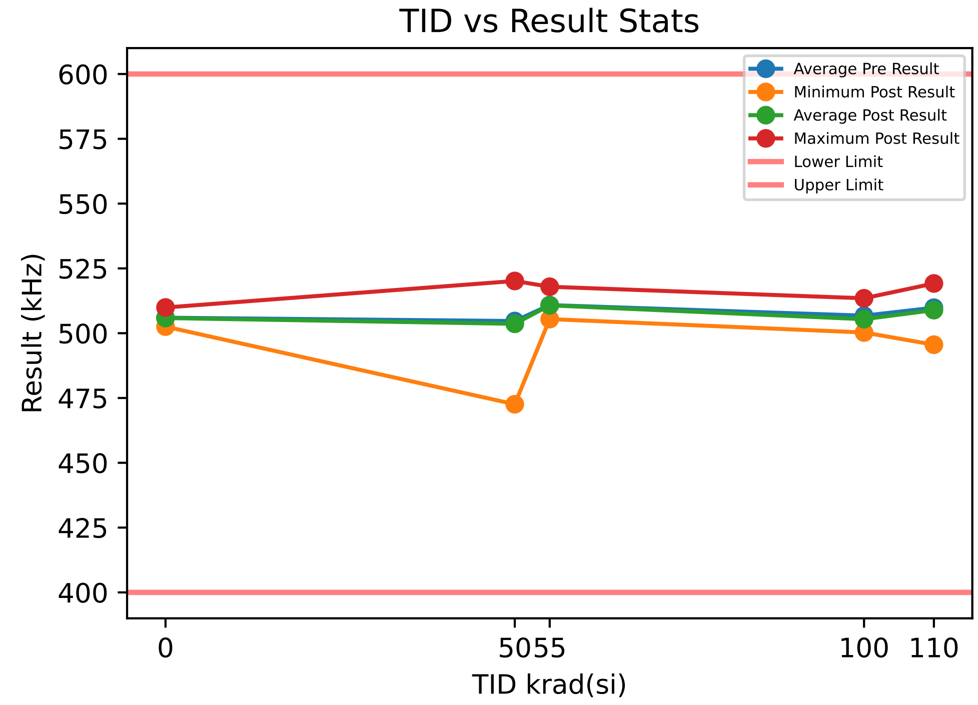
Test Results (Lower Limit = 400.0, Upper Limit = 600.0 (kHz))

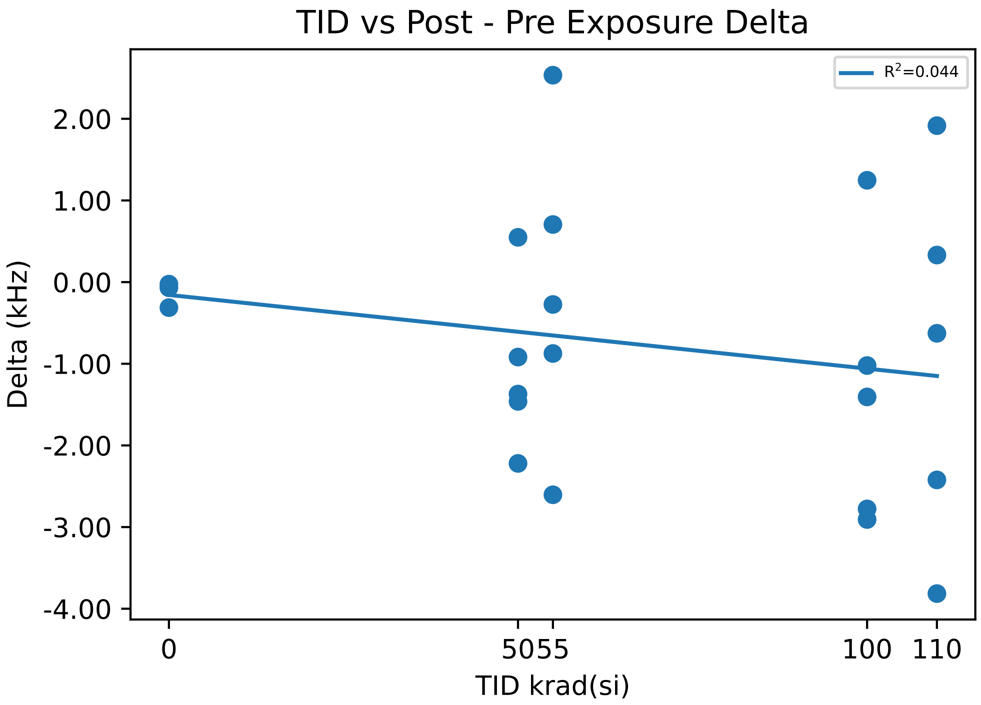
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	496.12	496.09	-0.0262
2	0	CU	502.49	502.46	-0.0238
3	0	CU	495.79	495.52	-0.2633
40	50	50krad Unbiased	504.39	503.43	-0.9586
41	50	50krad Unbiased	514.04	512.83	-1.2096
42	50	50krad Unbiased	495.61	494.21	-1.4019
43	50	50krad Unbiased	509.09	506.39	-2.6953
44	50	50krad Unbiased	466.02	466.25	0.2302
45	55	50krad Biased	507.64	509.73	2.0871
46	55	50krad Biased	501.13	500.28	-0.8488
47	55	50krad Biased	505.54	505.25	-0.2896
48	55	50krad Biased	502.53	503.08	0.5531
49	55	50krad Biased	501.04	498.38	-2.6644
50	100	100krad Unbiased	494.54	492.72	-1.8194
51	100	100krad Unbiased	501.89	497.76	-4.1356
52	100	100krad Unbiased	505.49	506.59	1.0987
53	100	100krad Unbiased	496.88	493.34	-3.5443
54	100	100krad Unbiased	500.26	498.57	-1.6907
55	110	100krad Biased	507.2	507.61	0.4175
56	110	100krad Biased	505.13	501.32	-3.8105
57	110	100krad Biased	501.93	499.42	-2.5103
58	110	100krad Biased	489.36	488.18	-1.1843
59	110	100krad Biased	510.11	512.24	2.1292

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	495.79	498.13	502.49	3.775	495.52	498.03	502.46	3.8518	-0.2633	-0.10443	-0.0238	0.13759
50	466.02	497.83	514.04	19.036	466.25	496.62	512.83	18.255	-2.6953	-1.207	0.2302	1.0465
55	501.04	503.58	507.64	2.9113	498.38	503.34	509.73	4.4309	-2.6644	-0.23252	2.0871	1.7532
100	494.54	499.81	505.49	4.2761	492.72	497.79	506.59	5.5576	-4.1356	-2.0183	1.0987	2.0417
110	489.36	502.75	510.11	8.0549	488.18	501.75	512.24	9.1409	-3.8105	-0.99168	2.1292	2.346

Device Test: 35.4 SWITCHING_FREQ|/CFLYP///0mA/6.3/@F_SW





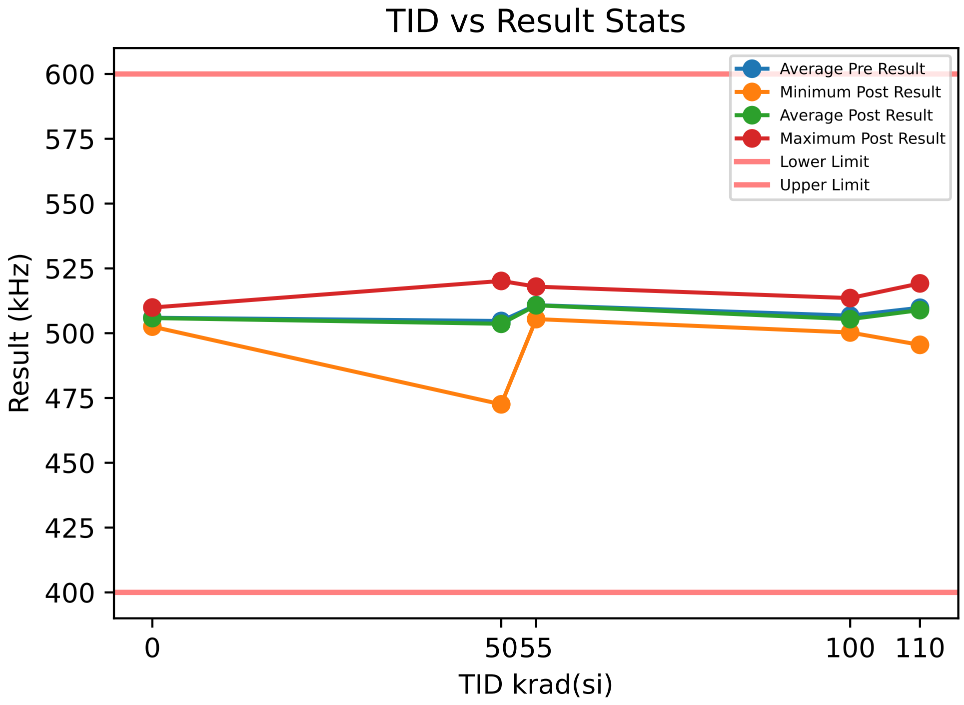
Test Results (Lower Limit = 400.0, Upper Limit = 600.0 (kHz))

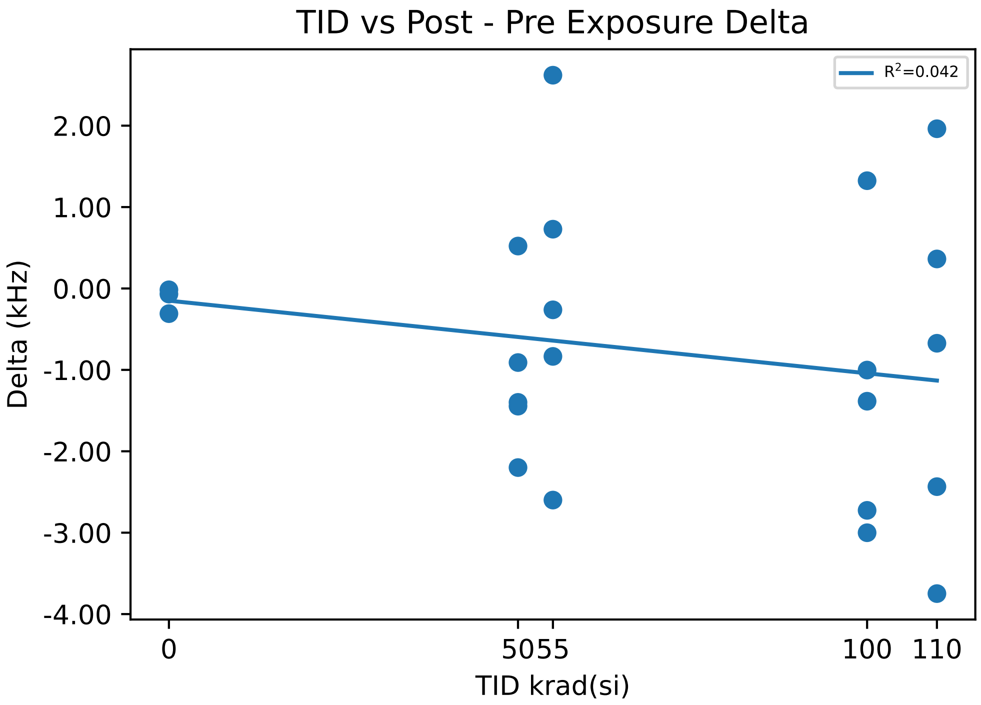
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	505.1	505.08	-0.0249
2	0	CU	509.98	509.91	-0.0687
3	0	CU	502.85	502.53	-0.3124
40	50	50krad Unbiased	511.19	510.27	-0.918
41	50	50krad Unbiased	521.52	520.15	-1.3712
42	50	50krad Unbiased	502.69	501.23	-1.4608
43	50	50krad Unbiased	516.08	513.86	-2.2205
44	50	50krad Unbiased	472.04	472.59	0.5483
45	55	50krad Biased	515.39	517.93	2.5339
46	55	50krad Biased	508.42	507.55	-0.8743
47	55	50krad Biased	512.77	512.49	-0.274
48	55	50krad Biased	509.61	510.32	0.7054
49	55	50krad Biased	508.05	505.44	-2.6044
50	100	100krad Unbiased	501.68	500.27	-1.4061
51	100	100krad Unbiased	509.31	506.4	-2.9072
52	100	100krad Unbiased	512.22	513.47	1.247
53	100	100krad Unbiased	503.63	500.85	-2.7777
54	100	100krad Unbiased	507.04	506.01	-1.0218
55	110	100krad Biased	513.64	513.97	0.3313
56	110	100krad Biased	512.01	508.19	-3.8147
57	110	100krad Biased	510.03	507.61	-2.4224
58	110	100krad Biased	496.19	495.56	-0.627
59	110	100krad Biased	517.27	519.19	1.9162

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	502.85	505.98	509.98	3.6488	502.53	505.84	509.91	3.75	-0.3124	-0.13533	-0.0249	0.1549
50	472.04	504.7	521.52	19.528	472.59	503.62	520.15	18.649	-2.2205	-1.0844	0.5483	1.0257
55	508.05	510.85	515.39	3.1461	505.44	510.75	517.93	4.8253	-2.6044	-0.10268	2.5339	1.9031
100	501.68	506.78	512.22	4.2435	500.27	505.4	513.47	5.3262	-2.9072	-1.3732	1.247	1.6819
110	496.19	509.83	517.27	8.072	495.56	508.9	519.19	8.8242	-3.8147	-0.92332	1.9162	2.2546

Device Test: 35.5 SWITCHING_FREQ|/CFLYP///10mA/6.3/@F_SW


TID vs Result Stats


TID vs Post - Pre Exposure Delta

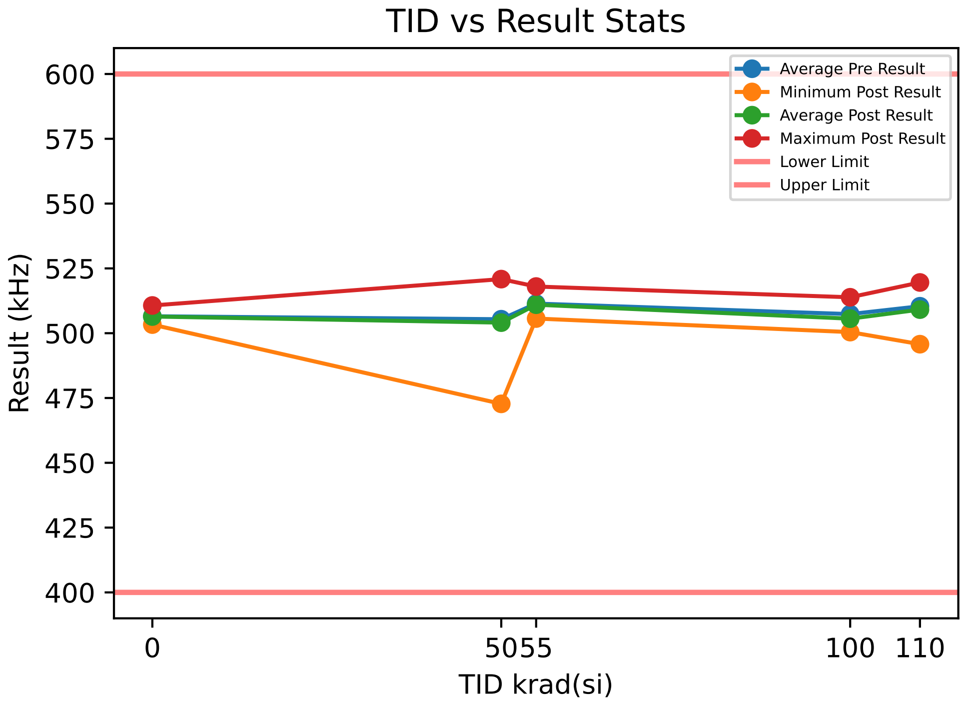
Test Results (Lower Limit = 400.0, Upper Limit = 600.0 (kHz))

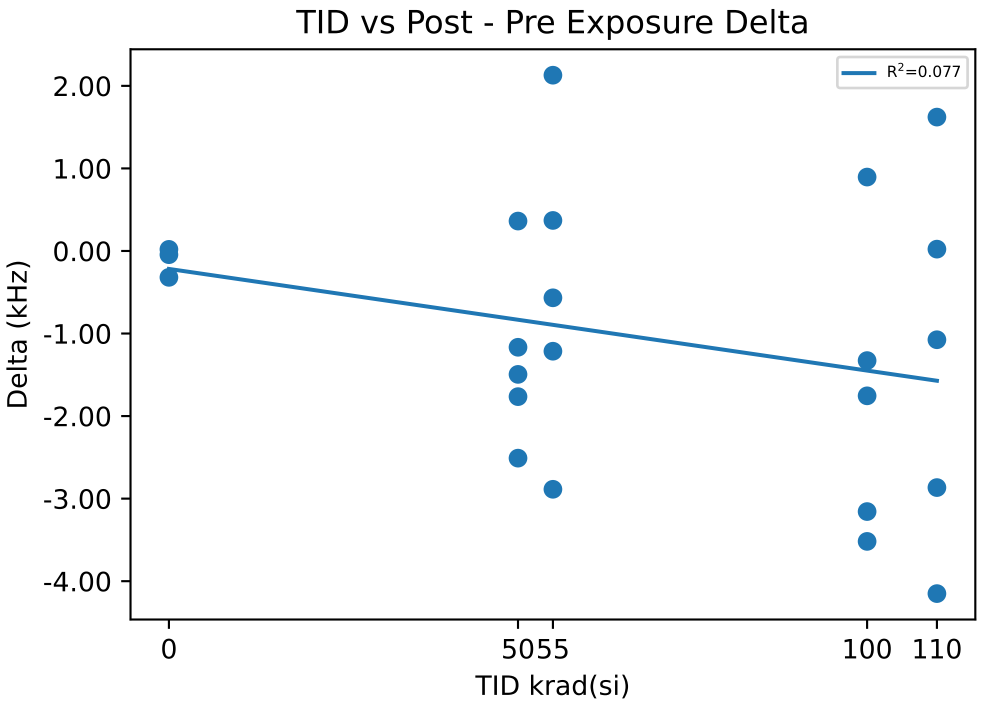
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	505.08	505.07	-0.0162
2	0	CU	509.98	509.91	-0.0686
3	0	CU	502.84	502.53	-0.3092
40	50	50krad Unbiased	511.19	510.28	-0.9099
41	50	50krad Unbiased	521.56	520.16	-1.3992
42	50	50krad Unbiased	502.7	501.26	-1.4456
43	50	50krad Unbiased	516.08	513.88	-2.2001
44	50	50krad Unbiased	472.04	472.56	0.5212
45	55	50krad Biased	515.34	517.96	2.62
46	55	50krad Biased	508.41	507.58	-0.8345
47	55	50krad Biased	512.75	512.49	-0.2623
48	55	50krad Biased	509.59	510.32	0.7283
49	55	50krad Biased	508.04	505.44	-2.5994
50	100	100krad Unbiased	501.66	500.27	-1.385
51	100	100krad Unbiased	509.36	506.36	-3.0006
52	100	100krad Unbiased	512.22	513.54	1.324
53	100	100krad Unbiased	503.63	500.9	-2.7257
54	100	100krad Unbiased	507.03	506.03	-1.0023
55	110	100krad Biased	513.64	514	0.3627
56	110	100krad Biased	512	508.25	-3.7483
57	110	100krad Biased	510.01	507.58	-2.4344
58	110	100krad Biased	496.18	495.51	-0.673
59	110	100krad Biased	517.25	519.21	1.9622

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	502.84	505.97	509.98	3.6487	502.53	505.84	509.91	3.7474	-0.3092	-0.13133	-0.0162	0.15625
50	472.04	504.71	521.56	19.535	472.56	503.63	520.16	18.664	-2.2001	-1.0867	0.5212	1.0103
55	508.04	510.83	515.34	3.1299	505.44	510.76	517.96	4.8332	-2.5994	-0.06958	2.62	1.9296
100	501.66	506.78	512.22	4.2569	500.27	505.42	513.54	5.3418	-3.0006	-1.3579	1.324	1.724
110	496.18	509.81	517.25	8.072	495.51	508.91	519.21	8.8592	-3.7483	-0.90616	1.9622	2.2531

Device Test: 35.6 SWITCHING_FREQ|/CFLYP///400mA/6.3/@F_SW





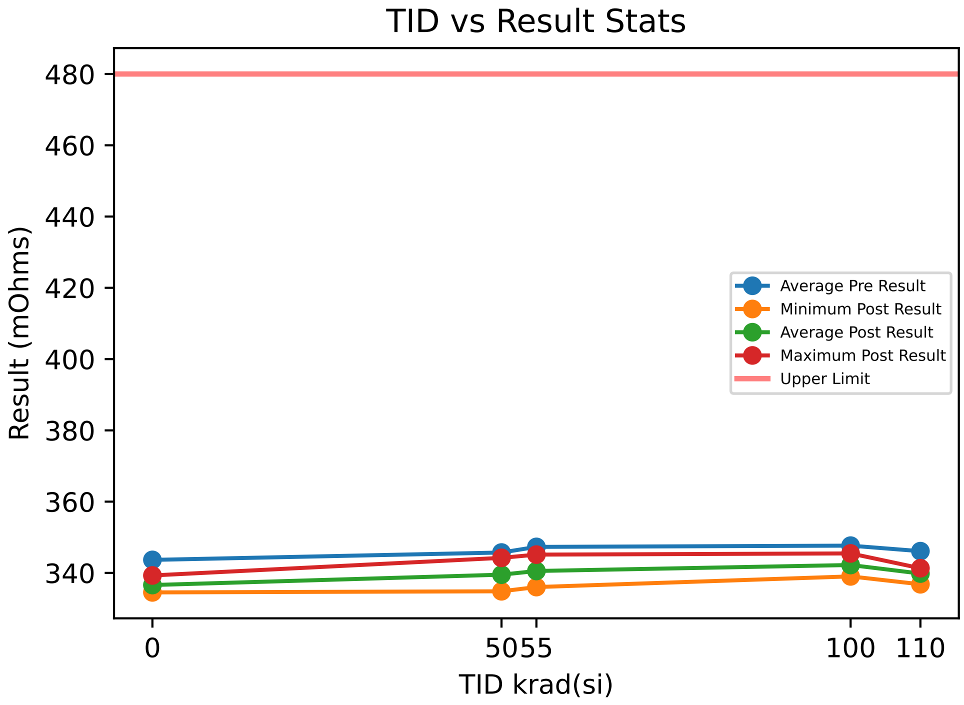
Test Results (Lower Limit = 400.0, Upper Limit = 600.0 (kHz))

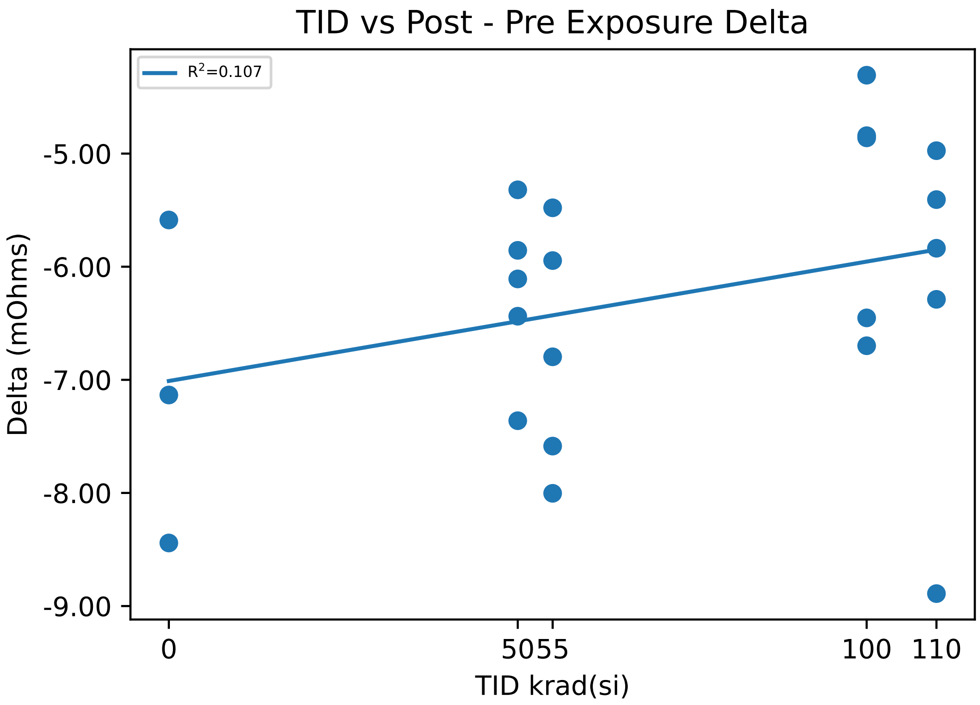
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	505.24	505.26	0.0195
2	0	CU	510.74	510.7	-0.0449
3	0	CU	503.64	503.32	-0.3194
40	50	50krad Unbiased	512.11	510.95	-1.1665
41	50	50krad Unbiased	522.36	520.87	-1.495
42	50	50krad Unbiased	503.48	501.72	-1.7645
43	50	50krad Unbiased	516.63	514.12	-2.5096
44	50	50krad Unbiased	472.38	472.74	0.3623
45	55	50krad Biased	515.87	518	2.1292
46	55	50krad Biased	509.17	507.96	-1.2144
47	55	50krad Biased	513.33	512.76	-0.5673
48	55	50krad Biased	510.21	510.58	0.3698
49	55	50krad Biased	508.54	505.66	-2.8868
50	100	100krad Unbiased	502.18	500.43	-1.7547
51	100	100krad Unbiased	509.93	506.41	-3.5181
52	100	100krad Unbiased	512.96	513.86	0.8953
53	100	100krad Unbiased	504.18	501.03	-3.1566
54	100	100krad Unbiased	507.6	506.28	-1.3277
55	110	100krad Biased	514.13	514.15	0.0222
56	110	100krad Biased	512.62	508.47	-4.1504
57	110	100krad Biased	510.43	507.56	-2.8661
58	110	100krad Biased	496.83	495.76	-1.0753
59	110	100krad Biased	517.95	519.57	1.6217

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	503.64	506.54	510.74	3.7234	503.32	506.43	510.7	3.8221	-0.3194	-0.11493	0.0195	0.17998
50	472.38	505.39	522.36	19.702	472.74	504.08	520.87	18.823	-2.5096	-1.3147	0.3623	1.0603
55	508.54	511.43	515.87	3.0932	505.66	510.99	518	4.7467	-2.8868	-0.4339	2.1292	1.8614
100	502.18	507.37	512.96	4.3292	500.43	505.6	513.86	5.4088	-3.5181	-1.7724	0.8953	1.752
110	496.83	510.39	517.95	8.0608	495.76	509.1	519.57	8.8876	-4.1504	-1.2896	1.6217	2.2865

Device Test: 40.2 RDSON|//SW1////@SW1_RDSON





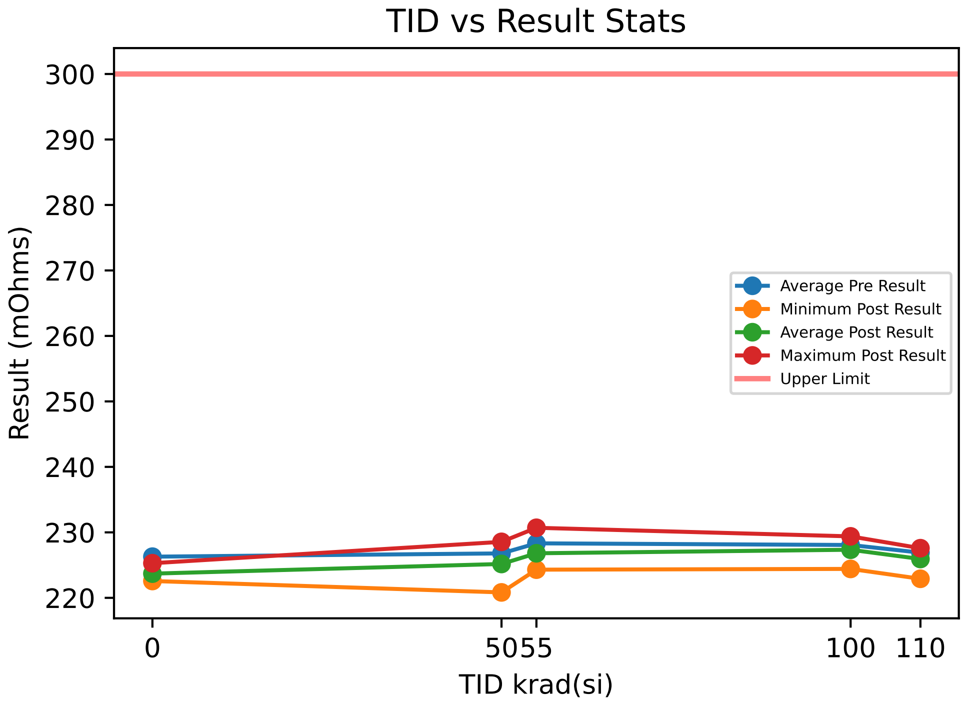
Test Results (Upper Limit = 480.0 (mOhms))

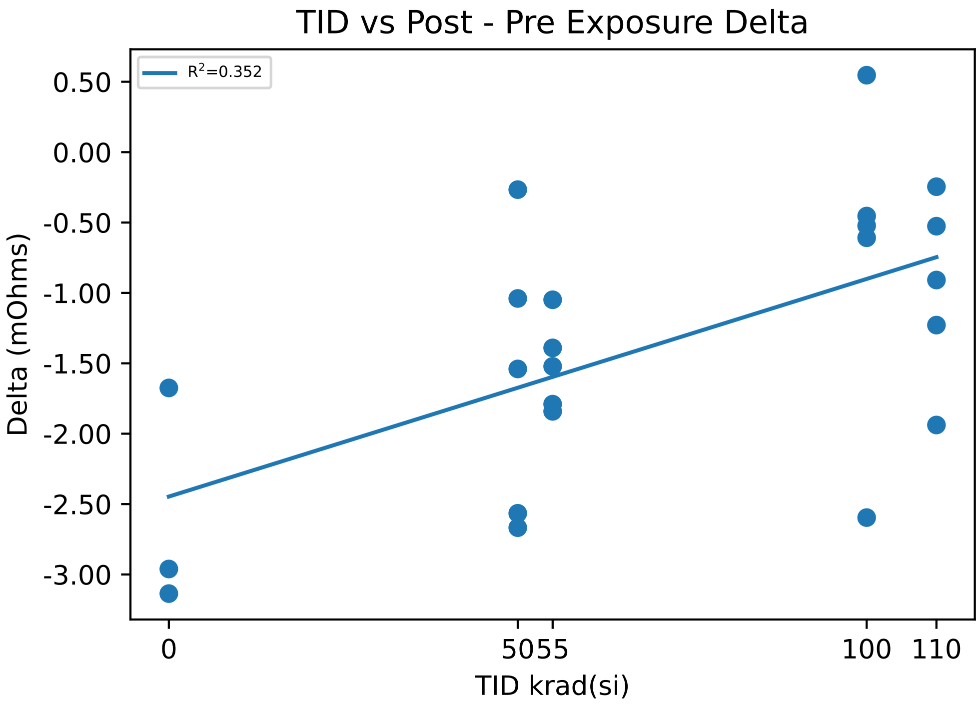
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	344.88	339.29	-5.5867
2	0	CU	343.11	335.98	-7.1341
3	0	CU	342.98	334.53	-8.4423
40	50	50krad Unbiased	346.1	339.99	-6.1079
41	50	50krad Unbiased	343.43	337.58	-5.8553
42	50	50krad Unbiased	350.66	344.23	-6.4376
43	50	50krad Unbiased	348.25	340.89	-7.3614
44	50	50krad Unbiased	340.16	334.84	-5.3202
45	55	50krad Biased	343.75	338.27	-5.4791
46	55	50krad Biased	347.96	341.16	-6.7964
47	55	50krad Biased	353.14	345.14	-8.0033
48	55	50krad Biased	343.61	336.03	-7.5858
49	55	50krad Biased	348.05	342.1	-5.9457
50	100	100krad Unbiased	346.68	341.84	-4.8416
51	100	100krad Unbiased	349.33	344.47	-4.8608
52	100	100krad Unbiased	351.92	345.47	-6.4524
53	100	100krad Unbiased	344.61	340.31	-4.3068
54	100	100krad Unbiased	345.72	339.02	-6.6986
55	110	100krad Biased	343.1	336.81	-6.2884
56	110	100krad Biased	346.23	341.26	-4.9741
57	110	100krad Biased	345.56	339.72	-5.8366
58	110	100krad Biased	346.72	341.32	-5.4066
59	110	100krad Biased	348.9	340.01	-8.8899

Test Statistics (mOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	342.98	343.65	344.88	1.06	334.53	336.6	339.29	2.4379	-8.4423	-7.0544	-5.5867	1.4295
50	340.16	345.72	350.66	4.0957	334.84	339.51	344.23	3.5317	-7.3614	-6.2165	-5.3202	0.75916
55	343.61	347.3	353.14	3.9138	336.03	340.54	345.14	3.5162	-8.0033	-6.7621	-5.4791	1.0645
100	344.61	347.65	351.92	2.9556	339.02	342.22	345.47	2.7216	-6.6986	-5.432	-4.3068	1.0708
110	343.1	346.1	348.9	2.0947	336.81	339.82	341.32	1.8302	-8.8899	-6.2791	-4.9741	1.5392

Device Test: 40.3 RDSON|//SW3////@SW3_RDSON





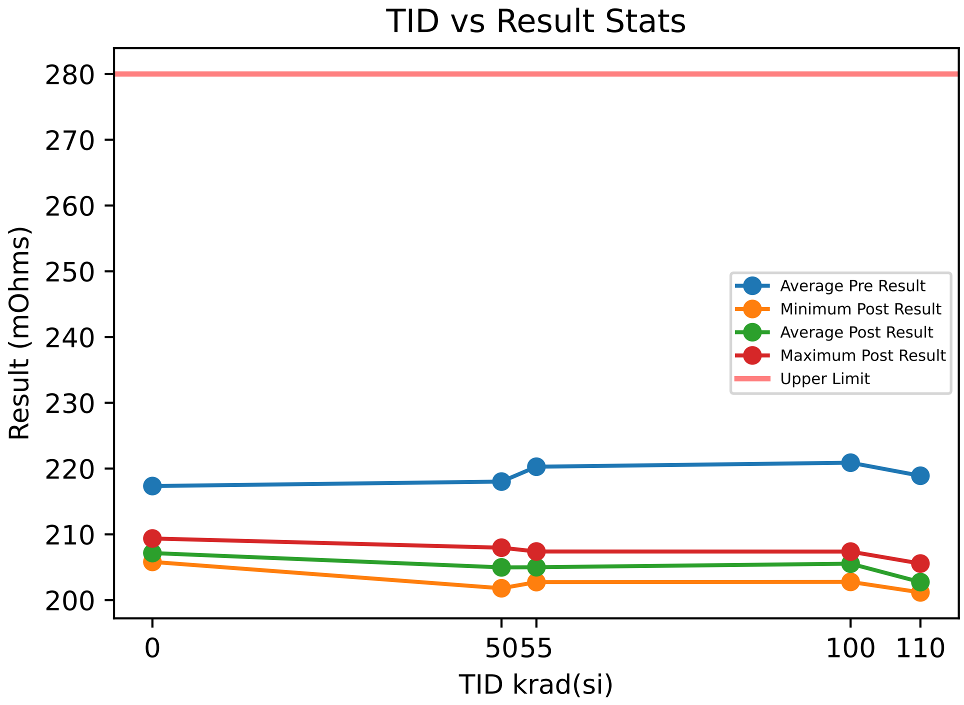
Test Results (Upper Limit = 300.0 (mOhms))

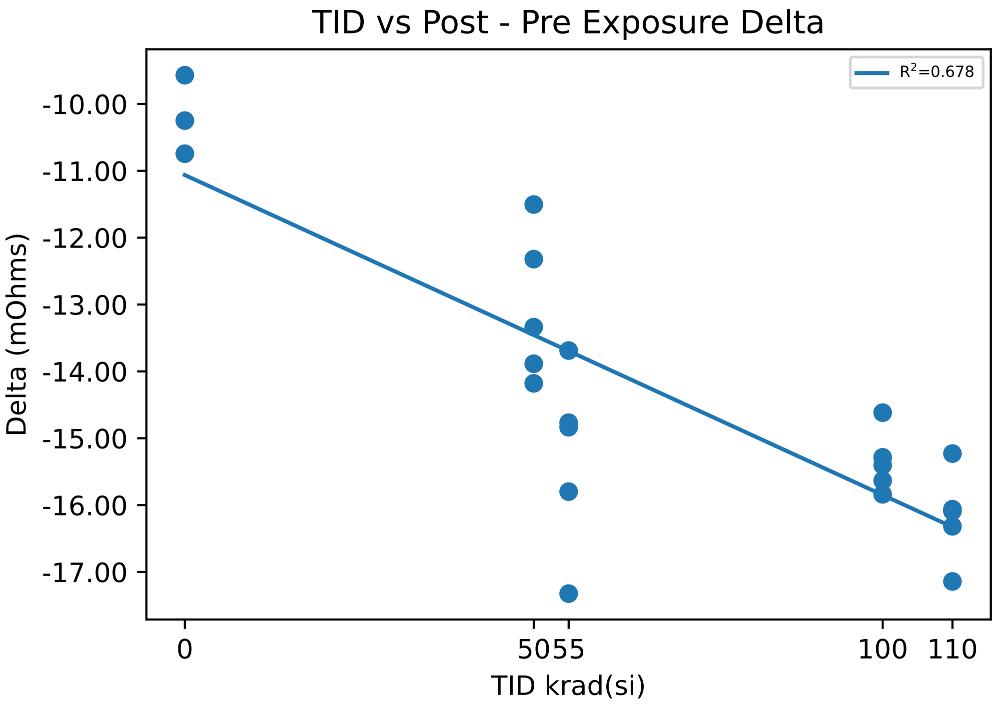
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	228.25	225.29	-2.9611
2	0	CU	224.91	223.23	-1.6749
3	0	CU	225.71	222.57	-3.1359
40	50	50krad Unbiased	227.3	225.76	-1.54
41	50	50krad Unbiased	223.79	223.52	-0.2662
42	50	50krad Unbiased	231.12	228.55	-2.5654
43	50	50krad Unbiased	229.86	227.19	-2.6676
44	50	50krad Unbiased	221.87	220.83	-1.0393
45	55	50krad Biased	226.42	225.03	-1.3904
46	55	50krad Biased	227.06	225.27	-1.7901
47	55	50krad Biased	232.22	230.7	-1.5218
48	55	50krad Biased	226.15	224.3	-1.8413
49	55	50krad Biased	229.78	228.73	-1.0486
50	100	100krad Unbiased	228.52	229.07	0.5467
51	100	100krad Unbiased	229.91	229.39	-0.5223
52	100	100krad Unbiased	230.78	228.18	-2.596
53	100	100krad Unbiased	226.13	225.67	-0.4539
54	100	100krad Unbiased	225.03	224.42	-0.6083
55	110	100krad Biased	223.82	222.91	-0.9083
56	110	100krad Biased	227.11	225.88	-1.2285
57	110	100krad Biased	227.83	227.58	-0.2453
58	110	100krad Biased	227.83	227.3	-0.5259
59	110	100krad Biased	227.93	225.99	-1.9382

Test Statistics (mOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	224.91	226.29	228.25	1.7456	222.57	223.7	225.29	1.4172	-3.1359	-2.5906	-1.6749	0.79785
50	221.87	226.79	231.12	3.9246	220.83	225.17	228.55	3.0581	-2.6676	-1.6157	-0.2662	1.0207
55	226.15	228.32	232.22	2.6114	224.3	226.81	230.7	2.7677	-1.8413	-1.5184	-1.0486	0.32218
100	225.03	228.07	230.78	2.4473	224.42	227.35	229.39	2.1912	-2.596	-0.72676	0.5467	1.1452
110	223.82	226.9	227.93	1.7541	222.91	225.93	227.58	1.8526	-1.9382	-0.96924	-0.2453	0.65773

Device Test: 40.5 RDSON|//SW2////@SW2_RDSON


TID vs Result Stats


TID vs Post - Pre Exposure Delta

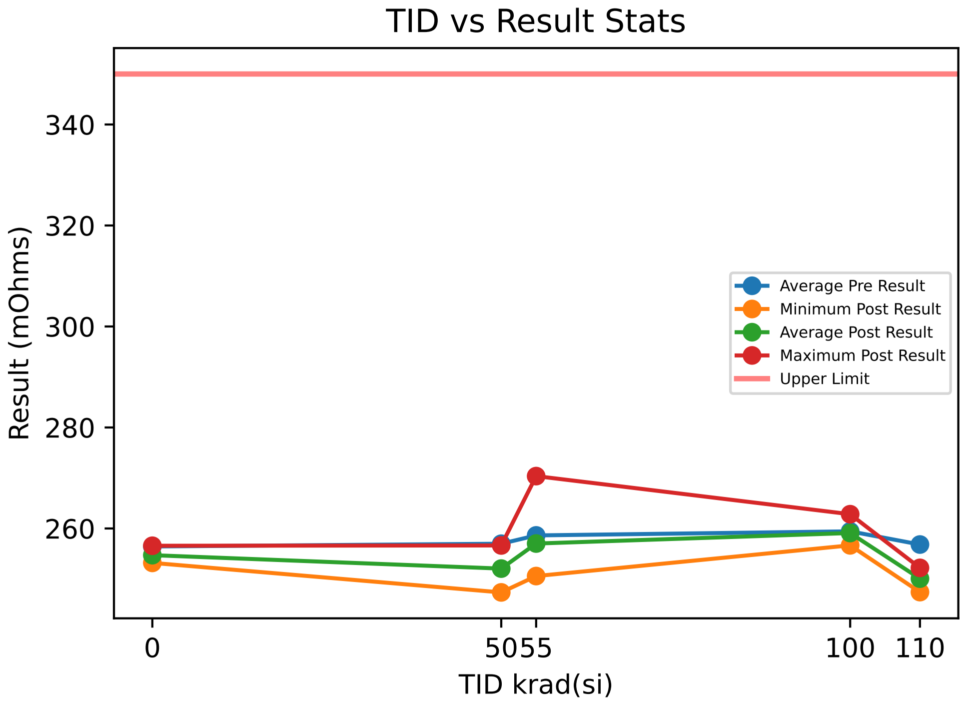
Test Results (Upper Limit = 280.0 (mOhms))

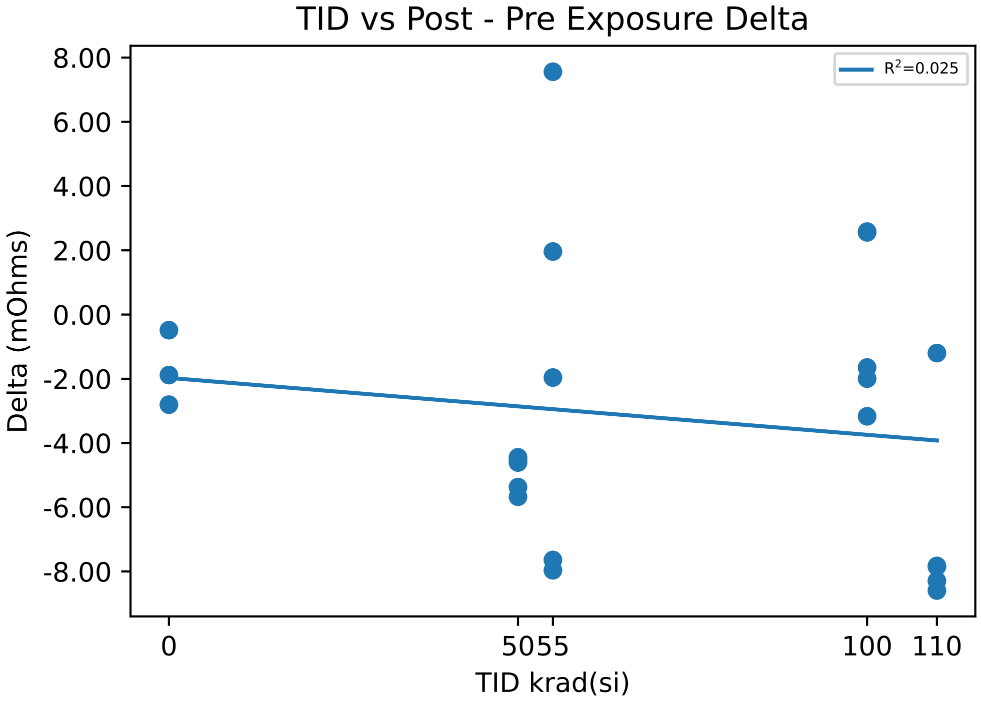
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	220.11	209.37	-10.744
2	0	CU	215.38	205.81	-9.5698
3	0	CU	216.54	206.29	-10.249
40	50	50krad Unbiased	218.3	204.96	-13.338
41	50	50krad Unbiased	216.94	203.06	-13.885
42	50	50krad Unbiased	218.59	207.08	-11.504
43	50	50krad Unbiased	220.29	207.97	-12.321
44	50	50krad Unbiased	215.98	201.8	-14.179
45	55	50krad Biased	219.27	204.43	-14.835
46	55	50krad Biased	218.54	202.74	-15.798
47	55	50krad Biased	221.08	207.39	-13.688
48	55	50krad Biased	221.84	204.52	-17.324
49	55	50krad Biased	220.68	205.91	-14.767
50	100	100krad Unbiased	222.78	207.37	-15.404
51	100	100krad Unbiased	222.44	207.15	-15.286
52	100	100krad Unbiased	220.92	205.28	-15.634
53	100	100krad Unbiased	220.95	205.11	-15.839
54	100	100krad Unbiased	217.39	202.77	-14.617
55	110	100krad Biased	217.49	201.17	-16.317
56	110	100krad Biased	217.84	201.78	-16.061
57	110	100krad Biased	220.79	205.56	-15.229
58	110	100krad Biased	220.27	203.13	-17.142
59	110	100krad Biased	218.15	202.06	-16.089

Test Statistics (mOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	215.38	217.34	220.11	2.469	205.81	207.15	209.37	1.9331	-10.744	-10.187	-9.5698	0.58948
50	215.98	218.02	220.29	1.6492	201.8	204.97	207.97	2.6061	-14.179	-13.046	-11.504	1.1154
55	218.54	220.28	221.84	1.3519	202.74	205	207.39	1.7467	-17.324	-15.282	-13.688	1.3638
100	217.39	220.89	222.78	2.1355	202.77	205.54	207.37	1.8636	-15.839	-15.356	-14.617	0.46462
110	217.49	218.91	220.79	1.5096	201.17	202.74	205.56	1.7275	-17.142	-16.168	-15.229	0.68385

Device Test: 40.6 RDSON|//SW4////@SW4_RDSON


TID vs Result Stats


TID vs Post - Pre Exposure Delta

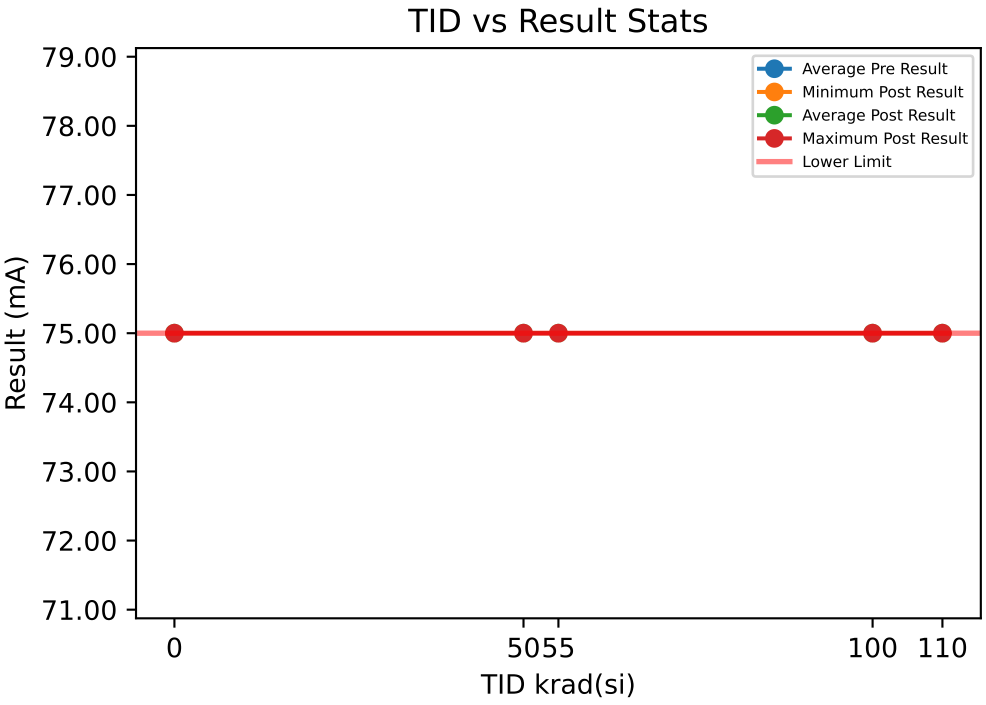
Test Results (Upper Limit = 350.0 (mOhms))

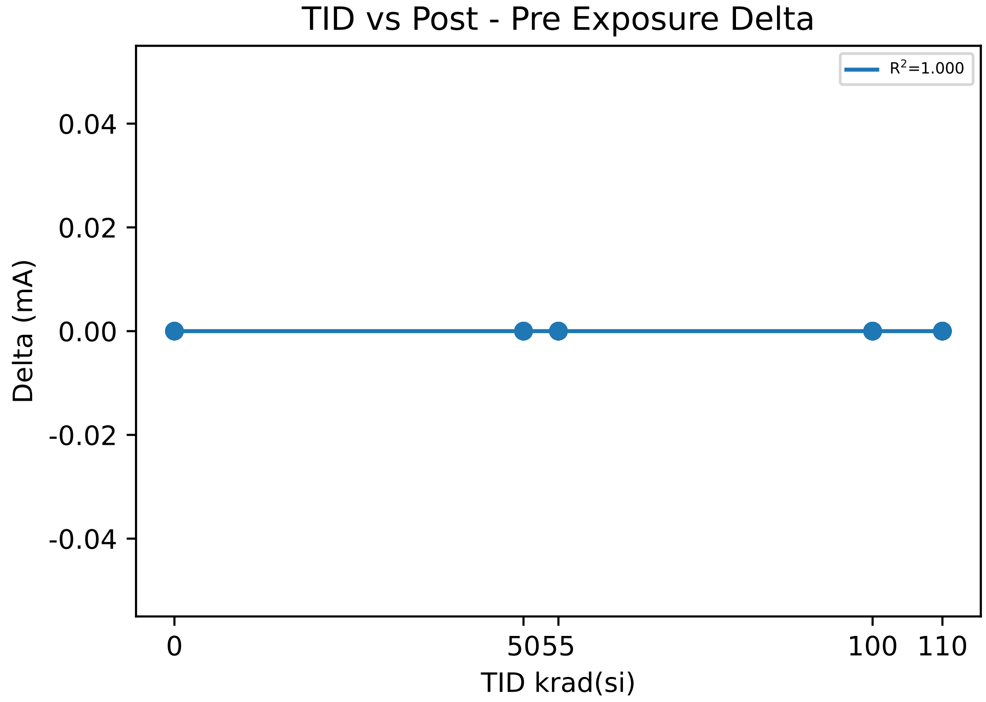
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	257.06	256.58	-0.487
2	0	CU	255.07	253.19	-1.8846
3	0	CU	257.18	254.37	-2.8057
40	50	50krad Unbiased	257.26	251.89	-5.372
41	50	50krad Unbiased	255.84	250.16	-5.6729
42	50	50krad Unbiased	261.16	256.64	-4.5274
43	50	50krad Unbiased	258.68	254.24	-4.4449
44	50	50krad Unbiased	251.95	247.34	-4.6077
45	55	50krad Biased	255.11	253.15	-1.9621
46	55	50krad Biased	256.37	258.34	1.962
47	55	50krad Biased	262.81	270.37	7.5593
48	55	50krad Biased	258.22	250.57	-7.6414
49	55	50krad Biased	260.62	252.66	-7.9631
50	100	100krad Unbiased	260.27	262.82	2.5582
51	100	100krad Unbiased	260.15	256.98	-3.168
52	100	100krad Unbiased	262.93	260.93	-1.9966
53	100	100krad Unbiased	258.3	256.66	-1.6491
54	100	100krad Unbiased	255.51	258.1	2.5833
55	110	100krad Biased	253.1	251.9	-1.1999
56	110	100krad Biased	256.21	247.92	-8.2934
57	110	100krad Biased	260.79	252.2	-8.5927
58	110	100krad Biased	258.76	250.93	-7.8279
59	110	100krad Biased	255.24	247.4	-7.8458

Test Statistics (mOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	255.07	256.44	257.18	1.1859	253.19	254.71	256.58	1.7209	-2.8057	-1.7258	-0.487	1.1675
50	251.95	256.98	261.16	3.4319	247.34	252.05	256.64	3.5912	-5.6729	-4.925	-4.4449	0.55866
55	255.11	258.63	262.81	3.1263	250.57	257.02	270.37	7.9922	-7.9631	-1.6091	7.5593	6.5897
100	255.51	259.43	262.93	2.7416	256.66	259.1	262.82	2.6788	-3.168	-0.33444	2.5833	2.7111
110	253.1	256.82	260.79	3.0084	247.4	250.07	252.2	2.2566	-8.5927	-6.7519	-1.1999	3.1203

Device Test: 44.1 DROPOUT_CURRENT|//GO_NOGO/1N8V/75mA/3/@I_DO_VIN_3V_VOUT_1N8





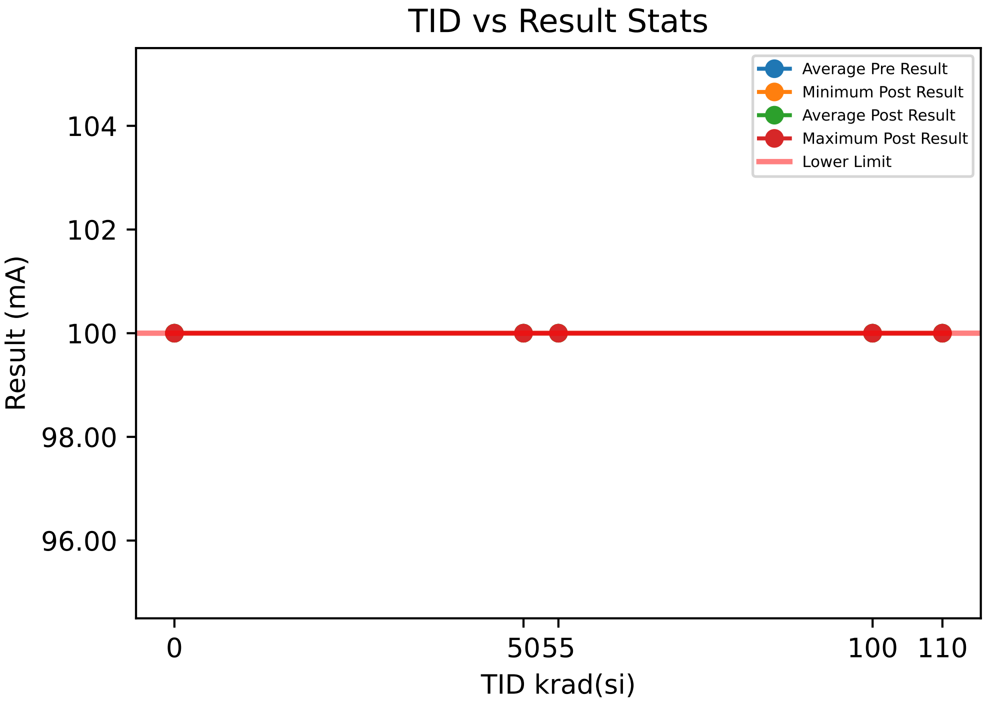
Test Results (Lower Limit = 75.0 (mA))

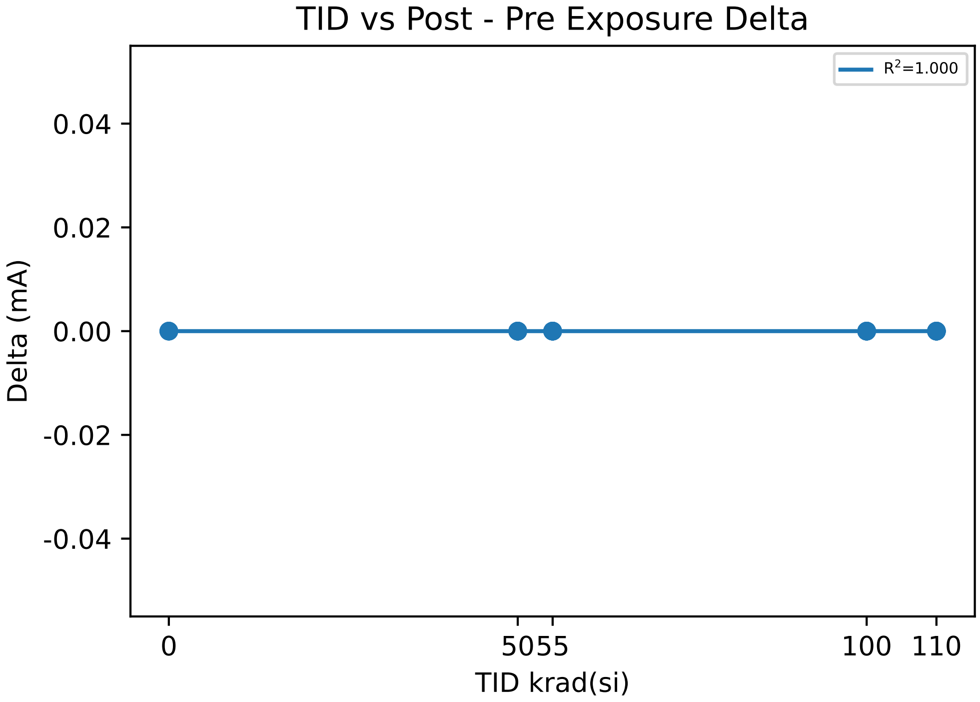
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	75	75	0
2	0	CU	75	75	0
3	0	CU	75	75	0
40	50	50krad Unbiased	75	75	0
41	50	50krad Unbiased	75	75	0
42	50	50krad Unbiased	75	75	0
43	50	50krad Unbiased	75	75	0
44	50	50krad Unbiased	75	75	0
45	55	50krad Biased	75	75	0
46	55	50krad Biased	75	75	0
47	55	50krad Biased	75	75	0
48	55	50krad Biased	75	75	0
49	55	50krad Biased	75	75	0
50	100	100krad Unbiased	75	75	0
51	100	100krad Unbiased	75	75	0
52	100	100krad Unbiased	75	75	0
53	100	100krad Unbiased	75	75	0
54	100	100krad Unbiased	75	75	0
55	110	100krad Biased	75	75	0
56	110	100krad Biased	75	75	0
57	110	100krad Biased	75	75	0
58	110	100krad Biased	75	75	0
59	110	100krad Biased	75	75	0

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	75	75	75	0	75	75	75	0	0	0	0	0
50	75	75	75	0	75	75	75	0	0	0	0	0
55	75	75	75	0	75	75	75	0	0	0	0	0
100	75	75	75	0	75	75	75	0	0	0	0	0
110	75	75	75	0	75	75	75	0	0	0	0	0

Device Test: 44.2 DROPOUT_CURRENT|//GO_NOGO/1N8V/100mA/3.3/@I_DO_VIN_3P3V_VOUT_1N8





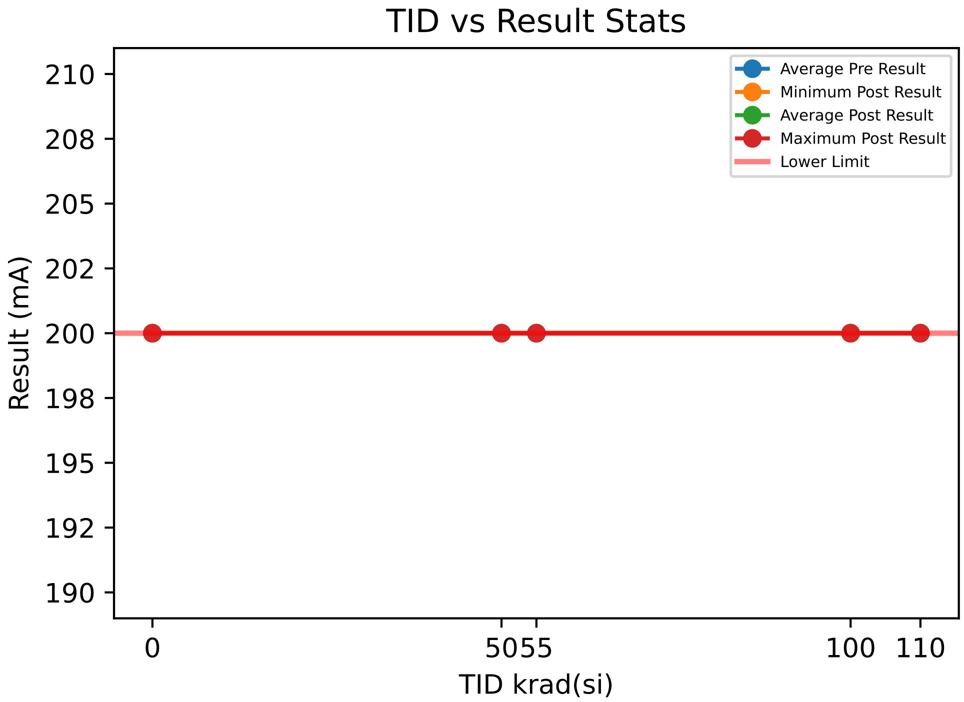
Test Results (Lower Limit = 100.0 (mA))

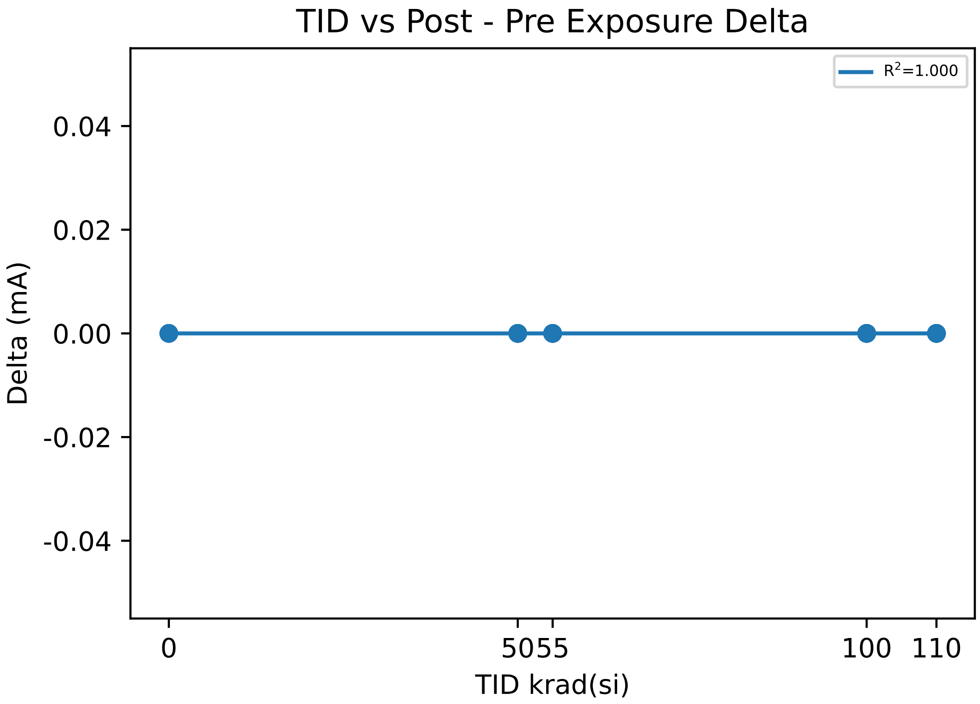
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	100	100	0
2	0	CU	100	100	0
3	0	CU	100	100	0
40	50	50krad Unbiased	100	100	0
41	50	50krad Unbiased	100	100	0
42	50	50krad Unbiased	100	100	0
43	50	50krad Unbiased	100	100	0
44	50	50krad Unbiased	100	100	0
45	55	50krad Biased	100	100	0
46	55	50krad Biased	100	100	0
47	55	50krad Biased	100	100	0
48	55	50krad Biased	100	100	0
49	55	50krad Biased	100	100	0
50	100	100krad Unbiased	100	100	0
51	100	100krad Unbiased	100	100	0
52	100	100krad Unbiased	100	100	0
53	100	100krad Unbiased	100	100	0
54	100	100krad Unbiased	100	100	0
55	110	100krad Biased	100	100	0
56	110	100krad Biased	100	100	0
57	110	100krad Biased	100	100	0
58	110	100krad Biased	100	100	0
59	110	100krad Biased	100	100	0

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0	100	100	100	0	0	0	0	0
50	100	100	100	0	100	100	100	0	0	0	0	0
55	100	100	100	0	100	100	100	0	0	0	0	0
100	100	100	100	0	100	100	100	0	0	0	0	0
110	100	100	100	0	100	100	100	0	0	0	0	0

Device Test: 44.3 DROPOUT_CURRENT|//GO_NOGO/1N8V/200mA/4/@I_DO_VIN_4V_VOUT_1N8





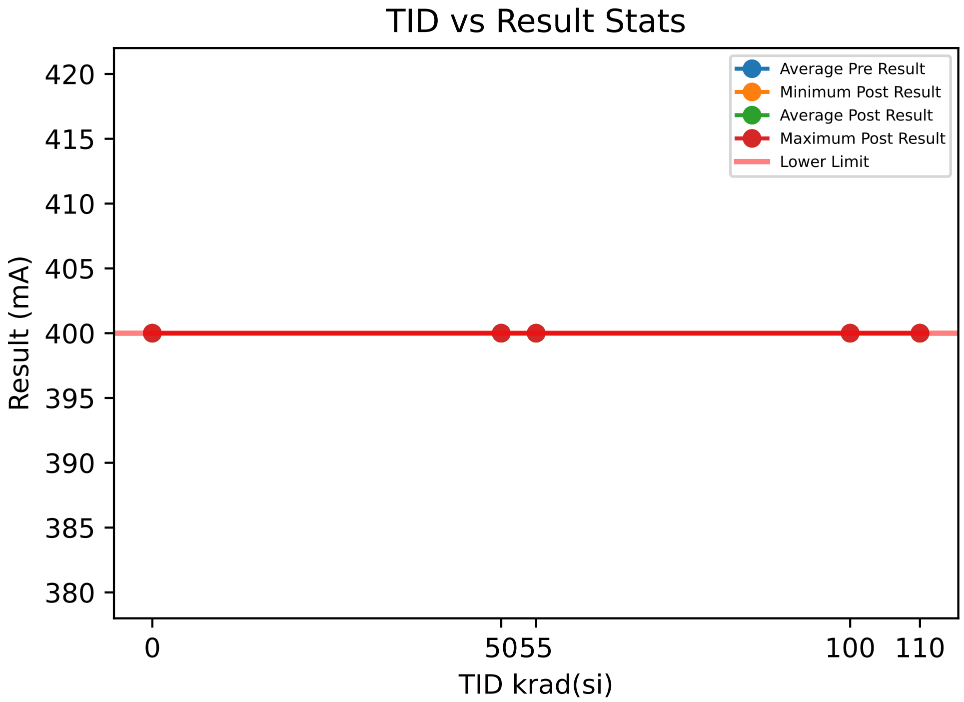
Test Results (Lower Limit = 200.0 (mA))

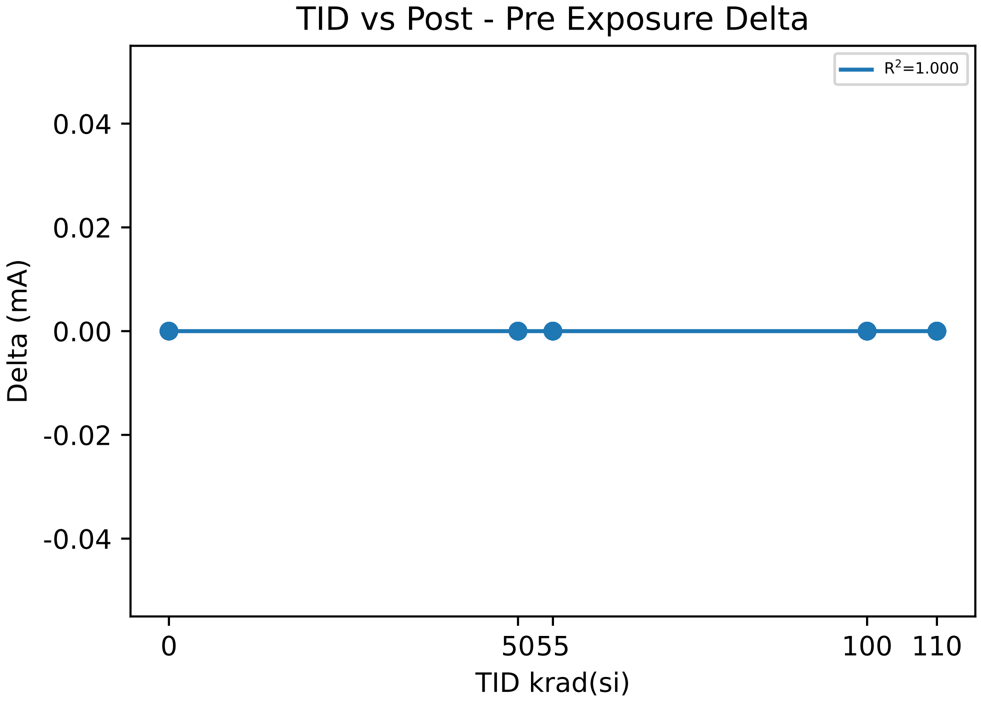
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	200	200	0
2	0	CU	200	200	0
3	0	CU	200	200	0
40	50	50krad Unbiased	200	200	0
41	50	50krad Unbiased	200	200	0
42	50	50krad Unbiased	200	200	0
43	50	50krad Unbiased	200	200	0
44	50	50krad Unbiased	200	200	0
45	55	50krad Biased	200	200	0
46	55	50krad Biased	200	200	0
47	55	50krad Biased	200	200	0
48	55	50krad Biased	200	200	0
49	55	50krad Biased	200	200	0
50	100	100krad Unbiased	200	200	0
51	100	100krad Unbiased	200	200	0
52	100	100krad Unbiased	200	200	0
53	100	100krad Unbiased	200	200	0
54	100	100krad Unbiased	200	200	0
55	110	100krad Biased	200	200	0
56	110	100krad Biased	200	200	0
57	110	100krad Biased	200	200	0
58	110	100krad Biased	200	200	0
59	110	100krad Biased	200	200	0

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200	200	200	0	200	200	200	0	0	0	0	0
50	200	200	200	0	200	200	200	0	0	0	0	0
55	200	200	200	0	200	200	200	0	0	0	0	0
100	200	200	200	0	200	200	200	0	0	0	0	0
110	200	200	200	0	200	200	200	0	0	0	0	0

Device Test: 44.4 DROPOUT_CURRENT|//GO_NOGO/1N8V/400mA/5/@I_DO_VIN_5V_VOUT_1N8





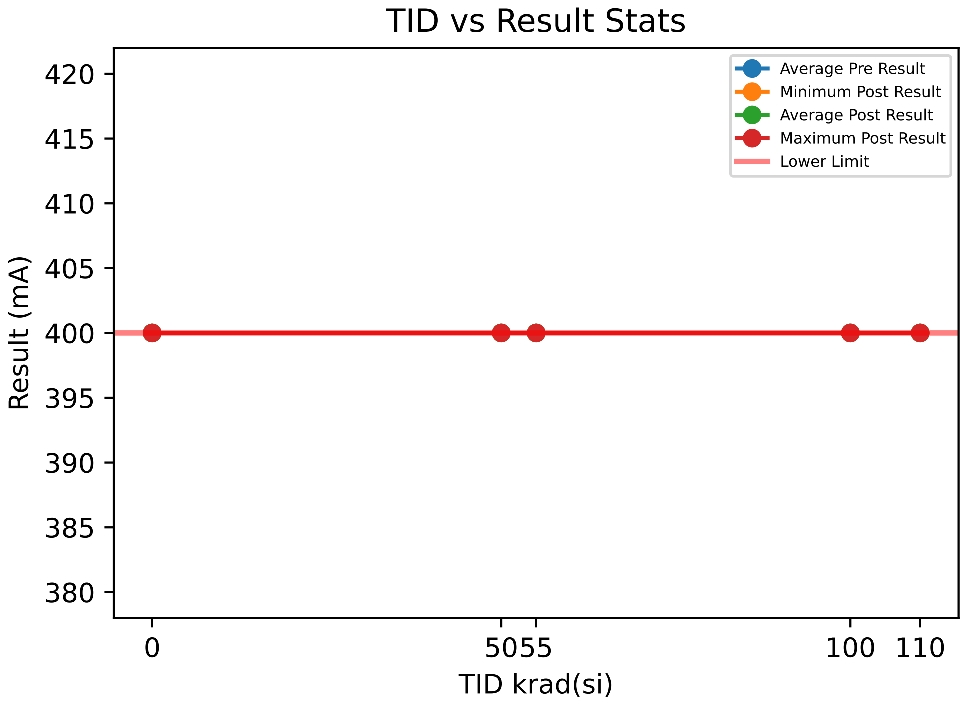
Test Results (Lower Limit = 400.0 (mA))

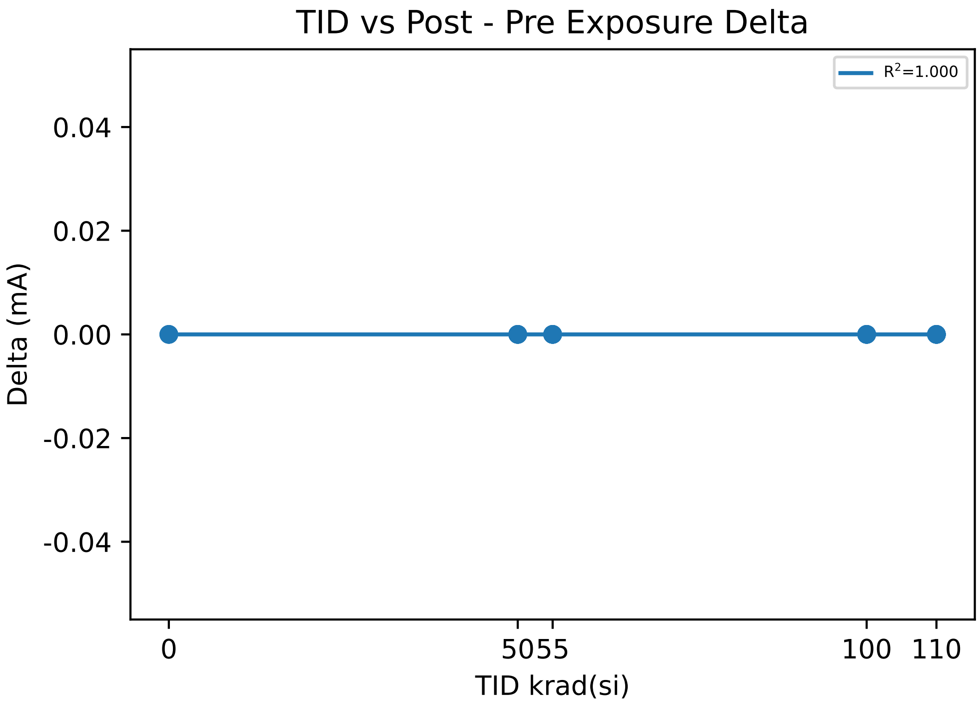
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	400	400	0
2	0	CU	400	400	0
3	0	CU	400	400	0
40	50	50krad Unbiased	400	400	0
41	50	50krad Unbiased	400	400	0
42	50	50krad Unbiased	400	400	0
43	50	50krad Unbiased	400	400	0
44	50	50krad Unbiased	400	400	0
45	55	50krad Biased	400	400	0
46	55	50krad Biased	400	400	0
47	55	50krad Biased	400	400	0
48	55	50krad Biased	400	400	0
49	55	50krad Biased	400	400	0
50	100	100krad Unbiased	400	400	0
51	100	100krad Unbiased	400	400	0
52	100	100krad Unbiased	400	400	0
53	100	100krad Unbiased	400	400	0
54	100	100krad Unbiased	400	400	0
55	110	100krad Biased	400	400	0
56	110	100krad Biased	400	400	0
57	110	100krad Biased	400	400	0
58	110	100krad Biased	400	400	0
59	110	100krad Biased	400	400	0

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	400	400	400	0	400	400	400	0	0	0	0	0
50	400	400	400	0	400	400	400	0	0	0	0	0
55	400	400	400	0	400	400	400	0	0	0	0	0
100	400	400	400	0	400	400	400	0	0	0	0	0
110	400	400	400	0	400	400	400	0	0	0	0	0

Device Test: 44.5 DROPOUT_CURRENT|//GO_NOGO/1N8V/400mA/6/@I_DO_VIN_6V_VOUT_1N8





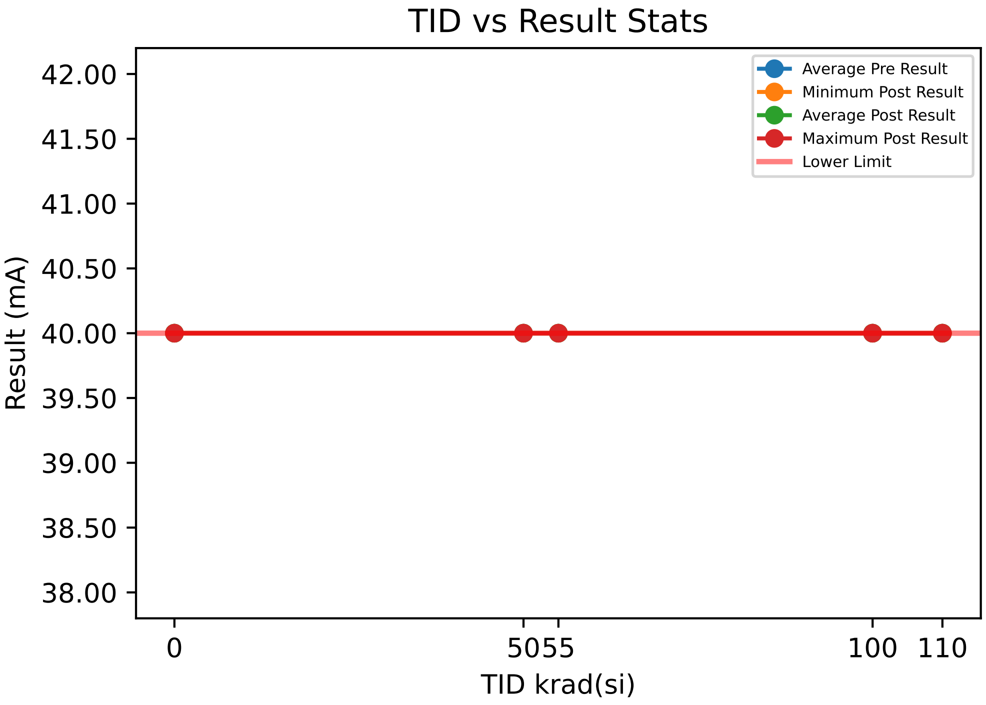
Test Results (Lower Limit = 400.0 (mA))

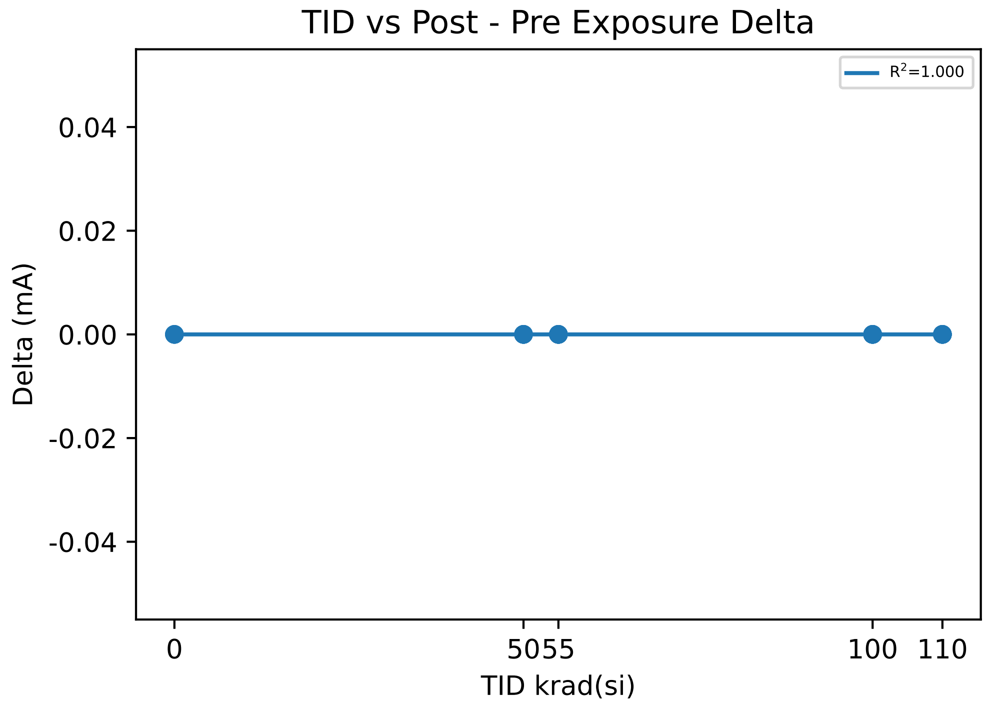
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	400	400	0
2	0	CU	400	400	0
3	0	CU	400	400	0
40	50	50krad Unbiased	400	400	0
41	50	50krad Unbiased	400	400	0
42	50	50krad Unbiased	400	400	0
43	50	50krad Unbiased	400	400	0
44	50	50krad Unbiased	400	400	0
45	55	50krad Biased	400	400	0
46	55	50krad Biased	400	400	0
47	55	50krad Biased	400	400	0
48	55	50krad Biased	400	400	0
49	55	50krad Biased	400	400	0
50	100	100krad Unbiased	400	400	0
51	100	100krad Unbiased	400	400	0
52	100	100krad Unbiased	400	400	0
53	100	100krad Unbiased	400	400	0
54	100	100krad Unbiased	400	400	0
55	110	100krad Biased	400	400	0
56	110	100krad Biased	400	400	0
57	110	100krad Biased	400	400	0
58	110	100krad Biased	400	400	0
59	110	100krad Biased	400	400	0

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	400	400	400	0	400	400	400	0	0	0	0	0
50	400	400	400	0	400	400	400	0	0	0	0	0
55	400	400	400	0	400	400	400	0	0	0	0	0
100	400	400	400	0	400	400	400	0	0	0	0	0
110	400	400	400	0	400	400	400	0	0	0	0	0

Device Test: 44.6 DROPOUT_CURRENT|//GO_NOGO/5N0V/40mA/5.5/@I_DO_VIN_5P5V_VOUT_5N0





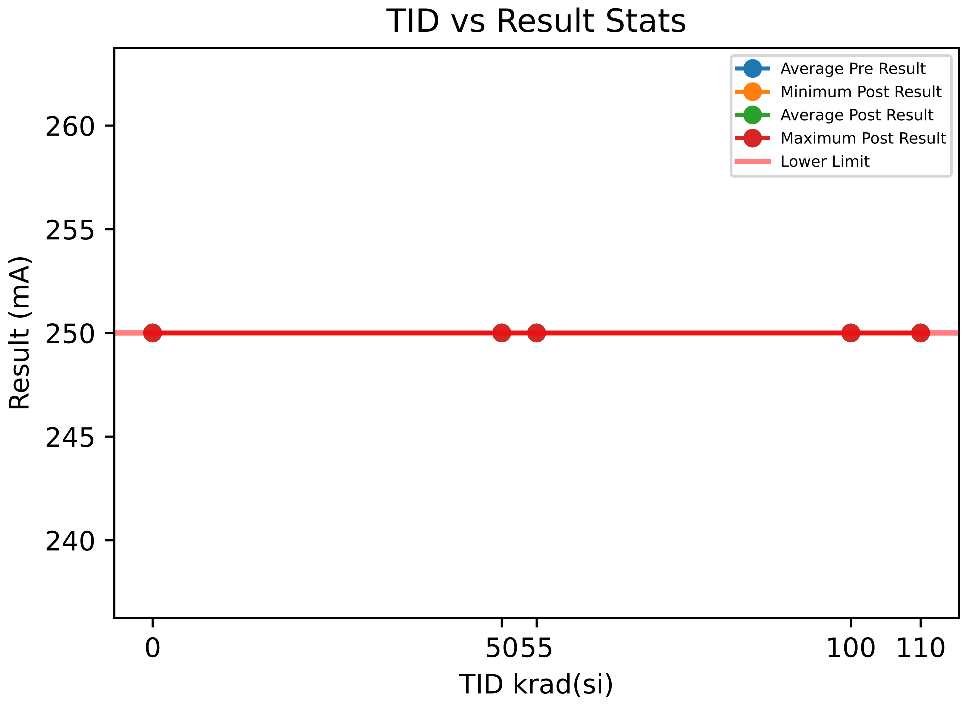
Test Results (Lower Limit = 40.0 (mA))

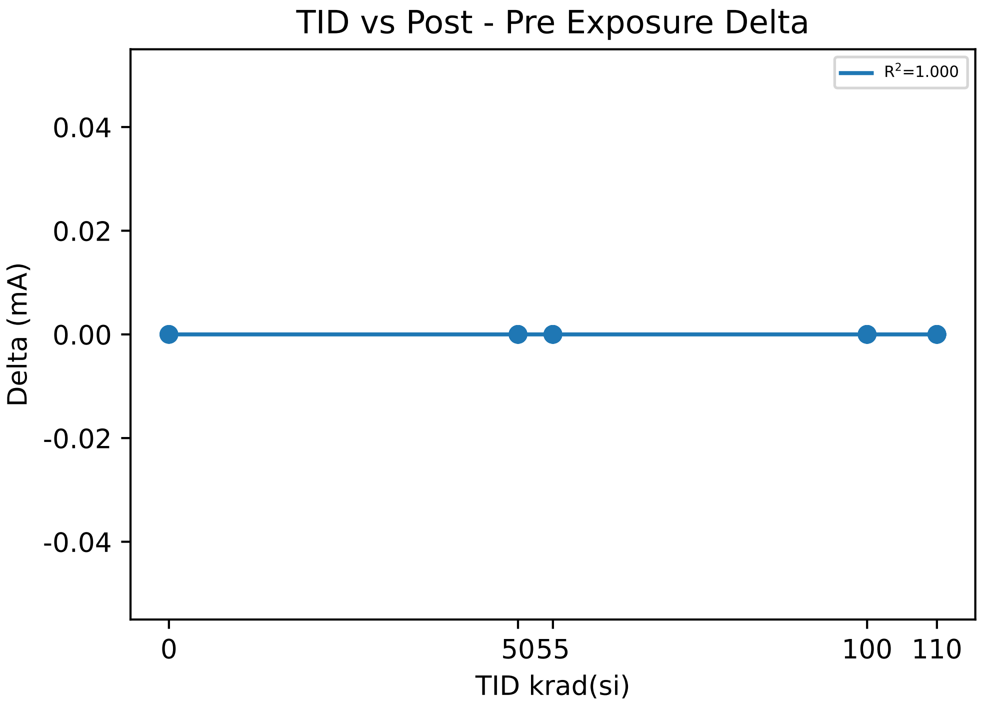
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	40	40	0
2	0	CU	40	40	0
3	0	CU	40	40	0
40	50	50krad Unbiased	40	40	0
41	50	50krad Unbiased	40	40	0
42	50	50krad Unbiased	40	40	0
43	50	50krad Unbiased	40	40	0
44	50	50krad Unbiased	40	40	0
45	55	50krad Biased	40	40	0
46	55	50krad Biased	40	40	0
47	55	50krad Biased	40	40	0
48	55	50krad Biased	40	40	0
49	55	50krad Biased	40	40	0
50	100	100krad Unbiased	40	40	0
51	100	100krad Unbiased	40	40	0
52	100	100krad Unbiased	40	40	0
53	100	100krad Unbiased	40	40	0
54	100	100krad Unbiased	40	40	0
55	110	100krad Biased	40	40	0
56	110	100krad Biased	40	40	0
57	110	100krad Biased	40	40	0
58	110	100krad Biased	40	40	0
59	110	100krad Biased	40	40	0

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	40	40	40	0	40	40	40	0	0	0	0	0
50	40	40	40	0	40	40	40	0	0	0	0	0
55	40	40	40	0	40	40	40	0	0	0	0	0
100	40	40	40	0	40	40	40	0	0	0	0	0
110	40	40	40	0	40	40	40	0	0	0	0	0

Device Test: 44.7 DROPOUT_CURRENT|//GO_NOGO/5N0V/250mA/6/@I_DO_VIN_6V_VOUT_5N0





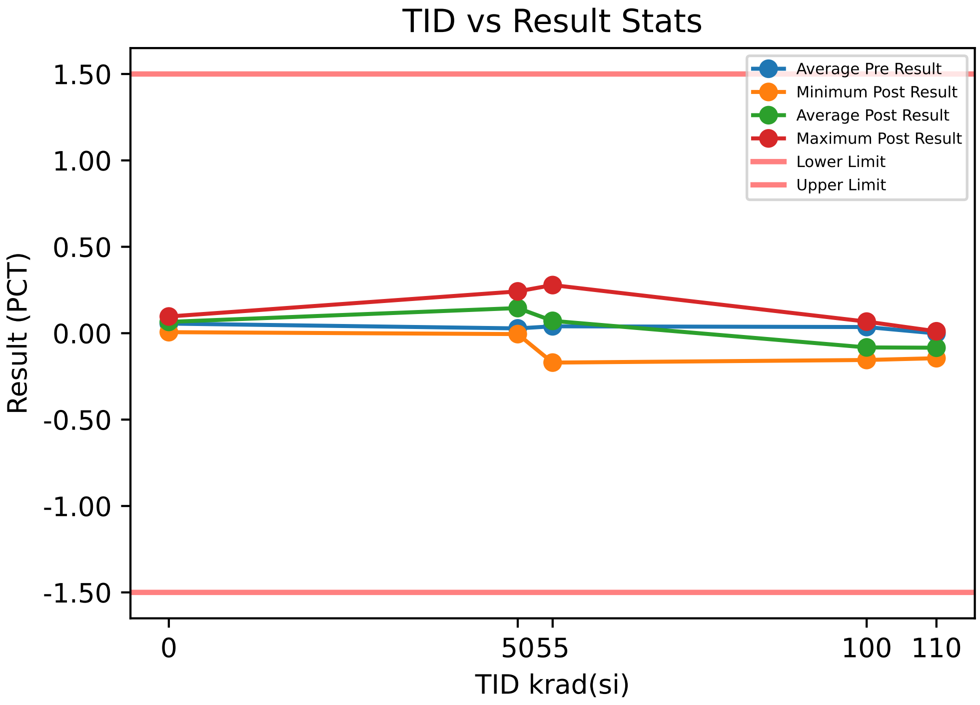
Test Results (Lower Limit = 250.0 (mA))

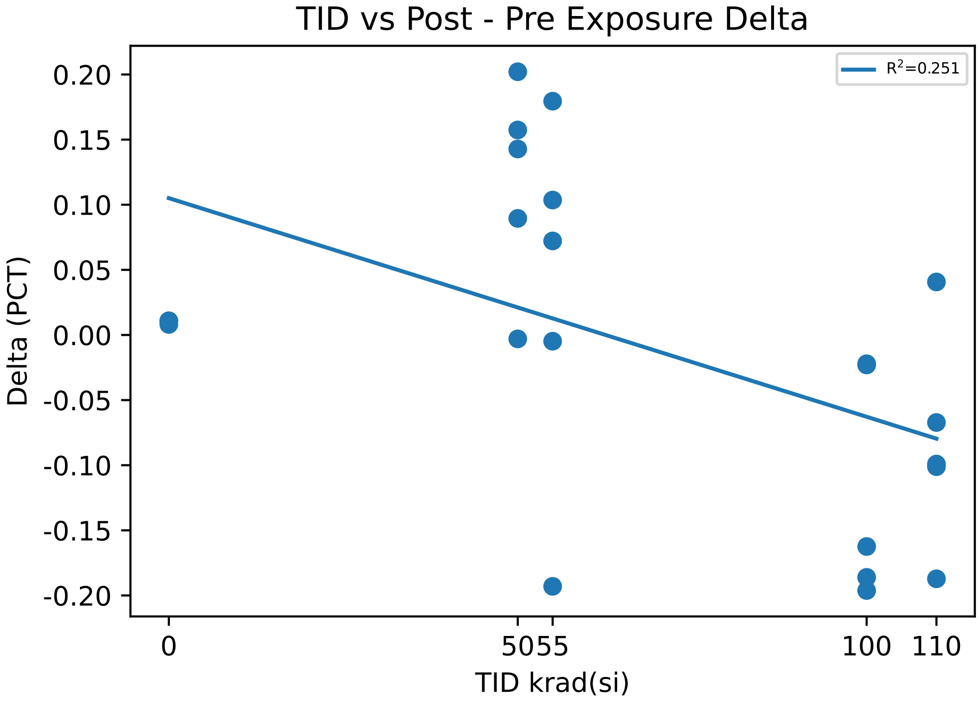
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	250	250	0
2	0	CU	250	250	0
3	0	CU	250	250	0
40	50	50krad Unbiased	250	250	0
41	50	50krad Unbiased	250	250	0
42	50	50krad Unbiased	250	250	0
43	50	50krad Unbiased	250	250	0
44	50	50krad Unbiased	250	250	0
45	55	50krad Biased	250	250	0
46	55	50krad Biased	250	250	0
47	55	50krad Biased	250	250	0
48	55	50krad Biased	250	250	0
49	55	50krad Biased	250	250	0
50	100	100krad Unbiased	250	250	0
51	100	100krad Unbiased	250	250	0
52	100	100krad Unbiased	250	250	0
53	100	100krad Unbiased	250	250	0
54	100	100krad Unbiased	250	250	0
55	110	100krad Biased	250	250	0
56	110	100krad Biased	250	250	0
57	110	100krad Biased	250	250	0
58	110	100krad Biased	250	250	0
59	110	100krad Biased	250	250	0

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	250	250	250	0	250	250	250	0	0	0	0	0
50	250	250	250	0	250	250	250	0	0	0	0	0
55	250	250	250	0	250	250	250	0	0	0	0	0
100	250	250	250	0	250	250	250	0	0	0	0	0
110	250	250	250	0	250	250	250	0	0	0	0	0

Device Test: 50.1 ACCURACY|//VOUT/0N6V/10mA/3/@ACC_VIN_3P0_VOUT_0N6_1MA


TID vs Result Stats


TID vs Post - Pre Exposure Delta

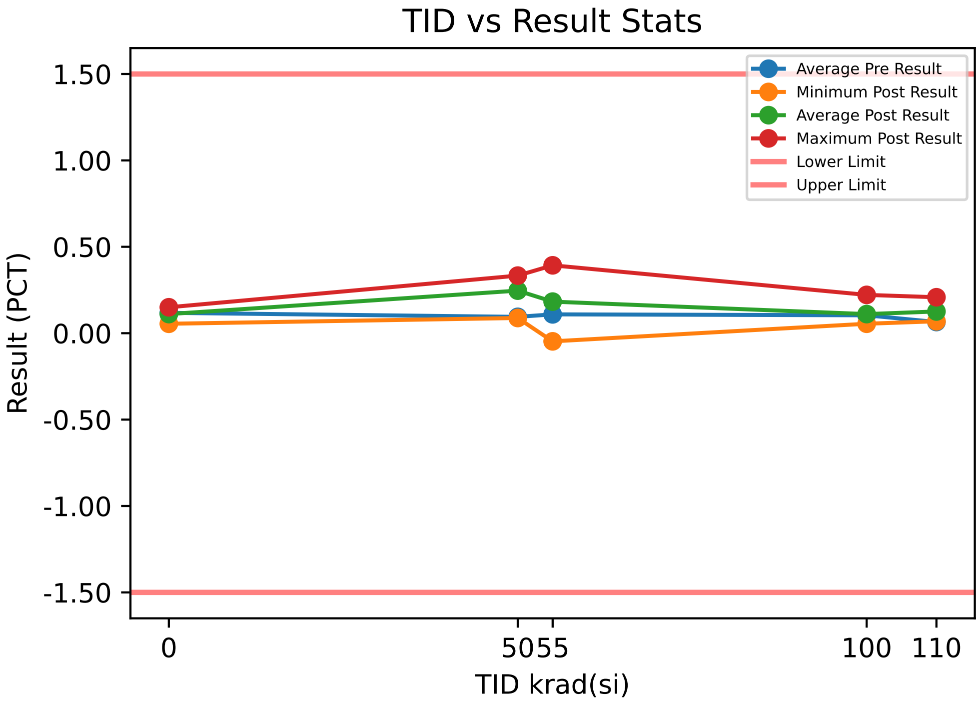
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

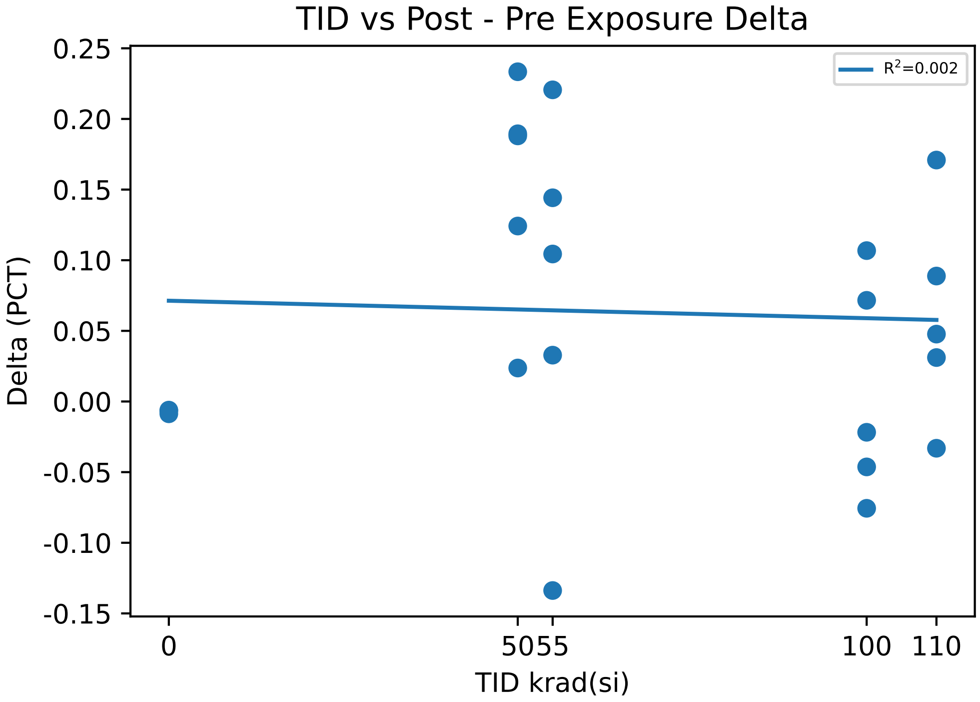
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.0828	0.0937	0.0109
2	0	CU	0.0886	0.0967	0.0081
3	0	CU	-0.0048	0.006	0.0108
40	50	50krad Unbiased	-0.0171	0.1403	0.1574
41	50	50krad Unbiased	0.0398	0.2419	0.2021
42	50	50krad Unbiased	0.0577	0.1472	0.0895
43	50	50krad Unbiased	0.0604	0.2032	0.1428
44	50	50krad Unbiased	-0.0022	-0.0052	-0.003
45	55	50krad Biased	0.0552	0.1588	0.1036
46	55	50krad Biased	0.0229	-0.1701	-0.193
47	55	50krad Biased	0.009	0.0042	-0.0048
48	55	50krad Biased	0.0134	0.0856	0.0722
49	55	50krad Biased	0.099	0.2785	0.1795
50	100	100krad Unbiased	-0.0598	-0.0819	-0.0221
51	100	100krad Unbiased	0.0676	-0.1185	-0.1861
52	100	100krad Unbiased	0.0731	-0.1231	-0.1962
53	100	100krad Unbiased	0.0074	-0.155	-0.1624
54	100	100krad Unbiased	0.09	0.067	-0.023
55	110	100krad Biased	-0.0312	-0.0984	-0.0672
56	110	100krad Biased	-0.0426	-0.1437	-0.1011
57	110	100krad Biased	-0.0297	0.011	0.0407
58	110	100krad Biased	0.0425	-0.1447	-0.1872
59	110	100krad Biased	0.0544	-0.0447	-0.0991

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0048	0.055533	0.0886	0.052331	0.006	0.065467	0.0967	0.051521	0.0081	0.0099333	0.0109	0.0015885
50	-0.0171	0.02772	0.0604	0.035415	-0.0052	0.14548	0.2419	0.094025	-0.003	0.11776	0.2021	0.07857
55	0.009	0.0399	0.099	0.03766	-0.1701	0.0714	0.2785	0.1685	-0.193	0.0315	0.1795	0.14184
100	-0.0598	0.03566	0.09	0.061818	-0.155	-0.0823	0.067	0.087394	-0.1962	-0.11796	-0.0221	0.087957
110	-0.0426	-0.00132	0.0544	0.0459	-0.1447	-0.0841	0.011	0.067129	-0.1872	-0.08278	0.0407	0.082152

Device Test: 50.10 ACCURACY|//VOUT/1N8V/400mA/5/@ACC_VIN_5P0_VOUT_1N8_400MA


TID vs Result Stats


TID vs Post - Pre Exposure Delta

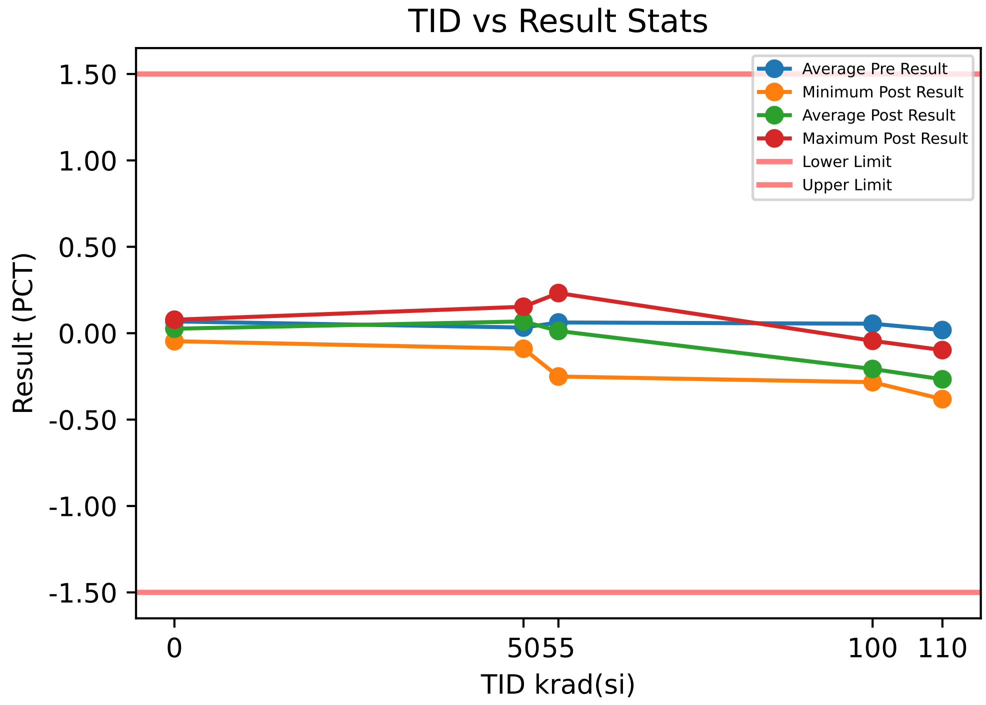
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

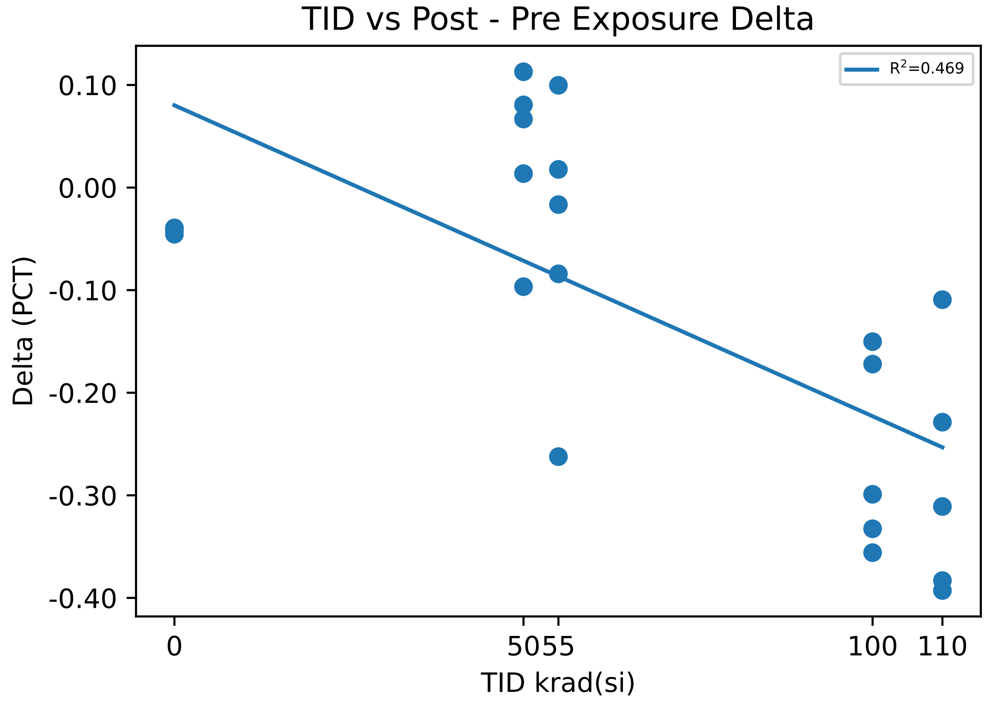
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.1335	0.1274	-0.0061
2	0	CU	0.1587	0.15	-0.0087
3	0	CU	0.0612	0.0546	-0.0066
40	50	50krad Unbiased	0.0562	0.2457	0.1895
41	50	50krad Unbiased	0.0998	0.3332	0.2334
42	50	50krad Unbiased	0.1273	0.2515	0.1242
43	50	50krad Unbiased	0.1252	0.3132	0.188
44	50	50krad Unbiased	0.0643	0.088	0.0237
45	55	50krad Biased	0.1201	0.2643	0.1442
46	55	50krad Biased	0.0866	-0.0472	-0.1338
47	55	50krad Biased	0.0857	0.1185	0.0328
48	55	50krad Biased	0.0806	0.185	0.1044
49	55	50krad Biased	0.1722	0.3928	0.2206
50	100	100krad Unbiased	0.0098	0.1166	0.1068
51	100	100krad Unbiased	0.1345	0.0882	-0.0463
52	100	100krad Unbiased	0.1473	0.0717	-0.0756
53	100	100krad Unbiased	0.0765	0.0547	-0.0218
54	100	100krad Unbiased	0.1501	0.2217	0.0716
55	110	100krad Biased	0.0256	0.1144	0.0888
56	110	100krad Biased	0.0213	0.069	0.0477
57	110	100krad Biased	0.0371	0.208	0.1709
58	110	100krad Biased	0.1136	0.0805	-0.0331
59	110	100krad Biased	0.1258	0.1569	0.0311

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0612	0.1178	0.1587	0.050611	0.0546	0.11067	0.15	0.049853	-0.0087	-0.0071333	-0.0061	0.0013796
50	0.0562	0.09456	0.1273	0.033262	0.088	0.24632	0.3332	0.096324	0.0237	0.15176	0.2334	0.081489
55	0.0806	0.10904	0.1722	0.038629	-0.0472	0.18268	0.3928	0.16415	-0.1338	0.07364	0.2206	0.13437
100	0.0098	0.10364	0.1501	0.060332	0.0547	0.11058	0.2217	0.06618	-0.0756	0.00694	0.1068	0.078464
110	0.0213	0.06468	0.1258	0.050741	0.069	0.12576	0.208	0.057298	-0.0331	0.06108	0.1709	0.075459

Device Test: 50.11 ACCURACY|//VOUT/5N0V/10mA/6.3/@ACC_VIN_6P3_VOUT_5N0_1MA





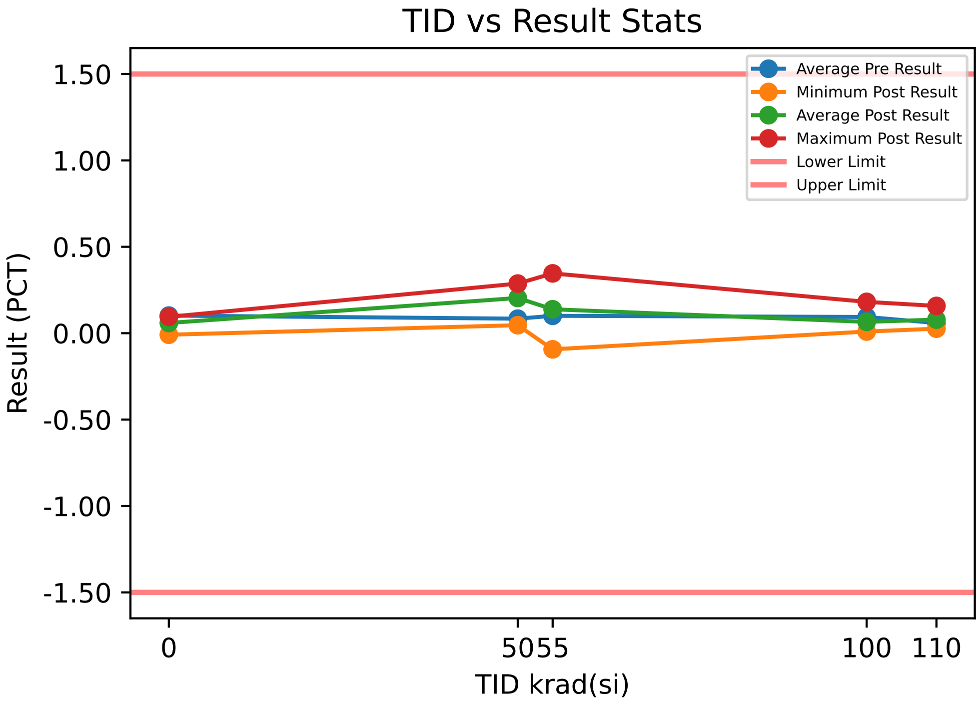
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

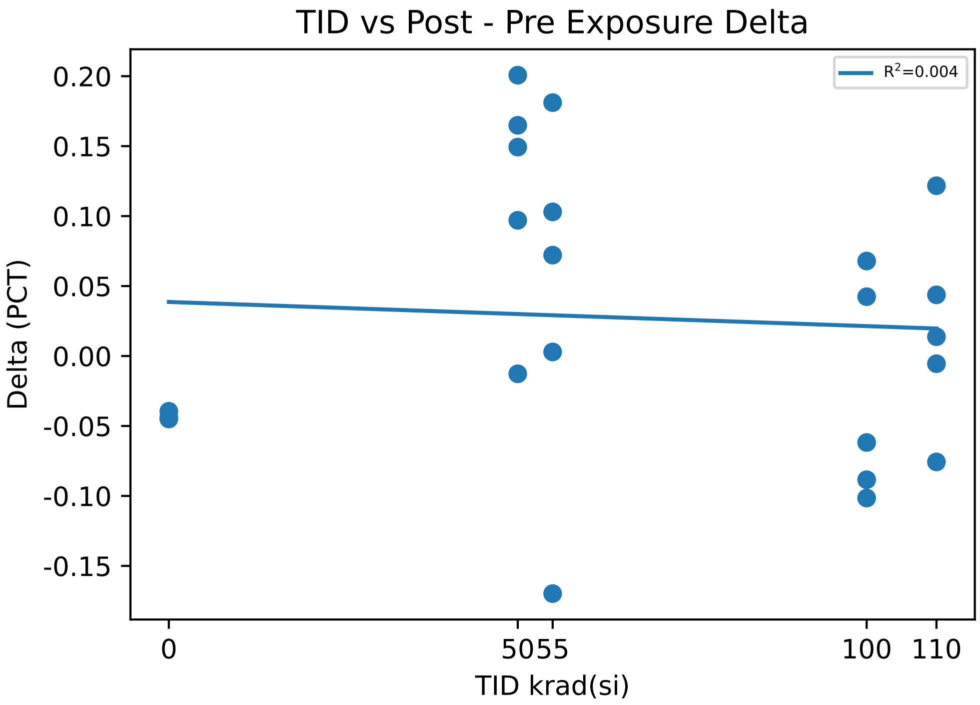
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.1173	0.078	-0.0393
2	0	CU	0.0916	0.0461	-0.0455
3	0	CU	-0.0044	-0.0462	-0.0418
40	50	50krad Unbiased	-0.022	0.0586	0.0806
41	50	50krad Unbiased	0.036	0.1489	0.1129
42	50	50krad Unbiased	0.0564	0.07	0.0136
43	50	50krad Unbiased	0.0863	0.1531	0.0668
44	50	50krad Unbiased	0.0067	-0.0899	-0.0966
45	55	50krad Biased	0.0943	0.112	0.0177
46	55	50krad Biased	0.0117	-0.2506	-0.2623
47	55	50krad Biased	0.0234	-0.0607	-0.0841
48	55	50krad Biased	0.0487	0.0321	-0.0166
49	55	50krad Biased	0.1327	0.2324	0.0997
50	100	100krad Unbiased	-0.0276	-0.1997	-0.1721
51	100	100krad Unbiased	0.0932	-0.2394	-0.3326
52	100	100krad Unbiased	0.0724	-0.2835	-0.3559
53	100	100krad Unbiased	0.0304	-0.2686	-0.299
54	100	100krad Unbiased	0.1061	-0.0441	-0.1502
55	110	100krad Biased	0.0016	-0.3815	-0.3831
56	110	100krad Biased	-0.0315	-0.3424	-0.3109
57	110	100krad Biased	0.0116	-0.0977	-0.1093
58	110	100krad Biased	0.0488	-0.344	-0.3928
59	110	100krad Biased	0.0603	-0.1684	-0.2287

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0044	0.068167	0.1173	0.064145	-0.0462	0.025967	0.078	0.064501	-0.0455	-0.0422	-0.0393	0.0031193
50	-0.022	0.03268	0.0863	0.042171	-0.0899	0.06814	0.1531	0.098503	-0.0966	0.03546	0.1129	0.082059
55	0.0117	0.06216	0.1327	0.050593	-0.2506	0.01304	0.2324	0.1825	-0.2623	-0.04912	0.0997	0.13633
100	-0.0276	0.0549	0.1061	0.054316	-0.2835	-0.20706	-0.0441	0.096548	-0.3559	-0.26196	-0.1502	0.094541
110	-0.0315	0.01816	0.0603	0.037074	-0.3815	-0.2668	-0.0977	0.12561	-0.3928	-0.28496	-0.1093	0.11827

Device Test: 50.12 ACCURACY|//VOUT/5N0V/250mA/6.3/@ACC_VIN_6P3_VOUT_5N0_250MA





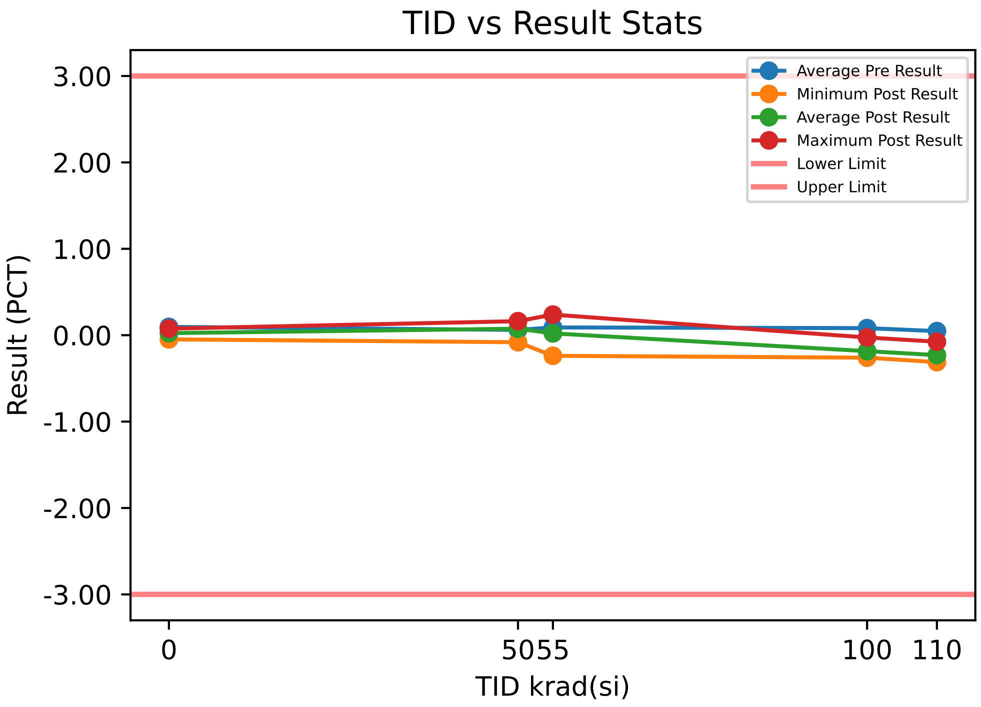
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

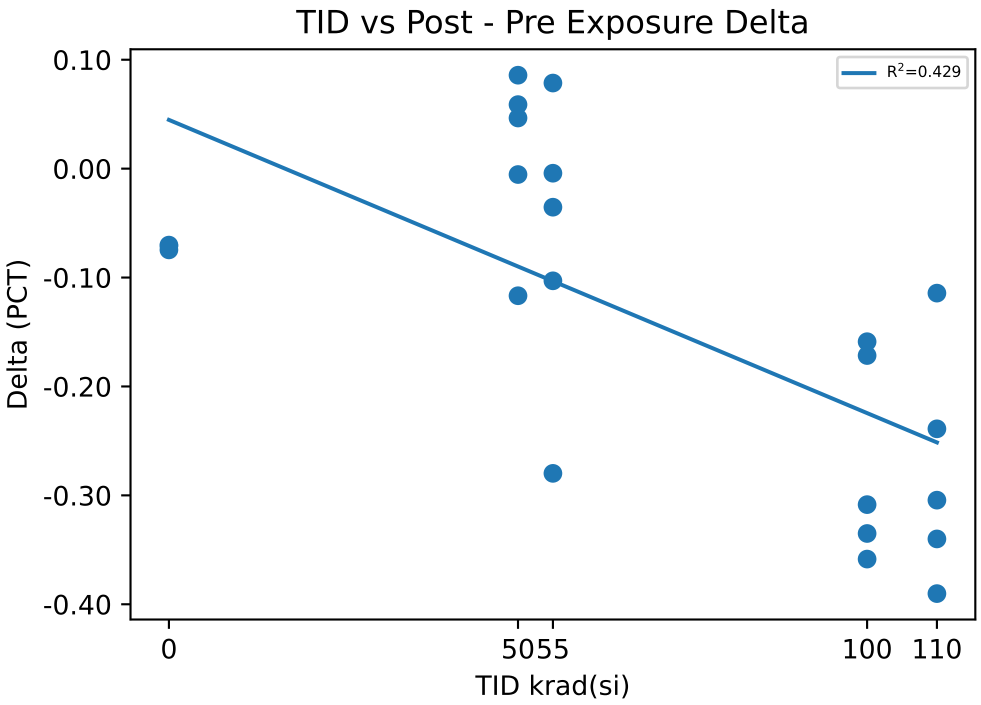
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.1342	0.0947	-0.0395
2	0	CU	0.1366	0.0916	-0.045
3	0	CU	0.035	-0.0088	-0.0438
40	50	50krad Unbiased	0.0406	0.2055	0.1649
41	50	50krad Unbiased	0.0864	0.2871	0.2007
42	50	50krad Unbiased	0.1148	0.2118	0.097
43	50	50krad Unbiased	0.1193	0.2686	0.1493
44	50	50krad Unbiased	0.059	0.0463	-0.0127
45	55	50krad Biased	0.1199	0.2229	0.103
46	55	50krad Biased	0.0764	-0.0934	-0.1698
47	55	50krad Biased	0.0692	0.0721	0.0029
48	55	50krad Biased	0.0724	0.1445	0.0721
49	55	50krad Biased	0.165	0.3461	0.1811
50	100	100krad Unbiased	0.0006	0.0685	0.0679
51	100	100krad Unbiased	0.1266	0.0382	-0.0884
52	100	100krad Unbiased	0.1321	0.0306	-0.1015
53	100	100krad Unbiased	0.0714	0.0096	-0.0618
54	100	100krad Unbiased	0.1389	0.1813	0.0424
55	110	100krad Biased	0.0348	0.0785	0.0437
56	110	100krad Biased	0.0138	0.0276	0.0138
57	110	100krad Biased	0.0361	0.1578	0.1217
58	110	100krad Biased	0.1019	0.0262	-0.0757
59	110	100krad Biased	0.1079	0.1024	-0.0055

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.035	0.10193	0.1366	0.057978	-0.0088	0.059167	0.0947	0.058881	-0.045	-0.042767	-0.0395	0.0028919
50	0.0406	0.08402	0.1193	0.034311	0.0463	0.20386	0.2871	0.094883	-0.0127	0.11984	0.2007	0.082954
55	0.0692	0.10058	0.165	0.041493	-0.0934	0.13844	0.3461	0.16465	-0.1698	0.03786	0.1811	0.13255
100	0.0006	0.09392	0.1389	0.058661	0.0096	0.06564	0.1813	0.06802	-0.1015	-0.02828	0.0679	0.078015
110	0.0138	0.0589	0.1079	0.042967	0.0262	0.0785	0.1578	0.055195	-0.0757	0.0196	0.1217	0.072026

Device Test: 50.13 ACCURACY|//VOUT/6N0V/10mA/6.3/@ACC_VIN_6P3_VOUT_6N0_10MA





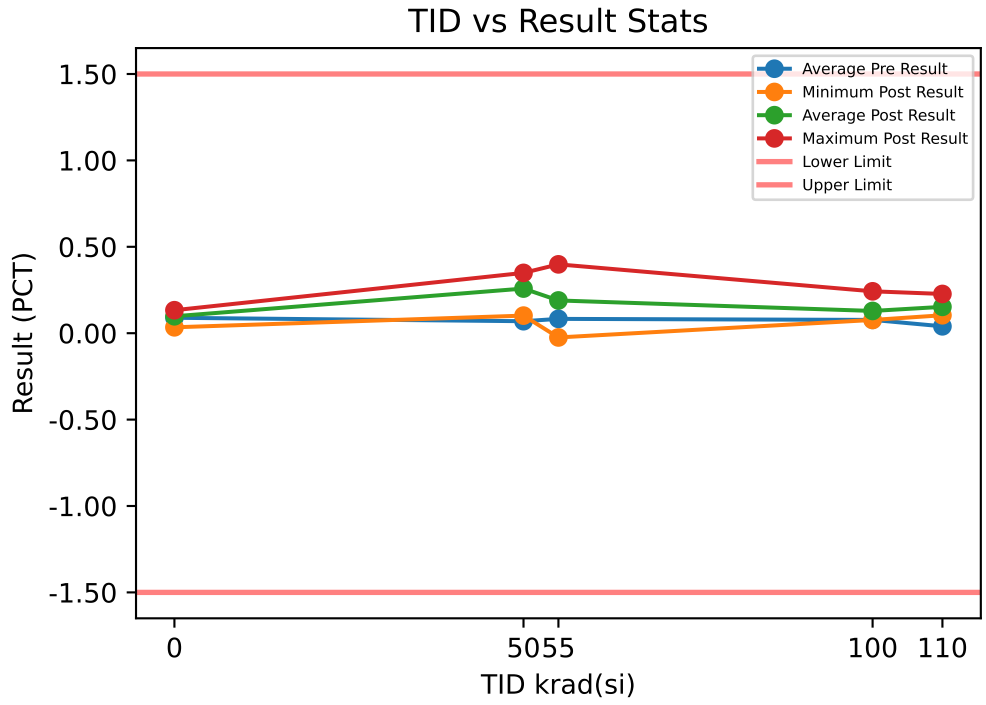
Test Results (Lower Limit = -3.0, Upper Limit = 3.0 (PCT))

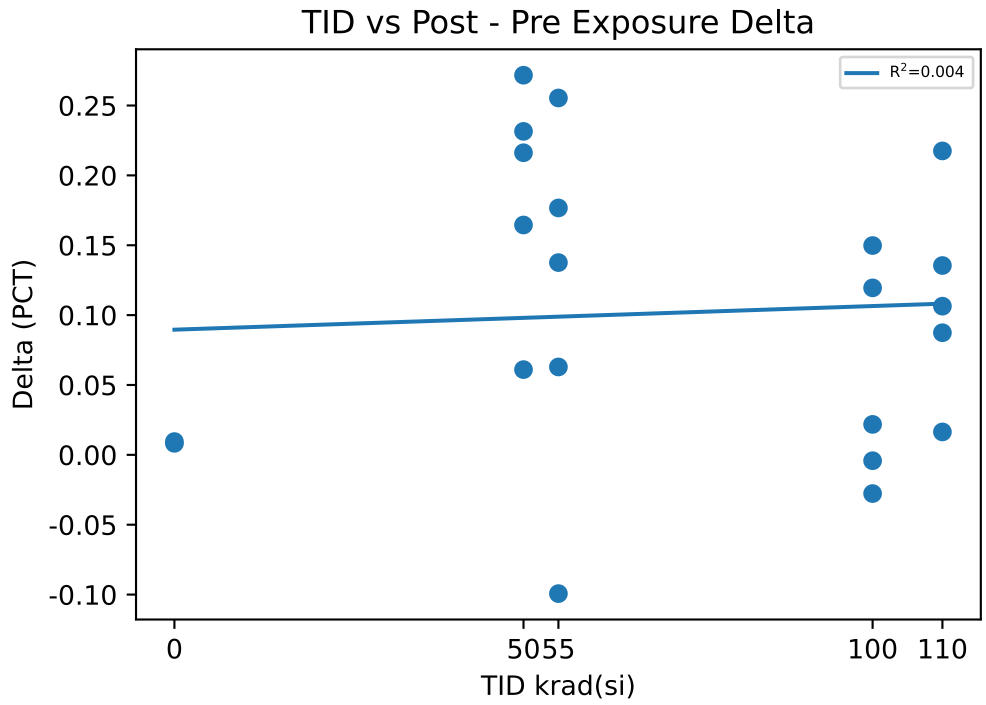
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.1462	0.076	-0.0702
2	0	CU	0.1194	0.0448	-0.0746
3	0	CU	0.0226	-0.0482	-0.0708
40	50	50krad Unbiased	0.007	0.0658	0.0588
41	50	50krad Unbiased	0.0633	0.1491	0.0858
42	50	50krad Unbiased	0.0851	0.0797	-0.0054
43	50	50krad Unbiased	0.1157	0.1622	0.0465
44	50	50krad Unbiased	0.0354	-0.0813	-0.1167
45	55	50krad Biased	0.1232	0.119	-0.0042
46	55	50krad Biased	0.0413	-0.2385	-0.2798
47	55	50krad Biased	0.0503	-0.0527	-0.103
48	55	50krad Biased	0.0745	0.0391	-0.0354
49	55	50krad Biased	0.1597	0.2383	0.0786
50	100	100krad Unbiased	0.0002	-0.1714	-0.1716
51	100	100krad Unbiased	0.1194	-0.2156	-0.335
52	100	100krad Unbiased	0.0984	-0.2601	-0.3585
53	100	100krad Unbiased	0.059	-0.2495	-0.3085
54	100	100krad Unbiased	0.1325	-0.0264	-0.1589
55	110	100krad Biased	0.0308	-0.3092	-0.34
56	110	100krad Biased	-0.0024	-0.3068	-0.3044
57	110	100krad Biased	0.039	-0.0753	-0.1143
58	110	100krad Biased	0.0786	-0.3116	-0.3902
59	110	100krad Biased	0.0894	-0.1495	-0.2389

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0226	0.096067	0.1462	0.06502	-0.0482	0.0242	0.076	0.064612	-0.0746	-0.071867	-0.0702	0.0023861
50	0.007	0.0613	0.1157	0.042276	-0.0813	0.0751	0.1622	0.096994	-0.1167	0.0138	0.0858	0.080121
55	0.0413	0.0898	0.1597	0.050369	-0.2385	0.02104	0.2383	0.18022	-0.2798	-0.06876	0.0786	0.13482
100	0.0002	0.0819	0.1325	0.053475	-0.2601	-0.1846	-0.0264	0.094967	-0.3585	-0.2665	-0.1589	0.094213
110	-0.0024	0.04708	0.0894	0.037293	-0.3116	-0.23048	-0.0753	0.11095	-0.3902	-0.27756	-0.1143	0.1066

Device Test: 50.2 ACCURACY|//VOUT/0N6V/150mA/3/@ACC_VIN_3P0_VOUT_0N6_150MA





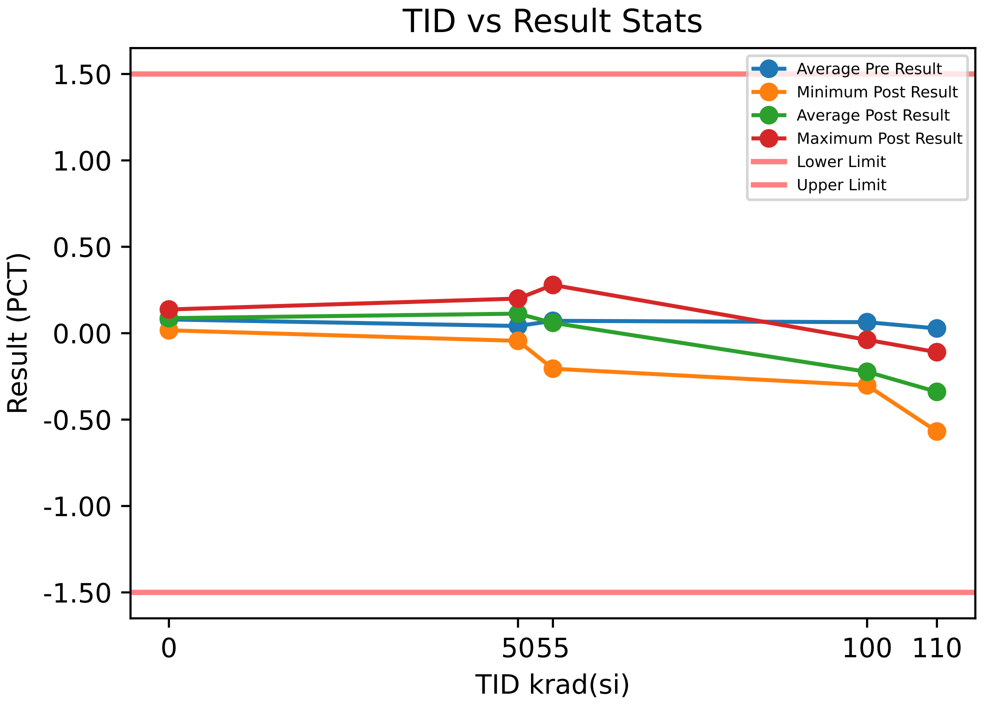
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

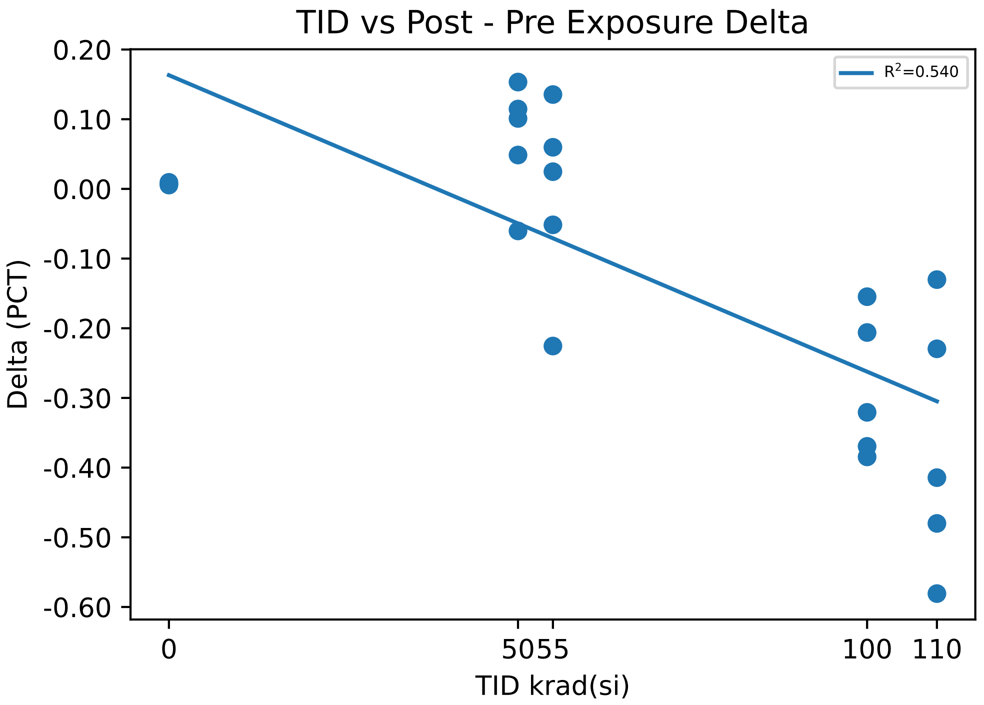
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.1183	0.1266	0.0083
2	0	CU	0.1247	0.133	0.0083
3	0	CU	0.0246	0.0341	0.0095
40	50	50krad Unbiased	0.0243	0.2558	0.2315
41	50	50krad Unbiased	0.0773	0.349	0.2717
42	50	50krad Unbiased	0.103	0.2675	0.1645
43	50	50krad Unbiased	0.1014	0.3176	0.2162
44	50	50krad Unbiased	0.0408	0.1018	0.061
45	55	50krad Biased	0.0944	0.2711	0.1767
46	55	50krad Biased	0.0747	-0.0246	-0.0993
47	55	50krad Biased	0.0563	0.1192	0.0629
48	55	50krad Biased	0.0459	0.1835	0.1376
49	55	50krad Biased	0.143	0.3984	0.2554
50	100	100krad Unbiased	-0.0206	0.1292	0.1498
51	100	100krad Unbiased	0.1095	0.1053	-0.0042
52	100	100krad Unbiased	0.1181	0.0904	-0.0277
53	100	100krad Unbiased	0.0548	0.0766	0.0218
54	100	100krad Unbiased	0.1229	0.2424	0.1195
55	110	100krad Biased	0.0055	0.141	0.1355
56	110	100krad Biased	-0.0025	0.1039	0.1064
57	110	100krad Biased	0.0096	0.2271	0.2175
58	110	100krad Biased	0.0897	0.1061	0.0164
59	110	100krad Biased	0.0971	0.1845	0.0874

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0246	0.0892	0.1247	0.056037	0.0341	0.0979	0.133	0.055345	0.0083	0.0087	0.0095	0.00069282
50	0.0243	0.06936	0.103	0.035593	0.1018	0.25834	0.349	0.095297	0.061	0.18898	0.2717	0.081194
55	0.0459	0.08286	0.143	0.038367	-0.0246	0.18952	0.3984	0.15899	-0.0993	0.10666	0.2554	0.13446
100	-0.0206	0.07694	0.1229	0.060973	0.0766	0.12878	0.2424	0.066439	-0.0277	0.05184	0.1498	0.078332
110	-0.0025	0.03988	0.0971	0.04912	0.1039	0.15252	0.2271	0.053001	0.0164	0.11264	0.2175	0.07324

Device Test: 50.3 ACCURACY|//VOUT/0N6V/10mA/6.3/@ACC_VIN_6P3_VOUT_0N6_1MA


TID vs Result Stats


TID vs Post - Pre Exposure Delta

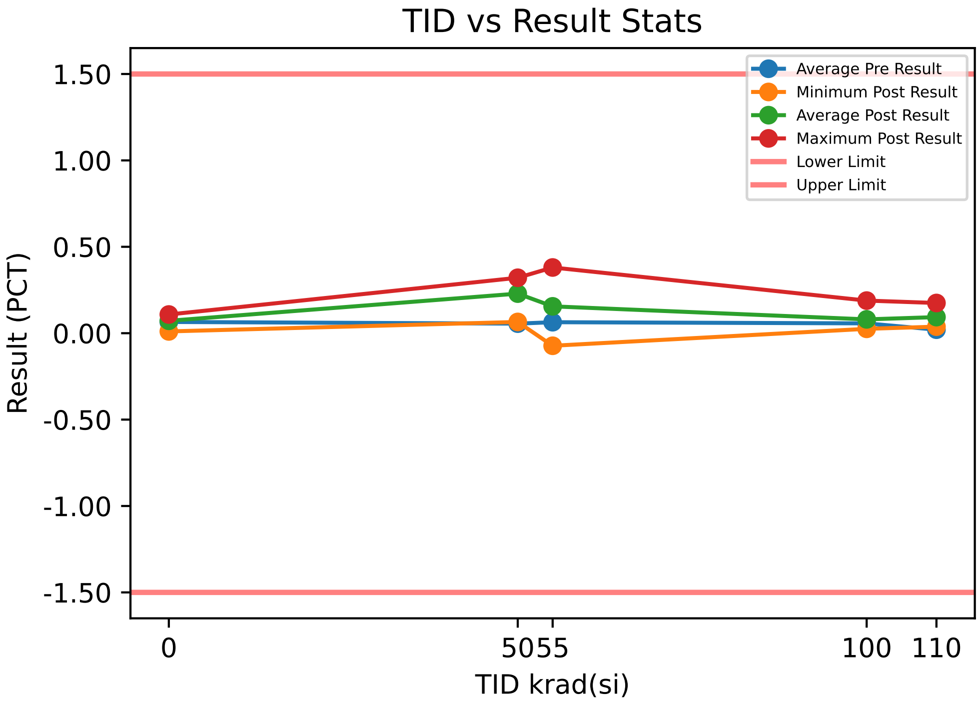
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

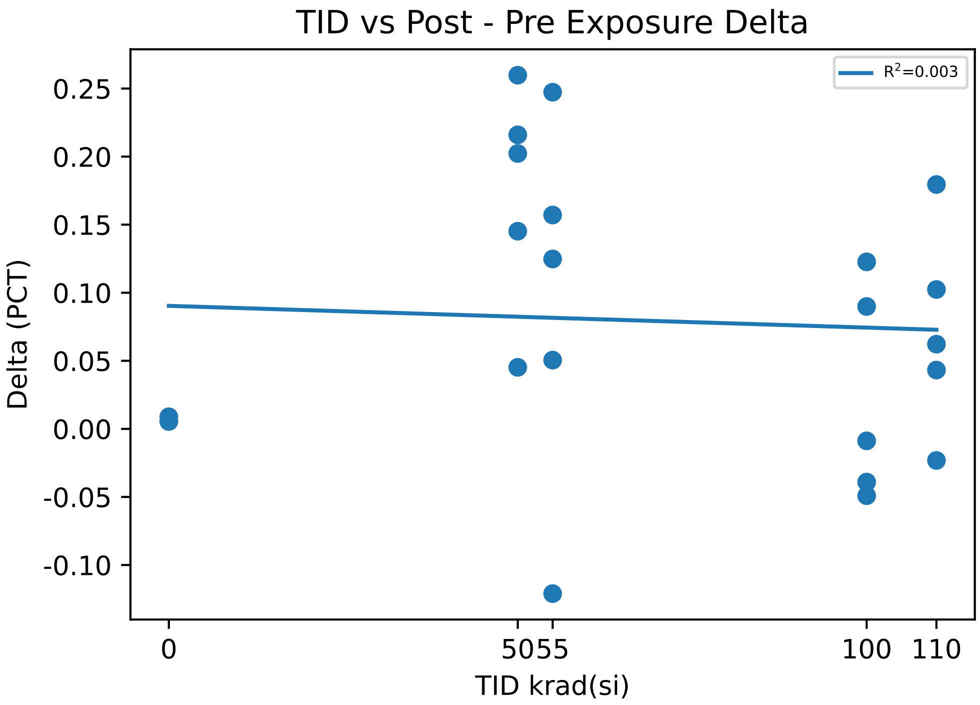
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.1301	0.1374	0.0073
2	0	CU	0.1013	0.1068	0.0055
3	0	CU	0.0073	0.0167	0.0094
40	50	50krad Unbiased	-0.0127	0.1019	0.1146
41	50	50krad Unbiased	0.0471	0.2004	0.1533
42	50	50krad Unbiased	0.0638	0.1124	0.0486
43	50	50krad Unbiased	0.0943	0.1954	0.1011
44	50	50krad Unbiased	0.016	-0.0443	-0.0603
45	55	50krad Biased	0.1045	0.1642	0.0597
46	55	50krad Biased	0.0201	-0.2054	-0.2255
47	55	50krad Biased	0.0316	-0.02	-0.0516
48	55	50krad Biased	0.0581	0.0828	0.0247
49	55	50krad Biased	0.1437	0.2791	0.1354
50	100	100krad Unbiased	-0.0183	-0.2244	-0.2061
51	100	100krad Unbiased	0.1023	-0.2672	-0.3695
52	100	100krad Unbiased	0.0829	-0.3017	-0.3846
53	100	100krad Unbiased	0.0358	-0.2849	-0.3207
54	100	100krad Unbiased	0.1164	-0.0383	-0.1547
55	110	100krad Biased	0.0119	-0.5689	-0.5808
56	110	100krad Biased	-0.0212	-0.4356	-0.4144
57	110	100krad Biased	0.0204	-0.1098	-0.1302
58	110	100krad Biased	0.0552	-0.4249	-0.4801
59	110	100krad Biased	0.0714	-0.1581	-0.2295

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0073	0.079567	0.1301	0.06422	0.0167	0.086967	0.1374	0.062747	0.0055	0.0074	0.0094	0.0019519
50	-0.0127	0.0417	0.0943	0.041546	-0.0443	0.11316	0.2004	0.099115	-0.0603	0.07146	0.1533	0.082645
55	0.0201	0.0716	0.1437	0.051757	-0.2054	0.06014	0.2791	0.18454	-0.2255	-0.01146	0.1354	0.13726
100	-0.0183	0.06382	0.1164	0.055087	-0.3017	-0.2233	-0.0383	0.10735	-0.3846	-0.28712	-0.1547	0.10188
110	-0.0212	0.02754	0.0714	0.036606	-0.5689	-0.33946	-0.1098	0.19674	-0.5808	-0.367	-0.1302	0.18421

Device Test: 50.4 ACCURACY|//VOUT/0N6V/400mA/6.3/@ACC_VIN_6P3_VOUT_0N6_400MA





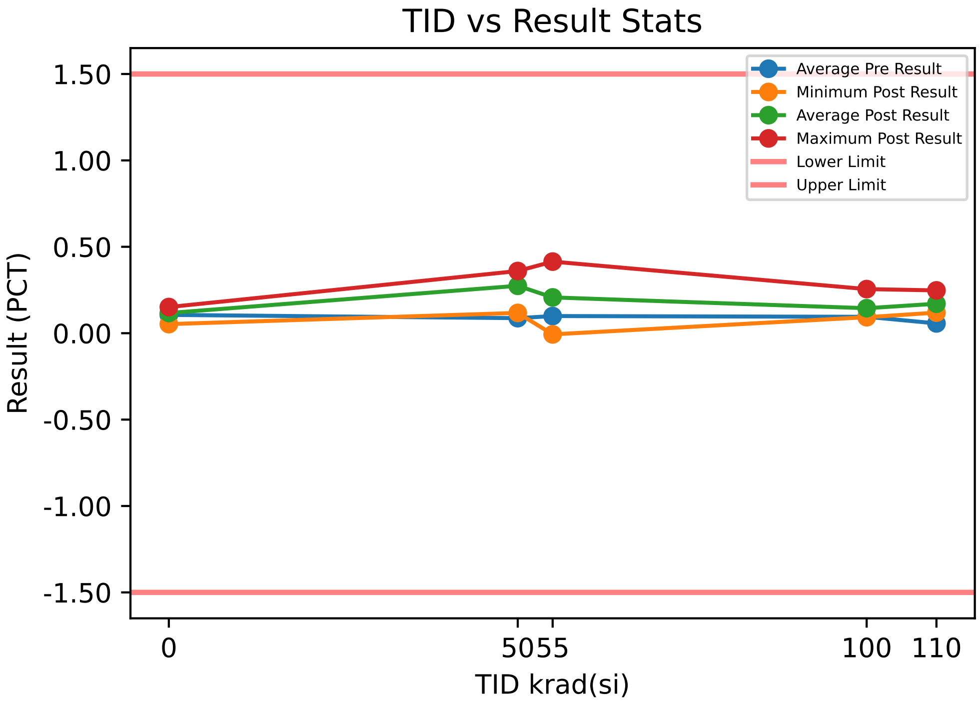
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

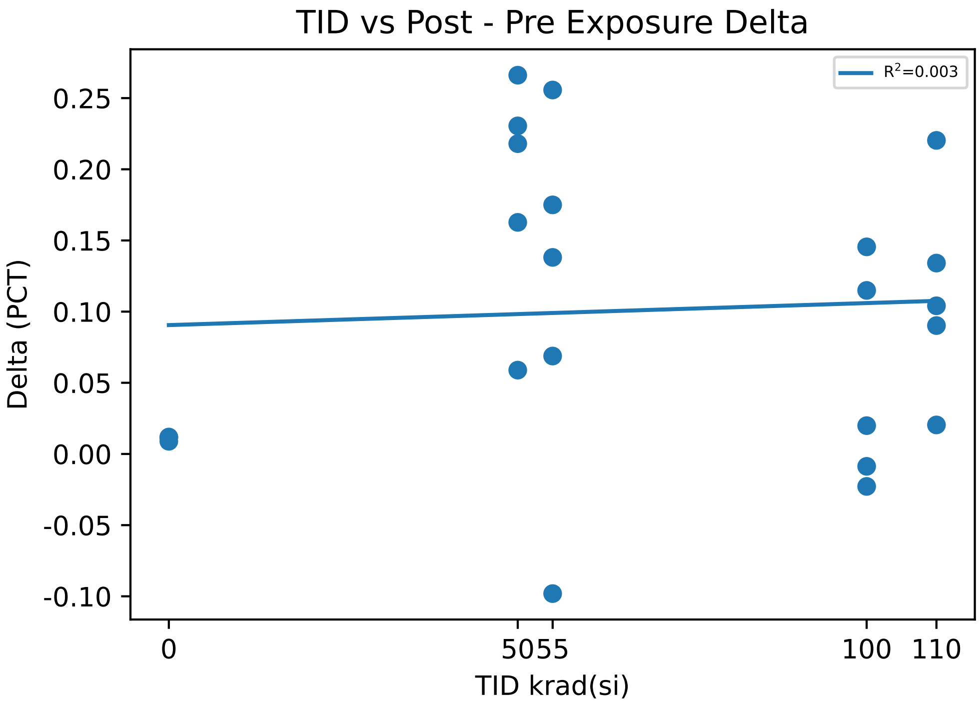
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.0878	0.0967	0.0089
2	0	CU	0.1028	0.1082	0.0054
3	0	CU	0.0046	0.0103	0.0057
40	50	50krad Unbiased	0.0195	0.2355	0.216
41	50	50krad Unbiased	0.061	0.3208	0.2598
42	50	50krad Unbiased	0.0923	0.2375	0.1452
43	50	50krad Unbiased	0.0841	0.2864	0.2023
44	50	50krad Unbiased	0.0199	0.0651	0.0452
45	55	50krad Biased	0.077	0.2341	0.1571
46	55	50krad Biased	0.0483	-0.0727	-0.121
47	55	50krad Biased	0.0366	0.0871	0.0505
48	55	50krad Biased	0.0233	0.1481	0.1248
49	55	50krad Biased	0.133	0.3803	0.2473
50	100	100krad Unbiased	-0.0407	0.082	0.1227
51	100	100krad Unbiased	0.086	0.0469	-0.0391
52	100	100krad Unbiased	0.1062	0.0571	-0.0491
53	100	100krad Unbiased	0.0341	0.0253	-0.0088
54	100	100krad Unbiased	0.0988	0.1887	0.0899
55	110	100krad Biased	-0.0129	0.0895	0.1024
56	110	100krad Biased	-0.0243	0.0379	0.0622
57	110	100krad Biased	-0.0047	0.1748	0.1795
58	110	100krad Biased	0.0623	0.0391	-0.0232
59	110	100krad Biased	0.0811	0.1243	0.0432

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0046	0.065067	0.1028	0.0529	0.0103	0.071733	0.1082	0.053513	0.0054	0.0066667	0.0089	0.0019399
50	0.0195	0.05536	0.0923	0.034517	0.0651	0.22906	0.3208	0.098361	0.0452	0.1737	0.2598	0.082682
55	0.0233	0.06364	0.133	0.04354	-0.0727	0.15538	0.3803	0.16846	-0.121	0.09174	0.2473	0.13831
100	-0.0407	0.05688	0.1062	0.061397	0.0253	0.08	0.1887	0.064093	-0.0491	0.02312	0.1227	0.078233
110	-0.0243	0.0203	0.0811	0.047898	0.0379	0.09312	0.1748	0.058362	-0.0232	0.07282	0.1795	0.074943

Device Test: 50.5 ACCURACY|//VOUT/1N2V/150mA/3/@ACC_VIN_3P0_VOUT_1N2_150MA





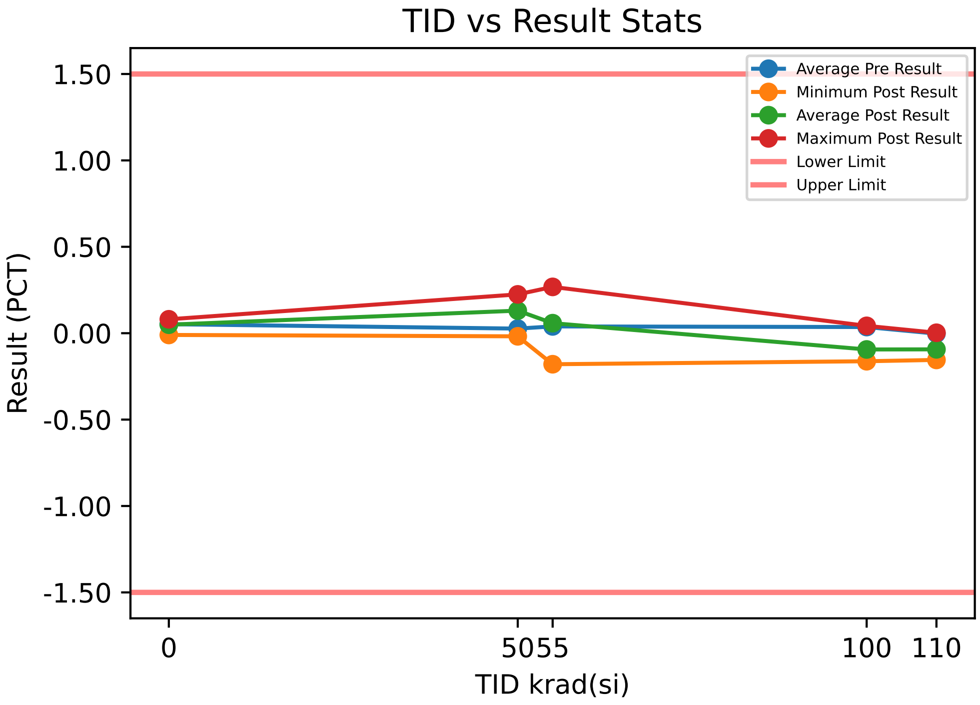
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

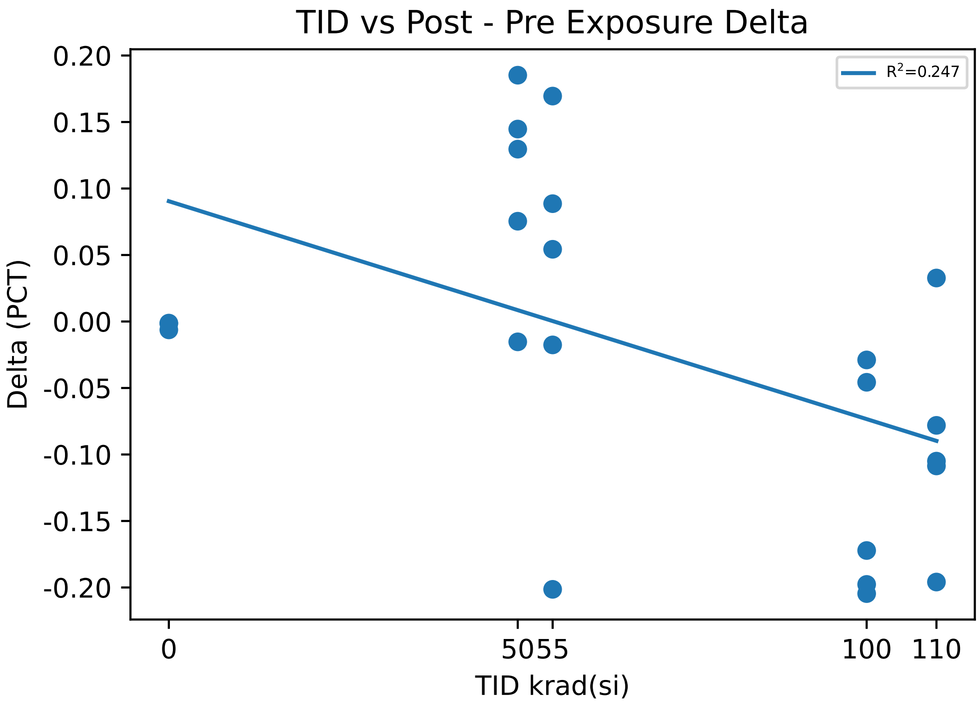
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.1348	0.1464	0.0116
2	0	CU	0.1424	0.1513	0.0089
3	0	CU	0.0407	0.0526	0.0119
40	50	50krad Unbiased	0.0426	0.2731	0.2305
41	50	50krad Unbiased	0.0937	0.3598	0.2661
42	50	50krad Unbiased	0.1213	0.284	0.1627
43	50	50krad Unbiased	0.1192	0.3372	0.218
44	50	50krad Unbiased	0.0585	0.1174	0.0589
45	55	50krad Biased	0.1111	0.2861	0.175
46	55	50krad Biased	0.0913	-0.0068	-0.0981
47	55	50krad Biased	0.073	0.1418	0.0688
48	55	50krad Biased	0.0621	0.2002	0.1381
49	55	50krad Biased	0.1586	0.4143	0.2557
50	100	100krad Unbiased	-0.0021	0.1434	0.1455
51	100	100krad Unbiased	0.1271	0.1184	-0.0087
52	100	100krad Unbiased	0.1361	0.1133	-0.0228
53	100	100krad Unbiased	0.0727	0.0926	0.0199
54	100	100krad Unbiased	0.1403	0.2552	0.1149
55	110	100krad Biased	0.0224	0.1565	0.1341
56	110	100krad Biased	0.015	0.1191	0.1041
57	110	100krad Biased	0.0274	0.2477	0.2203
58	110	100krad Biased	0.106	0.1264	0.0204
59	110	100krad Biased	0.1127	0.2029	0.0902

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0407	0.10597	0.1424	0.05665	0.0526	0.11677	0.1513	0.055624	0.0089	0.0108	0.0119	0.0016523
50	0.0426	0.08706	0.1213	0.035503	0.1174	0.2743	0.3598	0.094842	0.0589	0.18724	0.2661	0.080793
55	0.0621	0.09922	0.1586	0.038063	-0.0068	0.20712	0.4143	0.15751	-0.0981	0.1079	0.2557	0.13344
100	-0.0021	0.09482	0.1403	0.060616	0.0926	0.14458	0.2552	0.064428	-0.0228	0.04976	0.1455	0.075802
110	0.015	0.0567	0.1127	0.048323	0.1191	0.17052	0.2477	0.054296	0.0204	0.11382	0.2203	0.072679

Device Test: 50.6 ACCURACY|//VOUT/1N8V/10mA/3/@ACC_VIN_3P0_VOUT_1N8_1MA


TID vs Result Stats


TID vs Post - Pre Exposure Delta

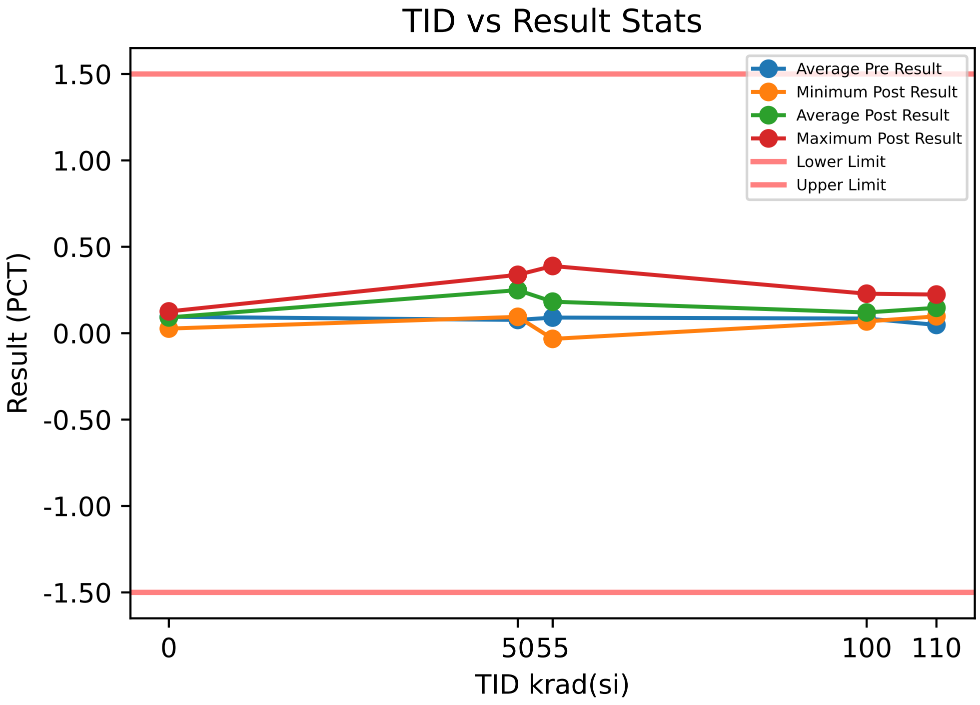
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

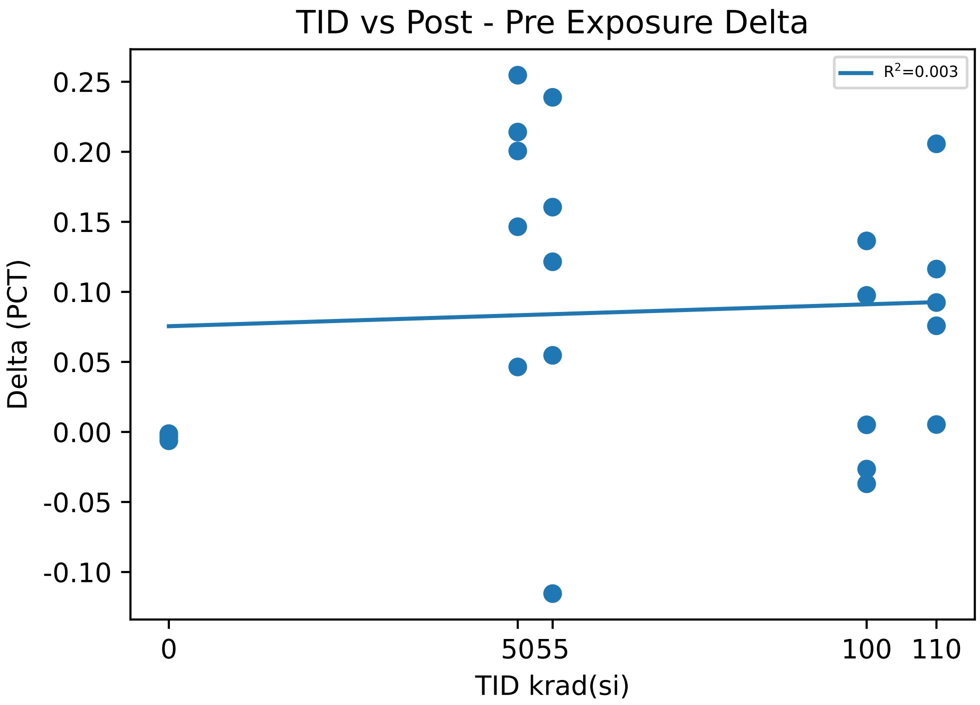
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.0782	0.077	-0.0012
2	0	CU	0.0868	0.0805	-0.0063
3	0	CU	-0.0086	-0.0101	-0.0015
40	50	50krad Unbiased	-0.0192	0.1255	0.1447
41	50	50krad Unbiased	0.0394	0.2246	0.1852
42	50	50krad Unbiased	0.0593	0.1347	0.0754
43	50	50krad Unbiased	0.0562	0.1858	0.1296
44	50	50krad Unbiased	-0.0028	-0.0181	-0.0153
45	55	50krad Biased	0.0547	0.1433	0.0886
46	55	50krad Biased	0.0218	-0.1796	-0.2014
47	55	50krad Biased	0.0094	-0.0082	-0.0176
48	55	50krad Biased	0.0122	0.0665	0.0543
49	55	50krad Biased	0.0985	0.268	0.1695
50	100	100krad Unbiased	-0.0608	-0.0897	-0.0289
51	100	100krad Unbiased	0.0668	-0.1309	-0.1977
52	100	100krad Unbiased	0.0743	-0.1303	-0.2046
53	100	100krad Unbiased	0.0099	-0.1623	-0.1722
54	100	100krad Unbiased	0.0882	0.0425	-0.0457
55	110	100krad Biased	-0.0311	-0.1092	-0.0781
56	110	100krad Biased	-0.0448	-0.1498	-0.105
57	110	100krad Biased	-0.0302	0.0025	0.0327
58	110	100krad Biased	0.0413	-0.1546	-0.1959
59	110	100krad Biased	0.0524	-0.0562	-0.1086

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0086	0.052133	0.0868	0.052772	-0.0101	0.049133	0.0805	0.051327	-0.0063	-0.003	-0.0012	0.0028618
50	-0.0192	0.02658	0.0593	0.035606	-0.0181	0.1305	0.2246	0.092246	-0.0153	0.10392	0.1852	0.077388
55	0.0094	0.03932	0.0985	0.037671	-0.1796	0.058	0.268	0.16754	-0.2014	0.01868	0.1695	0.14023
100	-0.0608	0.03568	0.0882	0.061627	-0.1623	-0.09414	0.0425	0.080615	-0.2046	-0.12982	-0.0289	0.085523
110	-0.0448	-0.00248	0.0524	0.045571	-0.1546	-0.09346	0.0025	0.066627	-0.1959	-0.09098	0.0327	0.082125

Device Test: 50.7 ACCURACY|//VOUT/1N8V/150mA/3/@ACC_VIN_3P0_VOUT_1N8_150MA





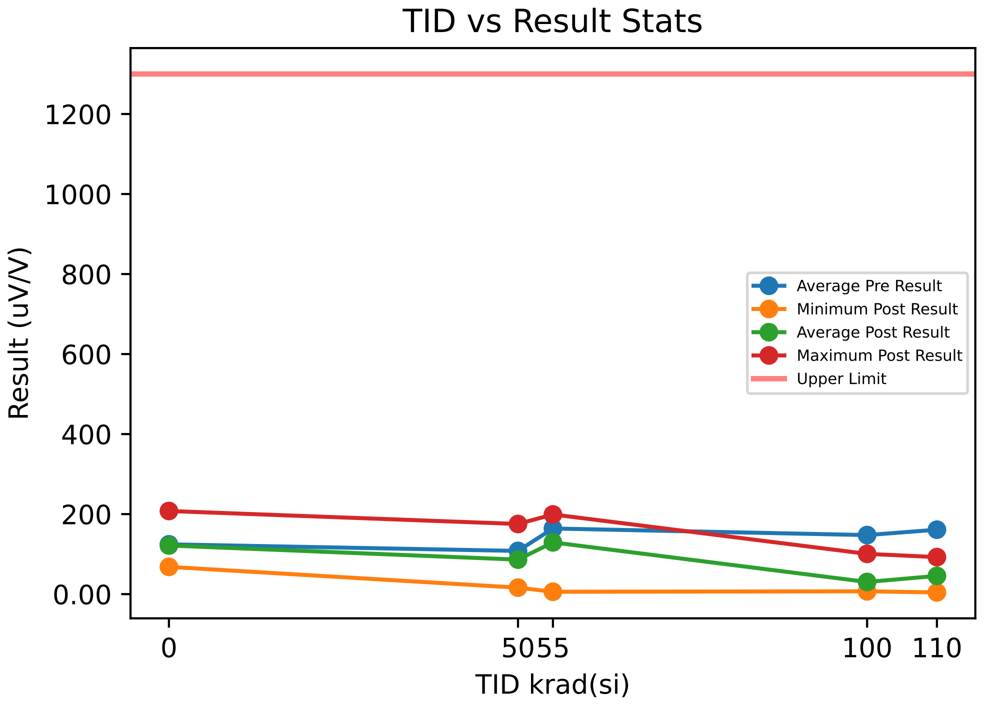
Test Results (Lower Limit = -1.5, Upper Limit = 1.5 (PCT))

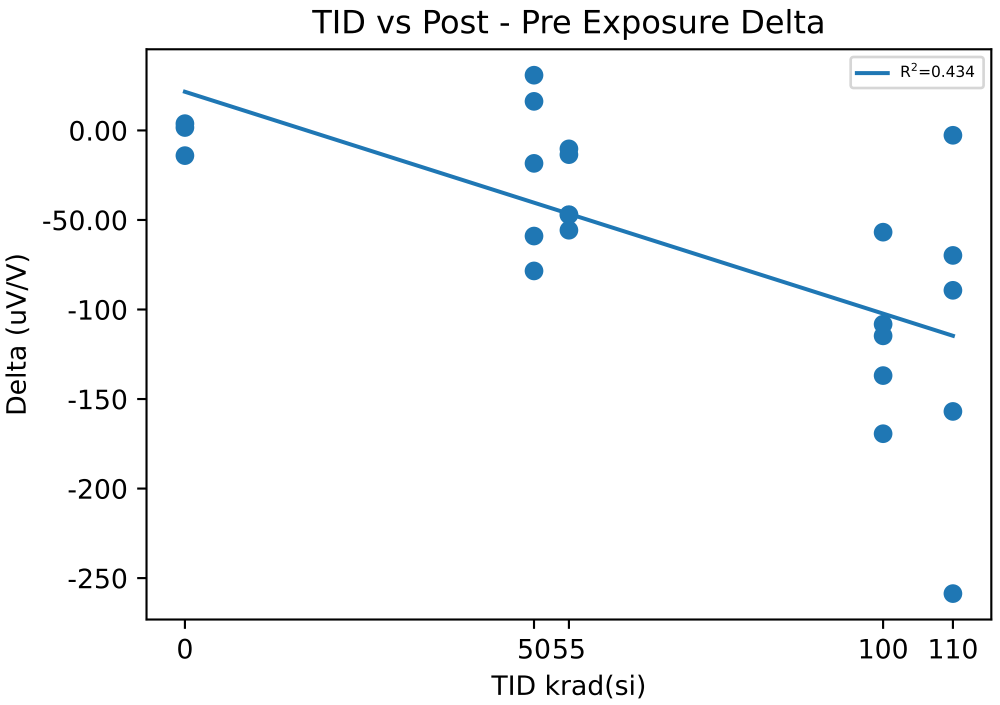
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.1224	0.1212	-0.0012
2	0	CU	0.1323	0.126	-0.0063
3	0	CU	0.0303	0.0267	-0.0036
40	50	50krad Unbiased	0.0323	0.2464	0.2141
41	50	50krad Unbiased	0.083	0.3377	0.2547
42	50	50krad Unbiased	0.1126	0.2591	0.1465
43	50	50krad Unbiased	0.108	0.3086	0.2006
44	50	50krad Unbiased	0.0482	0.0946	0.0464
45	55	50krad Biased	0.1022	0.2627	0.1605
46	55	50krad Biased	0.0825	-0.0329	-0.1154
47	55	50krad Biased	0.0635	0.1182	0.0547
48	55	50krad Biased	0.0538	0.1753	0.1215
49	55	50krad Biased	0.15	0.3889	0.2389
50	100	100krad Unbiased	-0.0123	0.1241	0.1364
51	100	100krad Unbiased	0.1184	0.0919	-0.0265
52	100	100krad Unbiased	0.1239	0.0869	-0.037
53	100	100krad Unbiased	0.0629	0.068	0.0051
54	100	100krad Unbiased	0.131	0.2285	0.0975
55	110	100krad Biased	0.0152	0.1315	0.1163
56	110	100krad Biased	0.0053	0.0977	0.0924
57	110	100krad Biased	0.018	0.2237	0.2057
58	110	100krad Biased	0.0976	0.1029	0.0053
59	110	100krad Biased	0.1033	0.1791	0.0758

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0303	0.095	0.1323	0.05625	0.0267	0.0913	0.126	0.055997	-0.0063	-0.0037	-0.0012	0.0025515
50	0.0323	0.07682	0.1126	0.035678	0.0946	0.24928	0.3377	0.094031	0.0464	0.17246	0.2547	0.080396
55	0.0538	0.0904	0.15	0.038135	-0.0329	0.18244	0.3889	0.15781	-0.1154	0.09204	0.2389	0.13374
100	-0.0123	0.08478	0.131	0.060622	0.068	0.11988	0.2285	0.063989	-0.037	0.0351	0.1364	0.077538
110	0.0053	0.04788	0.1033	0.048263	0.0977	0.14698	0.2237	0.053686	0.0053	0.0991	0.2057	0.072536

Device Test: 55.1 ACCURACY|//LINE_REGULATION_DN/1N8V/150mA//@LINE_REG





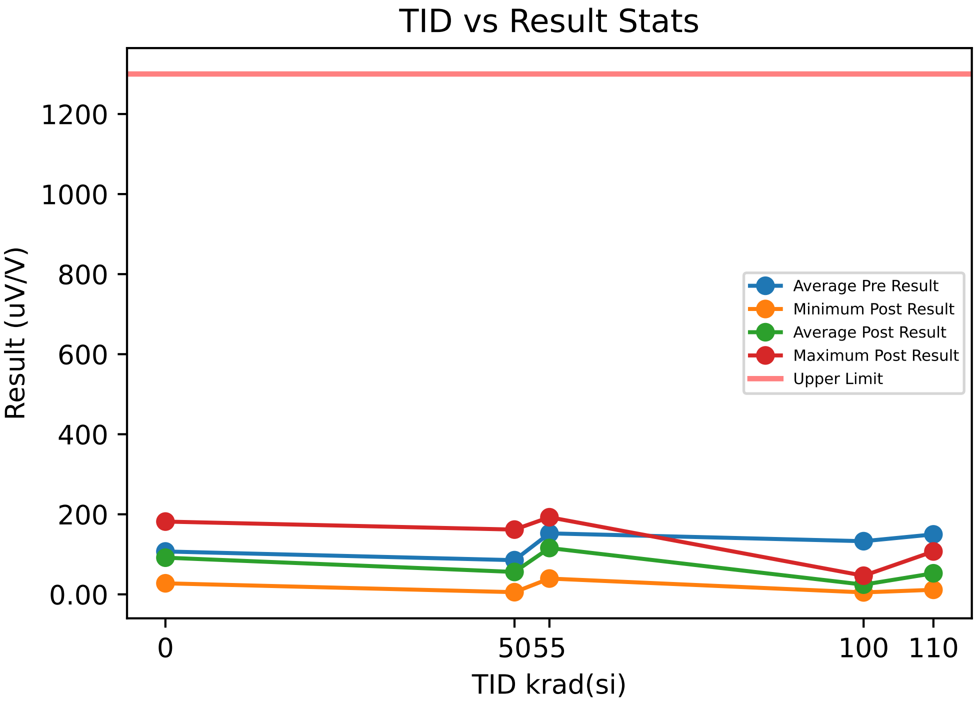
Test Results (Upper Limit = 1300.0 (uV/V))

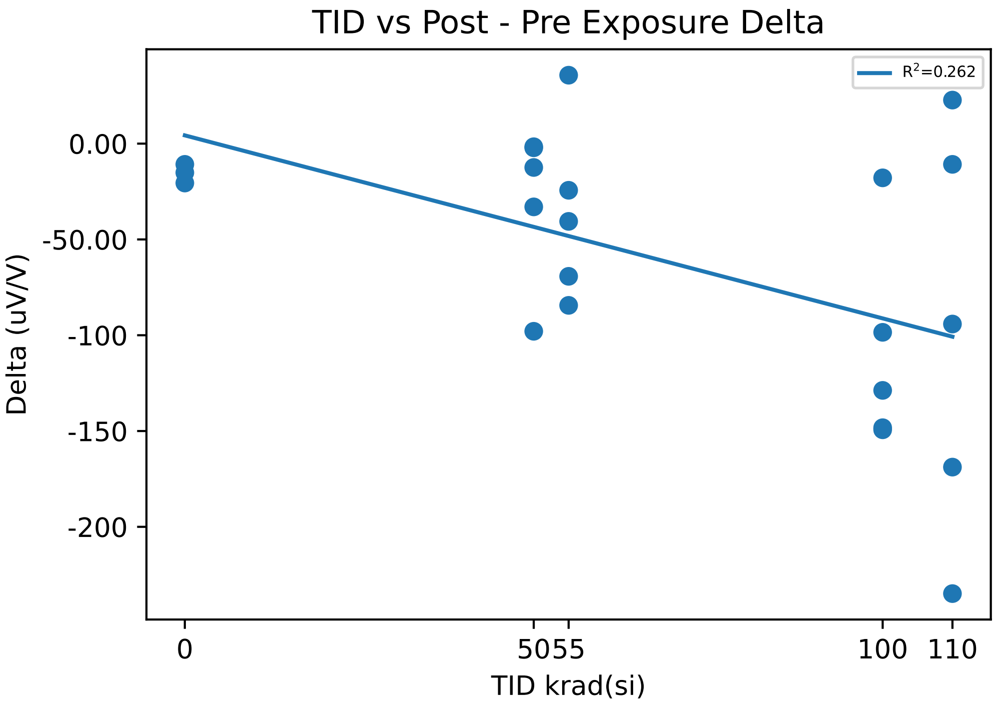
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	204	207.79	3.7927
2	0	CU	102.81	88.745	-14.067
3	0	CU	66.557	68.182	1.6249
40	50	50krad Unbiased	76.297	92.533	16.236
41	50	50krad Unbiased	75.215	16.234	-58.981
42	50	50krad Unbiased	58.441	89.286	30.846
43	50	50krad Unbiased	193.72	175.33	-18.394
44	50	50krad Unbiased	136.36	57.901	-78.461
45	55	50krad Biased	246.21	199.14	-47.073
46	55	50krad Biased	16.233	5.9524	-10.281
47	55	50krad Biased	125.54	78.464	-47.075
48	55	50krad Biased	220.23	164.5	-55.731
49	55	50krad Biased	212.12	198.59	-13.523
50	100	100krad Unbiased	208.87	100.65	-108.22
51	100	100krad Unbiased	176.4	7.0347	-169.37
52	100	100krad Unbiased	72.51	15.693	-56.817
53	100	100krad Unbiased	152.59	15.693	-136.9
54	100	100krad Unbiased	127.7	12.987	-114.72
55	110	100krad Biased	204	47.078	-156.92
56	110	100krad Biased	128.24	38.961	-89.283
57	110	100krad Biased	262.98	4.329	-258.65
58	110	100krad Biased	95.237	92.533	-2.7034
59	110	100krad Biased	114.72	44.914	-69.803

Test Statistics (uV/V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	66.557	124.46	204	71.232	68.182	121.57	207.79	75.373	-14.067	-2.8831	3.7927	9.746
50	58.441	108.01	193.72	56.321	16.234	86.256	175.33	58.5	-78.461	-21.751	30.846	46.965
55	16.233	164.07	246.21	94.273	5.9524	129.33	199.14	84.73	-55.731	-34.737	-10.281	21.173
100	72.51	147.62	208.87	51.583	7.0347	30.412	100.65	39.423	-169.37	-117.21	-56.817	41.36
110	95.237	161.04	262.98	70.337	4.329	45.563	92.533	31.435	-258.65	-115.47	-2.7034	97.092

Device Test: 55.2 ACCURACY|//LINE_REGULATION_UP/1N8V/150mA//@LINE_REG





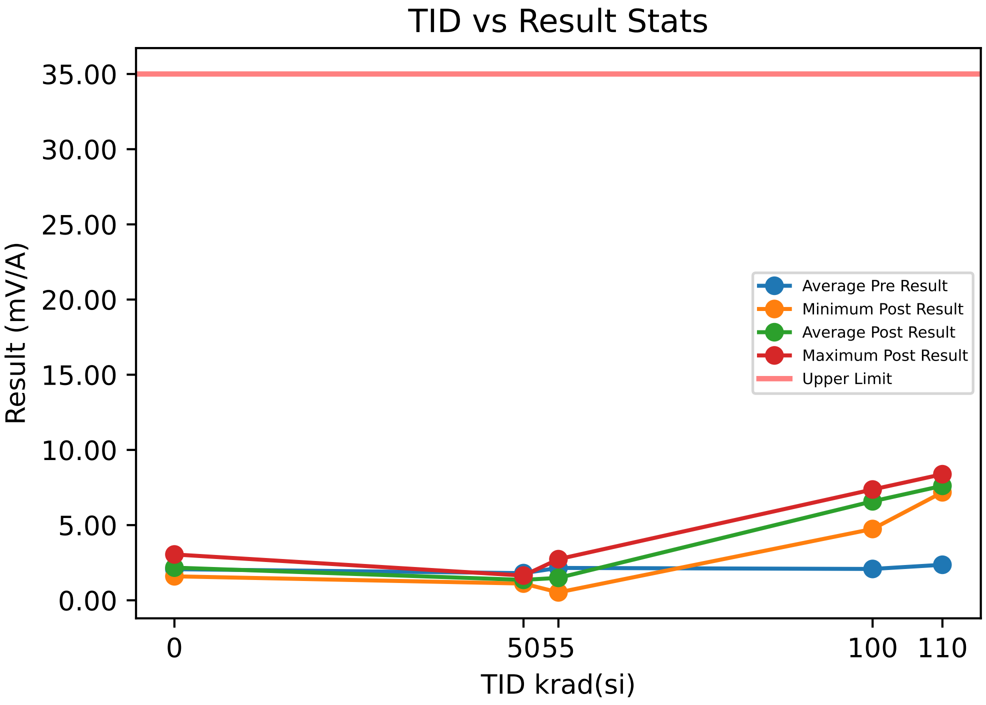
Test Results (Upper Limit = 1300.0 (uV/V))

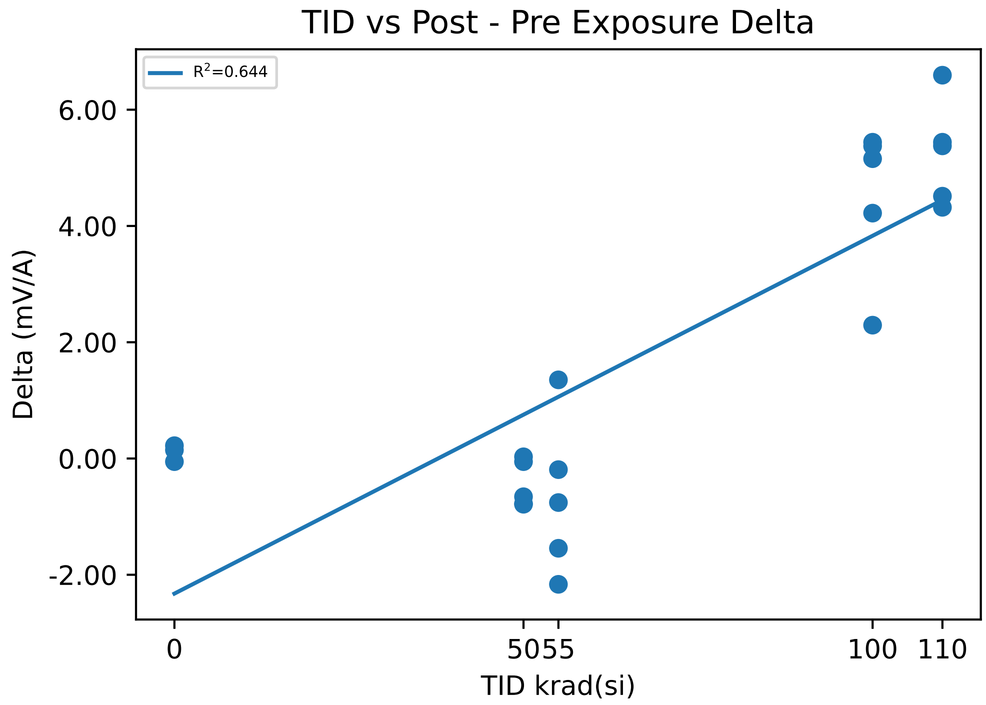
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	192.64	181.82	-10.818
2	0	CU	80.626	65.477	-15.15
3	0	CU	48.159	27.598	-20.562
40	50	50krad Unbiased	70.886	58.442	-12.444
41	50	50krad Unbiased	38.419	5.4113	-33.008
42	50	50krad Unbiased	33.008	30.844	-2.1637
43	50	50krad Unbiased	163.42	161.8	-1.6196
44	50	50krad Unbiased	121.21	23.269	-97.942
45	55	50krad Biased	233.22	192.64	-40.579
46	55	50krad Biased	10.822	46.537	35.715
47	55	50krad Biased	108.76	39.502	-69.262
48	55	50krad Biased	209.95	125.54	-84.411
49	55	50krad Biased	199.13	174.78	-24.346
50	100	100krad Unbiased	189.39	41.126	-148.27
51	100	100krad Unbiased	147.72	18.939	-128.79
52	100	100krad Unbiased	64.393	46.537	-17.856
53	100	100krad Unbiased	154.22	4.8702	-149.35
54	100	100krad Unbiased	108.22	9.7403	-98.483
55	110	100krad Biased	195.34	26.515	-168.83
56	110	100krad Biased	129.33	35.173	-94.154
57	110	100krad Biased	246.21	11.364	-234.84
58	110	100krad Biased	84.414	107.14	22.729
59	110	100krad Biased	93.613	82.793	-10.82

Test Statistics (uV/V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.159	107.14	192.64	75.801	27.598	91.631	181.82	80.369	-20.562	-15.51	-10.818	4.8818
50	33.008	85.388	163.42	55.973	5.4113	55.953	161.8	62.174	-97.942	-29.435	-1.6196	40.349
55	10.822	152.38	233.22	92.164	39.502	115.8	192.64	70.883	-84.411	-36.577	35.715	46.766
100	64.393	132.79	189.39	47.874	4.8702	24.243	46.537	18.68	-149.35	-108.55	-17.856	54.722
110	84.414	149.78	246.21	69.318	11.364	52.598	107.14	40.531	-234.84	-97.183	22.729	107.16

Device Test: 55.3 ACCURACY|//LOAD_REGULATION/1N8V//5/@LOAD_REG





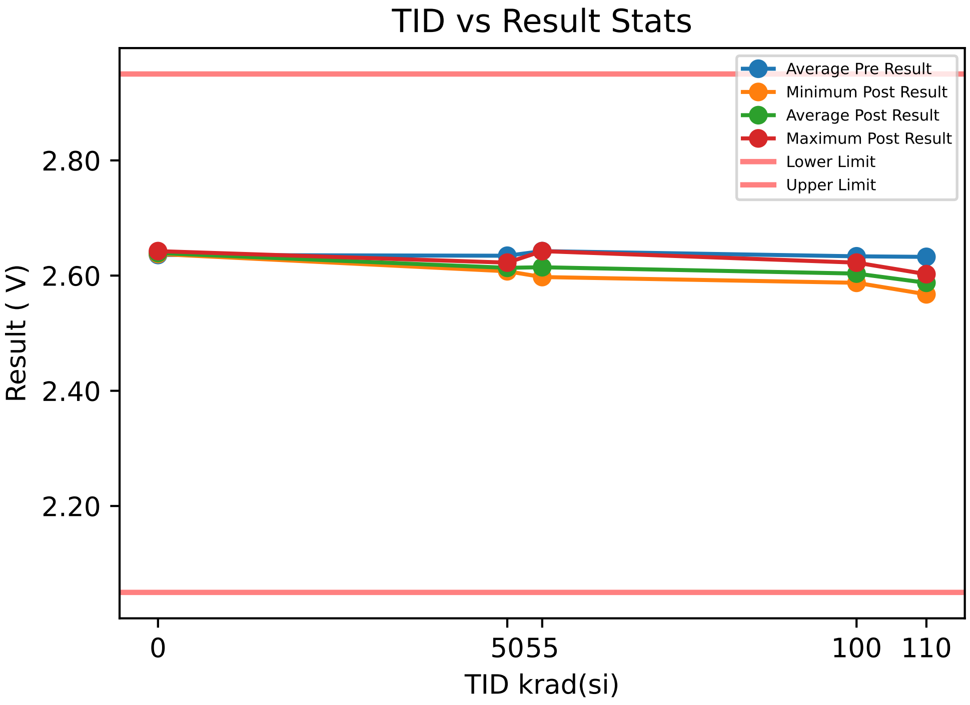
Test Results (Upper Limit = 35.0 (mV/A))

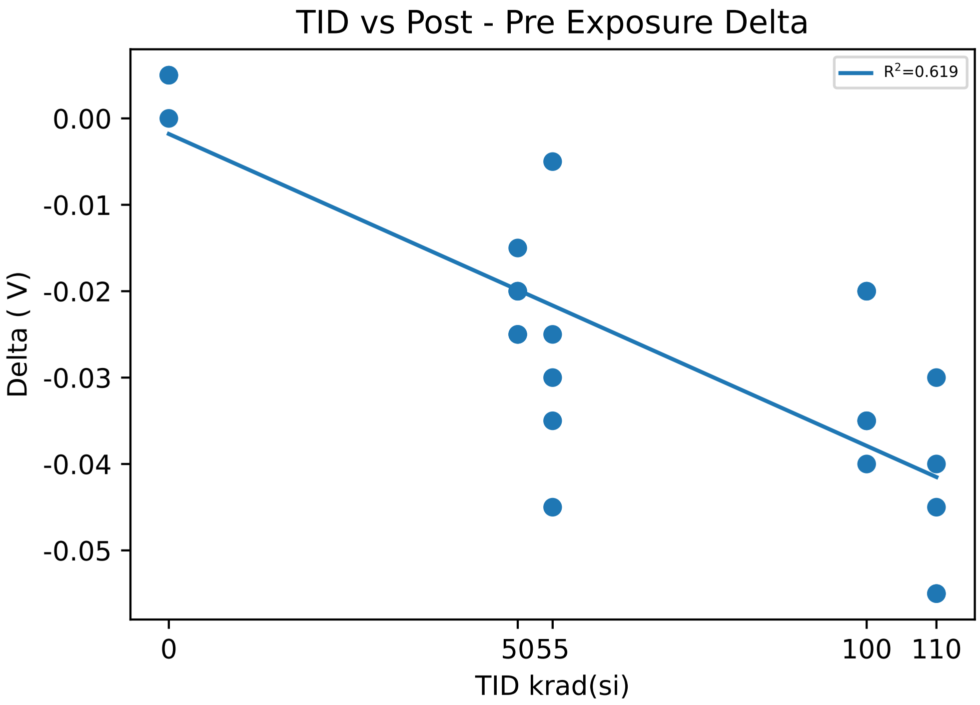
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	2.9012	3.047	0.1458
2	0	CU	1.6483	1.5943	-0.054
3	0	CU	1.6525	1.8731	0.2206
40	50	50krad Unbiased	1.615	1.6442	0.0292
41	50	50krad Unbiased	1.9106	1.1239	-0.7867
42	50	50krad Unbiased	1.5151	1.461	-0.0541
43	50	50krad Unbiased	2.102	1.4444	-0.6576
44	50	50krad Unbiased	1.8897	1.1114	-0.7783
45	55	50krad Biased	2.6681	1.1239	-1.5442
46	55	50krad Biased	1.3819	2.7348	1.3529
47	55	50krad Biased	1.8773	1.6858	-0.1915
48	55	50krad Biased	2.6889	0.5245	-2.1644
49	55	50krad Biased	2.1437	1.3861	-0.7576
50	100	100krad Unbiased	2.5474	6.7683	4.2209
51	100	100krad Unbiased	2.0271	7.1845	5.1574
52	100	100krad Unbiased	1.4027	6.8432	5.4405
53	100	100krad Unbiased	1.9938	7.3677	5.3739
54	100	100krad Unbiased	2.4475	4.7411	2.2936
55	110	100krad Biased	3.1676	7.4884	4.3208
56	110	100krad Biased	2.3102	7.6882	5.378
57	110	100krad Biased	2.8013	7.3136	4.5123
58	110	100krad Biased	1.7898	8.3833	6.5935
59	110	100krad Biased	1.7399	7.1804	5.4405

Test Statistics (mV/A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6483	2.0673	2.9012	0.72215	1.5943	2.1715	3.047	0.77094	-0.054	0.10413	0.2206	0.14196
50	1.5151	1.8065	2.102	0.23805	1.1114	1.357	1.6442	0.23216	-0.7867	-0.4495	0.0292	0.4033
55	1.3819	2.152	2.6889	0.55299	0.5245	1.491	2.7348	0.81622	-2.1644	-0.66096	1.3529	1.3533
100	1.4027	2.0837	2.5474	0.45344	4.7411	6.581	7.3677	1.0574	2.2936	4.4973	5.4405	1.3254
110	1.7399	2.3618	3.1676	0.62432	7.1804	7.6108	8.3833	0.47204	4.3208	5.249	6.5935	0.9035

Device Test: 60.2 UVLO|//RISE////@VUVLO_RISE





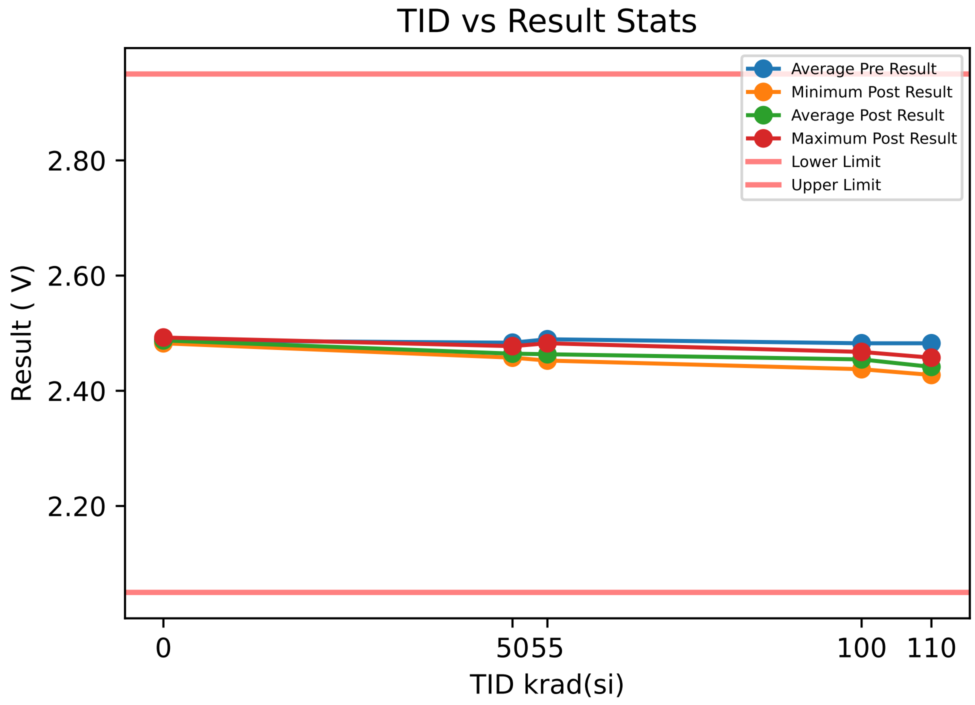
Test Results (Lower Limit = 2.05, Upper Limit = 2.95 (V))

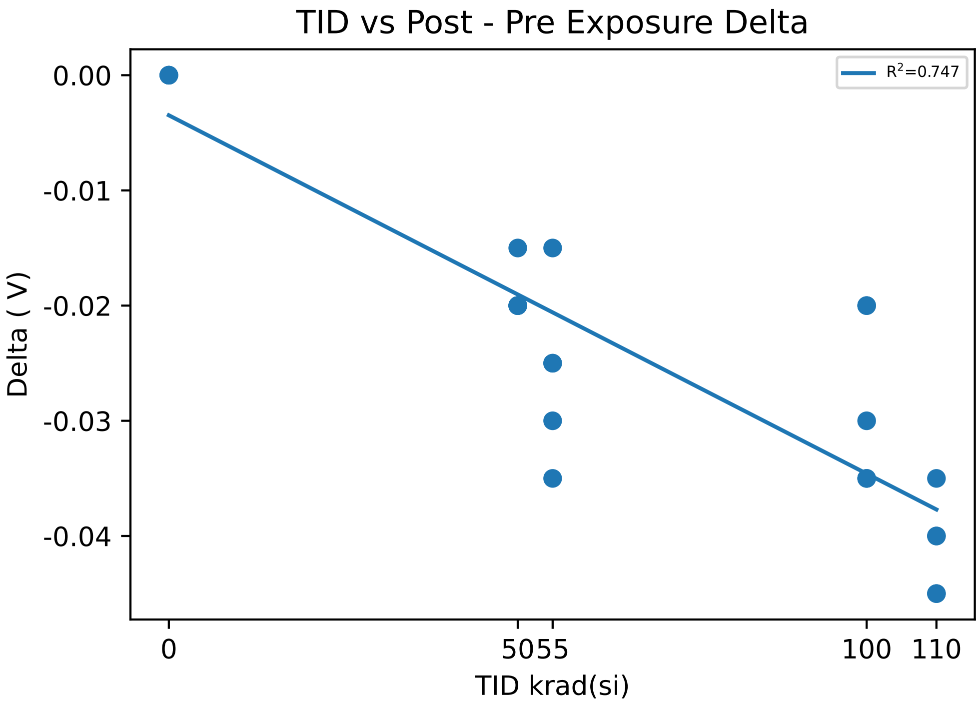
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	2.6375	2.6375	0
2	0	CU	2.6325	2.6375	0.005
3	0	CU	2.6375	2.6425	0.005
40	50	50krad Unbiased	2.6375	2.6175	-0.02
41	50	50krad Unbiased	2.6275	2.6075	-0.02
42	50	50krad Unbiased	2.6475	2.6225	-0.025
43	50	50krad Unbiased	2.6275	2.6125	-0.015
44	50	50krad Unbiased	2.6325	2.6075	-0.025
45	55	50krad Biased	2.6375	2.6125	-0.025
46	55	50krad Biased	2.6475	2.6125	-0.035
47	55	50krad Biased	2.6375	2.6075	-0.03
48	55	50krad Biased	2.6475	2.6425	-0.005
49	55	50krad Biased	2.6425	2.5975	-0.045
50	100	100krad Unbiased	2.6275	2.5925	-0.035
51	100	100krad Unbiased	2.6375	2.6175	-0.02
52	100	100krad Unbiased	2.6425	2.6225	-0.02
53	100	100krad Unbiased	2.6275	2.5875	-0.04
54	100	100krad Unbiased	2.6325	2.5975	-0.035
55	110	100krad Biased	2.6225	2.5675	-0.055
56	110	100krad Biased	2.6375	2.5825	-0.055
57	110	100krad Biased	2.6325	2.6025	-0.03
58	110	100krad Biased	2.6225	2.5825	-0.04
59	110	100krad Biased	2.6475	2.6025	-0.045

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6325	2.6358	2.6375	0.0028868	2.6375	2.6392	2.6425	0.0028868	0	0.0033333	0.005	0.0028868
50	2.6275	2.6345	2.6475	0.0083666	2.6075	2.6135	2.6225	0.0065192	-0.025	-0.021	-0.015	0.0041833
55	2.6375	2.6425	2.6475	0.005	2.5975	2.6145	2.6425	0.016808	-0.045	-0.028	-0.005	0.014832
100	2.6275	2.6335	2.6425	0.0065192	2.5875	2.6035	2.6225	0.015572	-0.04	-0.03	-0.02	0.0093541
110	2.6225	2.6325	2.6475	0.010607	2.5675	2.5875	2.6025	0.015	-0.055	-0.045	-0.03	0.010607

Device Test: 60.3 UVLO|//FALL////@VUVLO_FALL





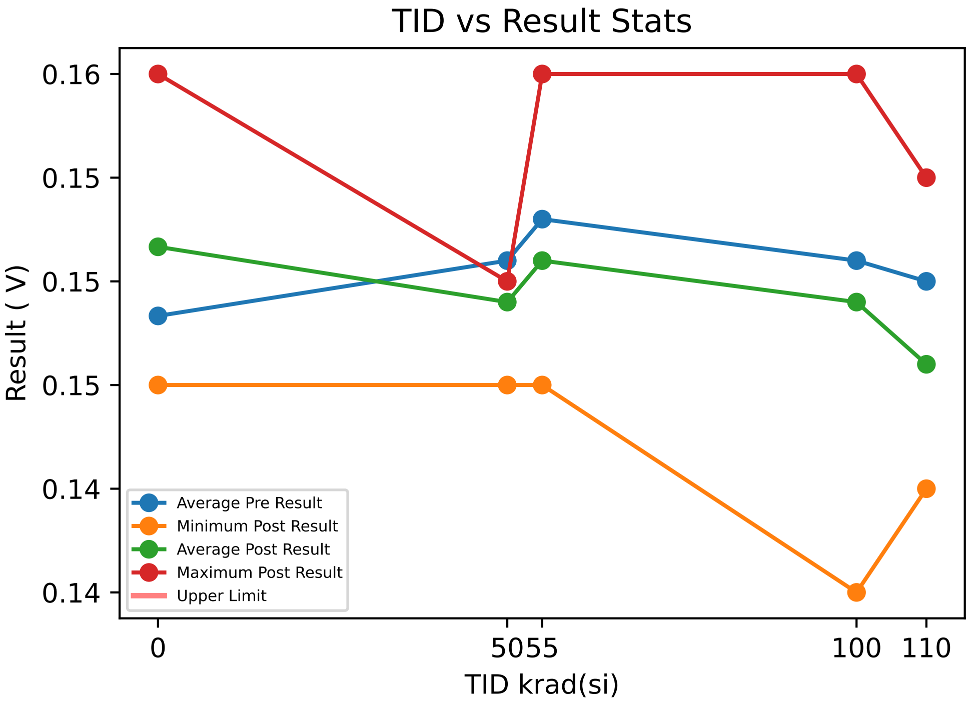
Test Results (Lower Limit = 2.05, Upper Limit = 2.95 (V))

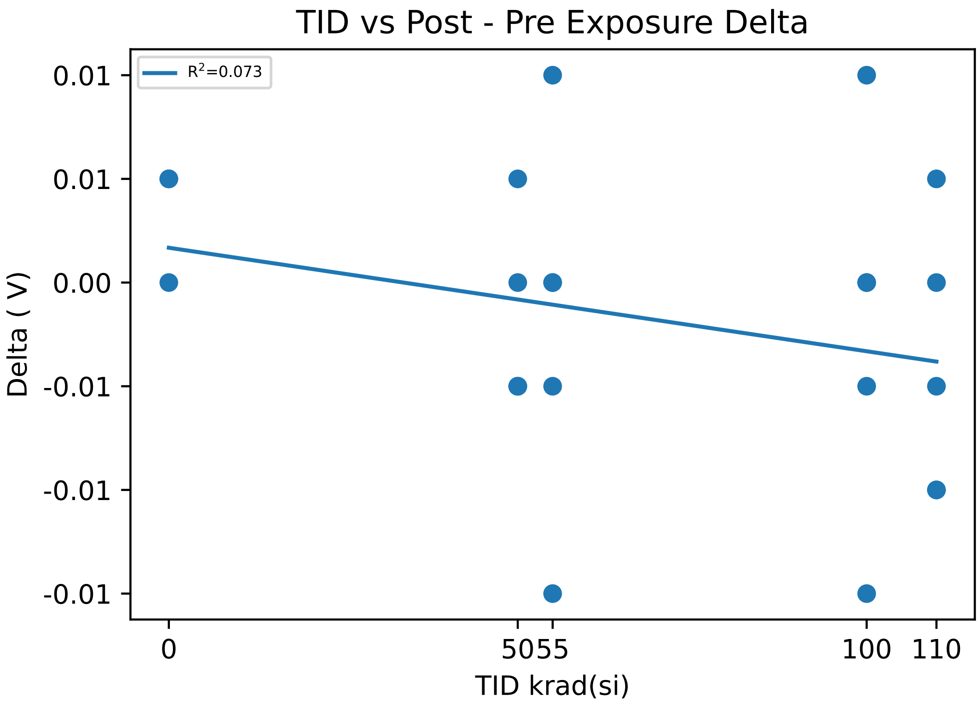
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	2.4925	2.4925	0
2	0	CU	2.4875	2.4875	0
3	0	CU	2.4825	2.4825	0
40	50	50krad Unbiased	2.4825	2.4675	-0.015
41	50	50krad Unbiased	2.4775	2.4575	-0.02
42	50	50krad Unbiased	2.4975	2.4775	-0.02
43	50	50krad Unbiased	2.4825	2.4625	-0.02
44	50	50krad Unbiased	2.4775	2.4575	-0.02
45	55	50krad Biased	2.4875	2.4625	-0.025
46	55	50krad Biased	2.4975	2.4625	-0.035
47	55	50krad Biased	2.4825	2.4575	-0.025
48	55	50krad Biased	2.4975	2.4825	-0.015
49	55	50krad Biased	2.4825	2.4525	-0.03
50	100	100krad Unbiased	2.4825	2.4475	-0.035
51	100	100krad Unbiased	2.4875	2.4575	-0.03
52	100	100krad Unbiased	2.4875	2.4675	-0.02
53	100	100krad Unbiased	2.4725	2.4375	-0.035
54	100	100krad Unbiased	2.4825	2.4625	-0.02
55	110	100krad Biased	2.4725	2.4275	-0.045
56	110	100krad Biased	2.4875	2.4425	-0.045
57	110	100krad Biased	2.4875	2.4525	-0.035
58	110	100krad Biased	2.4675	2.4275	-0.04
59	110	100krad Biased	2.4975	2.4575	-0.04

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4825	2.4875	2.4925	0.005	2.4825	2.4875	2.4925	0.005	0	0	0	0
50	2.4775	2.4835	2.4975	0.0082158	2.4575	2.4645	2.4775	0.0083666	-0.02	-0.019	-0.015	0.0022361
55	2.4825	2.4895	2.4975	0.0075829	2.4525	2.4635	2.4825	0.011402	-0.035	-0.026	-0.015	0.0074162
100	2.4725	2.4825	2.4875	0.0061237	2.4375	2.4545	2.4675	0.012042	-0.035	-0.028	-0.02	0.0075829
110	2.4675	2.4825	2.4975	0.012247	2.4275	2.4415	2.4575	0.013874	-0.045	-0.041	-0.035	0.0041833

Device Test: 60.4 UVLO|//HYSTERESIS////@VUVLO_HYS





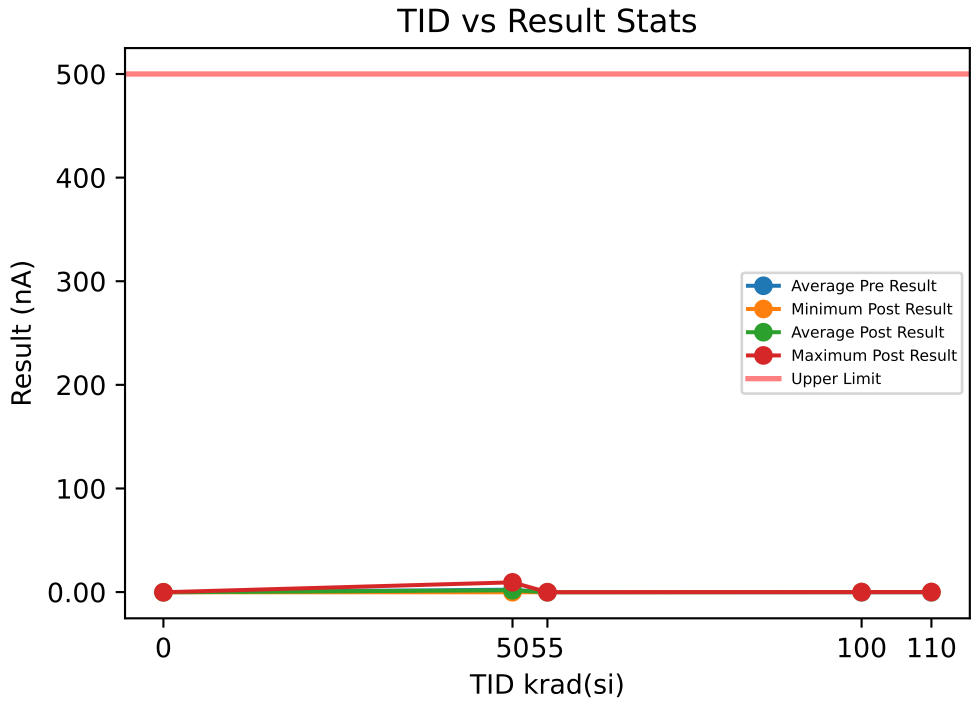
Test Results (No Limits Specified (V))

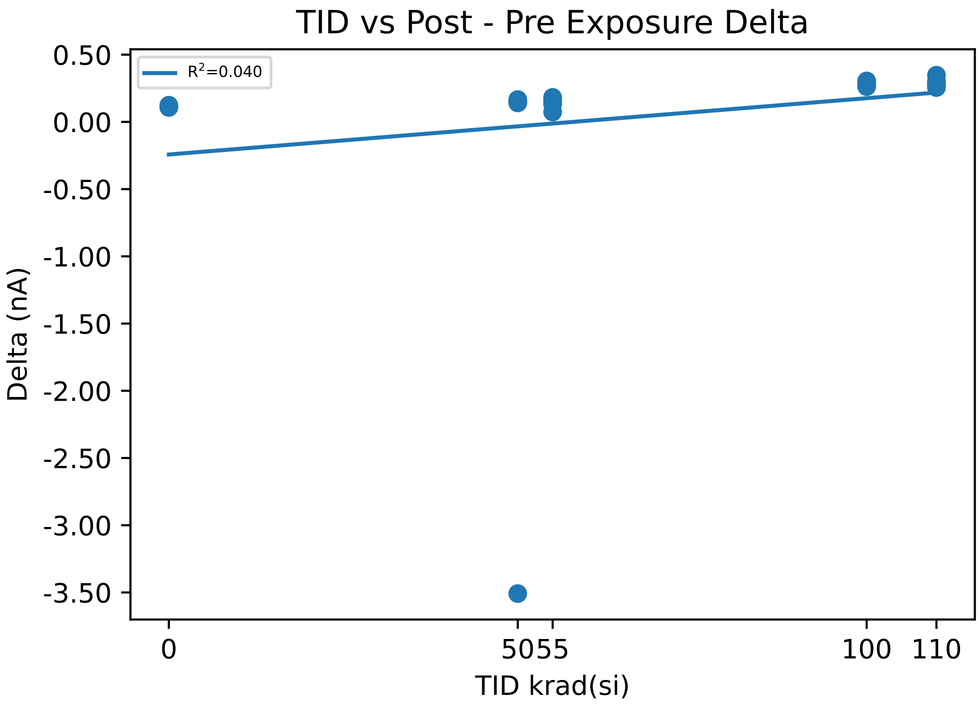
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.145	0.145	0
2	0	CU	0.145	0.15	0.005
3	0	CU	0.155	0.16	0.005
40	50	50krad Unbiased	0.155	0.15	-0.005
41	50	50krad Unbiased	0.15	0.15	0
42	50	50krad Unbiased	0.15	0.145	-0.005
43	50	50krad Unbiased	0.145	0.15	0.005
44	50	50krad Unbiased	0.155	0.15	-0.005
45	55	50krad Biased	0.15	0.15	0
46	55	50krad Biased	0.15	0.15	0
47	55	50krad Biased	0.155	0.15	-0.005
48	55	50krad Biased	0.15	0.16	0.01
49	55	50krad Biased	0.16	0.145	-0.015
50	100	100krad Unbiased	0.145	0.145	0
51	100	100krad Unbiased	0.15	0.16	0.01
52	100	100krad Unbiased	0.155	0.155	0
53	100	100krad Unbiased	0.155	0.15	-0.005
54	100	100krad Unbiased	0.15	0.135	-0.015
55	110	100krad Biased	0.15	0.14	-0.01
56	110	100krad Biased	0.15	0.14	-0.01
57	110	100krad Biased	0.145	0.15	0.005
58	110	100krad Biased	0.155	0.155	0
59	110	100krad Biased	0.15	0.145	-0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.145	0.14833	0.155	0.0057735	0.145	0.15167	0.16	0.0076376	0	0.0033333	0.005	0.0028868
50	0.145	0.151	0.155	0.0041833	0.145	0.149	0.15	0.0022361	-0.005	-0.002	0.005	0.0044721
55	0.15	0.153	0.16	0.0044721	0.145	0.151	0.16	0.0054772	-0.015	-0.002	0.01	0.009083
100	0.145	0.151	0.155	0.0041833	0.135	0.149	0.16	0.0096177	-0.015	-0.002	0.01	0.009083
110	0.145	0.15	0.155	0.0035355	0.14	0.146	0.155	0.0065192	-0.01	-0.004	0.005	0.0065192

Device Test: 65.1 LEAK|/EN/CURRENT///3/@I_EN_LKG





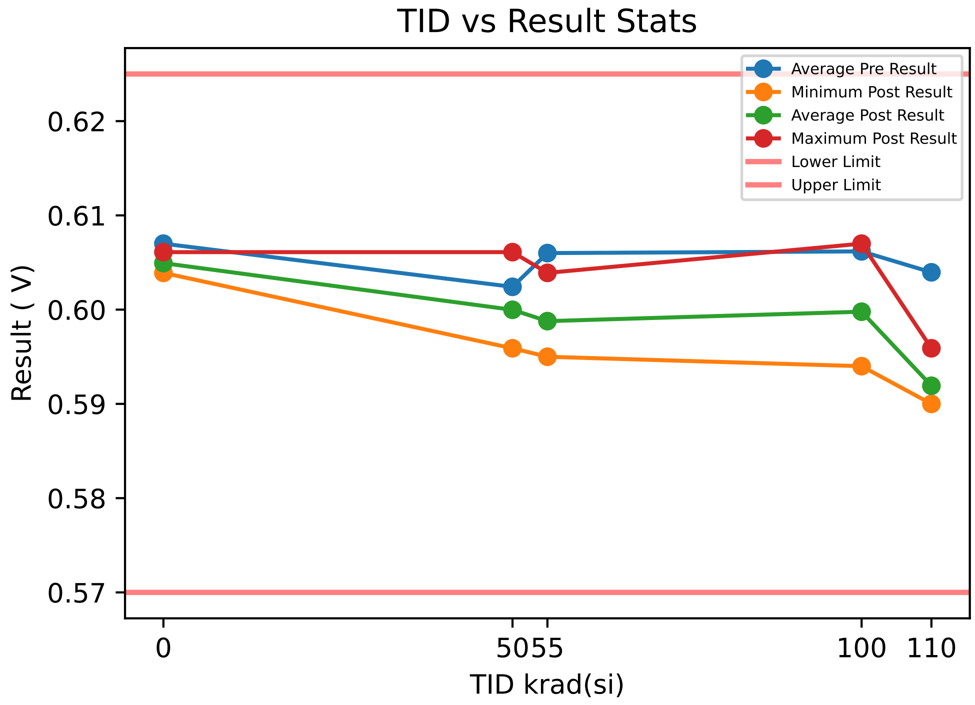
Test Results (Upper Limit = 500.0 (nA))

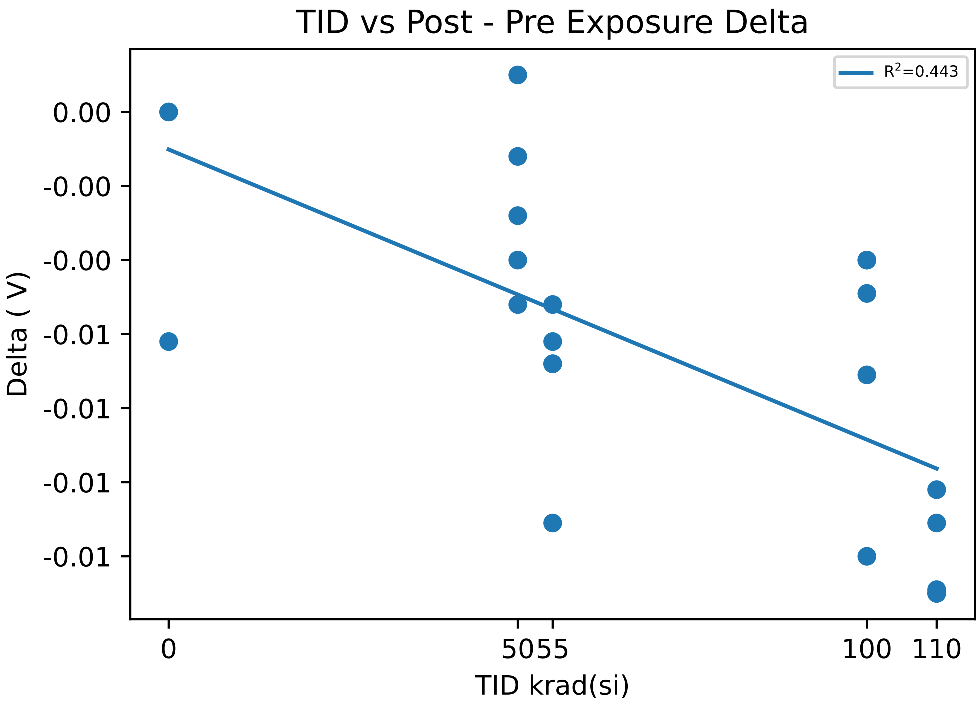
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	-0.2777	-0.1647	0.113
2	0	CU	-0.2965	-0.1889	0.1076
3	0	CU	-0.3425	-0.2184	0.1241
40	50	50krad Unbiased	-0.3441	-0.2029	0.1412
41	50	50krad Unbiased	-0.3308	-0.1795	0.1513
42	50	50krad Unbiased	-0.3019	-0.1359	0.166
43	50	50krad Unbiased	-0.2972	-0.1476	0.1496
44	50	50krad Unbiased	12.91	9.4014	-3.5085
45	55	50krad Biased	-0.3035	-0.1476	0.1559
46	55	50krad Biased	-0.2832	-0.1476	0.1356
47	55	50krad Biased	-0.2559	-0.1826	0.0733
48	55	50krad Biased	-0.259	-0.1274	0.1316
49	55	50krad Biased	-0.2988	-0.1165	0.1823
50	100	100krad Unbiased	-0.3074	-0.0029	0.3045
51	100	100krad Unbiased	-0.2785	0.0228	0.3013
52	100	100krad Unbiased	-0.2925	-0.0044	0.2881
53	100	100krad Unbiased	-0.3097	-0.0387	0.271
54	100	100krad Unbiased	-0.2644	-0.0021	0.2623
55	110	100krad Biased	-0.3043	0.043	0.3473
56	110	100krad Biased	-0.2699	0.0314	0.3013
57	110	100krad Biased	-0.2863	-0.0075	0.2788
58	110	100krad Biased	-0.2442	0.0111	0.2553
59	110	100krad Biased	-0.3292	-0.0449	0.2843

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3425	-0.30557	-0.2777	0.033338	-0.2184	-0.19067	-0.1647	0.026894	0.1076	0.1149	0.1241	0.0084125
50	-0.3441	2.3272	12.91	5.916	-0.2029	1.7471	9.4014	4.279	-3.5085	-0.58008	0.166	1.6371
55	-0.3035	-0.28008	-0.2559	0.02201	-0.1826	-0.14434	-0.1165	0.025234	0.0733	0.13574	0.1823	0.040281
100	-0.3097	-0.2905	-0.2644	0.019258	-0.0387	-0.00506	0.0228	0.021919	0.2623	0.28544	0.3045	0.018479
110	-0.3292	-0.28678	-0.2442	0.032422	-0.0449	0.00662	0.043	0.034682	0.2553	0.2934	0.3473	0.034334

Device Test: 65.2 ENABLE|/EN/RISE///3/@V_EN_RISING


TID vs Result Stats


TID vs Post - Pre Exposure Delta

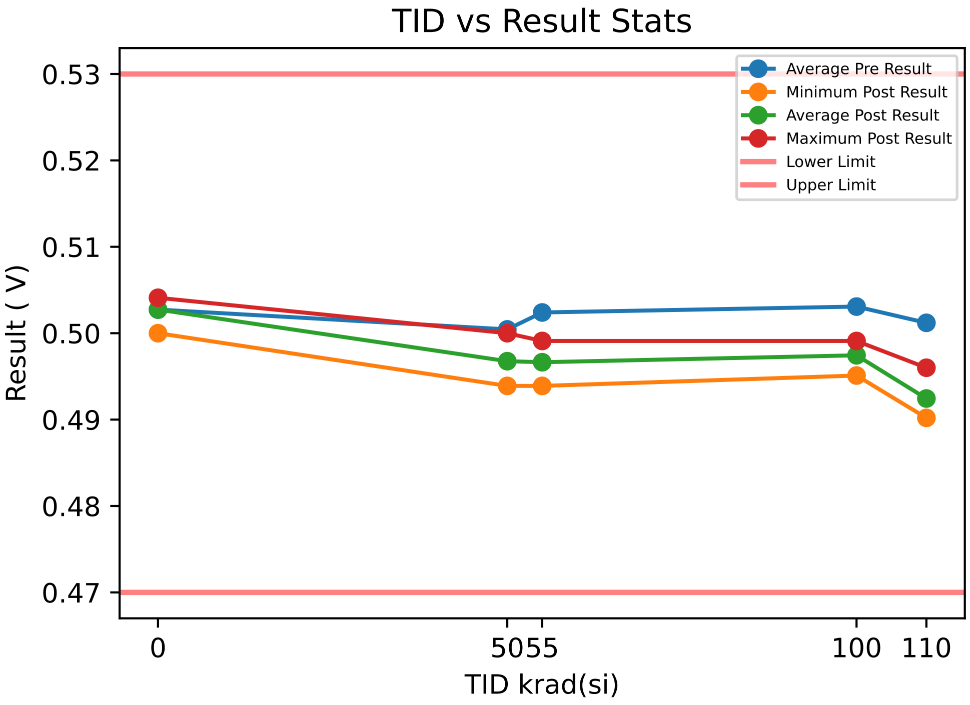
Test Results (Lower Limit = 0.57, Upper Limit = 0.625 (V))

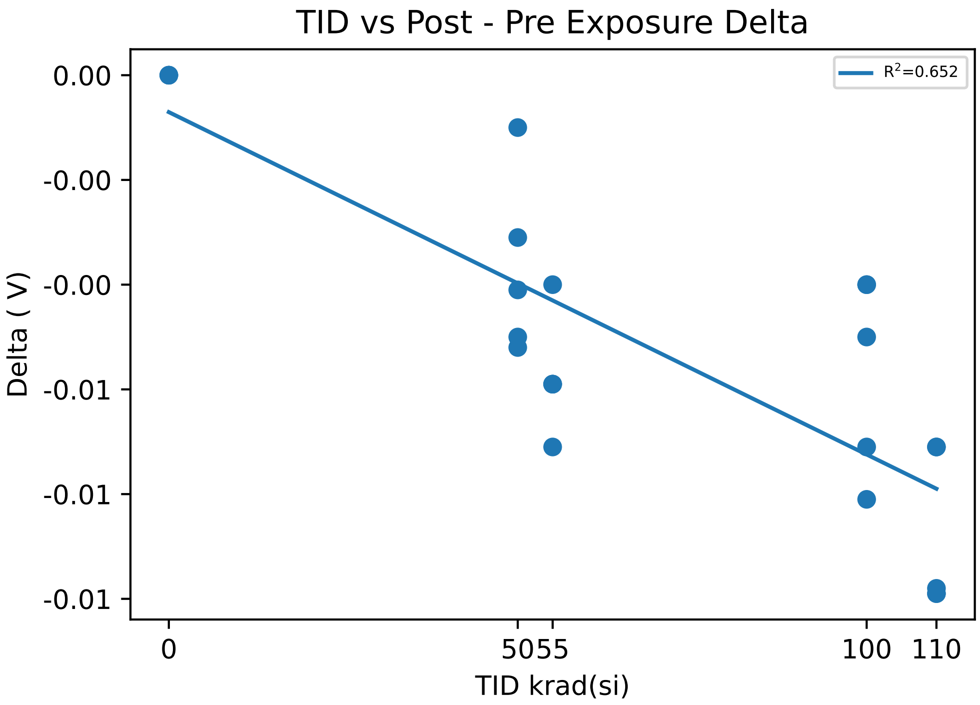
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.6101	0.6039	-0.0062
2	0	CU	0.6061	0.6061	0
3	0	CU	0.6048	0.6048	0
40	50	50krad Unbiased	0.6011	0.5959	-0.0052
41	50	50krad Unbiased	0.603	0.599	-0.004
42	50	50krad Unbiased	0.6011	0.5999	-0.0012
43	50	50krad Unbiased	0.6089	0.6061	-0.0028
44	50	50krad Unbiased	0.598	0.599	0.001
45	55	50krad Biased	0.6011	0.5959	-0.0052
46	55	50krad Biased	0.6101	0.6039	-0.0062
47	55	50krad Biased	0.6079	0.6011	-0.0068
48	55	50krad Biased	0.6061	0.595	-0.0111
49	55	50krad Biased	0.6048	0.598	-0.0068
50	100	100krad Unbiased	0.6079	0.5959	-0.012
51	100	100krad Unbiased	0.6039	0.599	-0.0049
52	100	100krad Unbiased	0.6101	0.603	-0.0071
53	100	100krad Unbiased	0.598	0.594	-0.004
54	100	100krad Unbiased	0.611	0.607	-0.004
55	110	100krad Biased	0.6011	0.59	-0.0111
56	110	100krad Biased	0.6011	0.5909	-0.0102
57	110	100krad Biased	0.6048	0.5919	-0.0129
58	110	100krad Biased	0.6039	0.5909	-0.013
59	110	100krad Biased	0.6089	0.5959	-0.013

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6048	0.607	0.6101	0.0027622	0.6039	0.60493	0.6061	0.001106	-0.0062	-0.0020667	0	0.0035796
50	0.598	0.60242	0.6089	0.0040419	0.5959	0.59998	0.6061	0.0037426	-0.0052	-0.00244	0.001	0.0024265
55	0.6011	0.606	0.6101	0.0033867	0.595	0.59878	0.6039	0.0037009	-0.0111	-0.00722	-0.0052	0.0022654
100	0.598	0.60618	0.611	0.0053308	0.594	0.59978	0.607	0.0052813	-0.012	-0.0064	-0.004	0.0033771
110	0.6011	0.60396	0.6089	0.0032199	0.59	0.59192	0.5959	0.0023242	-0.013	-0.01204	-0.0102	0.0013088

Device Test: 65.3 ENABLE|/EN/FALL///3/@V_EN_FALLING





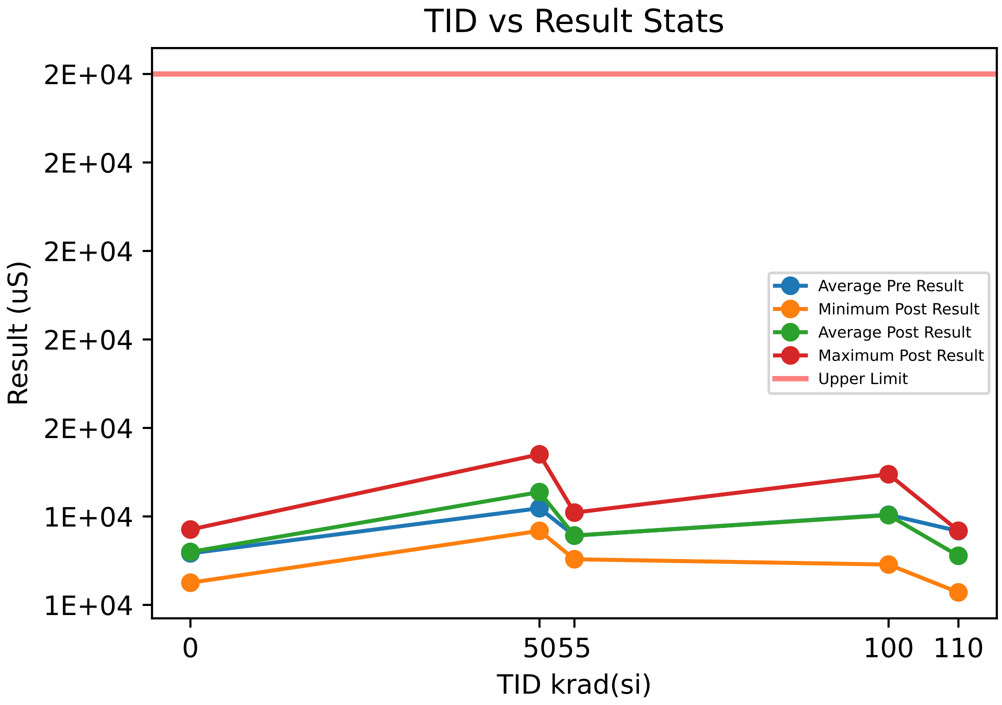
Test Results (Lower Limit = 0.47, Upper Limit = 0.53 (V))

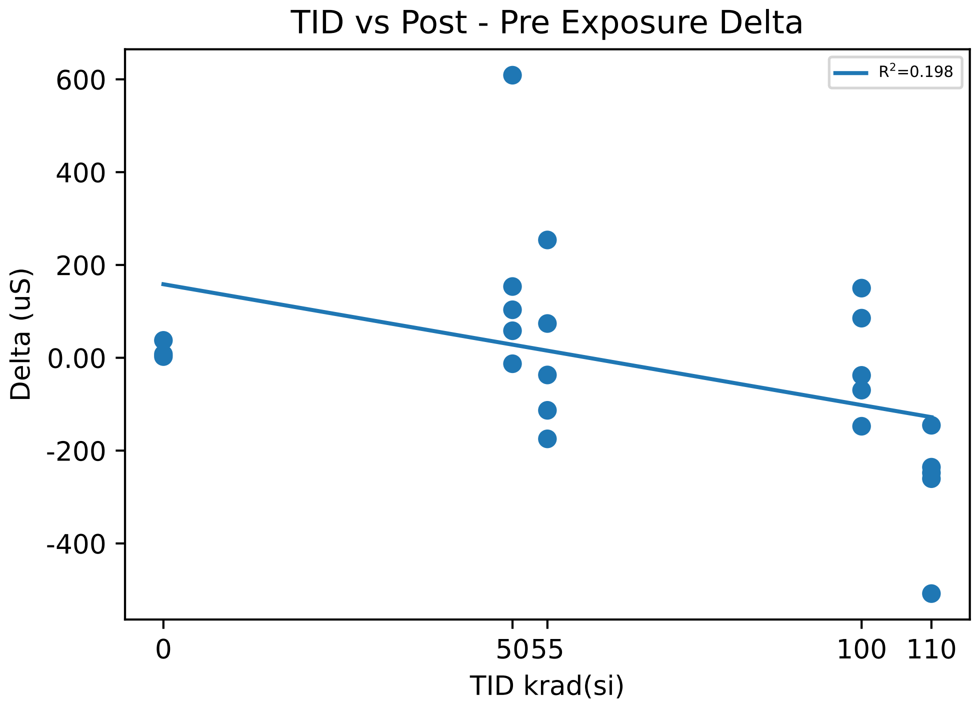
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.5041	0.5041	0
2	0	CU	0.5	0.5	0
3	0	CU	0.5041	0.5041	0
40	50	50krad Unbiased	0.501	0.496	-0.005
41	50	50krad Unbiased	0.501	0.4979	-0.0031
42	50	50krad Unbiased	0.4991	0.4939	-0.0052
43	50	50krad Unbiased	0.5041	0.5	-0.0041
44	50	50krad Unbiased	0.497	0.496	-0.001
45	55	50krad Biased	0.501	0.4939	-0.0071
46	55	50krad Biased	0.505	0.4991	-0.0059
47	55	50krad Biased	0.5019	0.496	-0.0059
48	55	50krad Biased	0.4991	0.4951	-0.004
49	55	50krad Biased	0.505	0.4991	-0.0059
50	100	100krad Unbiased	0.5041	0.496	-0.0081
51	100	100krad Unbiased	0.5041	0.4991	-0.005
52	100	100krad Unbiased	0.5031	0.4991	-0.004
53	100	100krad Unbiased	0.4991	0.4951	-0.004
54	100	100krad Unbiased	0.505	0.4979	-0.0071
55	110	100krad Biased	0.501	0.4911	-0.0099
56	110	100krad Biased	0.5	0.4902	-0.0098
57	110	100krad Biased	0.5	0.4929	-0.0071
58	110	100krad Biased	0.5019	0.492	-0.0099
59	110	100krad Biased	0.5031	0.496	-0.0071

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5	0.50273	0.5041	0.0023671	0.5	0.50273	0.5041	0.0023671	0	0	0	0
50	0.497	0.50044	0.5041	0.0026293	0.4939	0.49676	0.5	0.0022985	-0.0052	-0.00368	-0.001	0.0017138
55	0.4991	0.5024	0.505	0.0025797	0.4939	0.49664	0.4991	0.002366	-0.0071	-0.00576	-0.004	0.0011127
100	0.4991	0.50308	0.505	0.0023242	0.4951	0.49744	0.4991	0.0018215	-0.0081	-0.00564	-0.004	0.001869
110	0.5	0.5012	0.5031	0.0013248	0.4902	0.49244	0.496	0.00223	-0.0099	-0.00876	-0.0071	0.0015159

Device Test: 65.4 ENABLE|/EN/DELAY///3/@T_EN_DELAY





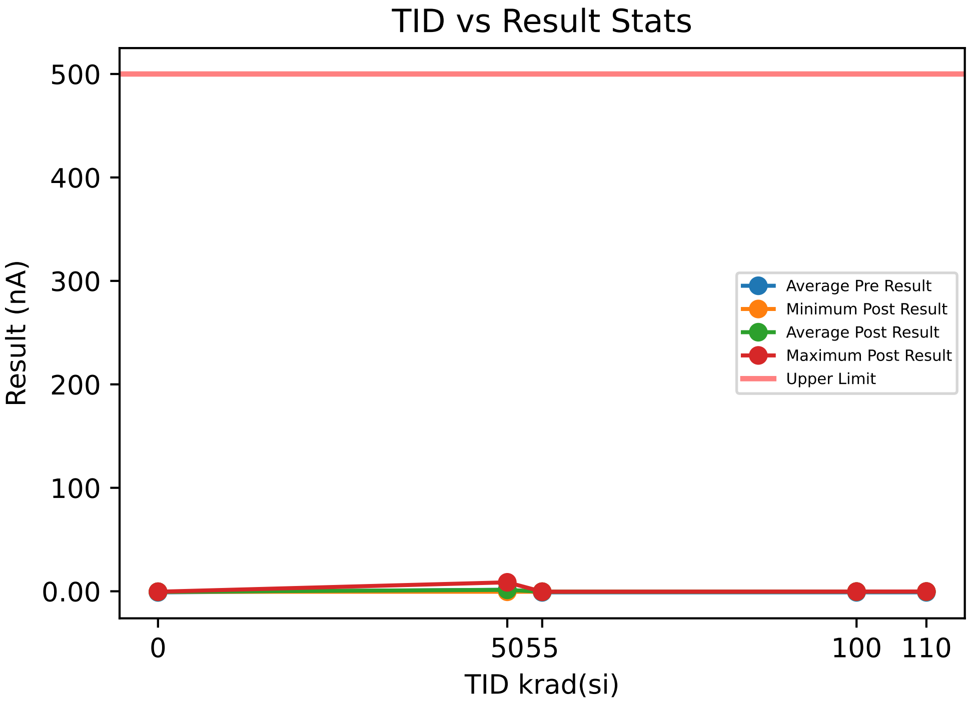
Test Results (Upper Limit = 19000.0 (uS))

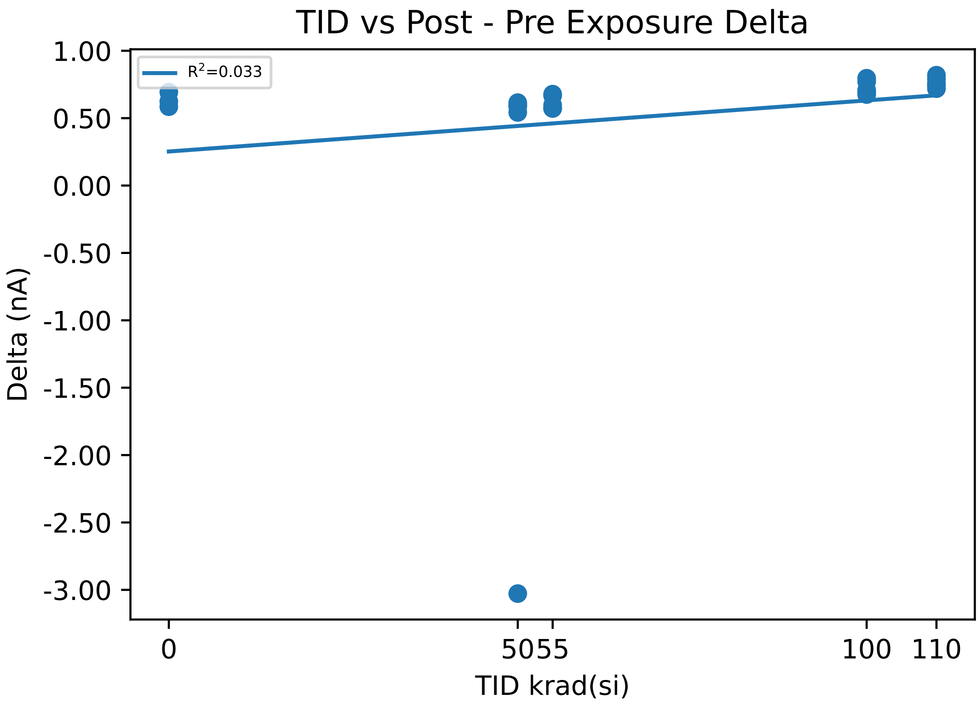
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	1.32e+04	1.33e+04	37.546
2	0	CU	1.37e+04	1.37e+04	7.7765
3	0	CU	1.38e+04	1.39e+04	2.603
40	50	50krad Unbiased	1.41e+04	1.47e+04	608.89
41	50	50krad Unbiased	1.45e+04	1.46e+04	103.44
42	50	50krad Unbiased	1.39e+04	1.4e+04	153.56
43	50	50krad Unbiased	1.38e+04	1.38e+04	-12.837
44	50	50krad Unbiased	1.41e+04	1.42e+04	58.253
45	55	50krad Biased	1.38e+04	1.38e+04	-36.987
46	55	50krad Biased	1.4e+04	1.4e+04	73.864
47	55	50krad Biased	1.37e+04	1.35e+04	-174.68
48	55	50krad Biased	1.36e+04	1.38e+04	253.88
49	55	50krad Biased	1.39e+04	1.38e+04	-113.2
50	100	100krad Unbiased	1.4e+04	1.4e+04	-37.877
51	100	100krad Unbiased	1.43e+04	1.41e+04	-147.5
52	100	100krad Unbiased	1.35e+04	1.35e+04	-69.673
53	100	100krad Unbiased	1.43e+04	1.45e+04	150.09
54	100	100krad Unbiased	1.39e+04	1.4e+04	85.382
55	110	100krad Biased	1.37e+04	1.32e+04	-508.09
56	110	100krad Biased	1.41e+04	1.38e+04	-260.51
57	110	100krad Biased	1.41e+04	1.38e+04	-235.74
58	110	100krad Biased	1.39e+04	1.38e+04	-145.43
59	110	100krad Biased	1.34e+04	1.31e+04	-247.86

Test Statistics (uS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.32e+04	1.36e+04	1.38e+04	330.25	1.33e+04	1.36e+04	1.39e+04	311.52	2.603	15.975	37.546	18.859
50	1.38e+04	1.41e+04	1.45e+04	261.7	1.38e+04	1.43e+04	1.47e+04	371.04	-12.837	182.26	608.89	246.22
55	1.36e+04	1.38e+04	1.4e+04	161.22	1.35e+04	1.38e+04	1.4e+04	187.13	-174.68	0.5747	253.88	169.27
100	1.35e+04	1.4e+04	1.43e+04	324.09	1.35e+04	1.4e+04	1.45e+04	368.78	-147.5	-3.9151	150.09	120.2
110	1.34e+04	1.38e+04	1.41e+04	291.81	1.31e+04	1.36e+04	1.38e+04	349.05	-508.09	-279.53	-145.43	135.56

Device Test: 65.5 LEAK|/EN/CURRENT///6.3/@I_EN_LKG





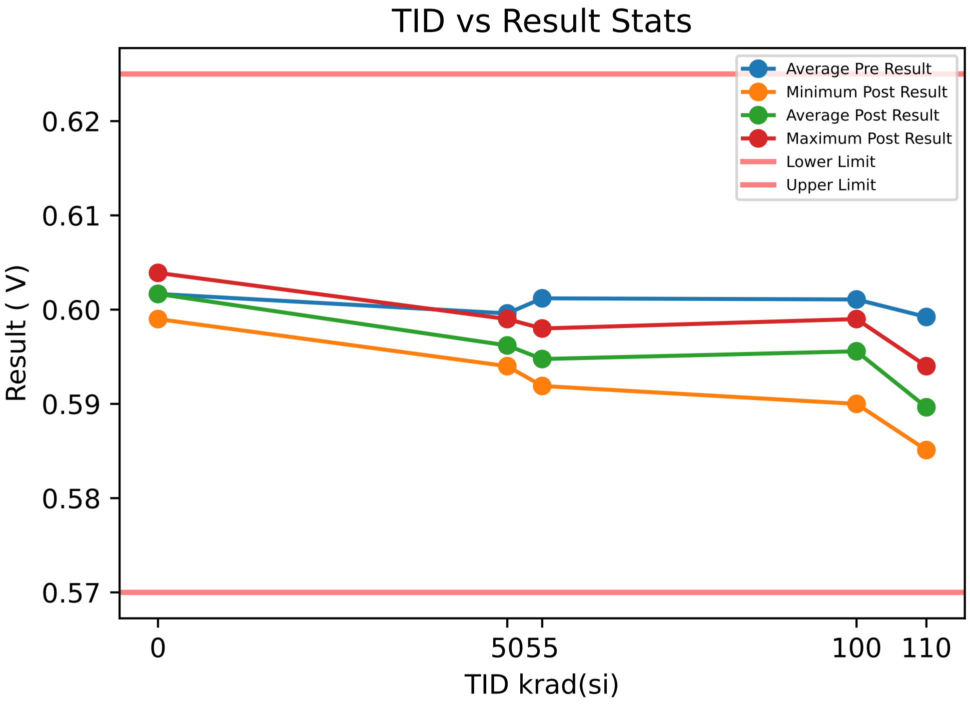
Test Results (Upper Limit = 500.0 (nA))

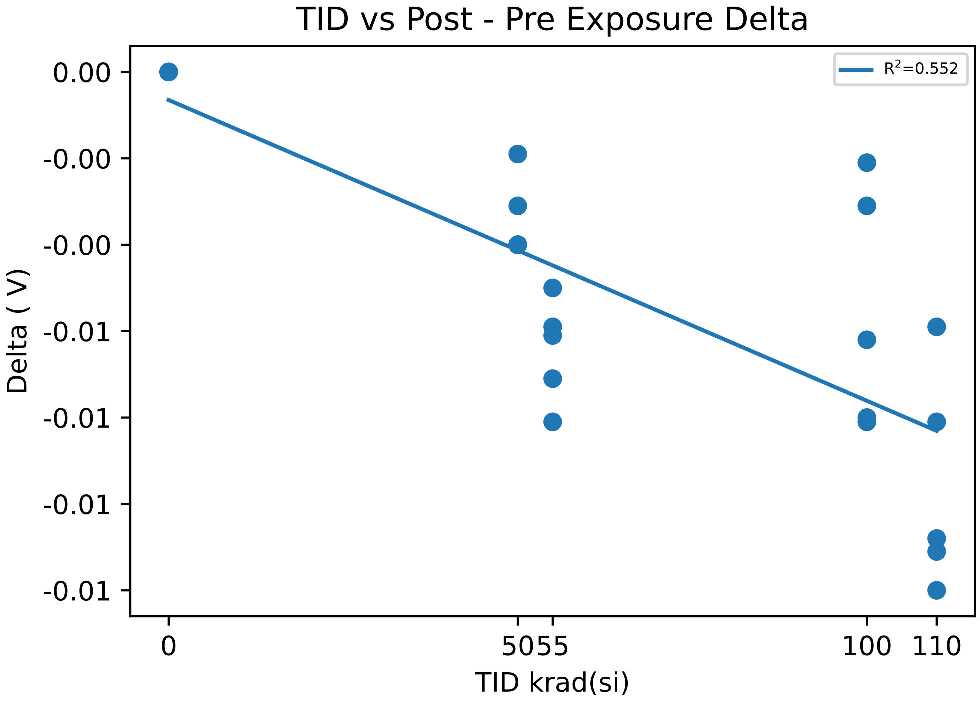
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	-1.0067	-0.4215	0.5852
2	0	CU	-1.1339	-0.441	0.6929
3	0	CU	-1.109	-0.4846	0.6244
40	50	50krad Unbiased	-1.0145	-0.4721	0.5424
41	50	50krad Unbiased	-1.0715	-0.4565	0.615
42	50	50krad Unbiased	-1.0582	-0.4597	0.5985
43	50	50krad Unbiased	-0.9997	-0.4137	0.586
44	50	50krad Unbiased	11.681	8.6528	-3.0278
45	55	50krad Biased	-1.1129	-0.4348	0.6781
46	55	50krad Biased	-0.9724	-0.3997	0.5727
47	55	50krad Biased	-1.0192	-0.4223	0.5969
48	55	50krad Biased	-1.0871	-0.42	0.6671
49	55	50krad Biased	-1.0239	-0.4519	0.572
50	100	100krad Unbiased	-1.0512	-0.255	0.7962
51	100	100krad Unbiased	-1.0426	-0.2706	0.772
52	100	100krad Unbiased	-0.9989	-0.2908	0.7081
53	100	100krad Unbiased	-0.9794	-0.304	0.6754
54	100	100krad Unbiased	-1.0411	-0.3484	0.6927
55	110	100krad Biased	-1.0411	-0.2496	0.7915
56	110	100krad Biased	-1.0473	-0.2285	0.8188
57	110	100krad Biased	-1.0543	-0.3126	0.7417
58	110	100krad Biased	-0.9474	-0.1881	0.7593
59	110	100krad Biased	-1.027	-0.3079	0.7191

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-1.1339	-1.0832	-1.0067	0.067411	-0.4846	-0.44903	-0.4215	0.032308	0.5852	0.63417	0.6929	0.05451
50	-1.0715	1.5073	11.681	5.6871	-0.4721	1.3702	8.6528	4.0712	-3.0278	-0.13718	0.615	1.6161
55	-1.1129	-1.0431	-0.9724	0.05645	-0.4519	-0.42574	-0.3997	0.019296	0.572	0.61736	0.6781	0.051561
100	-1.0512	-1.0226	-0.9794	0.031576	-0.3484	-0.29376	-0.255	0.035839	0.6754	0.72888	0.7962	0.052422
110	-1.0543	-1.0234	-0.9474	0.04367	-0.3126	-0.25734	-0.1881	0.053141	0.7191	0.76608	0.8188	0.039601

Device Test: 65.6 ENABLE|/EN/RISE///6.3/@V_EN_RISING





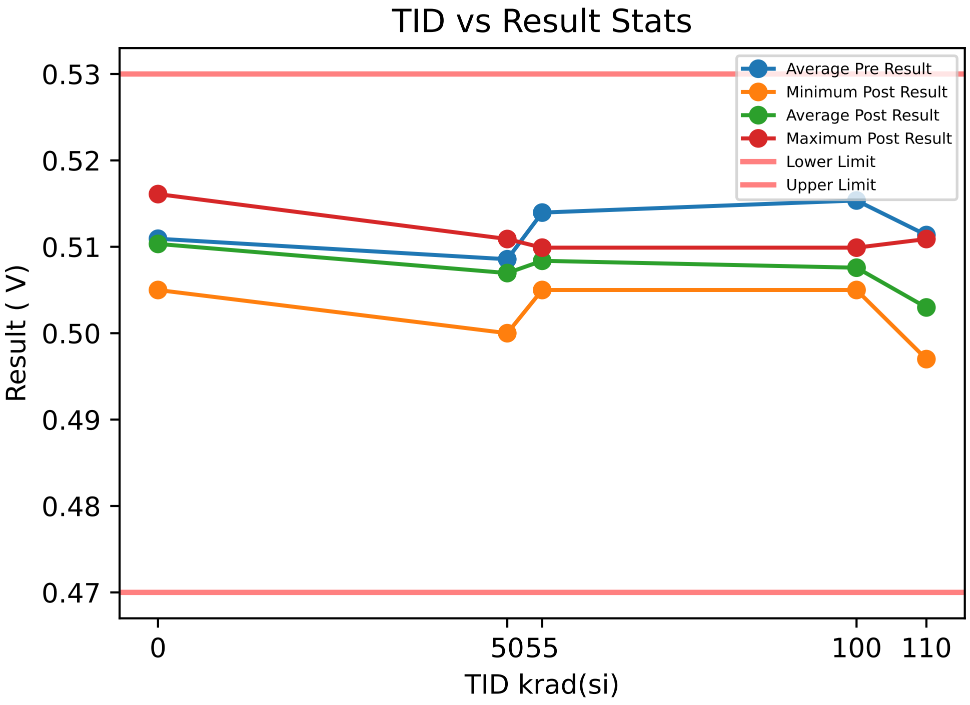
Test Results (Lower Limit = 0.57, Upper Limit = 0.625 (V))

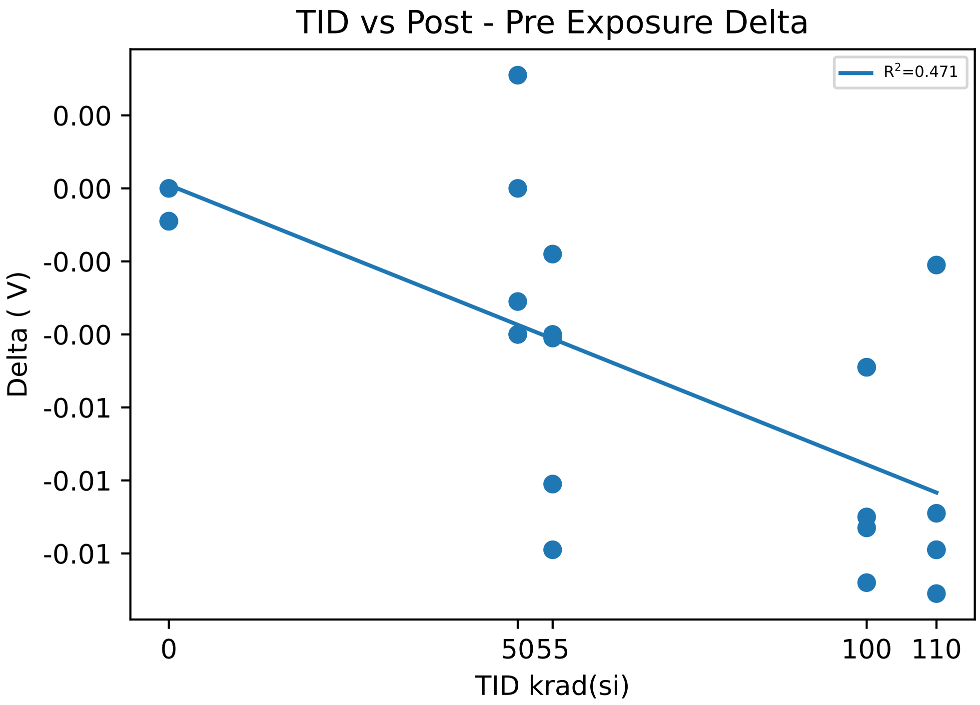
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.6039	0.6039	0
2	0	CU	0.599	0.599	0
3	0	CU	0.6021	0.6021	0
40	50	50krad Unbiased	0.599	0.595	-0.004
41	50	50krad Unbiased	0.6011	0.598	-0.0031
42	50	50krad Unbiased	0.599	0.595	-0.004
43	50	50krad Unbiased	0.603	0.599	-0.004
44	50	50krad Unbiased	0.5959	0.594	-0.0019
45	55	50krad Biased	0.598	0.5919	-0.0061
46	55	50krad Biased	0.6021	0.594	-0.0081
47	55	50krad Biased	0.603	0.5959	-0.0071
48	55	50krad Biased	0.5999	0.594	-0.0059
49	55	50krad Biased	0.603	0.598	-0.005
50	100	100krad Unbiased	0.6021	0.594	-0.0081
51	100	100krad Unbiased	0.6011	0.599	-0.0021
52	100	100krad Unbiased	0.6021	0.599	-0.0031
53	100	100krad Unbiased	0.598	0.59	-0.008
54	100	100krad Unbiased	0.6021	0.5959	-0.0062
55	110	100krad Biased	0.6011	0.5891	-0.012
56	110	100krad Biased	0.6011	0.59	-0.0111
57	110	100krad Biased	0.5959	0.59	-0.0059
58	110	100krad Biased	0.5959	0.5851	-0.0108
59	110	100krad Biased	0.6021	0.594	-0.0081

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.599	0.60167	0.6039	0.0024786	0.599	0.60167	0.6039	0.0024786	0	0	0	0
50	0.5959	0.5996	0.603	0.0026561	0.594	0.5962	0.599	0.0021679	-0.004	-0.0034	-0.0019	0.00092466
55	0.598	0.6012	0.603	0.002192	0.5919	0.59476	0.598	0.0022985	-0.0081	-0.00644	-0.005	0.0011908
100	0.598	0.60108	0.6021	0.0017754	0.59	0.59558	0.599	0.0037792	-0.0081	-0.0055	-0.0021	0.0027758
110	0.5959	0.59922	0.6021	0.0030581	0.5851	0.58964	0.594	0.0031691	-0.012	-0.00958	-0.0059	0.0025193

Device Test: 65.7 ENABLE|/EN/FALL///6.3/@V_EN_FALLING





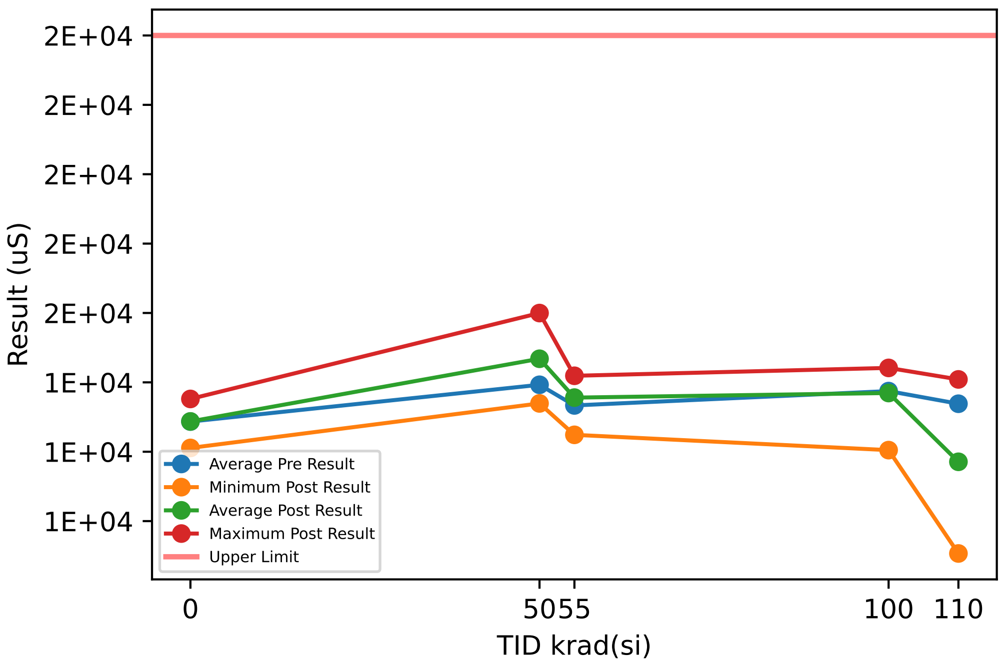
Test Results (Lower Limit = 0.47, Upper Limit = 0.53 (V))

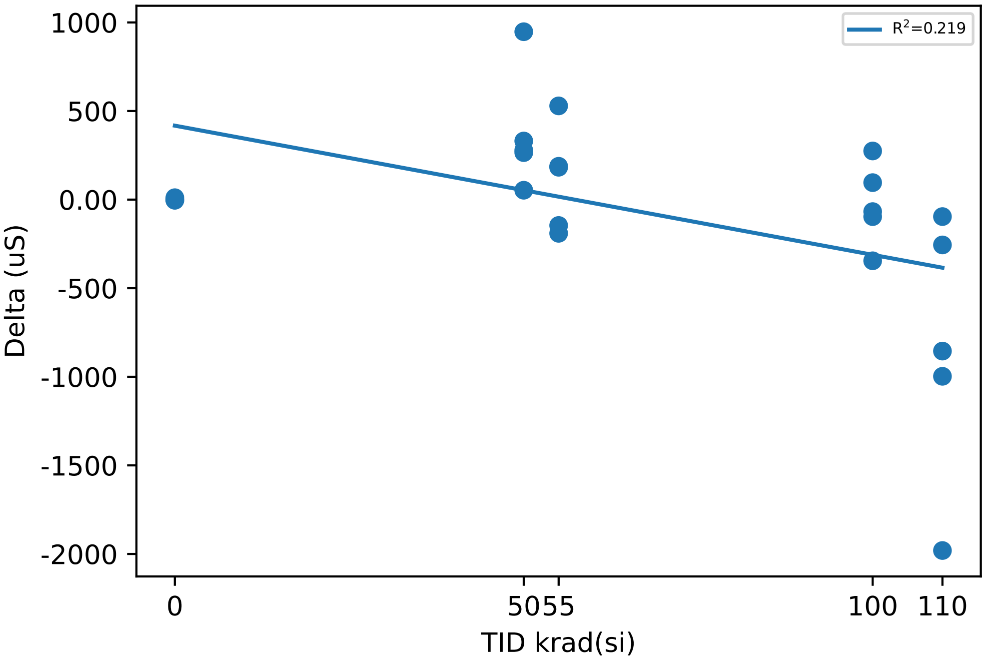
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.517	0.5161	-0.0009
2	0	CU	0.5059	0.505	-0.0009
3	0	CU	0.5099	0.5099	0
40	50	50krad Unbiased	0.5121	0.5081	-0.004
41	50	50krad Unbiased	0.5068	0.5068	0
42	50	50krad Unbiased	0.5031	0.5	-0.0031
43	50	50krad Unbiased	0.5149	0.5109	-0.004
44	50	50krad Unbiased	0.5059	0.509	0.0031
45	55	50krad Biased	0.5189	0.509	-0.0099
46	55	50krad Biased	0.514	0.5099	-0.0041
47	55	50krad Biased	0.509	0.505	-0.004
48	55	50krad Biased	0.5099	0.5081	-0.0018
49	55	50krad Biased	0.518	0.5099	-0.0081
50	100	100krad Unbiased	0.5189	0.5081	-0.0108
51	100	100krad Unbiased	0.5161	0.5068	-0.0093
52	100	100krad Unbiased	0.5099	0.505	-0.0049
53	100	100krad Unbiased	0.513	0.5081	-0.0049
54	100	100krad Unbiased	0.5189	0.5099	-0.009
55	110	100krad Biased	0.5099	0.501	-0.0089
56	110	100krad Biased	0.5081	0.497	-0.0111
57	110	100krad Biased	0.5149	0.505	-0.0099
58	110	100krad Biased	0.5109	0.501	-0.0099
59	110	100krad Biased	0.513	0.5109	-0.0021

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5059	0.51093	0.517	0.0056217	0.505	0.51033	0.5161	0.0055627	-0.0009	-0.0006	0	0.00051962
50	0.5031	0.50856	0.5149	0.0048144	0.5	0.50696	0.5109	0.0041669	-0.004	-0.0016	0.0031	0.0030992
55	0.509	0.51396	0.5189	0.0045225	0.505	0.50838	0.5099	0.0020315	-0.0099	-0.00558	-0.0018	0.0033162
100	0.5099	0.51536	0.5189	0.0039049	0.505	0.50758	0.5099	0.0018158	-0.0108	-0.00778	-0.0049	0.0027161
110	0.5081	0.51136	0.5149	0.0026548	0.497	0.50298	0.5109	0.0052538	-0.0111	-0.00838	-0.0021	0.0035961

Device Test: 65.8 ENABLE|/EN/DELAY///6.3/@T_EN_DELAY


TID vs Result Stats


TID vs Post - Pre Exposure Delta

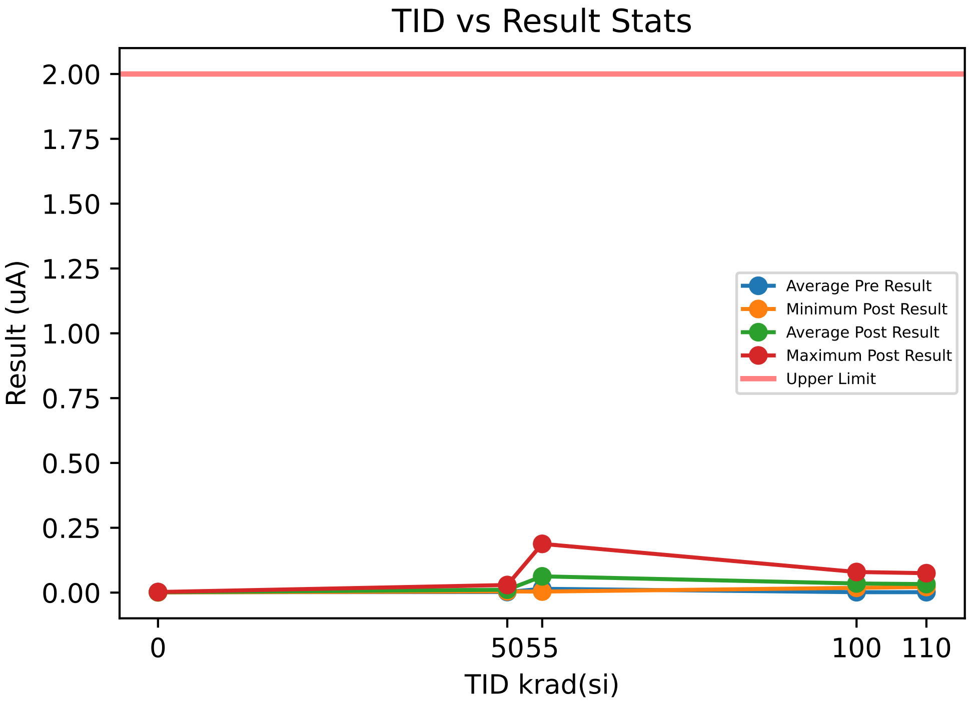
Test Results (Upper Limit = 19000.0 (uS))

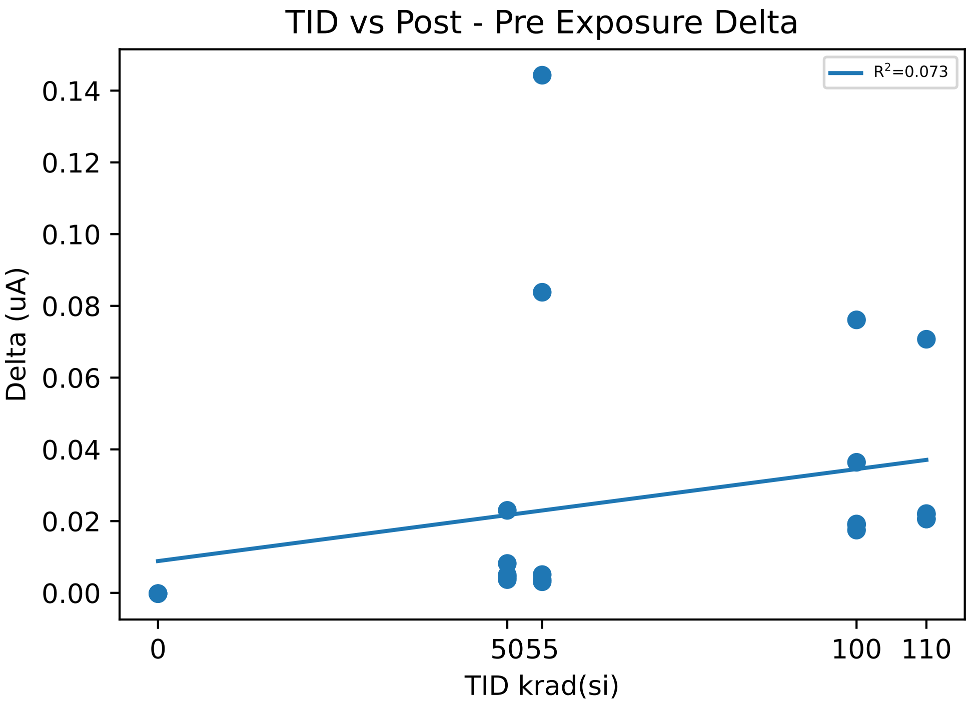
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	1.3e+04	1.31e+04	10.76
2	0	CU	1.35e+04	1.35e+04	-3.7197
3	0	CU	1.38e+04	1.38e+04	-2.7151
40	50	50krad Unbiased	1.41e+04	1.5e+04	947.59
41	50	50krad Unbiased	1.44e+04	1.46e+04	265.28
42	50	50krad Unbiased	1.37e+04	1.4e+04	330.72
43	50	50krad Unbiased	1.36e+04	1.37e+04	52.922
44	50	50krad Unbiased	1.41e+04	1.44e+04	278.82
45	55	50krad Biased	1.38e+04	1.4e+04	188.11
46	55	50krad Biased	1.38e+04	1.4e+04	182.65
47	55	50krad Biased	1.34e+04	1.32e+04	-190.24
48	55	50krad Biased	1.36e+04	1.41e+04	528.97
49	55	50krad Biased	1.37e+04	1.35e+04	-145.97
50	100	100krad Unbiased	1.39e+04	1.38e+04	-96.012
51	100	100krad Unbiased	1.42e+04	1.42e+04	-67.684
52	100	100krad Unbiased	1.34e+04	1.3e+04	-345.27
53	100	100krad Unbiased	1.41e+04	1.42e+04	95.832
54	100	100krad Unbiased	1.37e+04	1.4e+04	274.53
55	110	100krad Biased	1.35e+04	1.15e+04	-1980.6
56	110	100krad Biased	1.39e+04	1.29e+04	-997.26
57	110	100krad Biased	1.41e+04	1.4e+04	-95.779
58	110	100krad Biased	1.37e+04	1.28e+04	-854.93
59	110	100krad Biased	1.32e+04	1.29e+04	-255.83

Test Statistics (uS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.3e+04	1.34e+04	1.38e+04	363.91	1.31e+04	1.34e+04	1.38e+04	356.59	-3.7197	1.4417	10.76	8.0854
50	1.36e+04	1.4e+04	1.44e+04	314.41	1.37e+04	1.43e+04	1.5e+04	516.65	52.922	375.07	947.59	337.21
55	1.34e+04	1.37e+04	1.38e+04	172.13	1.32e+04	1.38e+04	1.41e+04	374.36	-190.24	112.7	528.97	292.64
100	1.34e+04	1.39e+04	1.42e+04	338.9	1.3e+04	1.38e+04	1.42e+04	483.31	-345.27	-27.721	274.53	231.15
110	1.32e+04	1.37e+04	1.41e+04	367	1.15e+04	1.29e+04	1.4e+04	890.24	-1980.6	-836.87	-95.779	745.13

Device Test: 70.1 LEAK|/PG/CURRENT/0N6V//3/@PWRGD_OUTPUT_HIGH_LEAK





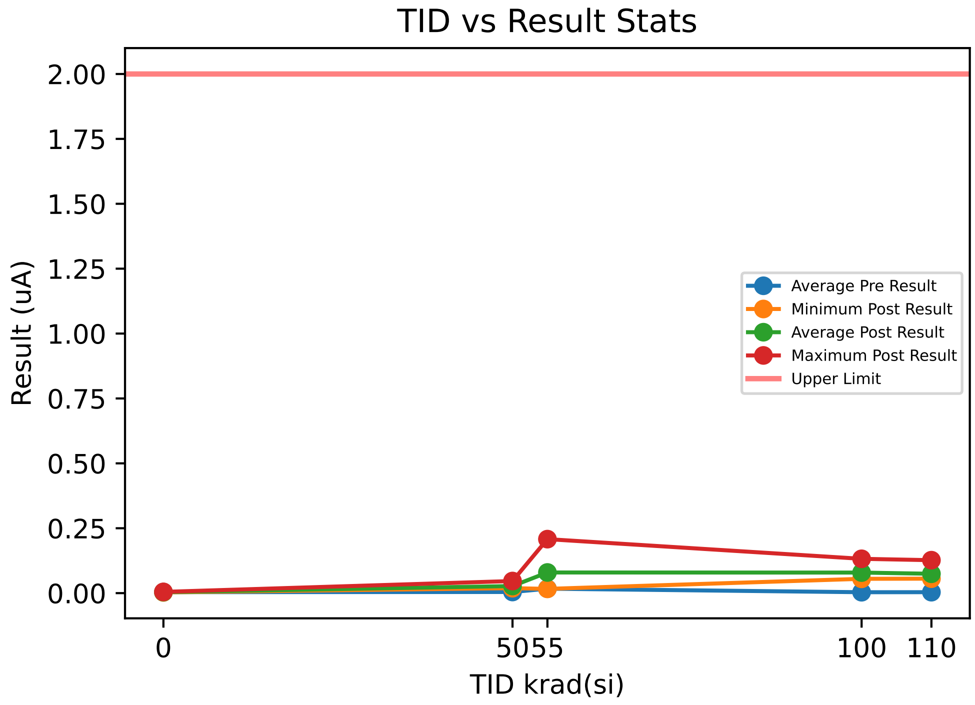
Test Results (Upper Limit = 2.0 (uA))

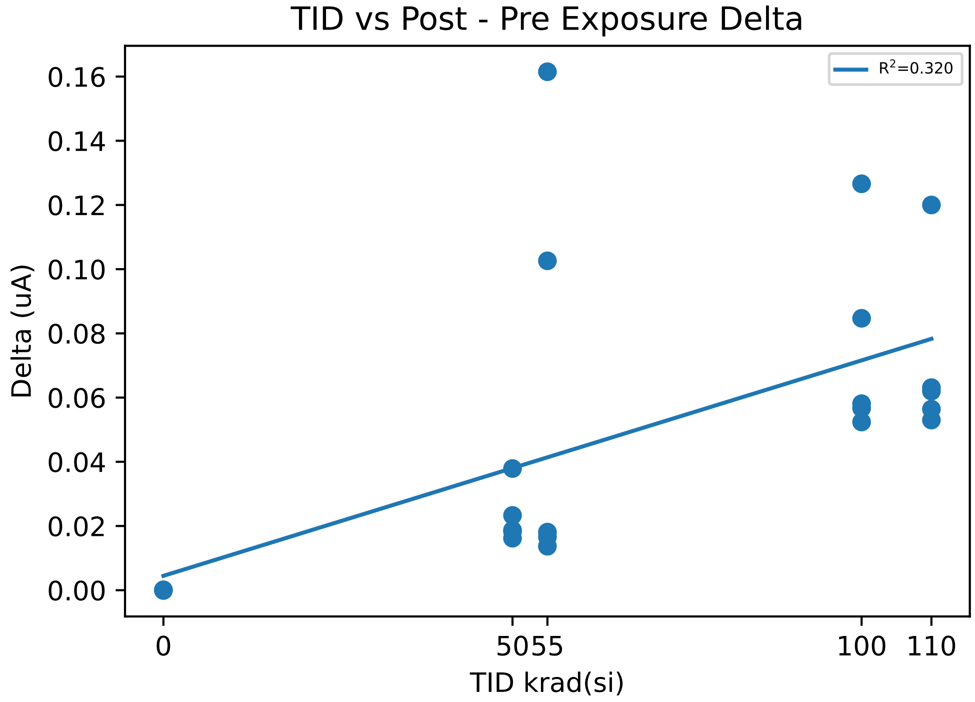
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.001	0.0008	-0.0002
2	0	CU	0.0025	0.0023	-0.0002
3	0	CU	0.0016	0.0014	-0.0002
40	50	50krad Unbiased	0.0018	0.01	0.0082
41	50	50krad Unbiased	0.0012	0.0062	0.005
42	50	50krad Unbiased	0.0011	0.0055	0.0044
43	50	50krad Unbiased	0.001	0.0047	0.0037
44	50	50krad Unbiased	0.0063	0.0293	0.023
45	55	50krad Biased	0.0437	0.188	0.1443
46	55	50krad Biased	0.001	0.0047	0.0037
47	55	50krad Biased	0.0013	0.0064	0.0051
48	55	50krad Biased	0.0266	0.1104	0.0838
49	55	50krad Biased	0.0009	0.004	0.0031
50	100	100krad Unbiased	0.0034	0.0795	0.0761
51	100	100krad Unbiased	0.0014	0.0378	0.0364
52	100	100krad Unbiased	0.0009	0.0199	0.019
53	100	100krad Unbiased	0.0009	0.0184	0.0175
54	100	100krad Unbiased	0.001	0.0202	0.0192
55	110	100krad Biased	0.0009	0.023	0.0221
56	110	100krad Biased	0.001	0.0216	0.0206
57	110	100krad Biased	0.0042	0.0749	0.0707
58	110	100krad Biased	0.001	0.0216	0.0206
59	110	100krad Biased	0.0011	0.023	0.0219

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.001	0.0017	0.0025	0.00075498	0.0008	0.0015	0.0023	0.00075498	-0.0002	-0.0002	-0.0002	6.0609e-20
50	0.001	0.00228	0.0063	0.0022687	0.0047	0.01114	0.0293	0.010353	0.0037	0.00886	0.023	0.00809
55	0.0009	0.0147	0.0437	0.019623	0.004	0.0627	0.188	0.083598	0.0031	0.048	0.1443	0.063981
100	0.0009	0.00152	0.0034	0.001071	0.0184	0.03516	0.0795	0.026032	0.0175	0.03364	0.0761	0.024969
110	0.0009	0.00164	0.0042	0.0014328	0.0216	0.03282	0.0749	0.023534	0.0206	0.03118	0.0707	0.022104

Device Test: 70.2 LEAK|/PG/CURRENT/6N0V//6.3/@PWRGD_OUTPUT_HIGH_LEAK





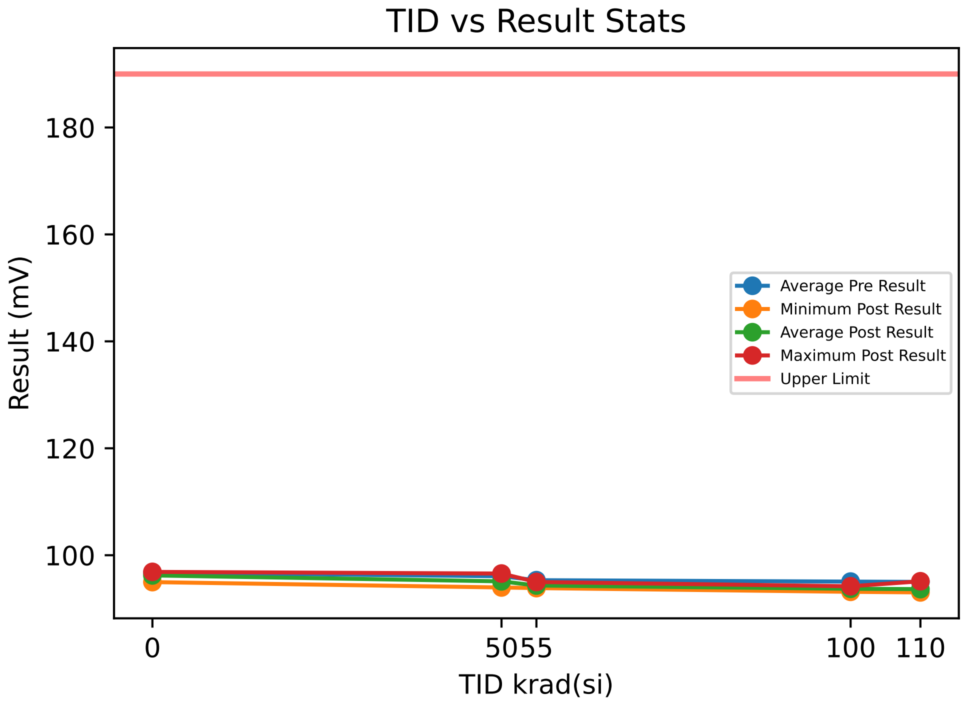
Test Results (Upper Limit = 2.0 (uA))

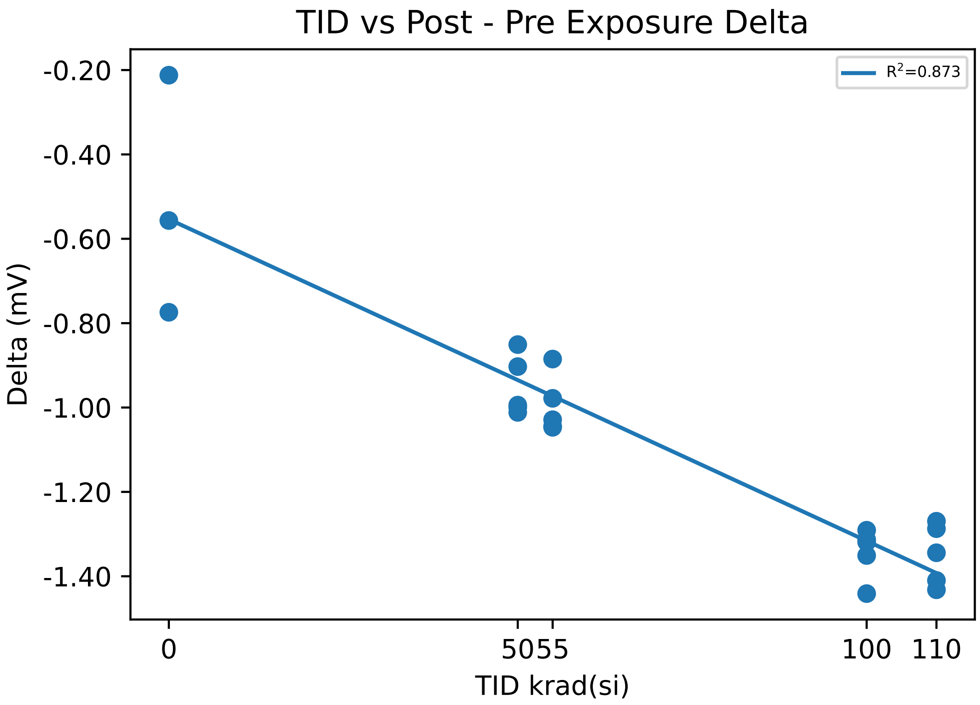
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.0027	0.0028	0.0001
2	0	CU	0.0047	0.0048	0.0001
3	0	CU	0.0039	0.0038	-0.0001
40	50	50krad Unbiased	0.0039	0.0272	0.0233
41	50	50krad Unbiased	0.0031	0.0218	0.0187
42	50	50krad Unbiased	0.0032	0.0215	0.0183
43	50	50krad Unbiased	0.0029	0.0191	0.0162
44	50	50krad Unbiased	0.0087	0.0466	0.0379
45	55	50krad Biased	0.0465	0.208	0.1615
46	55	50krad Biased	0.003	0.0196	0.0166
47	55	50krad Biased	0.0033	0.0214	0.0181
48	55	50krad Biased	0.0298	0.1324	0.1026
49	55	50krad Biased	0.0027	0.0164	0.0137
50	100	100krad Unbiased	0.0056	0.1322	0.1266
51	100	100krad Unbiased	0.0033	0.088	0.0847
52	100	100krad Unbiased	0.0029	0.0596	0.0567
53	100	100krad Unbiased	0.0027	0.0551	0.0524
54	100	100krad Unbiased	0.0029	0.061	0.0581
55	110	100krad Biased	0.0029	0.066	0.0631
56	110	100krad Biased	0.0027	0.0591	0.0564
57	110	100krad Biased	0.0069	0.1269	0.12
58	110	100krad Biased	0.0027	0.0557	0.053
59	110	100krad Biased	0.0031	0.0651	0.062

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0027	0.0037667	0.0047	0.0010066	0.0028	0.0038	0.0048	0.001	-0.0001	3.3333e-05	0.0001	0.00011547
50	0.0029	0.00436	0.0087	0.0024552	0.0191	0.02724	0.0466	0.011221	0.0162	0.02288	0.0379	0.008787
55	0.0027	0.01706	0.0465	0.020139	0.0164	0.07956	0.208	0.086971	0.0137	0.0625	0.1615	0.066837
100	0.0027	0.00348	0.0056	0.001205	0.0551	0.07918	0.1322	0.032337	0.0524	0.0757	0.1266	0.031167
110	0.0027	0.00366	0.0069	0.0018188	0.0557	0.07456	0.1269	0.029568	0.053	0.0709	0.12	0.027756

Device Test: 70.3 POWER_GOOD|//OUTPUT_LOW/0N6V//3/@V_PG_OL





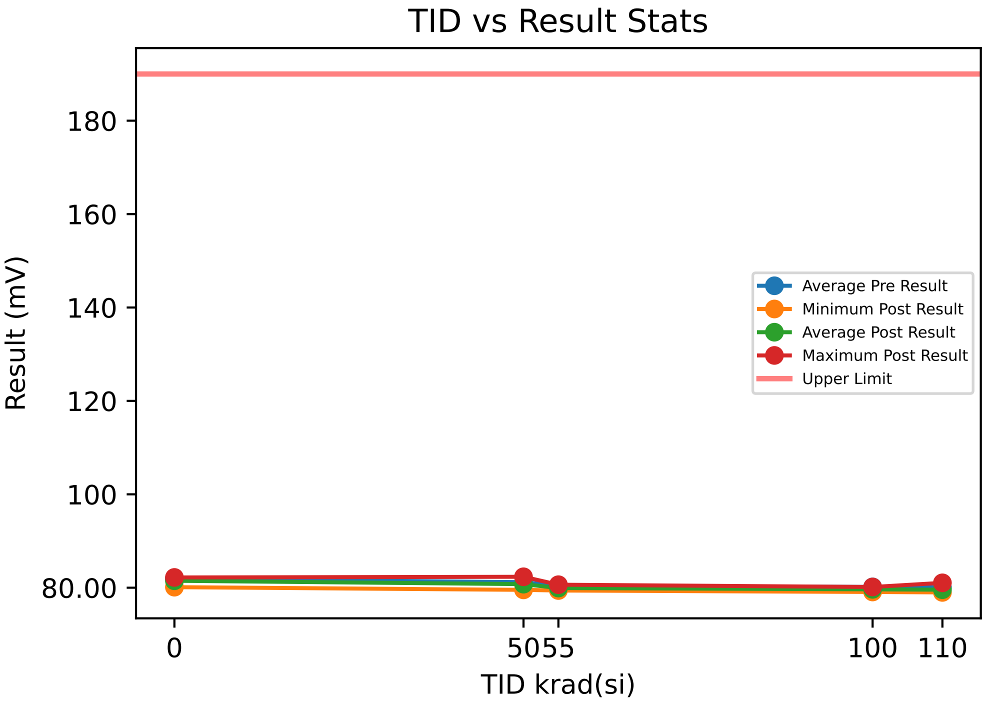
Test Results (Upper Limit = 190.0 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	95.531	94.975	-0.5567
2	0	CU	97.095	96.883	-0.2122
3	0	CU	97.582	96.808	-0.7742
40	50	50krad Unbiased	96.324	95.325	-0.9998
41	50	50krad Unbiased	96.456	95.552	-0.903
42	50	50krad Unbiased	94.82	93.969	-0.8508
43	50	50krad Unbiased	95.141	94.147	-0.9943
44	50	50krad Unbiased	97.586	96.574	-1.0115
45	55	50krad Biased	95.99	94.943	-1.0469
46	55	50krad Biased	94.913	93.885	-1.0289
47	55	50krad Biased	94.882	93.997	-0.8851
48	55	50krad Biased	95.975	94.996	-0.9782
49	55	50krad Biased	94.898	93.853	-1.0444
50	100	100krad Unbiased	95.513	94.194	-1.3189
51	100	100krad Unbiased	95.069	93.757	-1.3129
52	100	100krad Unbiased	94.507	93.157	-1.3508
53	100	100krad Unbiased	94.882	93.441	-1.4411
54	100	100krad Unbiased	95.369	94.078	-1.2909
55	110	100krad Biased	94.582	93.313	-1.2696
56	110	100krad Biased	94.479	93.047	-1.432
57	110	100krad Biased	96.415	95.128	-1.2872
58	110	100krad Biased	94.651	93.241	-1.41
59	110	100krad Biased	94.923	93.578	-1.3443

Test Statistics (mV)

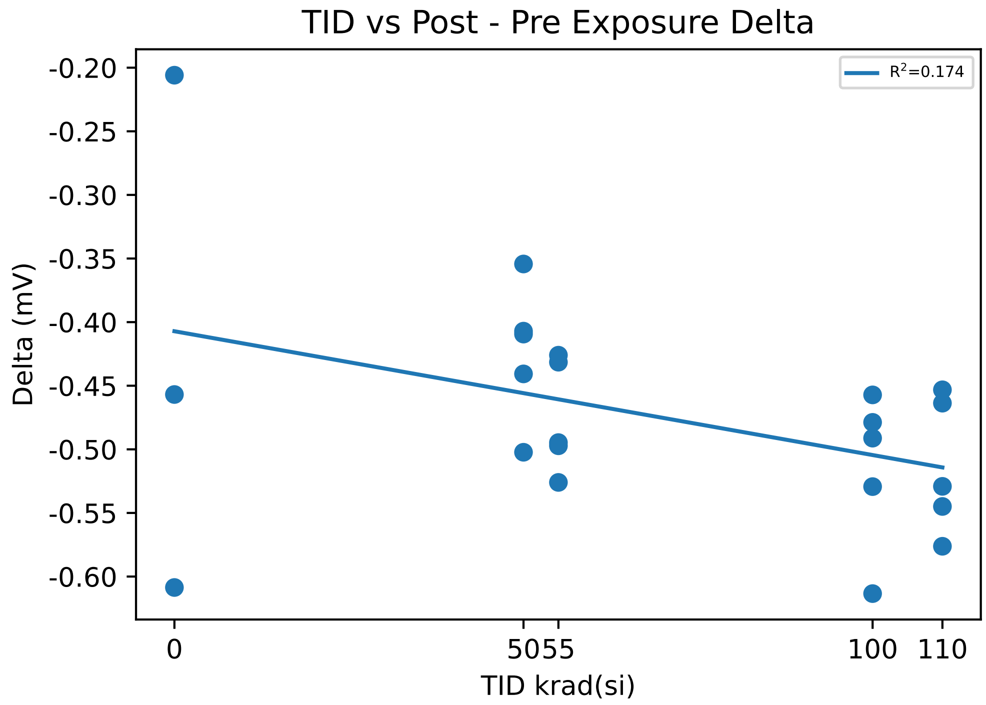
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	95.531	96.736	97.582	1.0716	94.975	96.222	96.883	1.0809	-0.7742	-0.51437	-0.2122	0.28338
50	94.82	96.065	97.586	1.1108	93.969	95.113	96.574	1.0741	-1.0115	-0.95188	-0.8508	0.071163
55	94.882	95.332	95.99	0.59428	93.853	94.335	94.996	0.58244	-1.0469	-0.9967	-0.8851	0.068244
100	94.507	95.068	95.513	0.39911	93.157	93.725	94.194	0.43276	-1.4411	-1.3429	-1.2909	0.058919
110	94.479	95.01	96.415	0.80226	93.047	93.662	95.128	0.84143	-1.432	-1.3486	-1.2696	0.072033

Device Test: 70.4 POWER_GOOD|//OUTPUT_LOW/6N0V//6.3/@V_PG_OL



Test Results (Upper Limit = 190.0 (mV))

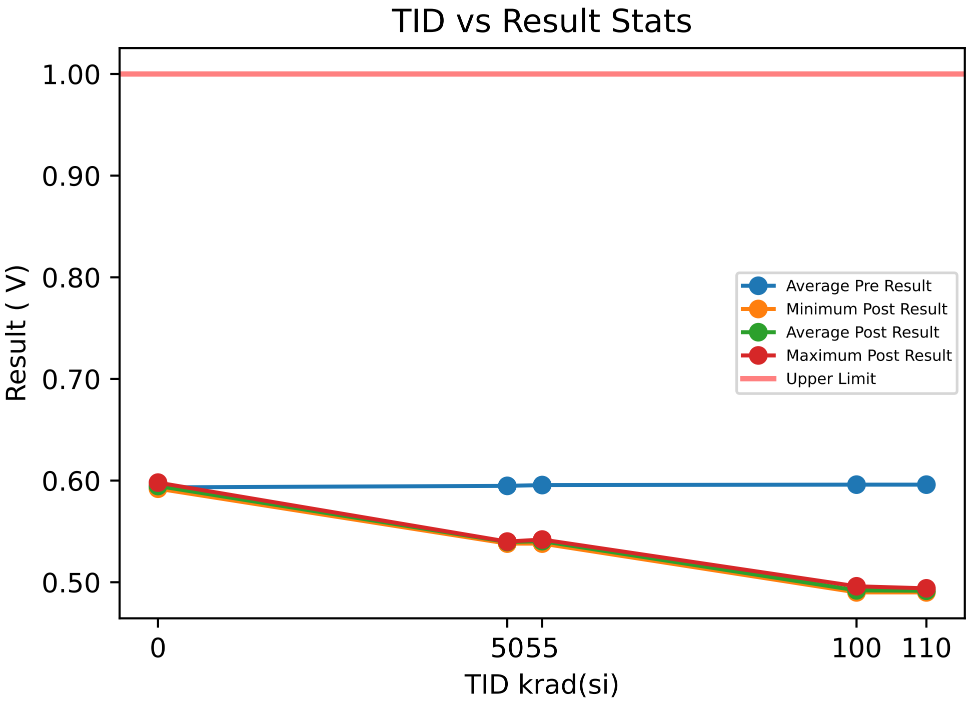
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	80.576	80.119	-0.4569
2	0	CU	82.346	82.14	-0.2059
3	0	CU	82.808	82.199	-0.6086
40	50	50krad Unbiased	81.412	80.972	-0.4407
41	50	50krad Unbiased	81.628	81.218	-0.4094
42	50	50krad Unbiased	79.895	79.541	-0.3543
43	50	50krad Unbiased	80.163	79.756	-0.4071
44	50	50krad Unbiased	82.842	82.34	-0.5023
45	55	50krad Biased	81.025	80.528	-0.4972
46	55	50krad Biased	80.014	79.519	-0.4947
47	55	50krad Biased	79.992	79.566	-0.426
48	55	50krad Biased	81.075	80.644	-0.4315
49	55	50krad Biased	79.926	79.4	-0.526
50	100	100krad Unbiased	80.647	80.156	-0.4912
51	100	100krad Unbiased	80.111	79.653	-0.4572
52	100	100krad Unbiased	79.617	79.088	-0.5293
53	100	100krad Unbiased	79.973	79.36	-0.6134
54	100	100krad Unbiased	80.494	80.016	-0.4788
55	110	100krad Biased	79.692	79.228	-0.4637
56	110	100krad Biased	79.574	78.997	-0.5762
57	110	100krad Biased	81.496	81.043	-0.4532
58	110	100krad Biased	79.723	79.178	-0.5449
59	110	100krad Biased	79.948	79.419	-0.5291

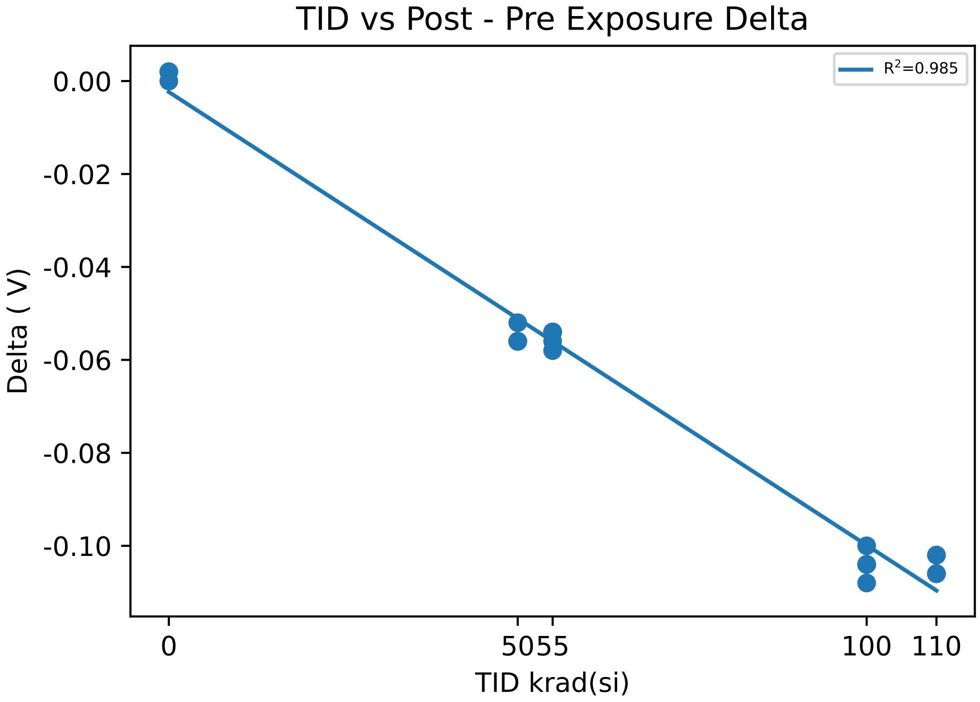


Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	80.576	81.91	82.808	1.1781	80.119	81.486	82.199	1.1843	-0.6086	-0.4238	-0.2059	0.20338
50	79.895	81.188	82.842	1.1937	79.541	80.765	82.34	1.1449	-0.5023	-0.42276	-0.3543	0.054219
55	79.926	80.406	81.075	0.58873	79.4	79.931	80.644	0.60181	-0.526	-0.47508	-0.426	0.044088
100	79.617	80.169	80.647	0.41262	79.088	79.655	80.156	0.44442	-0.6134	-0.51398	-0.4572	0.06144
110	79.574	80.087	81.496	0.79965	78.997	79.573	81.043	0.83535	-0.5762	-0.51342	-0.4532	0.053096

Device Test: 71.1 POWER_GOOD|//MIN_VIN_PG/0N6V///@MIN_VIN_FOR_PWRGD_OUTPUT





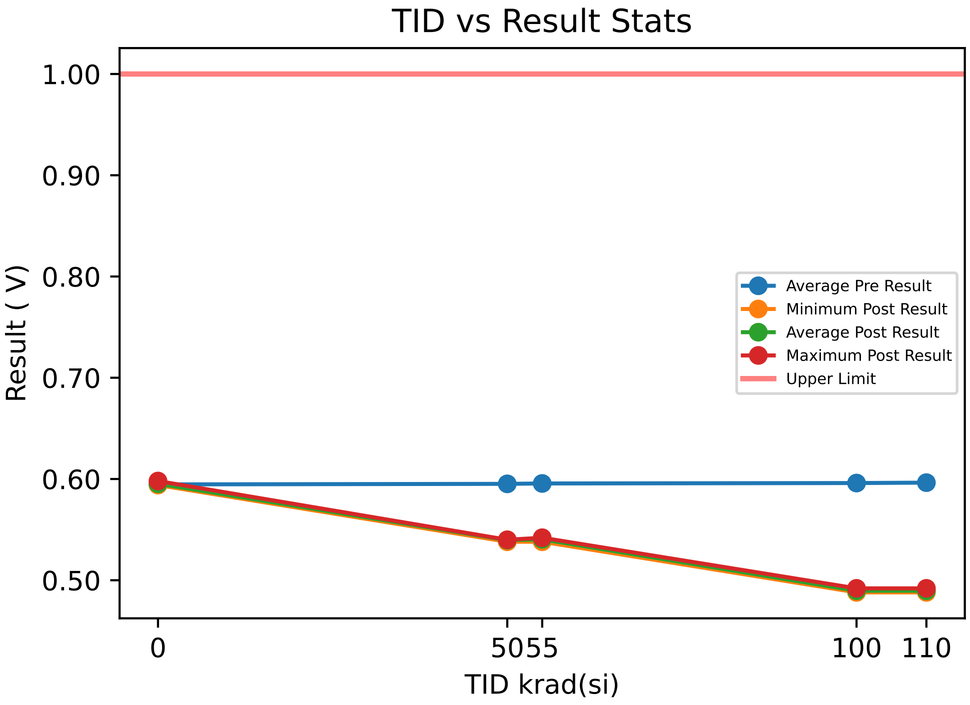
Test Results (Upper Limit = 1.0 (V))

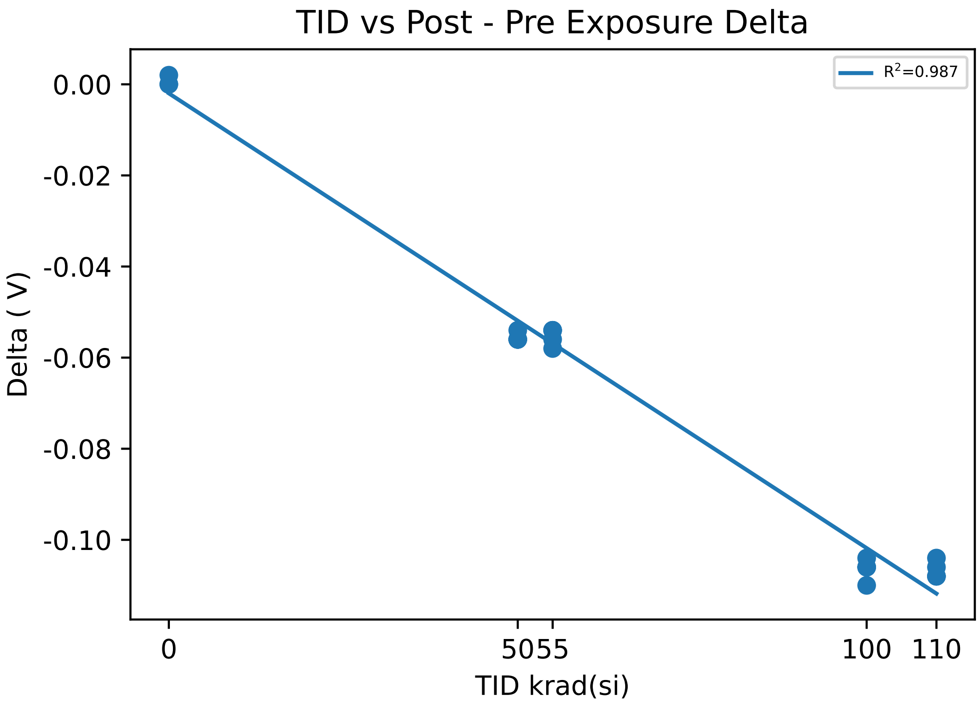
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.596	0.598	0.002
2	0	CU	0.592	0.592	0
3	0	CU	0.592	0.594	0.002
40	50	50krad Unbiased	0.596	0.54	-0.056
41	50	50krad Unbiased	0.594	0.538	-0.056
42	50	50krad Unbiased	0.596	0.54	-0.056
43	50	50krad Unbiased	0.596	0.54	-0.056
44	50	50krad Unbiased	0.592	0.54	-0.052
45	55	50krad Biased	0.596	0.542	-0.054
46	55	50krad Biased	0.596	0.538	-0.058
47	55	50krad Biased	0.596	0.54	-0.056
48	55	50krad Biased	0.594	0.54	-0.054
49	55	50krad Biased	0.596	0.542	-0.054
50	100	100krad Unbiased	0.596	0.492	-0.104
51	100	100krad Unbiased	0.598	0.49	-0.108
52	100	100krad Unbiased	0.594	0.49	-0.104
53	100	100krad Unbiased	0.596	0.492	-0.104
54	100	100krad Unbiased	0.596	0.496	-0.1
55	110	100krad Biased	0.596	0.49	-0.106
56	110	100krad Biased	0.596	0.49	-0.106
57	110	100krad Biased	0.596	0.494	-0.102
58	110	100krad Biased	0.596	0.49	-0.106
59	110	100krad Biased	0.596	0.494	-0.102

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.592	0.59333	0.596	0.0023094	0.592	0.59467	0.598	0.0030551	0	0.0013333	0.002	0.0011547
50	0.592	0.5948	0.596	0.0017889	0.538	0.5396	0.54	0.00089443	-0.056	-0.0552	-0.052	0.0017889
55	0.594	0.5956	0.596	0.00089443	0.538	0.5404	0.542	0.0016733	-0.058	-0.0552	-0.054	0.0017889
100	0.594	0.596	0.598	0.0014142	0.49	0.492	0.496	0.0024495	-0.108	-0.104	-0.1	0.0028284
110	0.596	0.596	0.596	0	0.49	0.4916	0.494	0.0021909	-0.106	-0.1044	-0.102	0.0021909

Device Test: 71.2 POWER_GOOD|//MIN_VIN_PG/6N0V///@MIN_VIN_FOR_PWRGD_OUTPUT





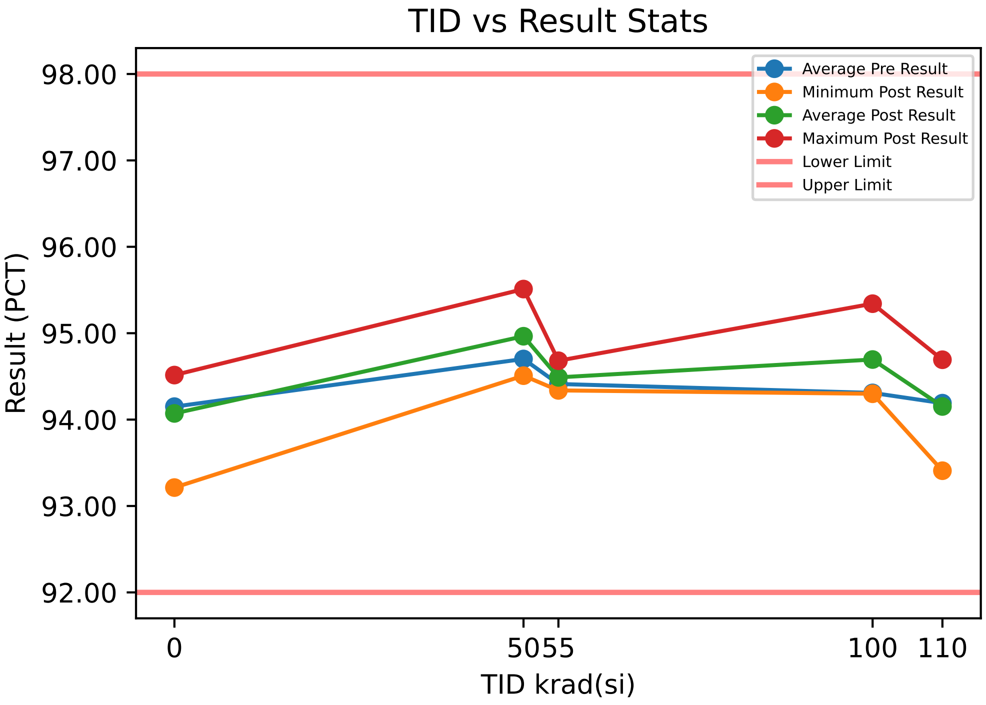
Test Results (Upper Limit = 1.0 (V))

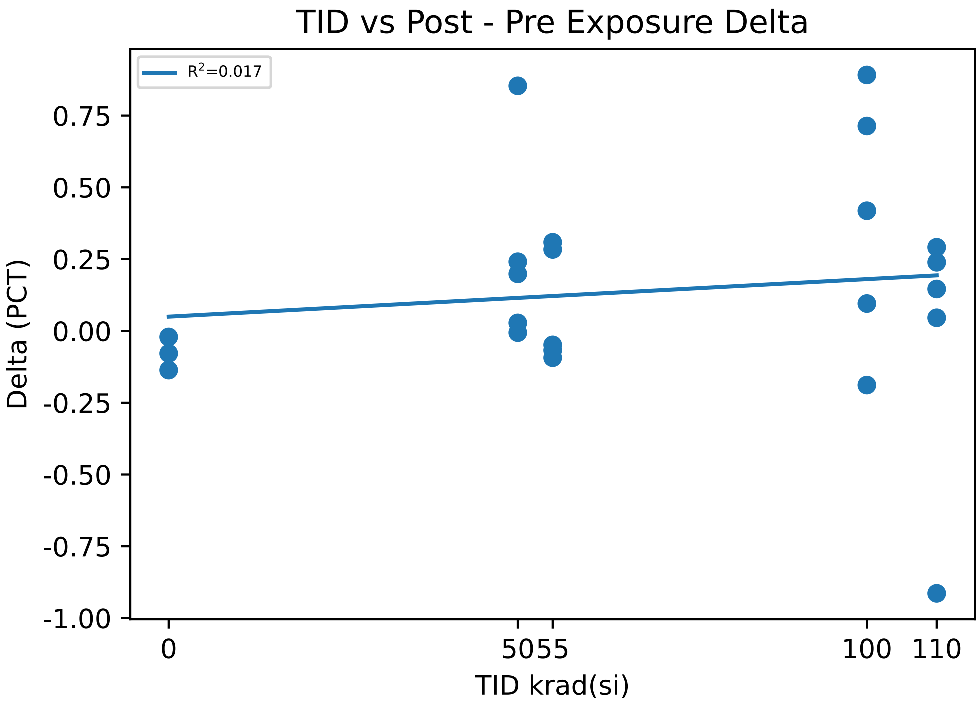
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	0.598	0.598	0
2	0	CU	0.594	0.594	0
3	0	CU	0.592	0.594	0.002
40	50	50krad Unbiased	0.596	0.54	-0.056
41	50	50krad Unbiased	0.594	0.538	-0.056
42	50	50krad Unbiased	0.596	0.54	-0.056
43	50	50krad Unbiased	0.596	0.54	-0.056
44	50	50krad Unbiased	0.594	0.54	-0.054
45	55	50krad Biased	0.596	0.542	-0.054
46	55	50krad Biased	0.596	0.538	-0.058
47	55	50krad Biased	0.596	0.54	-0.056
48	55	50krad Biased	0.594	0.54	-0.054
49	55	50krad Biased	0.596	0.542	-0.054
50	100	100krad Unbiased	0.596	0.49	-0.106
51	100	100krad Unbiased	0.598	0.488	-0.11
52	100	100krad Unbiased	0.594	0.488	-0.106
53	100	100krad Unbiased	0.596	0.49	-0.106
54	100	100krad Unbiased	0.596	0.492	-0.104
55	110	100krad Biased	0.596	0.488	-0.108
56	110	100krad Biased	0.596	0.488	-0.108
57	110	100krad Biased	0.596	0.492	-0.104
58	110	100krad Biased	0.596	0.488	-0.108
59	110	100krad Biased	0.598	0.492	-0.106

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.592	0.59467	0.598	0.0030551	0.594	0.59533	0.598	0.0023094	0	0.00066667	0.002	0.0011547
50	0.594	0.5952	0.596	0.0010954	0.538	0.5396	0.54	0.00089443	-0.056	-0.0556	-0.054	0.00089443
55	0.594	0.5956	0.596	0.00089443	0.538	0.5404	0.542	0.0016733	-0.058	-0.0552	-0.054	0.0017889
100	0.594	0.596	0.598	0.0014142	0.488	0.4896	0.492	0.0016733	-0.11	-0.1064	-0.104	0.0021909
110	0.596	0.5964	0.598	0.00089443	0.488	0.4896	0.492	0.0021909	-0.108	-0.1068	-0.104	0.0017889

Device Test: 71.3 POWER_GOOD|//RISE_THRESHOLD/0N6V///@V_PG_RISE


TID vs Result Stats


TID vs Post - Pre Exposure Delta

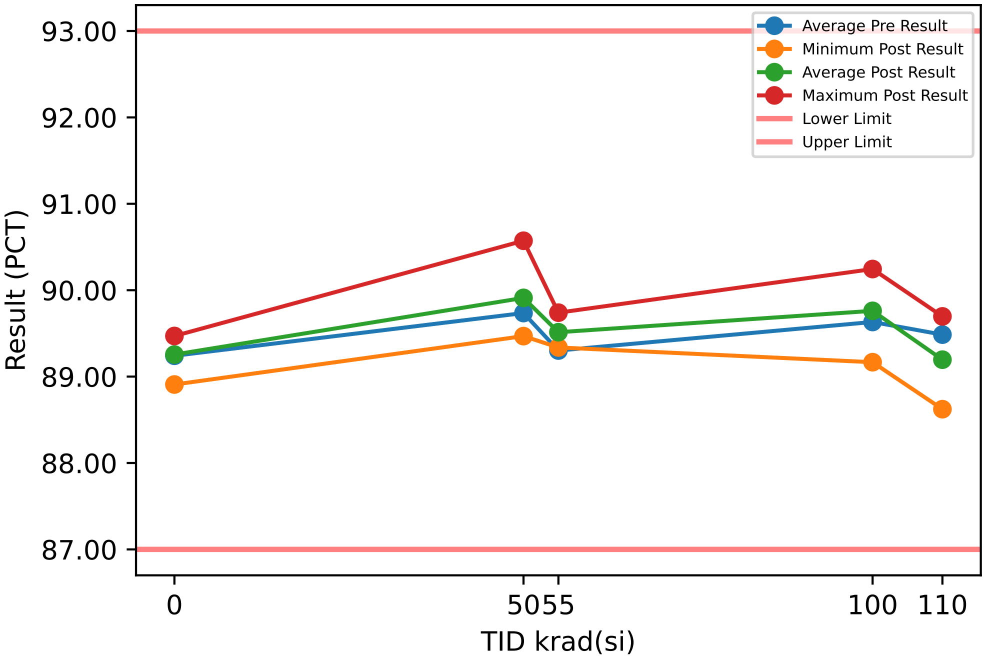
Test Results (Lower Limit = 92.0, Upper Limit = 98.0 (PCT))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	93.35	93.213	-0.1364
2	0	CU	94.594	94.515	-0.0783
3	0	CU	94.507	94.486	-0.0209
40	50	50krad Unbiased	94.657	95.511	0.8536
41	50	50krad Unbiased	95.465	95.493	0.028
42	50	50krad Unbiased	94.462	94.661	0.1988
43	50	50krad Unbiased	94.41	94.651	0.241
44	50	50krad Unbiased	94.514	94.509	-0.0059
45	55	50krad Biased	94.405	94.338	-0.0674
46	55	50krad Biased	94.373	94.681	0.3087
47	55	50krad Biased	94.576	94.528	-0.0485
48	55	50krad Biased	94.207	94.491	0.2838
49	55	50krad Biased	94.5	94.406	-0.0932
50	100	100krad Unbiased	94.565	94.66	0.0954
51	100	100krad Unbiased	94.359	94.778	0.4186
52	100	100krad Unbiased	93.506	94.397	0.8915
53	100	100krad Unbiased	94.628	95.342	0.7137
54	100	100krad Unbiased	94.488	94.299	-0.1885
55	110	100krad Biased	94.322	93.408	-0.9139
56	110	100krad Biased	94.313	94.605	0.2914
57	110	100krad Biased	94.647	94.693	0.0458
58	110	100krad Biased	94.341	94.487	0.1461
59	110	100krad Biased	93.327	93.567	0.2391

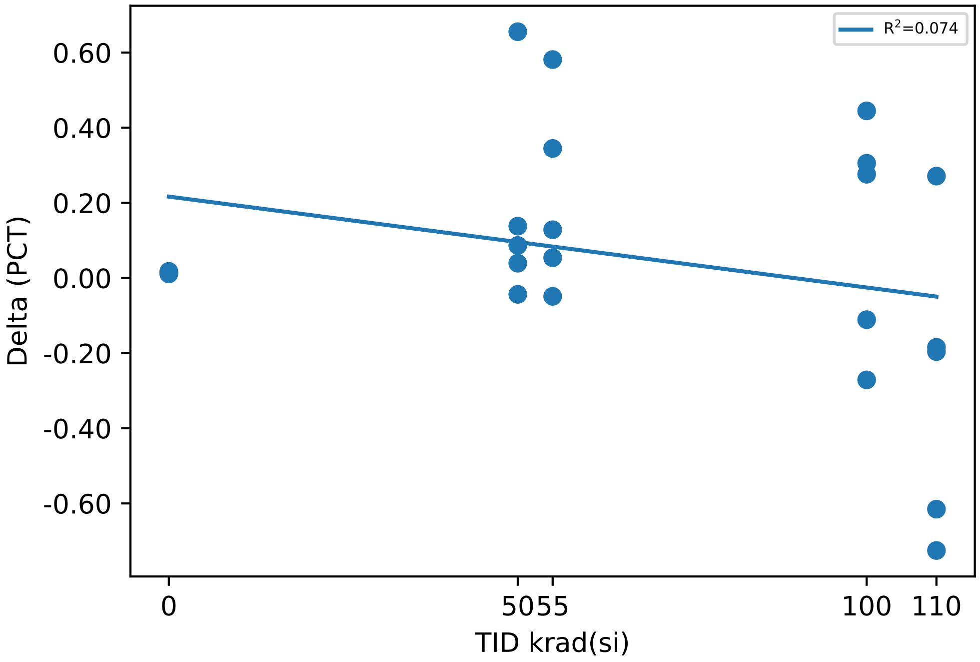
Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	93.35	94.15	94.594	0.69447	93.213	94.072	94.515	0.74337	-0.1364	-0.078533	-0.0209	0.05775
50	94.41	94.702	95.465	0.43647	94.509	94.965	95.511	0.49399	-0.0059	0.2631	0.8536	0.34675
55	94.207	94.412	94.576	0.13991	94.338	94.489	94.681	0.13048	-0.0932	0.07668	0.3087	0.20126
100	93.506	94.309	94.628	0.46012	94.299	94.695	95.342	0.40976	-0.1885	0.38614	0.8915	0.44116
110	93.327	94.19	94.647	0.50212	93.408	94.152	94.693	0.61352	-0.9139	-0.0383	0.2914	0.49835

Device Test: 71.4 POWER_GOOD|//FALL_THRESHOLD/0N6V///@V_PG_FALL



TID vs Result Stats



TID vs Post - Pre Exposure Delta

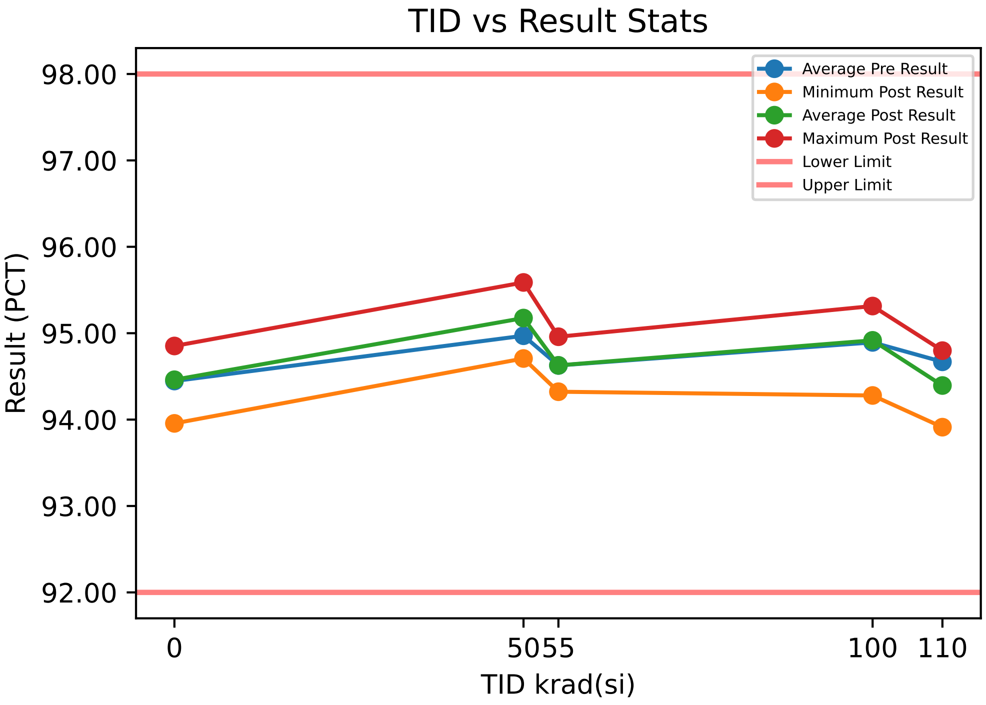
Test Results (Lower Limit = 87.0, Upper Limit = 93.0 (PCT))

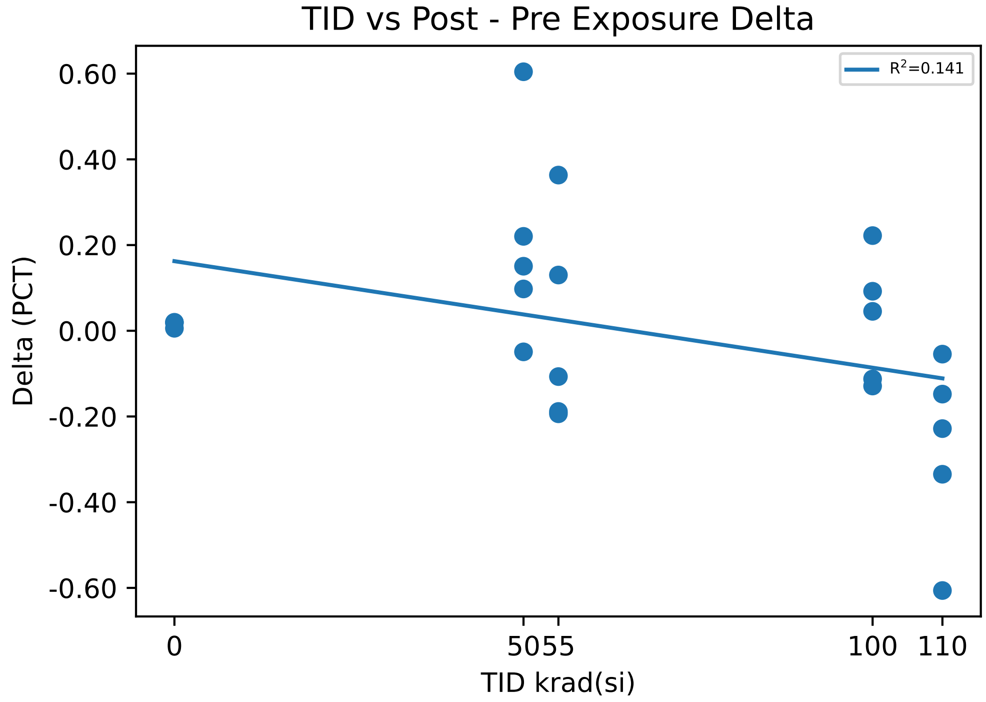
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	88.891	88.908	0.0176
2	0	CU	89.459	89.47	0.0108
3	0	CU	89.374	89.387	0.0137
40	50	50krad Unbiased	89.917	90.572	0.6555
41	50	50krad Unbiased	89.97	90.108	0.138
42	50	50krad Unbiased	89.429	89.469	0.0393
43	50	50krad Unbiased	89.43	89.517	0.0866
44	50	50krad Unbiased	89.932	89.888	-0.0436
45	55	50krad Biased	89.426	89.48	0.0539
46	55	50krad Biased	89.395	89.74	0.3448
47	55	50krad Biased	89.386	89.337	-0.0489
48	55	50krad Biased	88.836	89.417	0.5814
49	55	50krad Biased	89.465	89.594	0.1284
50	100	100krad Unbiased	89.876	89.765	-0.111
51	100	100krad Unbiased	89.993	89.721	-0.2712
52	100	100krad Unbiased	88.89	89.167	0.2762
53	100	100krad Unbiased	89.939	90.245	0.3054
54	100	100krad Unbiased	89.462	89.906	0.4448
55	110	100krad Biased	89.348	88.623	-0.7254
56	110	100krad Biased	89.893	89.697	-0.1959
57	110	100krad Biased	89.905	89.29	-0.6153
58	110	100krad Biased	89.414	89.685	0.2712
59	110	100krad Biased	88.869	88.684	-0.1846

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	88.891	89.241	89.459	0.30644	88.908	89.255	89.47	0.30318	0.0108	0.014033	0.0176	0.0034122
50	89.429	89.736	89.97	0.27984	89.469	89.911	90.572	0.45485	-0.0436	0.17516	0.6555	0.27671
55	88.836	89.302	89.465	0.26228	89.337	89.514	89.74	0.15738	-0.0489	0.21192	0.5814	0.25206
100	88.89	89.632	89.993	0.46457	89.167	89.761	90.245	0.39059	-0.2712	0.12884	0.4448	0.30425
110	88.869	89.486	89.905	0.43172	88.623	89.196	89.697	0.52178	-0.7254	-0.29	0.2712	0.39696

Device Test: 71.6 POWER_GOOD|//RISE_THRESHOLD/6N0V///@V_PG_RISE





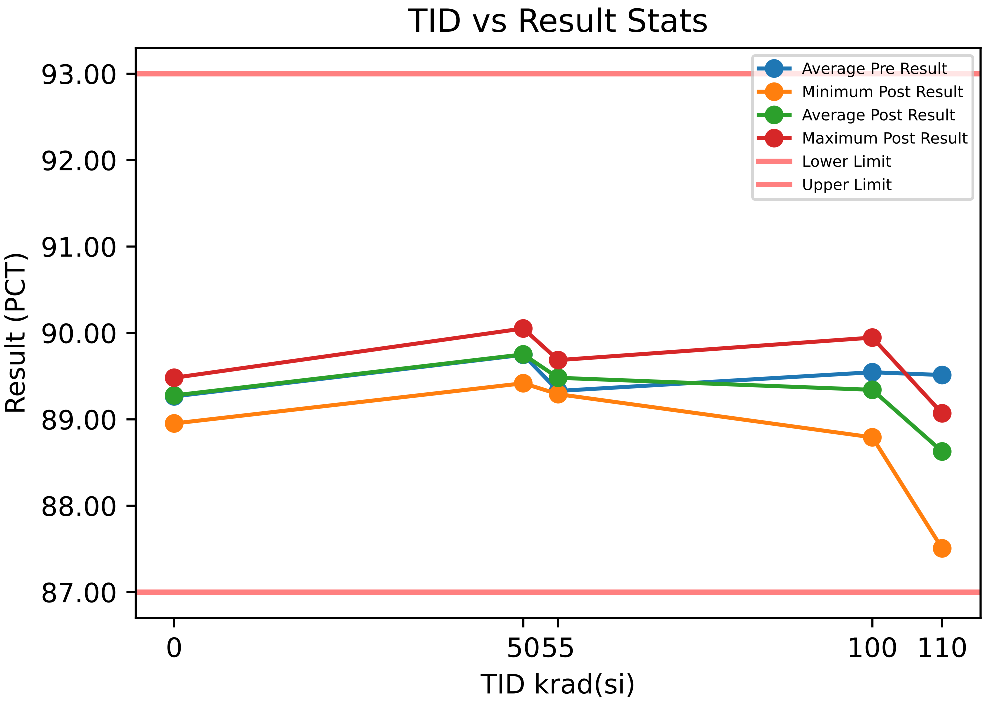
Test Results (Lower Limit = 92.0, Upper Limit = 98.0 (PCT))

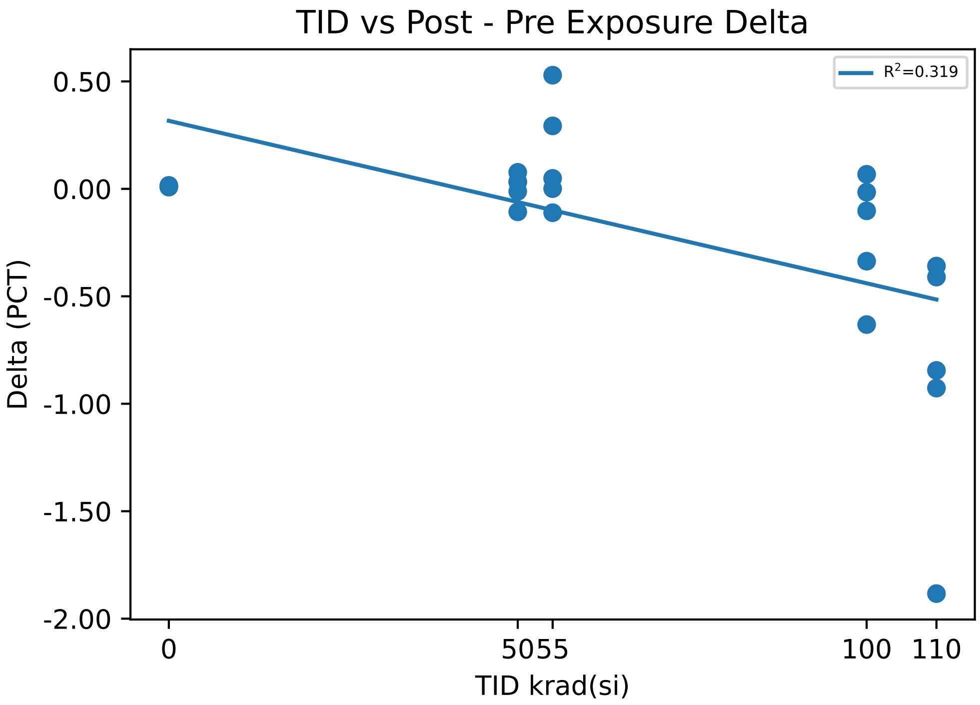
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	93.936	93.956	0.0198
2	0	CU	94.57	94.576	0.0058
3	0	CU	94.833	94.852	0.0191
40	50	50krad Unbiased	94.983	95.587	0.6044
41	50	50krad Unbiased	95.362	95.513	0.1506
42	50	50krad Unbiased	94.726	94.946	0.2203
43	50	50krad Unbiased	94.61	94.707	0.0976
44	50	50krad Unbiased	95.172	95.123	-0.0492
45	55	50krad Biased	94.769	94.662	-0.1069
46	55	50krad Biased	94.829	94.959	0.1301
47	55	50krad Biased	94.516	94.323	-0.1937
48	55	50krad Biased	94.231	94.594	0.3633
49	55	50krad Biased	94.789	94.6	-0.1883
50	100	100krad Unbiased	94.817	94.862	0.0453
51	100	100krad Unbiased	95.237	95.125	-0.1125
52	100	100krad Unbiased	94.408	94.279	-0.1289
53	100	100krad Unbiased	95.222	95.314	0.0922
54	100	100krad Unbiased	94.784	95.006	0.2221
55	110	100krad Biased	94.557	93.951	-0.6061
56	110	100krad Biased	94.972	94.744	-0.2283
57	110	100krad Biased	94.853	94.798	-0.0545
58	110	100krad Biased	94.715	94.567	-0.1478
59	110	100krad Biased	94.247	93.912	-0.3348

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	93.936	94.446	94.833	0.46085	93.956	94.461	94.852	0.45874	0.0058	0.0149	0.0198	0.0078886
50	94.61	94.971	95.362	0.30997	94.707	95.175	95.587	0.37357	-0.0492	0.20474	0.6044	0.24437
55	94.231	94.627	94.829	0.25305	94.323	94.628	94.959	0.22687	-0.1937	0.0009	0.3633	0.24151
100	94.408	94.894	95.237	0.34631	94.279	94.917	95.314	0.39328	-0.1289	0.02364	0.2221	0.14693
110	94.247	94.669	94.972	0.28214	93.912	94.395	94.798	0.43134	-0.6061	-0.2743	-0.0545	0.21224

Device Test: 71.7 POWER_GOOD|//FALL_THRESHOLD/6N0V///@V_PG_FALL





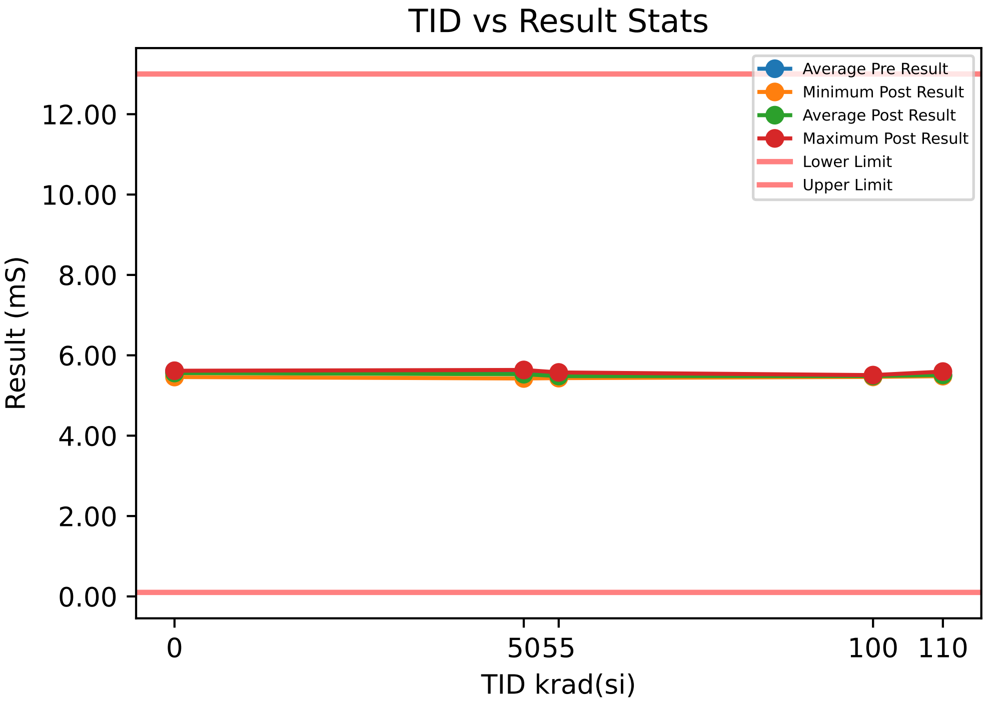
Test Results (Lower Limit = 87.0, Upper Limit = 93.0 (PCT))

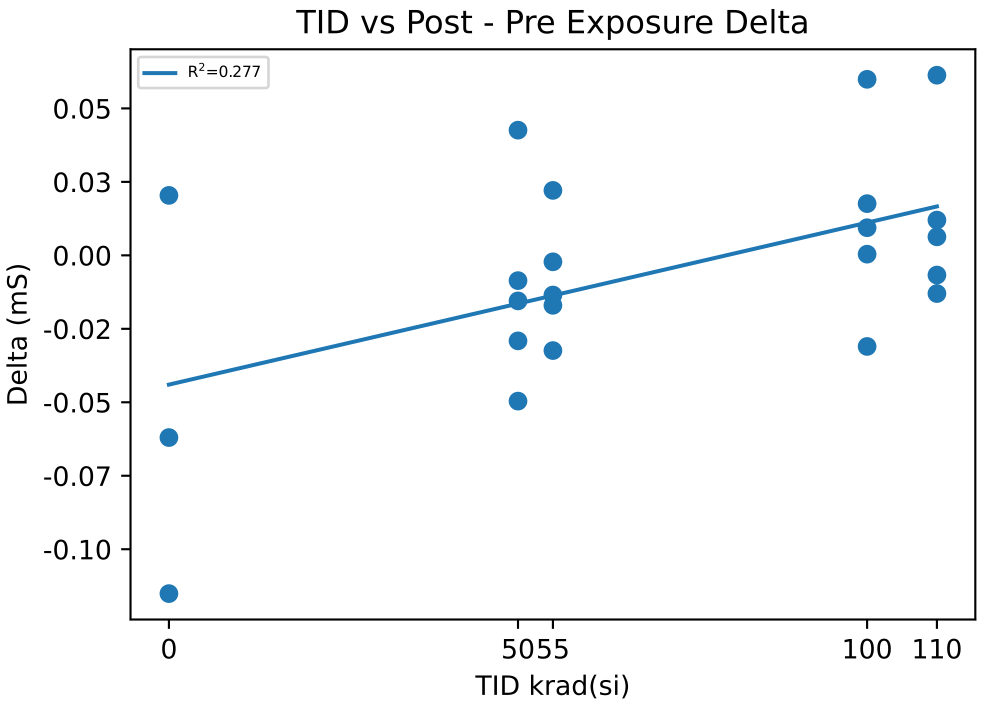
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	88.936	88.953	0.0162
2	0	CU	89.473	89.481	0.0081
3	0	CU	89.387	89.397	0.01
40	50	50krad Unbiased	89.921	89.954	0.0332
41	50	50krad Unbiased	89.975	90.052	0.0769
42	50	50krad Unbiased	89.43	89.418	-0.0118
43	50	50krad Unbiased	89.463	89.494	0.0312
44	50	50krad Unbiased	89.947	89.84	-0.107
45	55	50krad Biased	89.47	89.471	0.001
46	55	50krad Biased	89.393	89.686	0.293
47	55	50krad Biased	89.403	89.291	-0.111
48	55	50krad Biased	88.871	89.4	0.5288
49	55	50krad Biased	89.508	89.556	0.0487
50	100	100krad Unbiased	89.36	89.428	0.0677
51	100	100krad Unbiased	90.024	89.392	-0.6315
52	100	100krad Unbiased	88.894	88.792	-0.1023
53	100	100krad Unbiased	89.962	89.946	-0.0156
54	100	100krad Unbiased	89.487	89.15	-0.3366
55	110	100krad Biased	89.39	87.507	-1.8833
56	110	100krad Biased	89.915	89.07	-0.8449
57	110	100krad Biased	89.953	89.026	-0.9271
58	110	100krad Biased	89.427	89.067	-0.3593
59	110	100krad Biased	88.88	88.47	-0.4104

Test Statistics (PCT)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	88.936	89.266	89.473	0.2884	88.953	89.277	89.481	0.28417	0.0081	0.011433	0.0162	0.004236
50	89.43	89.747	89.975	0.27555	89.418	89.752	90.052	0.28137	-0.107	0.0045	0.0769	0.069779
55	88.871	89.329	89.508	0.26006	89.291	89.481	89.686	0.15008	-0.111	0.1521	0.5288	0.25715
100	88.894	89.545	90.024	0.46485	88.792	89.342	89.946	0.42266	-0.6315	-0.20366	0.0677	0.28284
110	88.88	89.513	89.953	0.44111	87.507	88.628	89.07	0.67621	-1.8833	-0.885	-0.3593	0.6127

Device Test: 75.1 CPOUT|//DISCHARGE_TIME///3/@I_CP_DISCHARGE





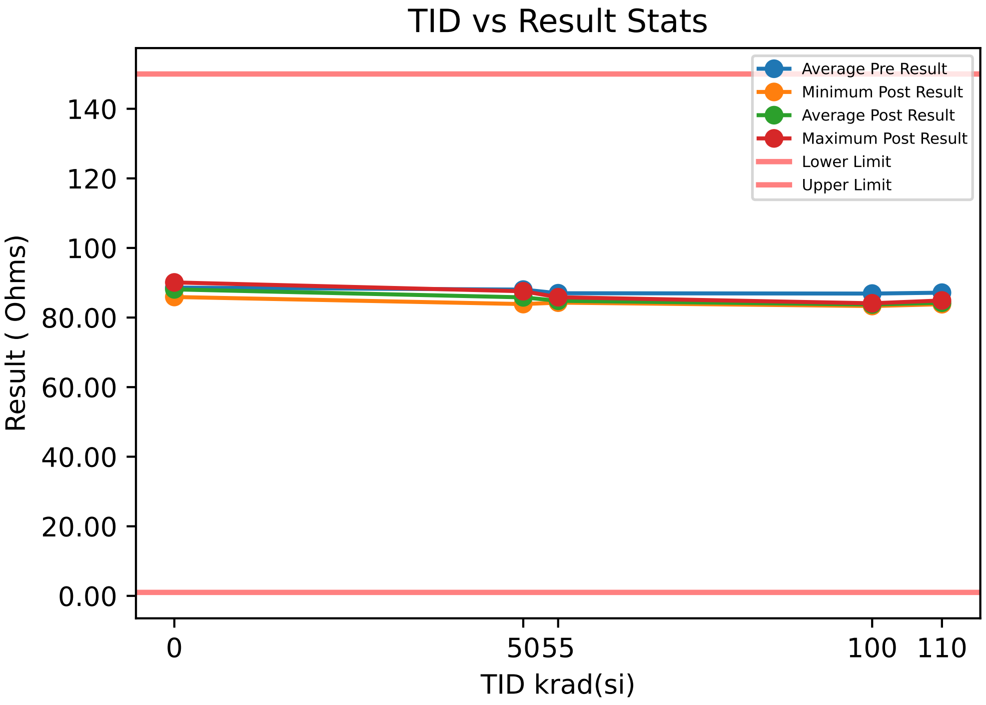
Test Results (Lower Limit = 0.1, Upper Limit = 13.0 (mS))

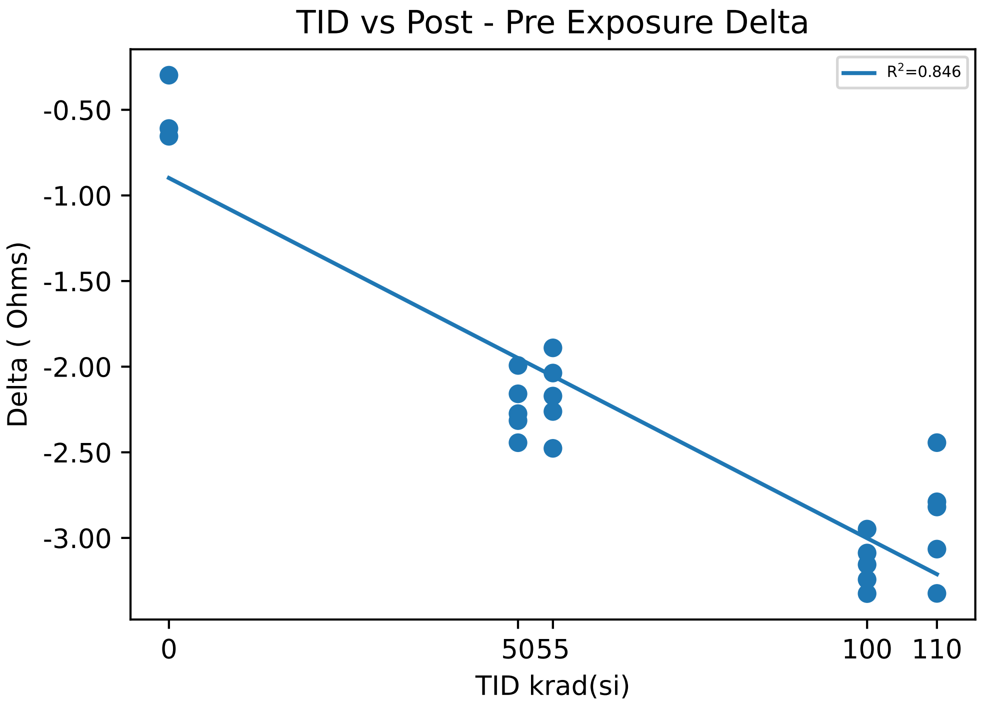
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	5.5213	5.4593	-0.062
2	0	CU	5.5805	5.6009	0.0204
3	0	CU	5.7308	5.6157	-0.1151
40	50	50krad Unbiased	5.5562	5.5476	-0.0086
41	50	50krad Unbiased	5.5871	5.5716	-0.0155
42	50	50krad Unbiased	5.4968	5.4677	-0.0291
43	50	50krad Unbiased	5.4726	5.423	-0.0496
44	50	50krad Unbiased	5.5931	5.6357	0.0426
45	55	50krad Biased	5.5425	5.5255	-0.017
46	55	50krad Biased	5.4816	5.4492	-0.0324
47	55	50krad Biased	5.4099	5.432	0.0221
48	55	50krad Biased	5.5874	5.5739	-0.0135
49	55	50krad Biased	5.4343	5.4321	-0.0022
50	100	100krad Unbiased	5.4918	5.5012	0.0094
51	100	100krad Unbiased	5.4646	5.4822	0.0176
52	100	100krad Unbiased	5.4682	5.4686	0.0004
53	100	100krad Unbiased	5.4928	5.4618	-0.031
54	100	100krad Unbiased	5.4473	5.5072	0.0599
55	110	100krad Biased	5.4908	5.5028	0.012
56	110	100krad Biased	5.4745	5.4808	0.0063
57	110	100krad Biased	5.5337	5.595	0.0613
58	110	100krad Biased	5.4952	5.4885	-0.0067
59	110	100krad Biased	5.4989	5.4859	-0.013

Test Statistics (mS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5213	5.6109	5.7308	0.108	5.4593	5.5586	5.6157	0.086343	-0.1151	-0.052233	0.0204	0.068276
50	5.4726	5.5412	5.5931	0.05409	5.423	5.5291	5.6357	0.084468	-0.0496	-0.01204	0.0426	0.034319
55	5.4099	5.4911	5.5874	0.073867	5.432	5.4825	5.5739	0.064036	-0.0324	-0.0086	0.0221	0.020276
100	5.4473	5.4729	5.4928	0.019362	5.4618	5.4842	5.5072	0.019793	-0.031	0.01126	0.0599	0.032838
110	5.4745	5.4986	5.5337	0.02171	5.4808	5.5106	5.595	0.047882	-0.013	0.01198	0.0613	0.029316

Device Test: 75.2 CPOUT|//DISHARGE_RESISTANCE///3/@R_CP_DISCHARGE





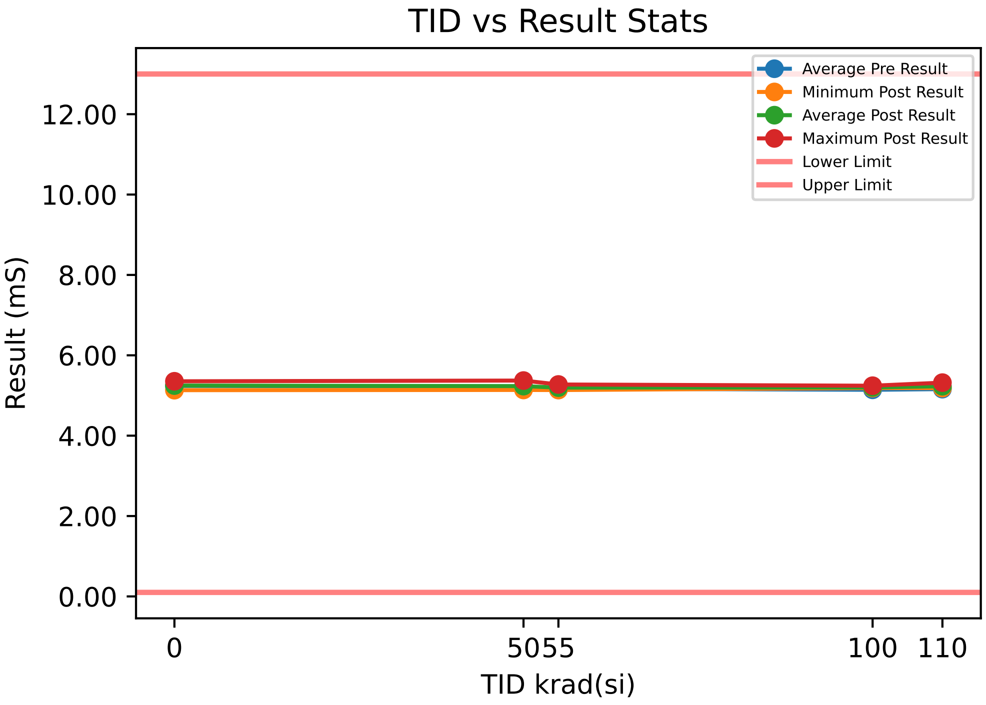
Test Results (Lower Limit = 1.0, Upper Limit = 150.0 (Ohms))

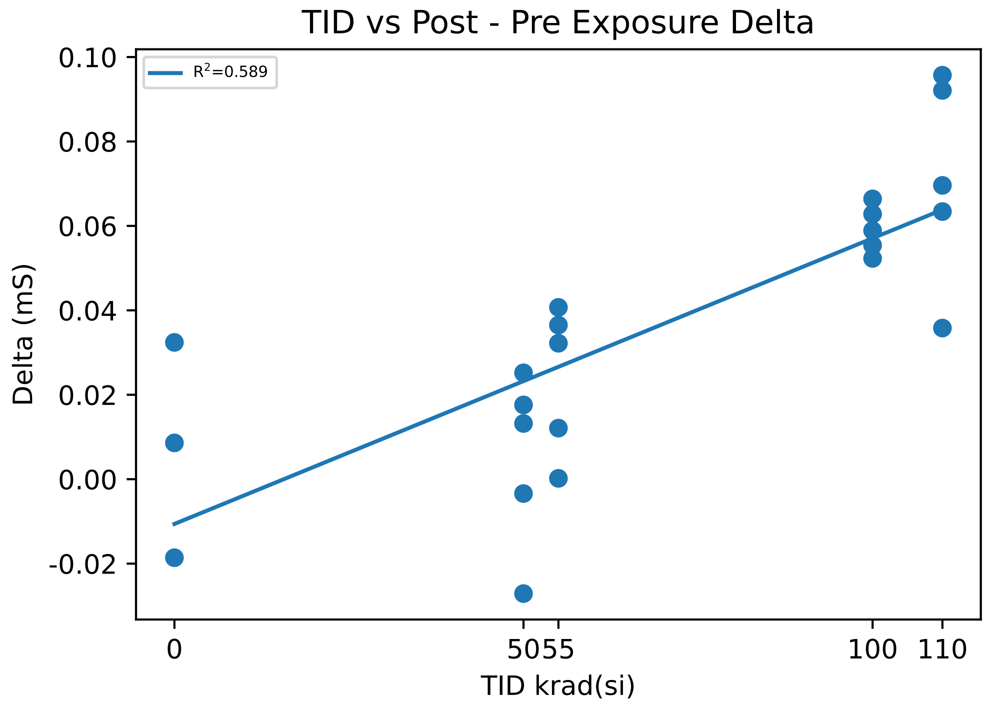
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	86.518	85.909	-0.6092
2	0	CU	88.565	88.267	-0.2979
3	0	CU	90.749	90.094	-0.6547
40	50	50krad Unbiased	88.512	86.197	-2.3149
41	50	50krad Unbiased	88.701	86.708	-1.9928
42	50	50krad Unbiased	86.932	84.658	-2.2743
43	50	50krad Unbiased	86.317	83.873	-2.444
44	50	50krad Unbiased	89.713	87.555	-2.1585
45	55	50krad Biased	87.47	85.208	-2.2617
46	55	50krad Biased	86.925	84.448	-2.4769
47	55	50krad Biased	86.207	84.317	-1.8901
48	55	50krad Biased	88.011	85.84	-2.1716
49	55	50krad Biased	86.321	84.284	-2.0371
50	100	100krad Unbiased	86.755	83.666	-3.0881
51	100	100krad Unbiased	86.631	83.306	-3.3251
52	100	100krad Unbiased	87.29	84.047	-3.2432
53	100	100krad Unbiased	86.73	83.574	-3.1559
54	100	100krad Unbiased	87.048	84.099	-2.9485
55	110	100krad Biased	86.938	84.149	-2.7891
56	110	100krad Biased	87.357	84.292	-3.0653
57	110	100krad Biased	87.354	84.91	-2.4436
58	110	100krad Biased	87.152	83.828	-3.324
59	110	100krad Biased	86.933	84.114	-2.8193

Test Statistics (Ohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.518	88.611	90.749	2.1157	85.909	88.09	90.094	2.0981	-0.6547	-0.5206	-0.2979	0.1942
50	86.317	88.035	89.713	1.3836	83.873	85.798	87.555	1.5068	-2.444	-2.2369	-1.9928	0.17037
55	86.207	86.987	88.011	0.76462	84.284	84.819	85.84	0.68362	-2.4769	-2.1675	-1.8901	0.22281
100	86.631	86.891	87.29	0.27214	83.306	83.739	84.099	0.33346	-3.3251	-3.1522	-2.9485	0.14473
110	86.933	87.147	87.357	0.20998	83.828	84.259	84.91	0.40129	-3.324	-2.8883	-2.4436	0.32921

Device Test: 75.3 CPOUT|//DISCHARGE_TIME///6.3/@I_CP_DISCHARGE





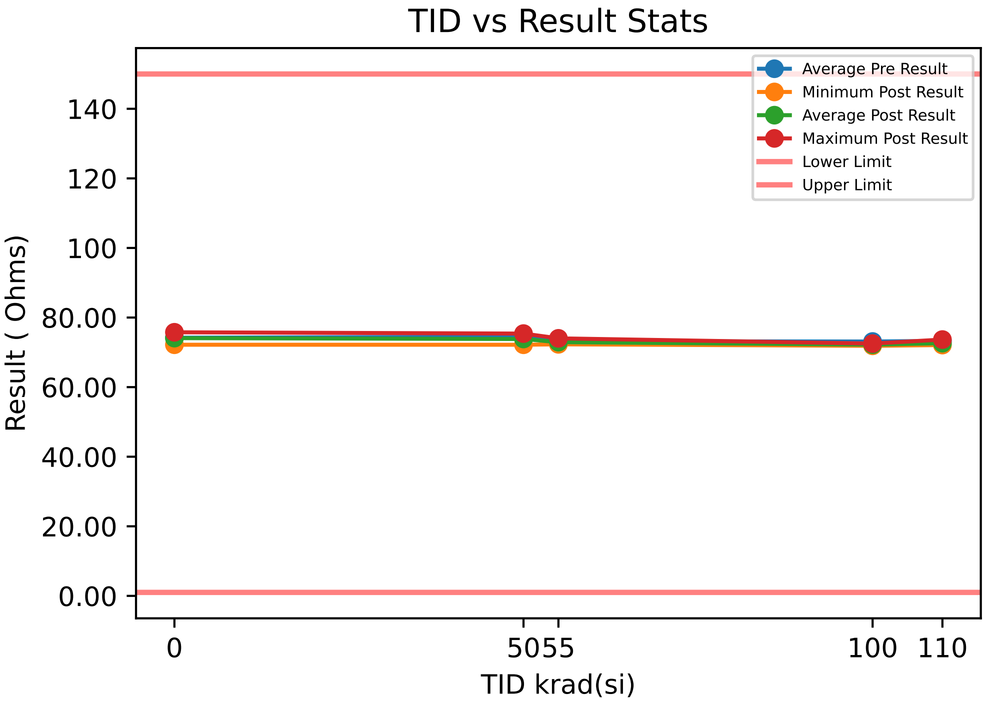
Test Results (Lower Limit = 0.1, Upper Limit = 13.0 (mS))

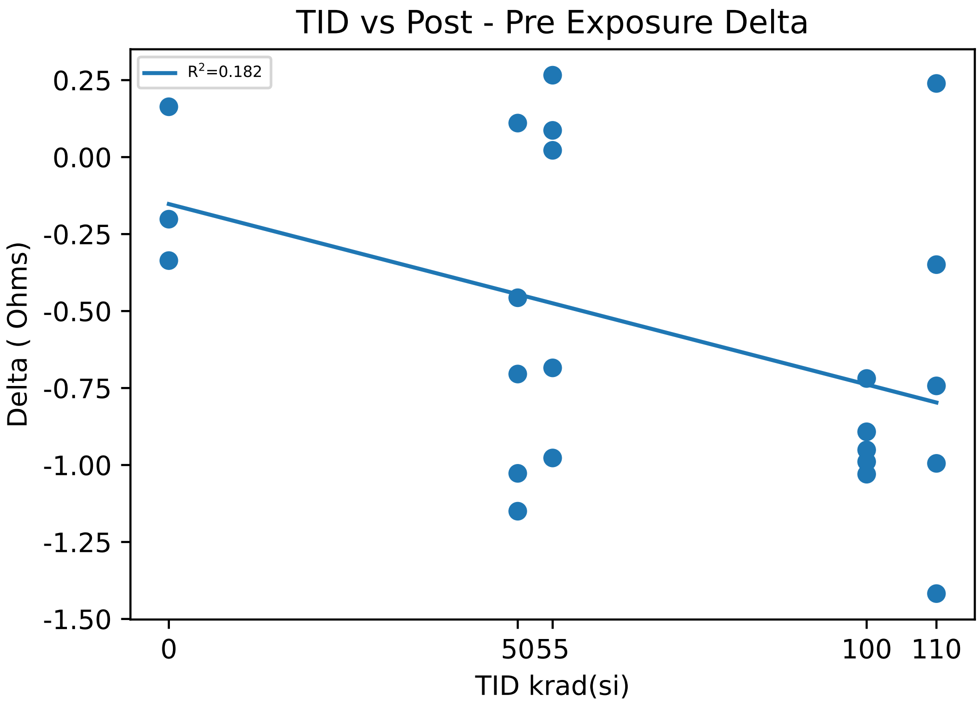
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	5.1508	5.1322	-0.0186
2	0	CU	5.2224	5.2548	0.0324
3	0	CU	5.3447	5.3533	0.0086
40	50	50krad Unbiased	5.2798	5.2527	-0.0271
41	50	50krad Unbiased	5.2381	5.2347	-0.0034
42	50	50krad Unbiased	5.1417	5.1669	0.0252
43	50	50krad Unbiased	5.12	5.1376	0.0176
44	50	50krad Unbiased	5.3583	5.3715	0.0132
45	55	50krad Biased	5.213	5.2537	0.0407
46	55	50krad Biased	5.1223	5.1588	0.0365
47	55	50krad Biased	5.1459	5.158	0.0121
48	55	50krad Biased	5.2416	5.2738	0.0322
49	55	50krad Biased	5.1347	5.1349	0.0002
50	100	100krad Unbiased	5.1878	5.2432	0.0554
51	100	100krad Unbiased	5.1349	5.1872	0.0523
52	100	100krad Unbiased	5.1188	5.1852	0.0664
53	100	100krad Unbiased	5.122	5.1848	0.0628
54	100	100krad Unbiased	5.1438	5.2027	0.0589
55	110	100krad Biased	5.1688	5.2384	0.0696
56	110	100krad Biased	5.1488	5.1846	0.0358
57	110	100krad Biased	5.2276	5.3197	0.0921
58	110	100krad Biased	5.1302	5.1936	0.0634
59	110	100krad Biased	5.1174	5.2131	0.0957

Test Statistics (mS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.1508	5.2393	5.3447	0.098049	5.1322	5.2468	5.3533	0.11077	-0.0186	0.0074667	0.0324	0.025519
50	5.12	5.2276	5.3583	0.098583	5.1376	5.2327	5.3715	0.090889	-0.0271	0.0051	0.0252	0.020826
55	5.1223	5.1715	5.2416	0.052599	5.1349	5.1958	5.2738	0.063133	0.0002	0.02434	0.0407	0.017391
100	5.1188	5.1415	5.1878	0.027785	5.1848	5.2006	5.2432	0.024928	0.0523	0.05916	0.0664	0.0056332
110	5.1174	5.1586	5.2276	0.0432	5.1846	5.2299	5.3197	0.054287	0.0358	0.07132	0.0957	0.024257

Device Test: 75.4 CPOUT|//DISHARGE_RESISTANCE///6.3/@R_CP_DISCHARGE





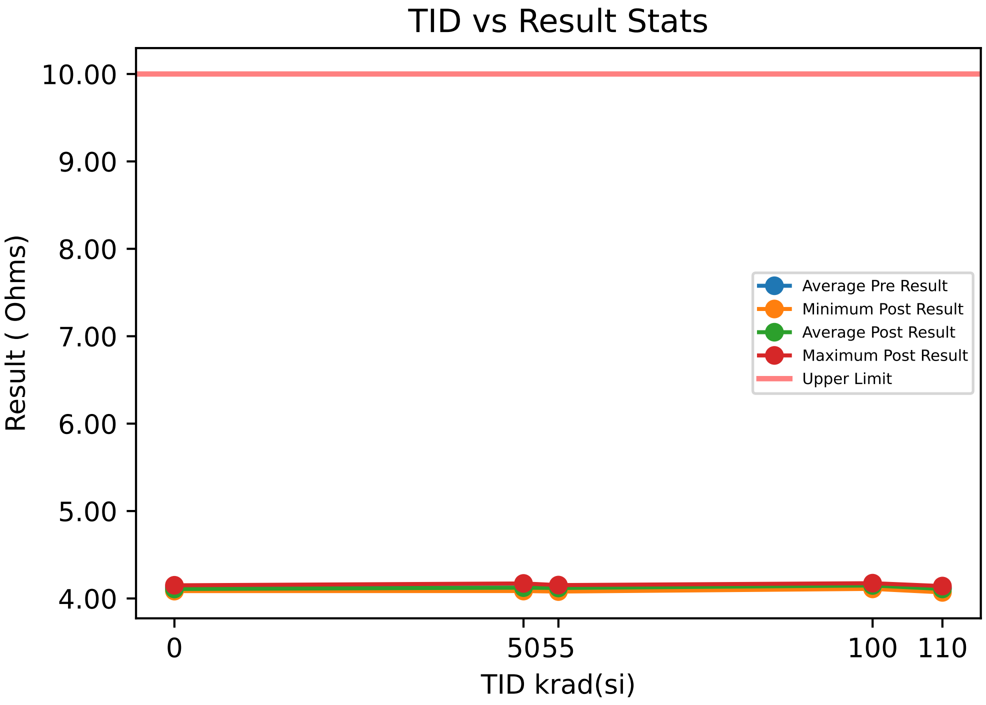
Test Results (Lower Limit = 1.0, Upper Limit = 150.0 (Ohms))

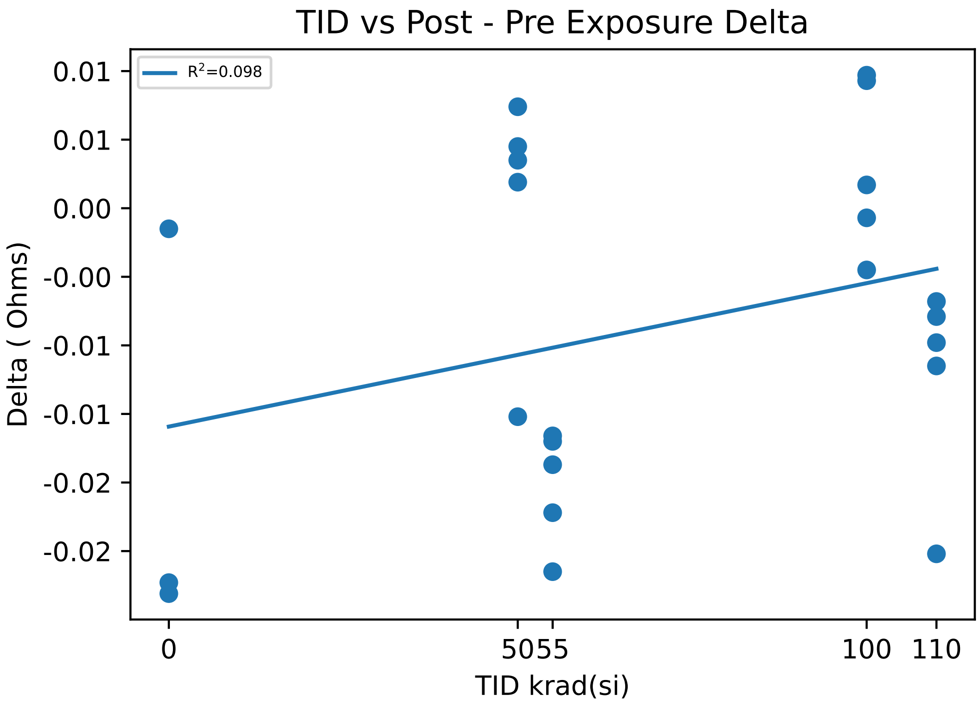
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	72.518	72.182	-0.3361
2	0	CU	74.136	74.3	0.1635
3	0	CU	75.967	75.765	-0.2016
40	50	50krad Unbiased	75.499	74.349	-1.15
41	50	50krad Unbiased	74.305	74.415	0.1105
42	50	50krad Unbiased	73.26	72.803	-0.4568
43	50	50krad Unbiased	72.884	72.18	-0.7045
44	50	50krad Unbiased	76.416	75.389	-1.0271
45	55	50krad Biased	73.148	73.235	0.0868
46	55	50krad Biased	72.415	72.437	0.022
47	55	50krad Biased	73.285	72.6	-0.6845
48	55	50krad Biased	73.754	74.02	0.266
49	55	50krad Biased	73.278	72.301	-0.9771
50	100	100krad Unbiased	73.549	72.519	-1.0298
51	100	100krad Unbiased	72.854	71.962	-0.8921
52	100	100krad Unbiased	73.128	72.139	-0.9893
53	100	100krad Unbiased	72.826	71.875	-0.9511
54	100	100krad Unbiased	73.217	72.498	-0.719
55	110	100krad Biased	73.959	72.541	-1.4176
56	110	100krad Biased	73.402	72.407	-0.9947
57	110	100krad Biased	74.021	73.672	-0.3492
58	110	100krad Biased	72.835	72.092	-0.743
59	110	100krad Biased	72.184	72.423	0.2392

Test Statistics (Ohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	72.518	74.207	75.967	1.7254	72.182	74.082	75.765	1.8015	-0.3361	-0.12473	0.1635	0.25852
50	72.884	74.473	76.416	1.4877	72.18	73.827	75.389	1.3059	-1.15	-0.64558	0.1105	0.50268
55	72.415	73.176	73.754	0.48379	72.301	72.919	74.02	0.71221	-0.9771	-0.25736	0.266	0.54103
100	72.826	73.115	73.549	0.29594	71.875	72.199	72.519	0.29855	-1.0298	-0.91626	-0.719	0.12138
110	72.184	73.28	74.021	0.77845	72.092	72.627	73.672	0.60715	-1.4176	-0.65306	0.2392	0.63202

Device Test: 80.1 CPOUT|//OUTPUT_RESISTANCE//150mA/3/@R_CP_OUT_3V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

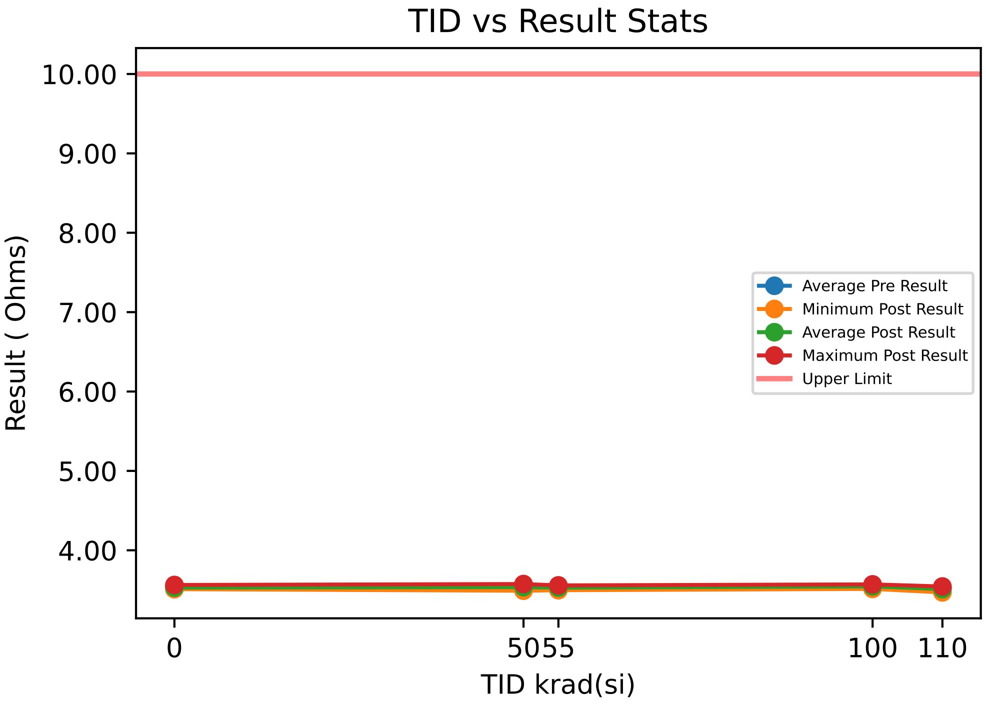
Test Results (Upper Limit = 10.0 (Ohms))

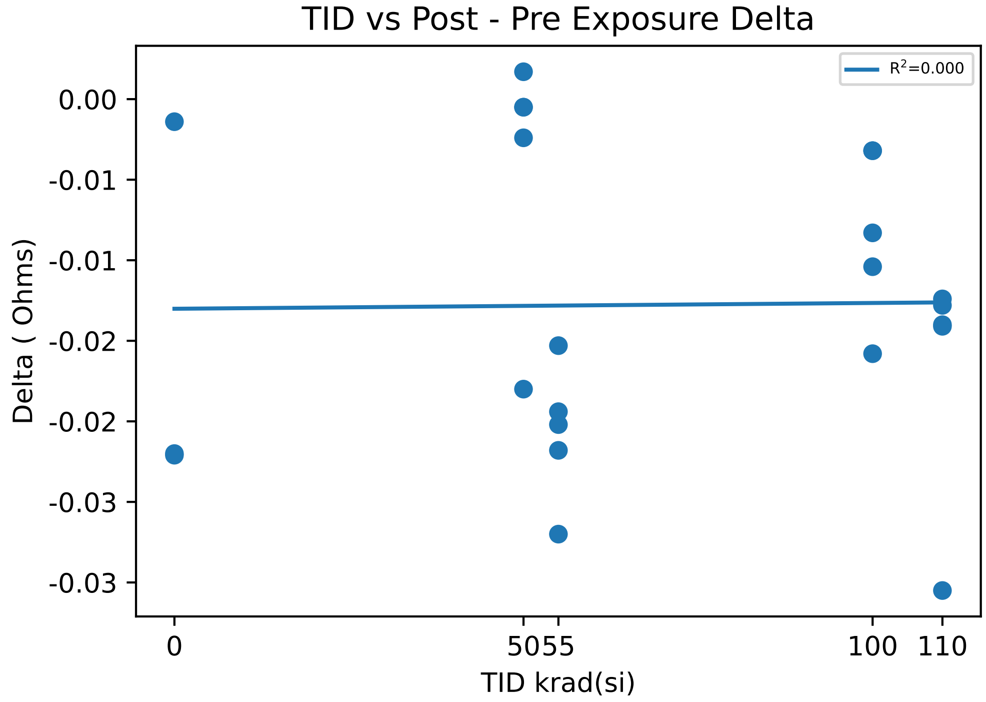
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	4.1787	4.1506	-0.0281
2	0	CU	4.0914	4.0899	-0.0015
3	0	CU	4.1113	4.084	-0.0273
40	50	50krad Unbiased	4.128	4.1354	0.0074
41	50	50krad Unbiased	4.0998	4.0846	-0.0152
42	50	50krad Unbiased	4.1673	4.1718	0.0045
43	50	50krad Unbiased	4.128	4.1299	0.0019
44	50	50krad Unbiased	4.0928	4.0963	0.0035
45	55	50krad Biased	4.0975	4.0788	-0.0187
46	55	50krad Biased	4.1477	4.1307	-0.017
47	55	50krad Biased	4.1752	4.153	-0.0222
48	55	50krad Biased	4.1096	4.0831	-0.0265
49	55	50krad Biased	4.1687	4.1521	-0.0166
50	100	100krad Unbiased	4.1544	4.1641	0.0097
51	100	100krad Unbiased	4.1655	4.1748	0.0093
52	100	100krad Unbiased	4.1553	4.1508	-0.0045
53	100	100krad Unbiased	4.1409	4.1426	0.0017
54	100	100krad Unbiased	4.11	4.1093	-0.0007
55	110	100krad Biased	4.0761	4.0693	-0.0068
56	110	100krad Biased	4.1313	4.1198	-0.0115
57	110	100krad Biased	4.1191	4.1093	-0.0098
58	110	100krad Biased	4.1498	4.1419	-0.0079
59	110	100krad Biased	4.1279	4.1027	-0.0252

Test Statistics (Ohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0914	4.1271	4.1787	0.045753	4.084	4.1082	4.1506	0.036867	-0.0281	-0.018967	-0.0015	0.015132
50	4.0928	4.1232	4.1673	0.029422	4.0846	4.1236	4.1718	0.034527	-0.0152	0.00042	0.0074	0.0089586
55	4.0975	4.1397	4.1752	0.034828	4.0788	4.1195	4.153	0.036373	-0.0265	-0.0202	-0.0166	0.0041575
100	4.11	4.1452	4.1655	0.021542	4.1093	4.1483	4.1748	0.025058	-0.0045	0.0031	0.0097	0.0062482
110	4.0761	4.1208	4.1498	0.027398	4.0693	4.1086	4.1419	0.026524	-0.0252	-0.01224	-0.0068	0.0074648

Device Test: 80.2 CPOUT|//OUTPUT_RESISTANCE//250mA/5/@R_CP_OUT_5V





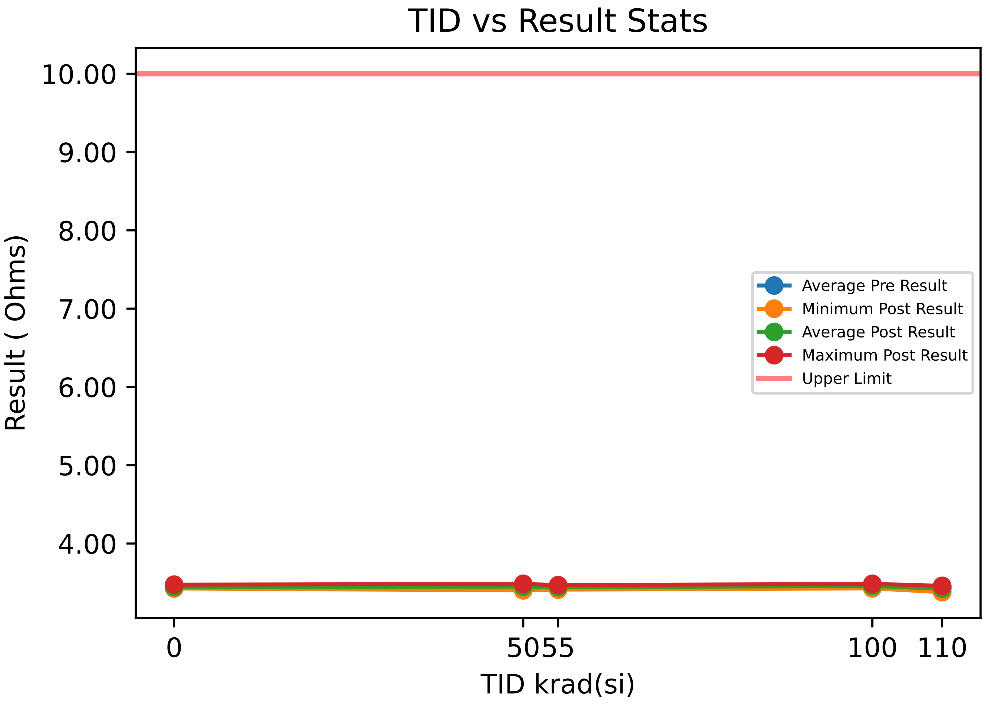
Test Results (Upper Limit = 10.0 (Ohms))

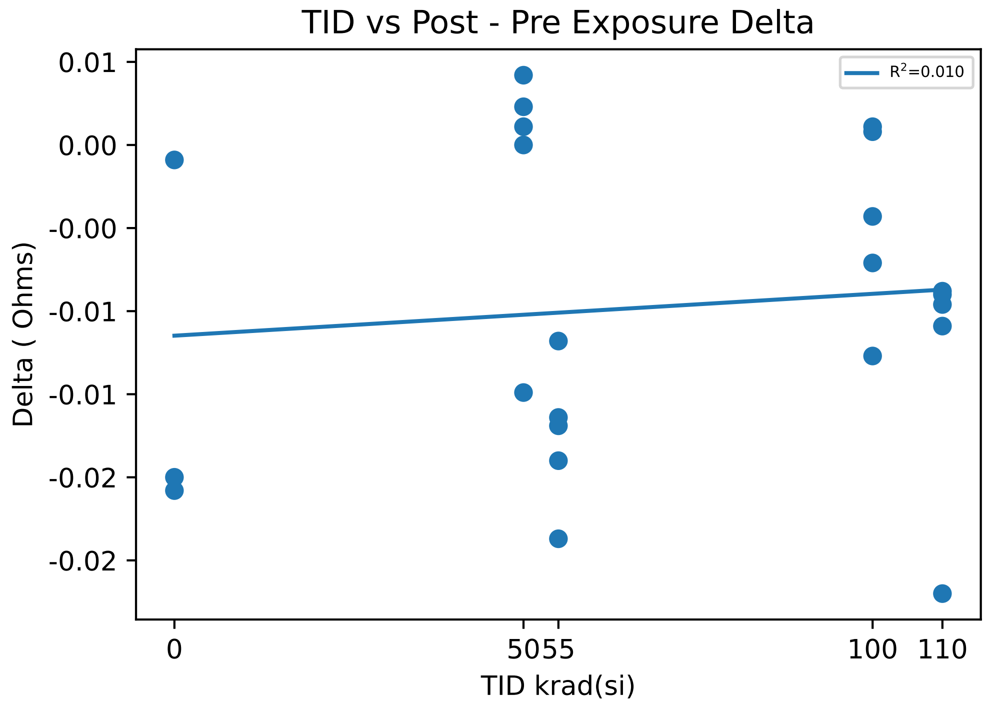
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	3.5848	3.5627	-0.0221
2	0	CU	3.5115	3.5101	-0.0014
3	0	CU	3.54	3.518	-0.022
40	50	50krad Unbiased	3.5386	3.5403	0.0017
41	50	50krad Unbiased	3.5086	3.4906	-0.018
42	50	50krad Unbiased	3.575	3.5745	-0.0005
43	50	50krad Unbiased	3.5324	3.53	-0.0024
44	50	50krad Unbiased	3.5446	3.5441	-0.0005
45	55	50krad Biased	3.519	3.4972	-0.0218
46	55	50krad Biased	3.5485	3.5291	-0.0194
47	55	50krad Biased	3.5777	3.5575	-0.0202
48	55	50krad Biased	3.5366	3.5096	-0.027
49	55	50krad Biased	3.569	3.5537	-0.0153
50	100	100krad Unbiased	3.5735	3.5703	-0.0032
51	100	100krad Unbiased	3.5708	3.5676	-0.0032
52	100	100krad Unbiased	3.5501	3.5343	-0.0158
53	100	100krad Unbiased	3.55	3.5417	-0.0083
54	100	100krad Unbiased	3.5238	3.5134	-0.0104
55	110	100krad Biased	3.4818	3.4694	-0.0124
56	110	100krad Biased	3.5279	3.5151	-0.0128
57	110	100krad Biased	3.5379	3.5239	-0.014
58	110	100krad Biased	3.5578	3.5437	-0.0141
59	110	100krad Biased	3.5326	3.5021	-0.0305

Test Statistics (Ohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5115	3.5454	3.5848	0.036951	3.5101	3.5303	3.5627	0.028364	-0.0221	-0.015167	-0.0014	0.011922
50	3.5086	3.5398	3.575	0.023936	3.4906	3.5359	3.5745	0.030263	-0.018	-0.00394	0.0017	0.0079927
55	3.519	3.5502	3.5777	0.023827	3.4972	3.5294	3.5575	0.0265	-0.027	-0.02074	-0.0153	0.0042424
100	3.5238	3.5536	3.5735	0.020032	3.5134	3.5455	3.5703	0.023842	-0.0158	-0.00818	-0.0032	0.0053058
110	3.4818	3.5276	3.5578	0.028022	3.4694	3.5108	3.5437	0.027668	-0.0305	-0.01676	-0.0124	0.0077164

Device Test: 80.3 CPOUT|//OUTPUT_RESISTANCE//250mA/6.3/@R_CP_OUT_6P3V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Upper Limit = 10.0 (Ohms))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU	3.4942	3.4742	-0.02
2	0	CU	3.4271	3.4262	-0.0009
3	0	CU	3.4551	3.4343	-0.0208
40	50	50krad Unbiased	3.4481	3.4523	0.0042
41	50	50krad Unbiased	3.4166	3.4017	-0.0149
42	50	50krad Unbiased	3.4829	3.4852	0.0023
43	50	50krad Unbiased	3.4365	3.4365	0
44	50	50krad Unbiased	3.4746	3.4757	0.0011
45	55	50krad Biased	3.4303	3.4113	-0.019
46	55	50krad Biased	3.4549	3.4385	-0.0164
47	55	50krad Biased	3.4847	3.4678	-0.0169
48	55	50krad Biased	3.4504	3.4267	-0.0237
49	55	50krad Biased	3.476	3.4642	-0.0118
50	100	100krad Unbiased	3.4841	3.4852	0.0011
51	100	100krad Unbiased	3.4796	3.4804	0.0008
52	100	100krad Unbiased	3.4535	3.4408	-0.0127
53	100	100krad Unbiased	3.4569	3.4526	-0.0043
54	100	100krad Unbiased	3.4346	3.4275	-0.0071
55	110	100krad Biased	3.3885	3.3789	-0.0096
56	110	100krad Biased	3.4355	3.4267	-0.0088
57	110	100krad Biased	3.449	3.44	-0.009
58	110	100krad Biased	3.47	3.4591	-0.0109
59	110	100krad Biased	3.4387	3.4117	-0.027

Test Statistics (Ohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.4271	3.4588	3.4942	0.033703	3.4262	3.4449	3.4742	0.025696	-0.0208	-0.0139	-0.0009	0.011265
50	3.4166	3.4517	3.4829	0.027267	3.4017	3.4503	3.4852	0.03324	-0.0149	-0.00146	0.0042	0.0076729
55	3.4303	3.4593	3.4847	0.021585	3.4113	3.4417	3.4678	0.024222	-0.0237	-0.01756	-0.0118	0.0043224
100	3.4346	3.4617	3.4841	0.020291	3.4275	3.4573	3.4852	0.024972	-0.0127	-0.00444	0.0011	0.0057765
110	3.3885	3.4363	3.47	0.029951	3.3789	3.4233	3.4591	0.030323	-0.027	-0.01306	-0.0088	0.0078357

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES “AS IS” AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI’s products are provided subject to TI’s Terms of Sale, TI’s General Quality Guidelines, or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI’s provision of these resources does not expand or otherwise alter TI’s applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2026, Texas Instruments Incorporated

Last updated 10/2025